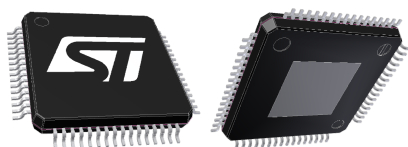


Automotive front door device with CAN FD and LIN



LQFP64L exposed pad down
(10x10x1.4 mm)

Product status link

[L99DZ300G](#)

Product summary

Order code	L99DZ300GTR
Package	LQFP-64
Packing	Tape and reel

Features



- AEC-Q100 qualified
- 1 half bridge for 7.5 A load ($R_{ON} = 100 \text{ m}\Omega$)
- 1 half bridge for 6 A load ($R_{ON} = 150 \text{ m}\Omega$)
- 2 half bridges for 0.5 A load ($R_{ON} = 1600 \text{ m}\Omega$)
- 2 half bridges for 3 A load ($R_{ON} = 300 \text{ m}\Omega$)
- 1 configurable high-side driver for up to 1.5 A ($R_{ON} = 300 \text{ m}\Omega$) or 0.35 A ($R_{ON} = 1600 \text{ m}\Omega$) load
- 2 high-side drivers for 0.5 A ($R_{ON} = 1.4 \text{ }\Omega$)
- 1 high-side driver for 0.5 A ($R_{ON} = 1.4 \text{ }\Omega$) to supply EC glass MOSFET
- 6 high-side drivers for 0.15 A ($R_{ON} = 7 \text{ }\Omega$)
- CAN FD transceiver supporting communication up to 5 Mbit/s (ISO 11898-2/2016 and SAE J2284 compliant) with local failure and bus failure diagnosis
- LIN transceiver ISO 17987-4/2016 compliant
- Advanced lock & fold closing by means of PWM control on HB1-HB6 and HB4-HB5
- Advanced short-circuit detection on all the half bridges
- All HS drivers with constant current mode at start-up to drive capacitive loads
- Internal 10-bit PWM timer for each stand-alone high-side driver
- Buffered supply for voltage regulators and 2 high-side drivers (HS15&HS0/both P-channel) to supply, for example, external contacts
- Programmable overcurrent recovery function, to drive loads with higher inrush currents as current limitation value (for HB1-HB6, HS7-HS10)
- Flexible HS drivers (HS7-HS15 and HS0), suitable to drive external LED modules with high input capacitance value
- Programmable periodic system wake-up feature
- Complete 2-channel contact monitoring interface, with programmable cyclic sense functionality, one of them also with DIR functionality
- Dedicated debug input pin
- Configurable window watchdog
- STM standard serial peripheral interface (32-bit/ST-SPI 4.0)
- Programmable reset generator for power-on and undervoltage
- Ultra low-quiescent current in standby modes
- No electrolytic capacitor required on regulator outputs
- Two 5 V voltage regulators for microcontroller and peripheral supply
- Central two-stage charge pumps
- Control block for electrochromic element
- Driver for external MOSFET in high-side configuration with SC protection/diagnosis and open-load diagnosis
- Motor bridge driver for 4 external MOSFETs, in H-bridge configuration with short-circuit protection/diagnosis and open-load diagnosis
- Diagnostic functions
- Current monitor output for all internal high-side drivers

- Digital thermal clusters
- Device contains temperature warning and protection
- Open-load diagnosis for all the outputs
- Overcurrent protection for all the outputs

Description

The L99DZ300G is a door zone system IC providing electronic control modules with enhanced power management power supply functionality, including various standby modes, as well as LIN and CAN FD physical communication layers. The device has two low drop voltage regulators to supply the system microcontroller and external peripheral loads such as sensors and provides enhanced system standby functionality with programmable local and remote wake-up capability. Moreover, the 10 high-side drivers (9 to supply LEDs and 1 to supply bulbs) increase the system integration level; all the high-side drivers support the constant current mode for LED module with high input capacitance. Up to 5 DC motors and 4 external MOS transistors in H-bridge configuration can be driven in PWM mode up to 25 kHz. An additional gate drive can control an external MOSFET in high-side configuration to supply a resistive load connected to GND (for example mirror heater). An electrochromic mirror glass can be controlled using the integrated SPI-driven module in conjunction with an external MOS transistor. All the outputs are SC protected and implement an open-load diagnosis. The ST standard SPI interface (4.0) allows control and diagnosis of the device and enables generic software development.

1 Block diagram and pin description

Figure 1. Block diagram

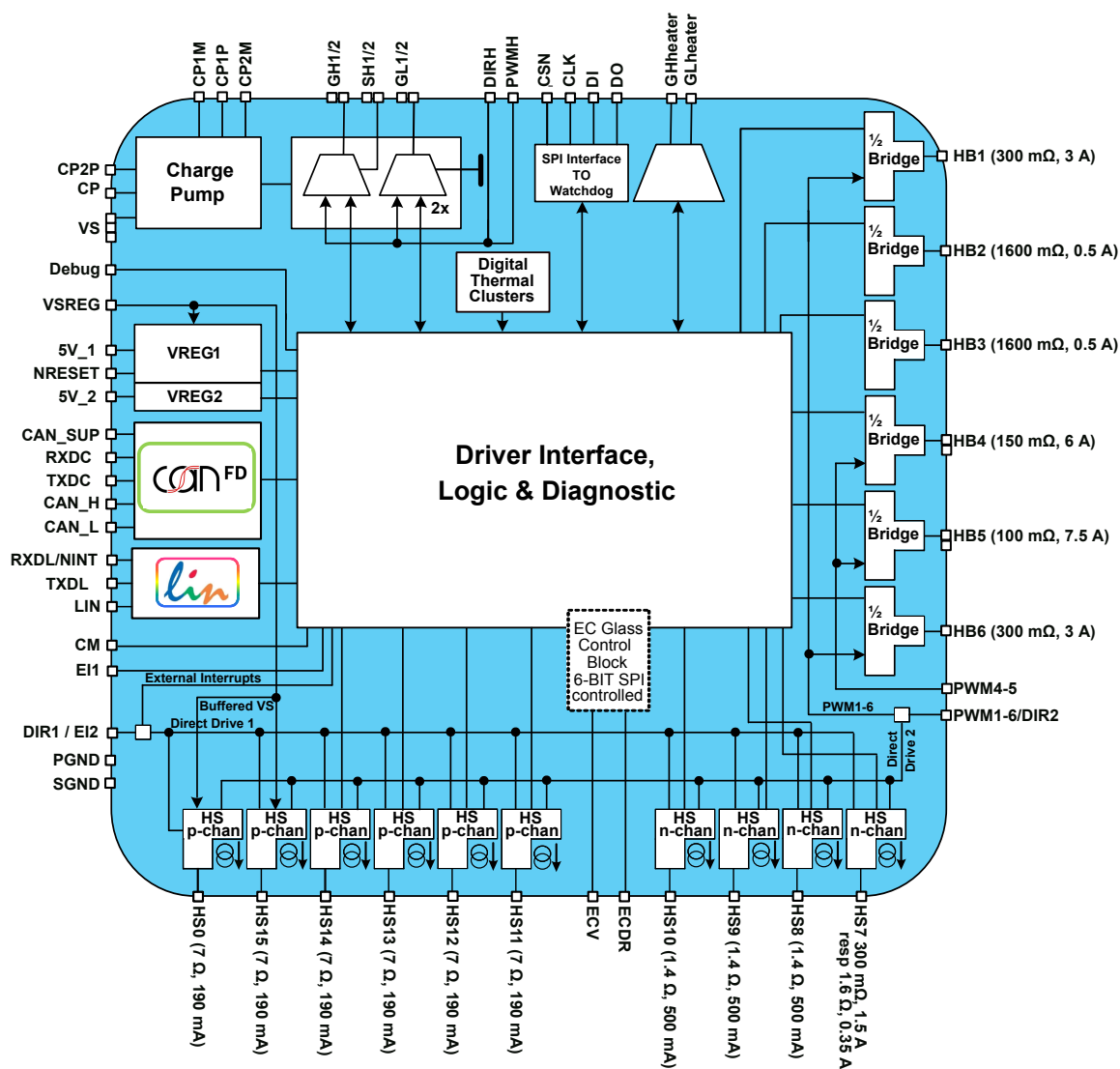
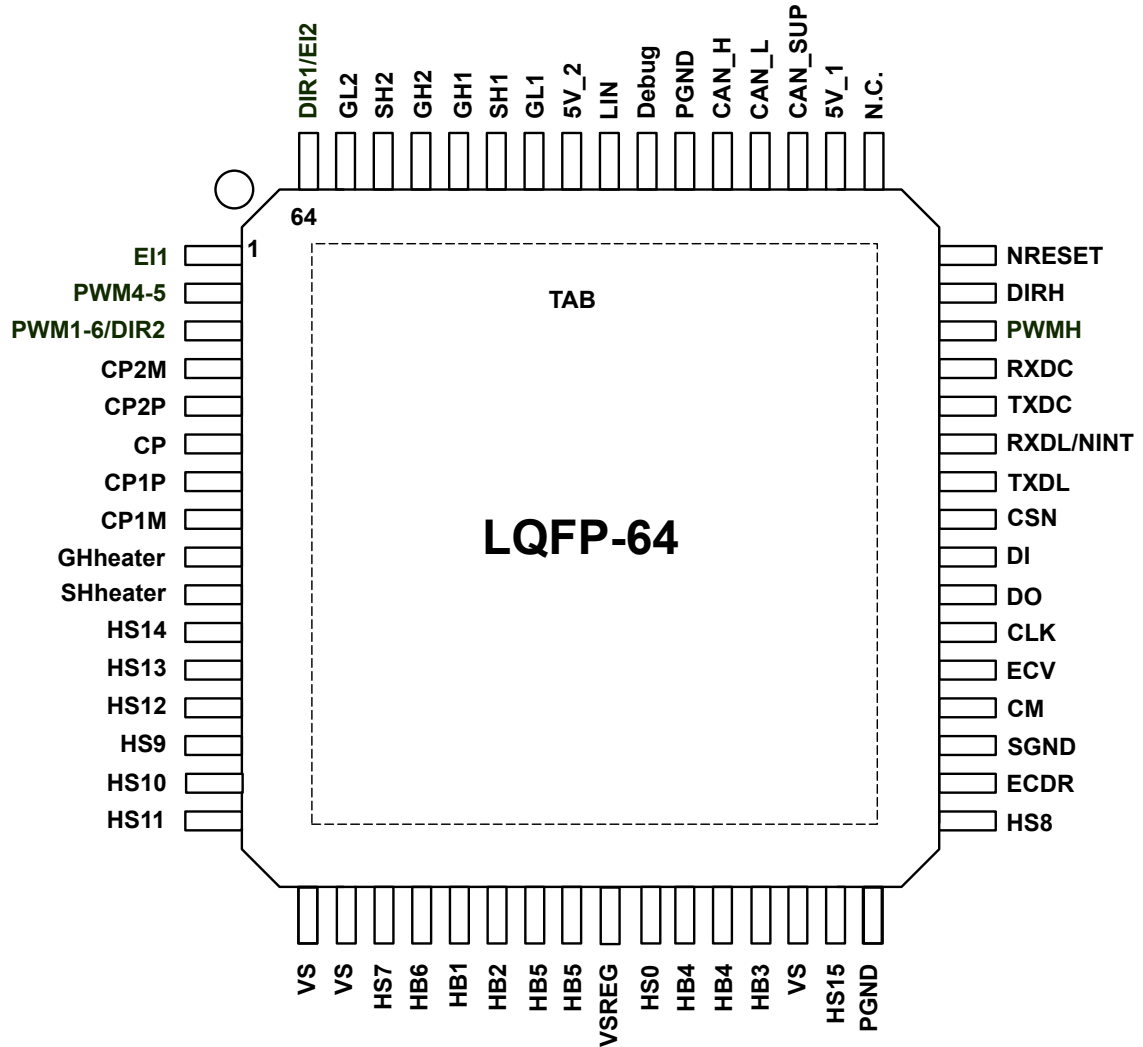


Figure 2. Pin connection (top view)

Table 1. Pin function

Pin	Name	Function
1	E11	External interrupt 1: input pin for static or cyclic monitoring of external contacts
2	PWM4-5	PWM input: this input signal can be used to control the HB4 or HB5
3	PWM1-6/ DIR2	PWM1-6 input -> this input signal can be used to control the HB1 or HB6; DIR2 -> direct HS drive 2
4	CP2M	Charge pump pin for capacitor 2, negative side
5	CP2P	Charge pump pin for capacitor 2, positive side
6	CP	Charge pump output
7	CP1P	Charge pump pin for capacitor 1, positive side
8	CP1M	Charge pump pin for capacitor 1, positive side

Pin	Name	Function
9	GHheater	Gate driver for external N-channel Power MOSFET in high-side configuration to control the heater
10	SHheater	Source of high-side Power MOSFET to control the heater
11	HS14	High-side driver output to drive LEDs
12	HS13	High-side driver output to drive LEDs
13	HS12	High-side driver output to drive LEDs
14	HS9	High-side driver output to drive LEDs. The channel is protected by overcurrent recovery feature
15	HS10	High-side driver output; important: beside the HS10 on/off bit, this output can be switched on setting the ECON bit for electrochrome control mode with higher priority. The channel is protected by overcurrent recovery feature
16	HS11	High-side driver output to drive LEDs
17	V _S	Power supply voltage for power stage outputs (external reverse battery protection required), for this input a ceramic capacitor as close as possible to GND is recommended. Important: for the capability of driving, the full current at the outputs all pins of VS must be connected externally
18	V _S ; 2 nd pin	Current capability (pin description see above)
19	HS7	High-side driver output to drive LEDs or a 10 W bulb (programmable R _{ds(on)}). The channel is protected by overcurrent recovery feature
20	HB6	Half-bridge outputs: the output is built by a high-side and a low-side switch which are internally connected. The output stage of both switches is a power DMOS transistor. Each driver has an internal parasitic reverse diode (bulk-drain diode: high-side driver from output to V _S , low-side driver from GND to output). The channel is protected by overcurrent recovery feature
21	HB1	Half-bridge outputs: the output is built by a high-side and a low-side switch which are internally connected. The output stage of both switches is a power DMOS transistor. Each driver has an internal parasitic reverse diode (bulk-drain diode: high-side driver from output to V _S , low-side driver from GND to output). The channel is protected by overcurrent recovery feature
22	HB2	Half-bridge outputs: the output is built by a high-side and a low-side switch which are internally connected. The output stage of both switches is a power DMOS transistor. Each driver has an internal parasitic reverse diode (bulk-drain diode: high-side driver from output to V _S , low-side driver from GND to output). The channel is protected by overcurrent recovery feature
23	HB5	Half-bridge outputs: the output is built by a high-side and a low-side switch which are internally connected. The output stage of both switches is a power DMOS transistor. Each driver has an internal parasitic reverse diode (bulk-drain diode: high-side driver from output to V _S , low-side driver from GND to output). The channel is protected by overcurrent recovery feature
24	HB5; 2 nd pin	Current capability (pin description see above)
25	VSREG	Power supply voltage to supply the internal voltage regulators and the HS0 (external reverse battery protection required / diode) for this input a ceramic capacitor as close as possible to GND and an electrolytic back up capacitor is recommended
26	HS0	High-side driver output to drive LEDs or to supply contacts
27	HB4	Half-bridge outputs: the output is built by a high-side and a low-side switch which are internally connected. The output stage of both switches is a power DMOS transistor. Each driver has an internal parasitic reverse diode (bulk-drain diode: high-side driver from output to V _S , low-side driver from GND to output). The channel is protected by overcurrent recovery feature
28	HB4; 2 nd pin	Current capability (pin description see above)
29	HB3	Half-bridge outputs: the output is built by a high-side and a low-side switch which are internally connected. The output stage of both switches is a power DMOS transistor. Each driver has an internal parasitic reverse diode (bulk-drain diode: high-side driver from output to V _S , low-side driver from GND to output). The channel is protected by overcurrent recovery feature
30	V _S 3 rd pin	Current capability (pin description see above)
31	HS15	High-side driver output to drive LEDs
32	PGND	Power GND
33	HS8	High-side driver output to drive LEDs. The channel is protected by overcurrent recovery feature

Pin	Name	Function
34	ECDR	ECDR: using the device in EC control mode this pin is used to control the gate of an external N-channel Power MOSFET
35	SGND	Signal ground
36	CM	Current monitor output: depending on the selected multiplexer bits of the control register this output sources an image of the instant current through the corresponding high-side driver with a fixed ratio
37	ECV	ECV: using the device in EC control mode this pin is used as voltage monitor input. For fast discharge an additional low-side switch is implemented
38	CLK	SPI: serial clock input
39	DO	SPI: serial data output (push pull output stage)
40	DI	SPI: serial data input
41	CSN	SPI: chip select not input
42	TXDL	LIN transmit data input
43	RXDL/NINT	RXDL -> LIN receive data output; NINT -> indicates local/remote wake-up events
44	TXDC	CAN transmit data input
45	RXDC	CAN receive data output (push pull output stages)
46	PWMH	PWMH input: this input signal can be used to control the H-bridge gate driver
47	DIRH	Direction Input: this input controls the H-bridge drivers for the external Power MOSFETs
48	NRESET	Power GND NReset output to microcontroller; internal pull-up of typical 110 kΩ (reset state = LOW) (open drain output stage)
49	N.C.	Not connected
50	5V_1	Voltage regulator output: 5 V supply for example microcontroller, CAN transceiver
51	CAN_SUP	CAN supply input; to allow external CAN supply from V1
52	CAN_L	CAN low level voltage I/O
53	CAN_H	CAN high level voltage I/O
54	PGND	Power GND
55	Debug	Debug input to deactivate the window watchdog (active high). Voltage capability linked to V _S
56	LIN	LIN bus line
57	5V_2	Voltage regulator output: 5 V supply for external loads (potentiometer, sensors). V2 is protected against reverse supply
58	GL1	Gate driver for Power MOSFET low-side switch in half bridge 1
59	SH1	Source of high-side switch in half bridge 1
60	GH1	Gate driver for Power MOSFET high-side switch in half bridge 1
61	GH2	Gate driver for Power MOSFET high-side switch in half bridge 2
62	SH2	Source of high-side switch in half bridge 2
63	GL2	Gate driver for Power MOSFET low-side switch in half bridge 2
64	DIR1/EI2	DIR1 -> direct HS drive 1; EI2 -> input pin for static or cyclic monitoring of external contacts
-	TAB	Ground connection

2 Electrical specifications

2.1 Absolute maximum ratings

Stressing the device above the rating listed in the Table 2. Absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the operating sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Table 2. Absolute maximum ratings

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
V_S, V_{Sreg}	DC supply voltage/jump start		-0.3		28	V
V_S, V_{Sreg}	DC supply voltage/load dump		-0.3		40	
5V1	Stabilized supply voltage, logic supply	$V_1 < V_{SREG}$	-0.3		6.5	V
5V2	Stabilized supply voltage ⁽¹⁾		-0.3		28	V
$V_{DI}, V_{CLK}, V_{CSN}, V_{DO}, V_{RXDL/NINT}, V_{RXDC}, V_{NRESET}, V_{CM}, V_{PWMH}, V_{DIRH}, V_{PWM1-6}, V_{PWM4-5}$	Logic input/output voltage range		-0.3		$V_1+0.3$	V
V_{TXDC}, V_{TXDL}	Logic input/output voltage range		-0.3		$V_1+0.3$	V
V_{Debug}	Debug input pin voltage range		-0.3		$V_S+0.3$	V
V_{EI1}	DC external input voltage/"jump start"		-0.3		28	V
$V_{DIR1/EI2}$	DC external input voltage/"jump start"		-0.3		28	V
V_{LIN}	LIN bus I/O voltage range		-27		40	V
I_{Input}	Current injection into V_S related input pins			20		mA
I_{out_inj}	Current injection into V_S related outputs			20		mA
V_{CANSUP}	CAN supply		-0.3		5.25	V
V_{CANH}, V_{CANL}	CAN bus I/O voltage range		-27		40	V
$V_{CANH} - V_{CANL}$	Differential CAN-bus voltage		-5		10	V
$V_{HBn}, V_{HSm}, V_{ECDR}, V_{ECV}, V_{HS0}$	Output voltage: • for HB (n = 1 to 6) • for HS (m = 7 to 15)		-0.3		$V_S+0.3$	V
$V_{GH1}, V_{GH2}, (V_{Gxy})$	High voltage signal pins	$V_{CP}+0.3$	$V_{Sxy}-0.3$		$V_{Sxy}+13$	V
V_{GL1}, V_{GL2}	High voltage signal pins	$V_{CP}+0.3$	-0.3		12	V
$V_{SH1}, V_{SH2}, (V_{Sxy})$	High voltage signal pins		-1		40	V
	High voltage signal pins; single pulse with $t_{max.} = 200$ ns		-5		40	V
V_{CP1P}	High voltage signal pins		$V_S-0.3$		V_S+10	V
V_{CP2P}	High voltage signal pins		$V_S-0.6$		V_S+10	V
V_{CP1M}, V_{CP2M}	High voltage signal pins		-0.3		$V_S+0.3$	V
V_{CP}	High voltage signal pin	$V_S \leq 26$ V	$V_S-0.3$		V_S+14	V

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
V_{CP}	High voltage signal pin	$V_S > 26\text{ V}$	$V_S - 0.3$		40	V
V_{GH_heater}		$V_{CP} + 0.3$	$V_{Sheater} - 0.3$		$V_{Sheater} + 13$	V
V_{SH_heater}			-0.3		40	V
$I_{ECV, HB2, HB3, HS9, HS10, HS11, HS12, HS13, HS14, HS15, HS0}$	Output current ⁽²⁾		-1.25		1.25	A
I_{HS8}	Output current ⁽²⁾		-2.5		2.5	A
I_{HS7}	Output current ⁽²⁾		-5		5	A
$I_{HB1,6}$	Output current ⁽²⁾		-5		5	A
$I_{HB4,5}$	Output current ⁽²⁾		-10		10	A
I_{VScum}	Maximum cumulated current at V_S drawn by HB1 & HB2 ⁽²⁾		-7.5		7.5	A
	Maximum cumulated current at V_S drawn by HB3, HS8 & HS10 ⁽²⁾		-2.5		2.5	
	Maximum cumulated current at V_S drawn by HB4 ⁽²⁾		-10		10	
	Maximum cumulated current at V_S drawn by HB5 ⁽²⁾		-10		10	
	Maximum cumulated current at V_S drawn by HB6 & HS7 ⁽²⁾		-7.5		7.5	
	Maximum cumulated current at V_S drawn by HS9, HS11, HS12, HS13, HS14, HS15 and CP		-2.5		2.5	
I_{VSREG}	Maximum current at V_{SREG} pin ⁽²⁾ (5V_1, 5V_2 and HS0)		-2.5		2.5	A
$I_{PGNDcum}$	Maximum cumulated current at PGND drawn by HB1 & HB6 ⁽²⁾		-7.5		7.5	A
	Maximum cumulated current at PGND drawn by HB2 & HB5 ⁽²⁾		-12.5		12.5	
	Maximum cumulated current at PGND drawn by HB3, HB4 & ECV ⁽²⁾		-12.5		12.5	
I_{SGND}	Maximum current at SGND ⁽²⁾		-1.25		1.25	A
GND pins	PGND vs SGND		-0.3		0.3	V

1. L99DZ300G is protected against 5V2 shorted to V_S and 5V2 reverse biasing when V_{SREG} is higher than 3.5 V.
2. Values for the absolute maximum DC current through the bond wires. This value does not consider maximum power dissipation or other limits.

Note:

1. All maximum ratings are absolute ratings. Leaving the limitation of any of these values may cause an irreversible damage of the integrated circuit.
2. Loss of ground or ground shift with externally grounded loads: ESD structures are configured for nominal currents only. If external loads are connected to different grounds, the current load must be limited to this nominal current.

2.2 ESD protection

Table 3. ESD protection

Parameter	Value	Unit
All pins ⁽¹⁾	±2	kV
All power output pins ⁽²⁾ : HB1–HB6, HS7 - HS15, HS0, ECV	±4	kV
LIN	±8 ⁽²⁾	kV
	±8 ⁽³⁾	
	±6 ⁽⁴⁾	
CAN_H, CAN_L	±8 ⁽²⁾	kV
	±6 ⁽⁴⁾	
All pins ⁽⁵⁾	±500	V
Corner pins ⁽⁵⁾	±750	V

1. HBM (human body model, 100 pF, 1.5 kΩ) according to AEC-Q100-002.
2. HBM with all none zapped pins grounded. HBx (x = 1, ..., 6) and HSy (y = 7, ..., 15, 0).
3. Indirect ESD Test according to IEC 61000-4-2 (150 pF, 330 Ω) and 'Hardware requirements for LIN, CAN and flexray interfaces in automotive applications' (version 1.3, May 2012).
4. Direct ESD test according to IEC 61000-4-2 (150 pF, 330 Ω) and 'Hardware Requirements for LIN, CAN and Flexray interfaces in automotive applications' (version 1.3, May 2012).
5. Charged device model according to AEC-Q100-011.

2.3 Thermal data

Table 4. Operation junction temperature

Symbol	Parameter	Typ. value	Unit
T _J	Operating junction temperature	-40 to 175	°C

All parameters are guaranteed in the temperature range -40 to 150°C (unless otherwise specified); the device is still operative and functional at higher temperatures (up to 175°C).

Note:

1. Parameters limits at higher temperatures than 150°C may change with respect to what is specified as per the standard temperature range.
2. Device functionality at high temperature is guaranteed by characterization.

Table 5. Temperature warning and thermal shutdown

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
T _W	Thermal overtemperature warning threshold	T _J ⁽¹⁾	140	150	160	°C	F.025
T _{SD1}	Thermal shutdown junction temperature 1	T _J ⁽¹⁾	165	175	185	°C	F.026
T _{SD2}	Thermal shutdown junction temperature 2	T _J ⁽¹⁾	175	185	195	°C	F.028
T _{SD12hys}		Hysteresis		5		°C	F.029
t _{TJTW}	Thermal warning/shutdown filter time	Tested by scan		32		μs	F.030

1. Non overlapping.

2.3.1 LQFP64 thermal data

Devices belonging to the L99DZxxx family embed a multitude of junctions (that is outputs based on a Power MOSFET stage) housed in a relatively small piece of silicon. The L99DZ300G contains, among all the described features, 6 half-bridges (12 N-channel Power MOSFET), 10 high-sides and two voltage regulators.

For this reason, using the thermal impedance of a single junction (that is voltage regulator or major power dissipation contributor) does not allow to predict thermal behavior of the whole device and therefore it is not possible to assess if a device is thermally suitable for a given activation profile and loads characteristics.

Some representative and realistic worst case thermal profiles are described in the below paragraph. The following measurement methods can be easily implemented, by the final user, for a specific activation profile.

2.3.2 L99DZ300G thermal profiles

Profile 1

Battery voltage: 16 V, ambient temperature start: 85°C

DC activation:

V1 charged with 100 mA (50 Ω - DC activation)

V2 charged with 30 mA (150 Ω - DC activation)

HS7: 150 Ω resistor (DC activation)

HS8: 330 Ω resistor (DC activation)

HS11: 470 Ω resistor (DC activation)

HS12: 470 Ω resistor (DC activation)

HS13: 470 Ω resistor (DC activation)

HS14: 470 Ω resistor (DC activation)

Cyclic activation

- HB4–HB5: 3.52 Ω (3.3 + 0.22) resistor placed across those outputs 10 activations of lock/unlock (250 ms ON lock; 1500 ms wait; 250 ms ON unlock; 1500 ms wait)
- HB5–HB6: 10 Ω resistor placed across those outputs 10 activations of safe lock/unlock (250 ms ON lock; 1500 ms wait; 250 ms ON unlock; 1500 ms wait)

Test execution:

Once thermal equilibrium is reached with all DC load active, the “cyclic activation” sequence is applied.

The device operates always without triggering the thermal warning threshold.

Profile 2

Battery voltage: 16 V, ambient temperature start: 85°C

DC activation:

V1 charged with 100 mA (50 Ω - DC activation)

V2 charged with 30 mA (150 Ω - DC activation)

HS7: 150 Ω resistor (DC activation)

HS8: 330 Ω resistor (DC activation)

HS11: 470 Ω resistor (DC activation)

HS12: 470 Ω resistor (DC activation)

HS13: 470 Ω resistor (DC activation)

HS14: 470 Ω resistor (DC activation)

Cyclic activation

- HB1–HB6: 6.8 Ω resistor placed across those outputs 2 activations of fold/unfold. (3 s fold; 1 s wait; 3 s unfold; 1 s wait)

Test execution:

Once thermal equilibrium is reached with all DC load active, the “cyclic activation” sequence is applied.

The device operates always without triggering the thermal warning threshold.

Profile 3

Battery voltage: 16 V, ambient temperature start: 85°C

DC activation:

V1 charged with 100 mA (50 Ω - DC activation)
V2 charged with 30 mA (150 Ω - DC activation)
HS7: 150 Ω resistor (DC activation)
HS8: 330 Ω resistor (DC activation)
HS11: 470 Ω resistor (DC activation)
HS12: 470 Ω resistor (DC activation)
HS13: 470 Ω resistor (DC activation)
HS14: 470 Ω resistor (DC activation)
Heater: DC activation

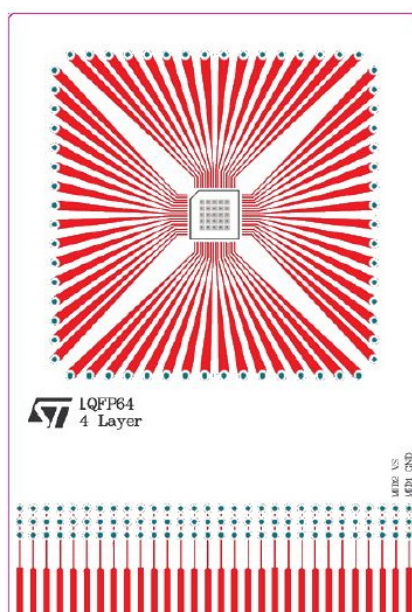
Cyclic activation

- Windows lift: real motor placed across external MOS 2 activations up/down. (5 s up; 5 s down)

Test execution:

Once thermal equilibrium is reached with all DC load active, the “cyclic activation” sequence is applied.
The device operates always without triggering the thermal warning threshold.

Figure 3. LQFP64 printed circuit board



Note: *Layout condition for thermal characterization: board finishing thickness 1.5 mm $\pm$ 10%, board four layers, board dimension 77 mm x 114 mm, board material FR4, Cu thickness 0.070 mm for outer layers, 0.0035 mm for inner layers, thermal vias separation 1.2 mm.*

2.4 Electrical characteristics

For an efficient and easy tracking, numbering has been added to each electrical parameter.

Device features are split into categories (see [Table 3. ESD protection](#), [Table 4. Operation junction temperature](#) and [Table 5. Temperature warning and thermal shutdown](#)) and each of them is represented by a letter (such as A, B, C); all parameters are completely identified by a letter and a three-digit number (for example B.125, C.096) for their whole lifetime.

New inserted parameters continue with the numbering of the related category, no matter of where they are placed.

To facilitate insertion, the last number inserted for each category is also reported in the second column of the table.

Table 6. Electrical parameters numbering

Category	Parameters numbering	Last Inserted
Analog I/O	A.xxx	A.197
Digital I/O	B.xxx	B.034
Voltage regulators	C.xxx	C.057
Outputs	D.xxx	D.137
Transceivers	E.xxx	E.124
Others	F.xxx	F.030

Due to these rules and taking into account that deleted parameter numbers are no more reassigned, numbering inside each category may not be sequential.

Note: For all the parameters described as "Tested by scan", the related timings are specified by design and have been measured in lab.

2.4.1 Supply, supply monitoring and current consumption

All SPI communication, logic and oscillator parameters are working down to $V_{SREG} = 3.5\text{ V}$ and parameters are as specified in the respective chapters.

- SPI thresholds
- Oscillator frequency (delay times correctly elapsed)
- Internal register status correctly kept (reset at default values for $V_S < V_{POR}$)
- Reset threshold correctly detected

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_S < 28\text{ V}$, $6\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40^\circ\text{C}$ to 150°C , unless otherwise specified.

Table 7. Supply monitoring and current consumption

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{SUV}	V_S undervoltage threshold	V_S increasing / decreasing	4.7		5.4	V	A.001
V_{hyst_UV}	V_S undervoltage hysteresis		0.025	0.1	0.2	V	A.002
V_{SOV}	V_S overvoltage threshold	V_S increasing	19		22.5	V	A.003
V_{SOV}	V_S overvoltage threshold	V_S decreasing	18.5		22.5	V	A.004
V_{hyst_OV}	V_S overvoltage hysteresis		0.5	1.3	1.7	V	A.005
V_{SREGUV}	V_{SREG} undervoltage threshold	V_{SREG} increasing/decreasing	4.2		4.9	V	A.006
V_{hyst_UV}	V_{SREG} undervoltage hysteresis		0.025	0.1	0.2	V	A.007
V_{SREGOV}	V_{SREG} overvoltage threshold	V_{SREG} increasing	19		22.5	V	A.008
V_{SREGOV}	V_{SREG} overvoltage threshold	V_{SREG} decreasing	18.5		22.5	V	A.009
V_{hyst_OV}	V_{SREG} overvoltage hysteresis		0.5	1.3	1.7	V	A.010
t_{ovuv_filt}	V_S / V_{SREG} overvoltage/undervoltage filter time	Tested by scan		64		μs	A.011
$I_{V(act)}$	Current consumption in active mode	$V_S = 12\text{ V}$, TXD CAN = high, TXD LIN = high, V1 = on, V2 = on, HS/LS driver OFF		6.2	12	mA	A.012
$I_{V(BAT)}$	Current consumption in VBAT_Standby mode ⁽¹⁾	$V_S = 12\text{ V}$, $T_J = 85^\circ\text{C}$, HS/LS driver OFF, CAN WU disabled	8	20	35	μA	A.013

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$I_{V(BAT)CS}$	Current consumption in VBAT_Standby mode with cyclic sense enabled ⁽¹⁾	$V_S = 12\text{ V}$, $T_J = 85^\circ\text{C}$, HS/LS driver OFF, CAN WU disabled, $T = 50\text{ ms}$, $t_{on} = 100\text{ }\mu\text{s}$	40	75	125	μA	A.014
$I_{V(BAT)CW}$	Current consumption in VBAT_Standby mode with cyclic wake enabled ⁽¹⁾	$V_S = 12\text{ V}$, $T_J = 85^\circ\text{C}$, HS/LS driver OFF, CAN WU disabled, $T = 50\text{ ms}$, $t_{on} = 100\text{ }\mu\text{s}$, In standby phase before waking up on timer expiration	40	75	125	μA	A.015
$I_{V(V1stby)_0}$	Current consumption in V1_Standby mode ⁽¹⁾	$V_S = 12\text{ V}$, $T_J = 85^\circ\text{C}$, voltage regulator V1 active, ($I_{V1} = 0$), HS/LS driver OFF, Voltage regulator V2 deactivated, CAN WU disabled	16	51	76	μA	A.016
$I_{V(V1stby)}$	Current consumption in V1_Standby mode ⁽¹⁾	$V_S = 12\text{ V}$, $T_J = 85^\circ\text{C}$, voltage regulator V1 active, ($I_{V1} < I_{cmp}$), HS/LS driver OFF		60	146	μA	A.017
$I_{qElx}^{(2)}$	Additional quiescent current for each Elx active ($x = 1, 2$)			200		nA	A.018
$I_{qCAN_WU}^{(2)}$	Additional quiescent current with CAN wake-up enabled (CAN_WU_EN = 1)			10		μA	A.019
$I_{HS0_HS15_DIR}^{(2)}$	Quiescent current adder if HS0 or HS15 is configured for direct drive; value during output OFF				5	μA	A.021

1. Conditions for specified current consumption:

- $V_{LIN} > (V_S - 1.5\text{ V})$
- $(CAN_H - CAN_L) < 0.4\text{ V}$ or $(CAN_H - CAN_L) > 1.2\text{ V}$
- $V_{WU} < 1\text{ V}$ or $V_{WU} > (V_S - 1.5\text{ V})$
- LIN wake-up is possible

2. Parameter specified by design, not tested in production.

2.4.2

Oscillator

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_S < 28\text{ V}$, $6\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40^\circ\text{C}$ to 150°C , unless otherwise specified.

Table 8. Oscillator

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$F_{CLK1}^{(1)}$	Oscillation frequency	-	0.80	1.0	1.20	MHz	A.023
$F_{CLK2}^{(1)}$	Oscillation frequency	-	12.8	16.0	19.2	MHz	A.024

1. 1 MHz clock is used in standby mode for low quiescent requirements; 16 MHz clock is used in active mode.

2.4.3 Power-on Reset (V_{SREG})

All outputs open; $T_J = -40\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$, unless otherwise specified.

Table 9. Power-on Reset

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{POR_R}	V_{POR} threshold rising	V_{SREG} rising		3.45	4.5	V	A.025
V_{POR_F}	V_{POR} threshold falling	V_{SREG} falling ⁽¹⁾	2.3		3.55	V	A.026

1. This threshold is valid if V_{SREG} has already reached $V_{POR_R(max)}$ previously.

2.4.4 Voltage regulator V1

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.

$4.5 < V_S < 28\text{ V}$, $4.5\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$, unless otherwise specified.

Table 10. Voltage regulator 1

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V1	Output voltage	$V_{SREG} \geq 5.6\text{ V}$		5.0		V	C.001
$V1_{10mA}$	Output voltage tolerance (0 ... I_{comp})	$I_{LOAD} = 100\text{ }\mu\text{A}$ to I_{comp} , $V_{SREG} = 13.5\text{ V}$	-3		3	%	C.003
$V1_{high_acc}$	Output voltage tolerance high accuracy mode	$I_{LOAD} = I_{comp}$ to 100 mA , active mode, $V_{SREG} = 13.5\text{ V}$	-2		2	%	C.004
$V1_{250mA}$	Output voltage tolerance (100 ... 250 mA)	$I_{LOAD} = 250\text{ mA}$, $V_{SREG} = 13.5\text{ V}$	-3		3	%	C.005
V_{DP1}	Drop-out voltage	$I_{LOAD} = 50\text{ mA}$		0.2	0.4	V	C.006
		$I_{LOAD} = 100\text{ mA}$		0.3	0.5		C.007
		$I_{LOAD} = 150\text{ mA}$		0.45	0.65		C.008
I_{CC1}	Output current in active mode (to GND)	Maximum continuous load current			250	mA	C.009
I_{CCmax1}	Short-circuit output current (to GND)	Current limitation	340	600	900	mA	C.010
C_{load1} ⁽¹⁾	Load capacitor 1	Ceramic ($\pm 20\%$)	1 ⁽²⁾	2.2	10	μF	C.011
t_{TSD}	V1 deactivation time after thermal shutdown	Tested by scan		1.5		s	C.012
I_{CMP_ris} ⁽³⁾	Current comp. rising threshold (to GND)	Rising current	6	12	21	mA	C.013
I_{CMP_fal} ⁽³⁾	Current comp. falling threshold (to GND)	Falling current	5	10	18	mA	C.014
I_{CMP_hys} ⁽³⁾	Current comp. hysteresis			2		mA	C.015
$V1_{fail}$	V1 fail threshold	V1 forced		2		V	C.019
t_{V1fail}	V1 fail filter time	Tested by scan	6	13	20	μs	C.020
$t_{V1short}$	V1 short filter time	Tested by scan	2	4	5	ms	C.021
t_{V1FS}	V1 fail-safe filter time	Tested by scan	1.43	2	2.06	ms	C.022
t_{V1off}	V1 deactivation time after 8 consecutive WD failures	Tested by scan		200	270	ms	C.023

1. Specified by design, not tested in production.
2. Nominal capacitor value required for stability of the regulator. Tested with $1\text{ }\mu\text{F}$ ceramic ($\pm 20\%$). Capacitor must be located close to the regulator output pin. A $2.2\text{ }\mu\text{F}$ capacitor value is recommended to minimize the DPI stress in the application.
3. In active mode, V1 regulator is switched to high accuracy mode. Below the I_{CMP} threshold, regulator switches in any case to nominal accuracy mode (same behavior applies also in case of high current).

2.4.5 Voltage regulator V2

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.
 $4.5\text{ V} < V_S < 28\text{ V}$, $4.5\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$, unless otherwise specified.

Table 11. Voltage regulator 2

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V2	Output voltage	$V_{SREG} \geq 5.6\text{ V}$		5.0		V	C.024
ΔV_o	Output voltage tracking accuracy	$I_{CC2} = 100\text{ }\mu\text{A}$ to 50 mA , $I_{CC1} = 30\text{ mA}$, $V_{SREG} = 6.5\text{ V}$ to 28 V	-20		20	mV	C.038
I_{CCmax2}	Output current limitation		80		170	mA	C.040
$C_{load2}^{(1)}$	Load capacitor 2	Ceramic ($\pm 20\%$)	1 ⁽²⁾		10	μF	C.042
V_{2fail}	V2 fail threshold	V2 forced		2	3	V	C.043
t_{V2fail}	V2 fail filter time	Tested by scan		12		μs	C.056
$t_{V2short}$	V2 short filter time	Tested by scan		4		ms	C.044

1. Specified by design, not tested in production.
2. Nominal capacitor value required for stability of the regulator. Tested with $1\text{ }\mu\text{F}$ ceramic ($\pm 20\%$). Capacitor must be located close to the regulator output pin. A $2.2\text{ }\mu\text{F}$ capacitor value is recommended to minimize the DPI stress in the application.

2.4.6 Reset output

The voltages are referred to GND and currents are assumed positive, when the current flows into the pin.
 $4\text{ V} \leq V_S \leq 28\text{ V}$, $4\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40\text{ to }150^\circ\text{C}$, unless otherwise specified.

Table 12. Reset output

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{RT1}	Reset threshold voltage1	V_{V1} decreasing	3.3	3.5	3.7	V	C.045
V_{RT2}	Reset threshold voltage2	V_{V1} decreasing	3.6	3.8	4	V	C.046
V_{RT3}	Reset threshold voltage3	V_{V1} decreasing	3.8	4.0	4.2	V	C.047
V_{RT4-1}	Reset threshold voltage4	V_{V1} decreasing	4.1	4.3	4.5	V	C.048
V_{RT4-2}	Reset threshold voltage4	V_{V1} increasing	4.6	4.75	4.9	V	C.049
V_{RESET}	Reset pin low output voltage	$V1 > 1\text{V}$, $I_{RESET} = 5\text{ mA}$		0.3	0.5	V	C.050
R_{RESET}	Reset pull-up int. resistor		70	110	180	k Ω	C.051
t_{RR}	Reset reaction time	Tested by scan	6		40	μs	C.052
t_{UV1}	V1 undervoltage filter time	Tested by scan		16		μs	C.053
t_{RD}	Reset pulse duration	Tested by scan	1.5	2.0	2.5	ms	C.054

2.4.7 Watchdog

(see also [Section 3.6: Configurable window watchdog](#))

$4.5\text{ V} < V_S < 28\text{ V}$, $4.5\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40^\circ\text{C to }150^\circ\text{C}$, unless otherwise specified.

Table 13. Watchdog

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
t_{LW}	Long open window	Tested by scan	246	300	375	ms	A.027
T_{EFW1}	Early Failure window 1	Tested by scan			4.5	ms	A.028
T_{LFW1}	Late Failure window 1	Tested by scan	20			ms	A.029
T_{SW1}	Safe window 1	Tested by scan	7.5		12	ms	A.030
T_{EFW2}	Early Failure window 2	Tested by scan			22.3	ms	A.031
T_{LFW2}	Late Failure window 2	Tested by scan	100			ms	A.032
T_{SW2}	Safe window 2	Tested by scan	37.5		60	ms	A.033

Figure 4. Watchdog timing

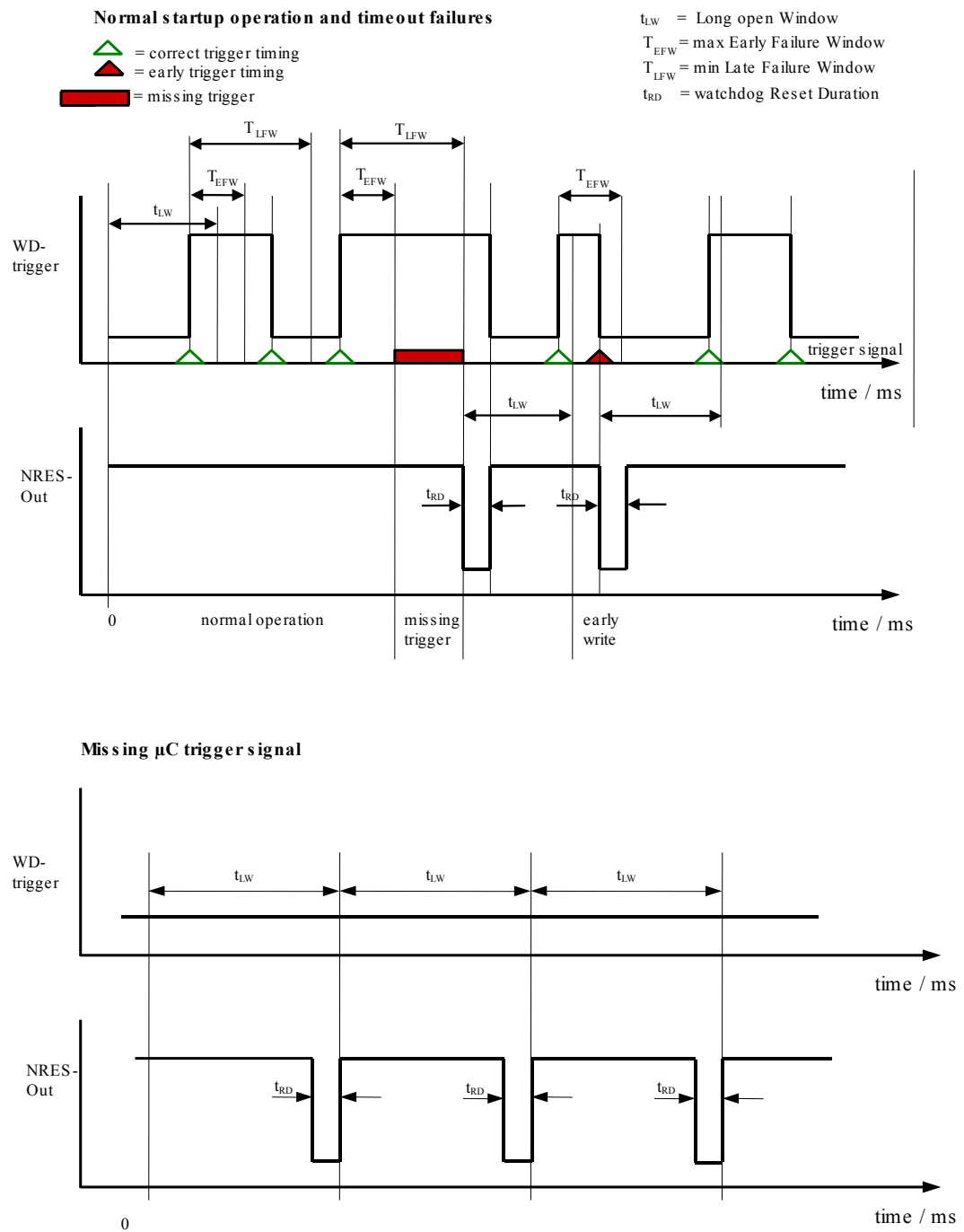
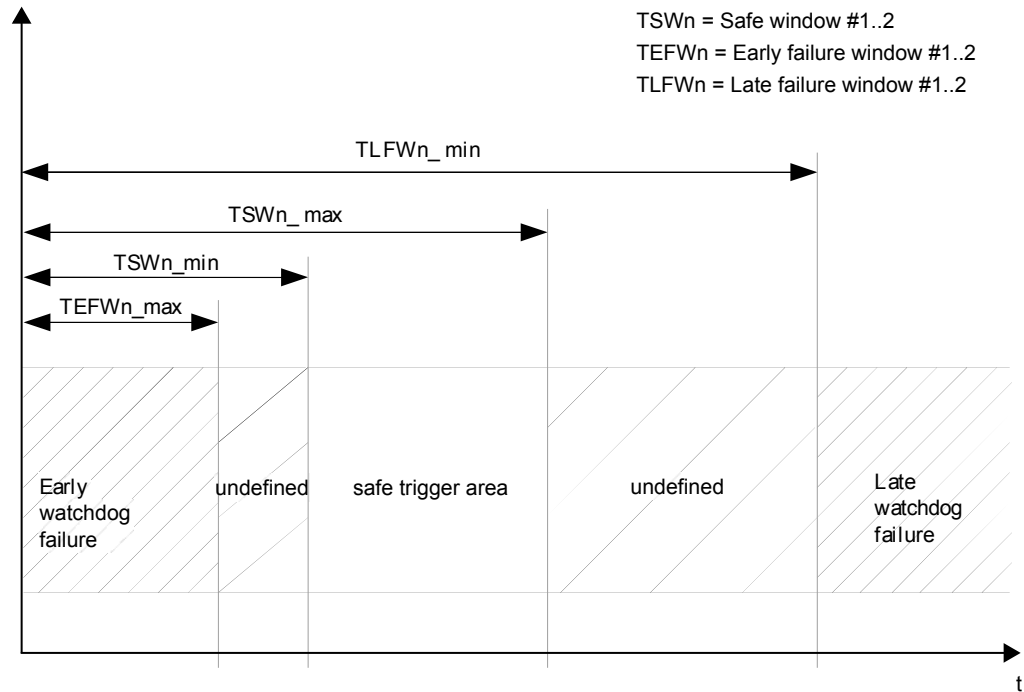


Figure 5. Watchdog early, late and safe windows



2.4.8 Current monitor output

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.
6 V < V_S < 28 V, 6 V < V_{SREG} < 28 V, T_J = -40 °C to 150 °C, unless otherwise specified.

Table 14. Current monitor output

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V _{CM}	Functional voltage range		0		V1-1V	V	A.040
I _{CMr}	Current monitor output ratio: I _{CM} /I _{HB1,HB6}	0 V ≤ V _{CM} ≤ V1 - 1 V		1/9750			A.041
	I _{CM} /I _{HS7} (low on-resistance)			1/10000			A.191
	I _{CM} /I _{HB4}			1/9920			A.042
	I _{CM} /I _{HB5}			1/10300			A.192
	I _{CM} /I _{HS7} (high on-resistance)			1/2000			A.043
	I _{CM} /I _{HB2}			1/2020			A.044
	I _{CM} /I _{HB3}			1/2050			A.193
	I _{CM} /I _{HS8,HS9,HS10}			1/1010			A.045
	I _{CM} /I _{HS11,HS12,HS13,HS14}			1/990			A.194
	I _{CM} /I _{HS15, HS0}			1/1000			A.195
I _{CM acc}	Current monitor accuracy for HB1, ..., HB6, HS7, ..., HS10	Ranges extracted at the output: I _{HB2,HB3min} = 100 mA, I _{HB2,HB3max} = 0.4 A	-8% I _{HS} *I _{CMr_typ} - 2% FS ⁽¹⁾	0	8% I _{HS} *I _{CMr_typ} + 2% FS ⁽¹⁾	A	A.046

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$I_{CM\ acc}$	Current monitor accuracy for HB1, ..., HB6, HS7, ..., HS10	$I_{HB1,HB6min} = 500\text{ mA}$, $I_{HB1,HB6max} = 2.9\text{ A}$	$-8\% I_{HS}$ $*I_{CMr_typ} - 2\% FS^{(1)}$	0	$8\% I_{HS}$ $*I_{CMr_typ} + 2\% FS^{(1)}$	A	A.046
		$I_{HB4min} = 500\text{ mA}$, $I_{HB4max} = 5.9\text{ A}$					
		$I_{HB5min} = 500\text{ mA}$, $I_{HB5max} = 7.4\text{ A}$					
		$I_{HS8,HS9,HS10min} = 100\text{ mA}$, $I_{HS8,HS9,HS10max} = 0.3\text{ A}$					
		$I_{HS7(High\ on-resistance)}$, $I_{HSmin} = 100\text{ mA}$, $I_{HSmax} = 300\text{ mA}$					
		$I_{HS7(Low\ on-resistance)}$, $I_{HSmin} = 500\text{ mA}$, $I_{HSmax} = 1.4\text{ A}$					
	Current monitor accuracy for HS11, ..., HS15, HS0	$I_{HS11,HS12,HS13,HS14,HS15\ and\ HS0}$ $I_{HSmin} = 100\text{ mA}$, $I_{HSmax} = 0.13\text{ A}$	$-8\% I_{HS}$ $*I_{CMr_typ} - 4\% FS^{(1)}$	0	$8\% I_{HS}$ $*I_{CMr_typ} + 4\% FS^{(1)}$	A	A.047
$t_{cmb}^{(2)}$	Current monitor setting time			32		μs	A.051

1. FS (full scale) = $I_{HB(HS)max} * I_{CMr_typ}$.

2. Parameter is specified by design, not tested in production.

2.4.9 Charge pump

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_S < 28\text{ V}$, $T_J = -40\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$, unless otherwise specified.

Table 15. Charge pump

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Items
V_{CP}	Charge pump output voltage	$V_S = 6\text{ V}$, $I_{CP} = -15\text{ mA}$	$V_S + 6$	$V_S + 7$		V	A.052
		$V_S \geq 10\text{ V}$, $I_{CP} = -15\text{ mA}$	$V_S + 11$	$V_S + 12$	$V_S + 13.5$	V	A.053
I_{CP}	Charge pump output current ⁽¹⁾	$V_{CP} = V_S + 10\text{ V}$; $V_S = 13.5\text{ V}$; $C_1 = C_2 = C_{CP} = 100\text{ nF}$	22			mA	A.054
I_{CPlim}	Charge pump output current limitation ⁽²⁾	$V_{CP} = V_S$; $V_S = 13.5\text{ V}$; $C_1 = C_2 = C_{CP} = 100\text{ nF}$	25		70	mA	A.055
V_{CP_low}	Charge pump low threshold voltage		$V_S + 4.5$	$V_S + 5$	$V_S + 5.5$	V	A.056
T_{CP}	Charge pump low filter time	Tested by scan	44	64	77	μs	A.057
$t_{set,CP}$	Charge pump startup blanking time	Tested by scan	358	576	692	μs	A.183
f_{CP}	Charge pump frequency	Tested by scan		400		kHz	A.058

1. I_{CP} is the minimum current the device can provide to an external circuit without V_{CP} going below $V_S + 10\text{ V}$.

2. I_{CPlim} is the maximum current, which flows out of the device in case of a short to V_S .

2.4.10 Outputs HB1-HB6, HS7-HS15, HS0, ECV, ECDR

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} \leq V_S \leq 18\text{ V}$, all outputs open, $T_J = -40\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$, unless otherwise specified.

Table 16. Outputs HB1–HB6, HS7–HS15, HS0, ECV, ECDR

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$r_{\text{ON HB1, HB6}}$	On-resistance to supply or GND	$V_S = 13.5\text{ V}$, $T_A = 25\text{ }^{\circ}\text{C}$, $I_{\text{HB1,HB6}} = \pm 1.5\text{ A}$		300	400	m Ω	D.001
		$V_S = 13.5\text{ V}$, $T_A = 125\text{ }^{\circ}\text{C}$, $I_{\text{HB1,HB6}} = \pm 1.5\text{ A}$		450	600	m Ω	D.002
$r_{\text{ON HB2, HB3}}$	On-resistance to supply or GND	$V_S = 13.5\text{ V}$, $T_A = 25\text{ }^{\circ}\text{C}$, $I_{\text{HB2,HB3}} = \pm 0.4\text{ A}$		1600	2200	m Ω	D.005
		$V_S = 13.5\text{ V}$, $T_A = 125\text{ }^{\circ}\text{C}$, $I_{\text{HB2,HB3}} = \pm 0.4\text{ A}$		2500	3400	m Ω	D.006
$r_{\text{ON HB4}}$	On-resistance to supply or GND	$V_S = 13.5\text{ V}$, $T_A = 25\text{ }^{\circ}\text{C}$, $I_{\text{HB4}} = \pm 3\text{ A}$		150	200	m Ω	D.093
		$V_S = 13.5\text{ V}$, $T_A = 125\text{ }^{\circ}\text{C}$, $I_{\text{HB4}} = \pm 3\text{ A}$		225	300	m Ω	D.094
$r_{\text{ON HB5}}$	On-resistance to supply or GND	$V_S = 13.5\text{ V}$, $T_A = 25\text{ }^{\circ}\text{C}$, $I_{\text{HB5}} = \pm 3\text{ A}$		100	140	m Ω	D.095
		$V_S = 13.5\text{ V}$, $T_A = 125\text{ }^{\circ}\text{C}$, $I_{\text{HB5}} = \pm 3\text{ A}$		140	190	m Ω	D.096
$r_{\text{ON HS7}}$	On-resistance to supply in low resistance mode	$V_S = 13.5\text{ V}$, $T_A = 25\text{ }^{\circ}\text{C}$, $I_{\text{HS7}} = -1.1\text{ A}$		300	420	m Ω	D.007
		$V_S = 13.5\text{ V}$, $T_A = 125\text{ }^{\circ}\text{C}$, $I_{\text{HS7}} = -1.1\text{ A}$		450	620	m Ω	D.008
	On-resistance to supply in high resistance mode	$V_S = 13.5\text{ V}$, $T_A = 25\text{ }^{\circ}\text{C}$, $I_{\text{HS7}} = -0.2\text{ A}$		1600	2200	m Ω	D.009
		$V_S = 13.5\text{ V}$, $T_A = 125\text{ }^{\circ}\text{C}$, $I_{\text{HS7}} = -0.2\text{ A}$		2500	3400	m Ω	D.010
$r_{\text{ON HS8, HS9, HS10}}$	On-resistance to supply	$V_S = 13.5\text{ V}$, $T_A = 25\text{ }^{\circ}\text{C}$, $I_{\text{HS8,HS9,HS10}} = -0.4\text{ A}$		1400	2200	m Ω	D.011
		$V_S = 13.5\text{ V}$, $T_A = 125\text{ }^{\circ}\text{C}$, $I_{\text{HS8,HS9,HS10}} = -0.4\text{ A}$		2700	3400	m Ω	D.012
$r_{\text{ON HS0, HS11, HS12, HS13, HS14, HS15}}$	On-resistance to supply	$V_S = 13.5\text{ V}$, $T_A = 25\text{ }^{\circ}\text{C}$, $I_{\text{HS0,HS11,HS12,HS13,HS14,HS15}} = -60\text{ mA}$		7	9	Ω	D.017
		$V_S = 13.5\text{ V}$, $T_A = 125\text{ }^{\circ}\text{C}$, $I_{\text{HS0,HS11,HS12,HS13,HS14,HS15}} = -60\text{ mA}$		11	14	Ω	D.018
$r_{\text{ON ECV}}$	On-resistance to GND	$V_S = 13.5\text{ V}$, $T_A = 25\text{ }^{\circ}\text{C}$, $I_{\text{OUTECV,ECFD}} = +0.4\text{ A}$		1600	2200	m Ω	D.019
		$V_S = 13.5\text{ V}$, $T_A = 125\text{ }^{\circ}\text{C}$, $I_{\text{OUTECV,ECFD}} = 0.4\text{ A}$		2500	3400	m Ω	D.020
I_{QLH}	Switched-off output current high-side drivers of HS7-HS15, HS0 ⁽¹⁾	$V_{\text{OUT}} = 0\text{ V}$, standby mode	-5			μA	D.021
		$V_{\text{OUT}} = 0\text{ V}$, active mode	-10			μA	D.022
	Switched-off output current high-side drivers of HB1-HB6 ⁽¹⁾	$V_{\text{OUT}} = 0\text{ V}$, standby mode	-6			μA	D.023
		$V_{\text{OUT}} = 0\text{ V}$, active mode	-100			μA	D.024

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
I _{QLL}	Switched-off output current low-side drivers of	V _{OUT} = V _S , standby mode			165	μA	D.025
	HB1-HB6 ⁽¹⁾	V _{OUT} = V _S - 0.5 V, active mode	-100				D.026
	Switched-off output current	V _{OUT} = V _S - 2.5 V, standby mode (with E _{CDR} = V _S)	-15		15	μA	D.027
	low-side driver of ECV ⁽¹⁾	V _{OUT} = V _S - 2.5 V, active mode (with E _{CDR} = V _S)	-10			μA	D.028

1. Negative value: leakage internally sink from driver output pin to internal IC ground. Positive value: leakage sourced from internal driver output pin to external ground.

2.4.11 Power outputs switching times

Table 17. Power outputs switching times

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Items
t _{d ON H}	Output delay time high-side driver on HS7 low resistance	V _S = 13.5 V ⁽¹⁾⁽²⁾	5.5		77.5	μs	D.099
	Output delay time high-side driver on HS7 high resistance	See Figure 13. SPI CSN output timing	15	35	60	μs	D.100
t _{d OFF H}	Output delay time high-side driver off HS7 low resistance	V _S = 13.5 V ⁽¹⁾⁽²⁾	7	150	300	μs	D.101
	Output delay time high-side driver off HS7 high resistance	See Figure 13. SPI CSN output timing	9	18	45	μs	D.102
t _{d ON H}	Output delay time high-side driver on (HB1,HB6)	V _S = 13.5 V ⁽²⁾ corresponding high-side driver is not active; Rload = 16 Ω (from CSN 50% to OUT 20%)	0.05		5	μs	D.029
t _{d OFF H}	Output delay time high-side driver off (HB1,HB6)	V _S = 13.5 V ⁽²⁾ Rload = 16 Ω (from CSN 50% to OUT 80%)	0.05		7	μs	D.031
t _{d ON L}	Output delay time low-side driver on (HB1,HB6)	V _S = 13.5 V ⁽²⁾ corresponding high-side driver is not active 3 Rload = 16 Ω (from CSN 50% to OUT 80%)	0.05		3	μs	D.035
t _{d OFF L}	Output delay time low-side driver off (HB1,HB6)	V _S = 13.5 V ⁽¹⁾ corresponding high-side driver is not active 1 (from CSN 50% to OUT 20%)	0.05		3	μs	D.036
t _{d ON H}	Output delay time high-side driver on (HB2,HB3)	V _S = 13.5 V ⁽²⁾ corresponding high-side driver is not active; (from CSN 50% to OUT 20%)	5.5		77.5	μs	D.103
t _{d OFF H}	Output delay time high-side driver off (HB2,HB3)	V _S = 13.5 V ⁽²⁾ (from CSN 50% to OUT 80%)	20	70	140	μs	D.104
t _{d ON L}	Output delay time low-side driver on (HB2,HB3)	V _S = 13.5 V ⁽²⁾ corresponding high-side driver is not active; (from CSN 50% to OUT 80%)	10	30	70	μs	D.105

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Items
$t_{d\ OFF\ L}$	Output delay time low-side driver off (HB2,HB3)	$V_S = 13.5\ V^{(2)}$ (from CSN 50% to OUT 20%)	35	150	300	μs	D.106
$t_{d\ ON\ H}$	Output delay time high-side driver on (HB4)	$V_S = 13.5\ V^{(3)}$ corresponding high-side driver is not active; (from CSN 50% to OUT 20%)	0.05		5	μs	D.107
$t_{d\ OFF\ H}$	Output delay time high-side driver off (HB4)	$V_S = 13.5\ V^{(3)}$ (from CSN 50% to OUT 80%)	0.05		7	μs	D.108
$t_{d\ ON\ L}$	Output delay time low-side driver on (HB4)	$V_S = 13.5\ V^{(3)}$ corresponding high-side driver is not active; (from CSN 50% to OUT 80%)	0.05		3	μs	D.109
$t_{d\ OFF\ L}$	Output delay time low-side driver off (HB4)	$V_S = 13.5\ V^{(3)}$ (from CSN 50% to OUT 20%)	0.05		3	μs	D.110
$t_{d\ ON\ H}$	Output delay time high-side driver on (HB5)	$V_S = 13.5\ V^{(3)}$ corresponding high-side driver is not active; (from CSN 50% to OUT 20%)	0.05		5	μs	D.111
$t_{d\ OFF\ H}$	Output delay time high-side driver off (HB5)	$V_S = 13.5\ V^{(3)}$ (from CSN 50% to OUT 80%)	0.05		7	μs	D.112
$t_{d\ ON\ L}$	Output delay time low-side driver on (HB5)	$V_S = 13.5\ V^{(3)}$ corresponding high-side driver is not active; (from CSN 50% to OUT 80%)	0.05		3	μs	D.113
$t_{d\ OFF\ L}$	Output delay time low-side driver off (HB5)	$V_S = 13.5\ V^{(3)}$ (from CSN 50% to OUT 20%)	0.05		3	μs	D.114
$T_{d\ OFF\ H}$	Output delay time high-side driver HS8,HS9,HS10 OFF (delay between CSN or DIR 50% to OUT at 20% of VS)	$V_S = 13.5\ V, V_1 = 5\ V,$ $R_{load} = 128\ \Omega$	5		70	μs	D.115
$T_{d\ ON\ H}$	Output delay time high-side driver HS8,HS9,HS10 ON (delay between CSN or DIR 50% to OUT at 20% of VS)	$V_S = 13.5\ V, V_1 = 5\ V,$ $R_{load} = 128\ \Omega$	2		50	μs	D.116
$T_{d\ OFF\ H}$	Output delay time high-side driver OFF (HS11,...,HS15,HS0) (delay between CSN or DIR 50% to OUT at 20% of VS)	$V_S = 13.5\ V, V_1 = 5\ V,$ $R_{load} = 128\ \Omega$	20		140	μs	D.034
$T_{d\ ON\ H}$	Output delay time high-side driver ON (HS11,...,HS15,HS0) (delay between CSN or DIR 50% to OUT at 80% of VS)	$V_S = 13.5\ V, V_1 = 5\ V,$ $R_{load} = 128\ \Omega$	10		60	μs	D.033
$t_{d\ ON\ L}$	Output delay time low-side driver on (ECV)	$V_S = 13.5\ V^{(1)(2)(3)}$ See Figure 13. SPI CSN output timing	10	30	70	μs	D.134
$t_{d\ OFF\ L}$	Output delay time low-side driver off (ECV)	$V_S = 13.5\ V^{(1)(2)(3)}$ See Figure 13. SPI CSN output timing	25	90	200	μs	D.037
t_{CCP}	Cross current protection time HB1,... HB6		180	300	500	μs	D.038
$d_{VOUT/dt}$	Slew rate for drivers HB2,HB3, HS7-HS15, HS0, LS ECV	$V_S = 13.5\ V^{(1)(2)(3)(4)}$		0.2		V/ μs	D.040

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Items
$d_{VOUT/dt}$	Slew rate on output drivers HB1, HB4, HB5, HB6 controlled by PWM4-5 / PWM1-6	$V_S = 13.5 \text{ V}^{(1)(2)(3)(4)}$	6	10	20	V/ μ s	D.117
$d_{Vmax/dt}^{(5)}$	Maximum external applied slew rate on HB1-HB6 without switching on the LS and HS		20			V/ μ s	D.041
f_{PWM1}	PWM switching frequency Tested by scan	$V_S/V_{SREG} = 13.5 \text{ V}$		100		Hz	D.043
f_{PWM2}	PWM switching frequency Tested by scan	$V_S/V_{SREG} = 13.5 \text{ V}$		200		Hz	D.044
DC1	SPI configurable duty cycle for HS7... HS15 and HS0 Tested by scan	0.1% steps	0.1		100	%	D.118

1. $R_{load} = 16 \Omega$ at HB1, HB6 and HS7 in low on-resistance mode.
2. $R_{load} = 128 \Omega$ at HB2, HB3, HS8, HS9, HS10, HS11, HS12, HS13, HS14, HS15, HS0, ECV and HS7 in high on-resistance mode.
3. $R_{load} = 4 \Omega$ at HB4, HB5.
4. Slope $d_{VOUT/dt}$ is measured between 20% and 80% of the final output voltage value.
5. Parameter specified by design, not tested in production.

2.4.12

Output current thresholds

The voltages are referred to power ground and currents are assumed positive, when the current flows into the pin.
 $6 \text{ V} < V_S < 28 \text{ V}$; $6 \text{ V} < V_{SREG} < 28 \text{ V}$; $T_J = -40^\circ\text{C}$ to 150°C , unless otherwise specified.

Table 18. Output current thresholds

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$ I_{SC1} $ $ I_{SC6} $	Short-current threshold HS and LS	$V_S = 13.5 \text{ V}$, $V_1 = 5 \text{ V}$, sink full V_S range is specified by design	5		11	A	D.049
$ I_{SC2} $ $ I_{SC3} $	Short-current threshold HS and LS	$V_S = 13.5 \text{ V}$, $V_1 = 5 \text{ V}$, sink full V_S range is specified by design	0.9		1.8	A	D.047
$ I_{SC4} $	Short-current threshold HS and LS	$V_S = 13.5 \text{ V}$, $V_1 = 5 \text{ V}$, sink full V_S range is specified by design	9		19	A	D.119
$ I_{SC5} $	Short-current threshold HS and LS	$V_S = 13.5 \text{ V}$, $V_1 = 5 \text{ V}$, sink full V_S range is specified by design	10		21	A	D.120
$ I_{OC1th1} $	Overcurrent threshold HS and LS of HB1 (config. 1)	$V_S = 13.5 \text{ V}$, Current limitation set by CR16, bit 12 and 13	1.5	2	2.7	A	D.121
$ I_{OC1th2} $	Overcurrent threshold HS and LS of HB1 (config. 2)		2.25	3	4	A	D.122
$ I_{OC1th3} $	Overcurrent threshold HS and LS of HB1 (config. 3)		3	4	4.9	A	D.123
$ I_{OC2} $ $ I_{OC3} $	Overcurrent threshold HS and LS	$V_S = 13.5 \text{ V}$, sink and source	0.5		1.0	A	D.050
$ I_{OC4} $			6		9.2	A	D.124
$ I_{OC5th1} $	Overcurrent threshold HS and LS of HB5 (config. 1)	$V_S = 13.5 \text{ V}$, Current limitation set by CR16, bit 14 and 15	3.4	4	5.3	A	D.125
$ I_{OC5th2} $	Overcurrent threshold HS and LS of HB5 (config. 2)		5.1	6	7.9	A	D.126
$ I_{OC5th3} $	Overcurrent threshold HS and LS of HB5 (config. 3)		7.5		10.5	A	D.127

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item						
I_{OC6th1}	Overcurrent threshold HS and LS of HB6 (config. 1)	$V_S = 13.5\text{ V}$, Current limitation set by CR16, bit 16 and 17	1.5	2	2.7	A	D.128						
I_{OC6th2}	Overcurrent threshold HS and LS of HB6 (config. 2)		2.25	3	4	A	D.129						
I_{OC6th3}	Overcurrent threshold HS and LS (config. 3)		3	4	4.9	A	D.052						
I_{OC7}	Overcurrent threshold HS in low on-resistance mode	$V_S = 13.5\text{ V}$, source	1.5		2.5	A	D.053						
	Overcurrent threshold HS in high on-resistance mode		0.35		0.65	A	D.054						
I_{OC8} I_{OC9} I_{OC10}	Overcurrent threshold HS		0.5		1	A	D.059						
I_{OC11} I_{OC12} I_{OC13} I_{OC14} I_{OC15} I_{OC0}			0.19		0.35	A	D.062						
I_{OCECV}			Output current limitation LS	$V_S = 13.5\text{ V}$, sink	0.5		1.0	A	D.063				
I_{CCM7} I_{CCM8} I_{CCM9} I_{CCM10} I_{CCM11} I_{CCM12} I_{CCM13} I_{CCM14} I_{CCM15} I_{CCM0}			Constant current mode value for HS7 (in high on-resistance mode) to HS15 and HS0	$V_S = 13.5\text{ V}$; $HSx_CCM = 1$ (x = 7 to 15, 0)	100		mA	D.064					
$t_{CCMtimeout}$									Constant current mode expiration time	$HSx_CCM = 1$ (x = 7 to 15, 0) tested by scan		20	ms
t_{FSC}	Filter time of short-current signal in half bridge outputs	Tested by scan							1	3	6.5	μs	D.066
t_{FOC}	Filter time of overcurrent signal in HS11, ..., HS15 and HS0	Tested by scan							38.4	48	67.6	μs	D.137
t_{BLK}	Blanking time of overcurrent signal (all outputs) and of short-circuit current signal in half bridges	Tested by scan							32	40	58	μs	D.067
$t_{FOC_PWM}^{(1)}$	Filter time of overcurrent signal in all half bridges in PWM mode (no blanking time t_{BLK} applied)		5	9	12	μs	D.135						
$t_{FSC_PWM}^{(1)}$	Filter time of short-circuit current signal in all half bridges in PWM mode (no blanking time t_{BLK} applied)		4	7	10	μs	D.136						

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
t _{OCR00}	T _{ON} time of overcurrent signal in HB1,... HB6, HS7, ..., HS10 (includes blanking time t _{BLK} and is also valid if OCR is disabled)	xx_OCR_TON[0,1] = 00		88		μs	D.068
t _{OCR01}		xx_OCR_TON[0,1] = 01		80		μs	D.069
t _{OCR10}		xx_OCR_TON[0,1] = 10		72		μs	D.070
t _{OCR11}		xx_OCR_TON[0,1] = 11		64		μs	D.071
f _{OCR00}	Recovery frequency for OC	xx_OCR_FREQ[0,1] = 00		1.7		kHz	D.072
f _{OCR01}		xx_OCR_FREQ[0,1] = 01		2.2		kHz	D.073
f _{OCR10}		xx_OCR_FREQ[0,1] = 10		3		kHz	D.074
f _{OCR11}		xx_OCR_FREQ[0,1] = 11		4.4		kHz	D.075
I _{OLD1} ⁽²⁾ I _{OLD6} ⁽²⁾	Undercurrent threshold HS and LS	V _S = 13.5 V, sink and source	1	30	95	mA	D.079
I _{OLD2} ⁽²⁾ I _{OLD3} ⁽²⁾			1	20	36	mA	D.078
I _{OLD4} ⁽²⁾ I _{OLD5} ⁽²⁾			30	150	300	mA	D.133
I _{OLD7} ⁽²⁾	Undercurrent threshold HS in low on-resistance mode	V _S / V _{SREG} = 13.5 V source	15	50	90	mA	D.081
	Undercurrent threshold HS in high on-resistance mode		3	12	25	mA	D.082
I _{OLD8} ⁽²⁾ I _{OLD9} I _{OLD10} ⁽²⁾	Undercurrent threshold HS		10	20	30	mA	D.083
I _{OLD11} ⁽²⁾ I _{OLD12} ⁽²⁾ I _{OLD13} ⁽²⁾ I _{OLD14} ⁽²⁾ I _{OLD15} I _{OLD0} ⁽²⁾	Undercurrent threshold HS		0.2	0.65	1.5	mA	D.086
I _{OLDECv} ⁽²⁾	Undercurrent threshold LS		2	20	35	mA	D.091
t _{FOL}	Filter time of open-load signal	Duration of open-load condition to set the status bit. Tested by scan		200		μs	D.092

1. Parameter specified by design, not tested in production.
2. I_{OLD} parameters, in the range 8 V to 16 V, are specified by design and evaluated by characterization. Production testing is done at 13.5 V.

2.4.13 Heater

The voltages are referred to power ground and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_S < 28\text{ V}$, $T_J = -40\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$, unless otherwise specified.

Table 19. Heater

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$I_{GHheater}$	Average charge current (charge sage)	$T_J = 25^{\circ}\text{C}$		0.3		A	A.059
$V_{GHheater}$	Gate-on voltage	$V_S = SH = 6\text{ V}$; No load	$V_{SHeater} + 6$			V	A.062
		$V_S = SH = 12\text{ V}$; No load	$V_{SHeater} + 8$	$V_{SHeater} + 10$	$V_{SHeater} + 12$	V	A.063
$R_{GSHeater}$	Passive gate clamp resistance	Measurement of the slope between $V_{GHx} = 6\text{ V}$ and $V_{GHx} = 3\text{ V}$		15		k Ω	A.064
$T_{G(HL)xHL}$	Propagation delay time high to low (switch mode) ¹	$V_S = 13.5\text{ V}$, $V_{SHx} = 0\text{ V}$, $R_G = 0\text{ }\Omega$, $C_G = 2.7\text{ nF}$		1.5		μs	A.065
$T_{G(HL)xLH}$	Propagation delay time low to high (switch mode)	$V_S = 13.5\text{ V}$, $V_{SLx} = 0$, $R_G = 0\text{ }\Omega$, $C_G = 2.7\text{ nF}$		1.5		μs	A.066
$t_{0GHheater}$	Rise time (switch mode)	$V_S = 13.5\text{ V}$, $V_{SHeater} = 0$, $R_G = 0\text{ }\Omega$, $C_G = 2.7\text{ nF}$		45		ns	A.067
$t_{0GHheaterf}$	Fall Time (switch mode)	$V_S = 13.5\text{ V}$, $V_{SHeater} = 0$, $R_G = 0\text{ }\Omega$, $C_G = 2.7\text{ nF}$		85		ns	A.068

2.4.14 H-bridge driver

The voltages are referred to power ground and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_S < 28\text{ V}$, $6\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$, unless otherwise specified.

Table 20. H-bridge driver

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$I_{GHx(Ch)}$	Average charge current (charge stage)	$T_J = 25^{\circ}\text{C}$	0.1	0.3	0.75	A	A.069
R_{GHx}	On-resistance (discharge stage)	$V_{SHx} = 0\text{ V}$, $I_{GHx} = 50\text{ mA}$, $T_J = 25^{\circ}\text{C}$	4	8	12	Ω	A.070
		$V_{SHx} = 0\text{ V}$, $I_{GHx} = 50\text{ mA}$, $T_J = 125^{\circ}\text{C}$		12	18	Ω	A.071
V_{GHx}	Gate on voltage	$V_S = SH = 6\text{ V}$; $I_{CP} = 15\text{ mA}$	$V_{SHx} + 6$			V	A.072
		$V_S = SH = 12\text{ V}$; $I_{CP} = 15\text{ mA}$	$V_{SHx} + 8$	$V_{SHx} + 10$	$V_{SHx} + 11.5$	V	A.073
R_{GSx}	Passive gate clamp resistance	Measurement of the slope between $V_{GHx} = 6\text{ V}$ and $V_{GHx} = 3\text{ V}$		15		k Ω	A.074
Drivers for external low-side Power MOSFET							
$I_{GLx(Ch)}$	Average charge current (charge stage)	$T_J = 25^{\circ}\text{C}$	0.1	0.3	0.75	A	A.075
R_{GLx}	On-resistance (discharge stage)	$V_{SLx} = 0\text{ V}$, $I_{GLx} = 50\text{ mA}$, $T_J = 25^{\circ}\text{C}$	4	8	12	Ω	A.076
		$V_{SLx} = 0\text{ V}$, $I_{GLx} = 50\text{ mA}$, $T_J = 125^{\circ}\text{C}$		12	18	Ω	A.077
V_{GHLx}	Gate on voltage	$V_S = 6\text{ V}$; $I_{CP} = 15\text{ mA}$	$V_{SLx} + 6$			V	A.078
		$V_S = 12\text{ V}$; $I_{CP} = 15\text{ mA}$	$V_{SLx} + 8$	$V_{SLx} + 10$	$V_{SLx} + 11.5$	V	A.079
R_{GSLx}	Passive gate clamp resistance			15		k Ω	A.080

2.4.15 Gate drivers for the external Power MOSFET switching times

The voltages are referred to power ground and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_S < 28\text{ V}$; $6\text{ V} < V_{SREG} < 28\text{ V}$; $T_J = -40\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$, unless otherwise specified.

Table 21. Gate drivers for external Power MOSFET switching times

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$T_{G(HL)xHL}$	Propagation delay time high to low (switch mode) ⁽¹⁾	$V_S = 13.5\text{ V}$, $V_{SHx} = 0$, $R_G = 0\text{ }\Omega$, $C_G = 2.7\text{ nF}$		1.5		μs	A.081
$T_{G(HL)xLH}$	Propagation delay time low to high (switch mode) ⁽¹⁾	$V_S = 13.5\text{ V}$, $V_{SLx} = 0$, $R_G = 0\text{ }\Omega$, $C_G = 2.7\text{ nF}$		1.5		μs	A.082
$I_{GHx\text{max}}$	Maximum source current (current mode)	$V_S = 13.5\text{ V}$, $V_{SHx} = 0$, $V_{GHx} = 1\text{ V}$, $\text{SLEW}<4:0> = 1\text{ FH}$		32		mA	A.083
$I_{GHx\text{fmax}}$	Maximum sink current (current mode)	$V_S = 13.5\text{ V}$, $V_{SHx} = 0$, $V_{GHx} = 2\text{ V}$, $\text{SLEW}<4:0> = 1\text{ FH}$		32		mA	A.084
d_{IIGHxr}	Source current accuracy	$V_S = 13.5\text{ V}$, $V_{SHx} = 0\text{ V}$, $V_{GHx} = 1\text{ V}$		See Figure 7. I_{GHxr} range (a)			A.085
d_{IIGHxf}	Sink current accuracy	$V_S = 13.5\text{ V}$, $V_{SHx} = 0\text{ V}$, $V_{GHx} = 2\text{ V}$		See Figure 8. I_{GHxf} range (b)			A.086
$V_{DSHxrSW}^{(2)}$	Switching voltage ($V_S - V_{SH}$) between current mode and switch mode (rising)	$V_S = 13.5\text{ V}$	0.4	1.5	2.6	V	A.087
$V_{DSHxfSW}^{(2)}$	Switching voltage ($V_S - V_{SH}$) between switch mode and current mode (falling)	$V_S = 13.5\text{ V}$	0.4	1.5	2.6	V	A.088
t_{0GHxr}	Rise time (switch mode)	$V_S = 13.5\text{ V}$, $V_{SHx} = 0\text{ V}$, $R_G = 0\text{ }\Omega$, $C_G = 2.7\text{ nF}$		45		ns	A.089
t_{0GHxf}	Fall time (switch mode)	$V_S = 13.5\text{ V}$, $V_{SHx} = 0\text{ V}$, $R_G = 0\text{ }\Omega$, $C_G = 2.7\text{ nF}$		85		ns	A.090
t_{0GLxr}	Rise time	$V_S = 13.5\text{ V}$, $V_{SLx} = 0\text{ V}$, $R_G = 0\text{ }\Omega$, $C_G = 2.7\text{ nF}$		45		ns	A.091
t_{0GLxf}	Fall time	$V_S = 13.5\text{ V}$, $V_{SLx} = 0\text{ V}$, $R_G = 0\text{ }\Omega$, $C_G = 2.7\text{ nF}$		85		ns	A.092
$t_{ccp0010}$	Programmable cross current protection time	Tested by scan		750		ns	A.095
$t_{ccp0011}$	Programmable cross current protection time	Tested by scan		1000		ns	A.096
$t_{ccp0100}$	Programmable cross current protection time	Tested by scan		1250		ns	A.097
$t_{ccp0101}$	Programmable cross current protection time	Tested by scan		1500		ns	A.098
$t_{ccp0110}$	Programmable cross current protection time	Tested by scan		1750		ns	A.099
$t_{ccp0111}$	Programmable cross current protection time	Tested by scan		2000		ns	A.100
$t_{ccp1000}$	Programmable cross current protection time	Tested by scan		2250		ns	A.101

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$t_{ccp1001}$	Programmable cross current protection time	Tested by scan		2500		ns	A.102
$t_{ccp1010}$	Programmable cross current protection time	Tested by scan		2750		ns	A.103
$t_{ccp1011}$	Programmable cross current protection time	Tested by scan		3000		ns	A.104
$t_{ccp1100}$	Programmable cross current protection time	Tested by scan		3250		ns	A.105
$t_{ccp1101}$	Programmable cross current protection time	Tested by scan		3500		ns	A.106
$t_{ccp1110}$	Programmable cross current protection time	Tested by scan		3750		ns	A.107
$t_{ccp1111}$	Programmable cross current protection time	Tested by scan		4000		ns	A.108
f_{PWMH}	PWMH switching frequency ⁽¹⁾	$V_S = 13.5\text{ V}$, $V_{SLx} = 0$, $R_G = 0\ \Omega$, $C_G = 2.7\text{ nF}$, PWMH-duty-cycle = 50%			50	kHz	A.109

1. Without cross-current protection time t_{CCP} .
2. Specified by design, not tested in production.

Figure 6. H-Driver delay times

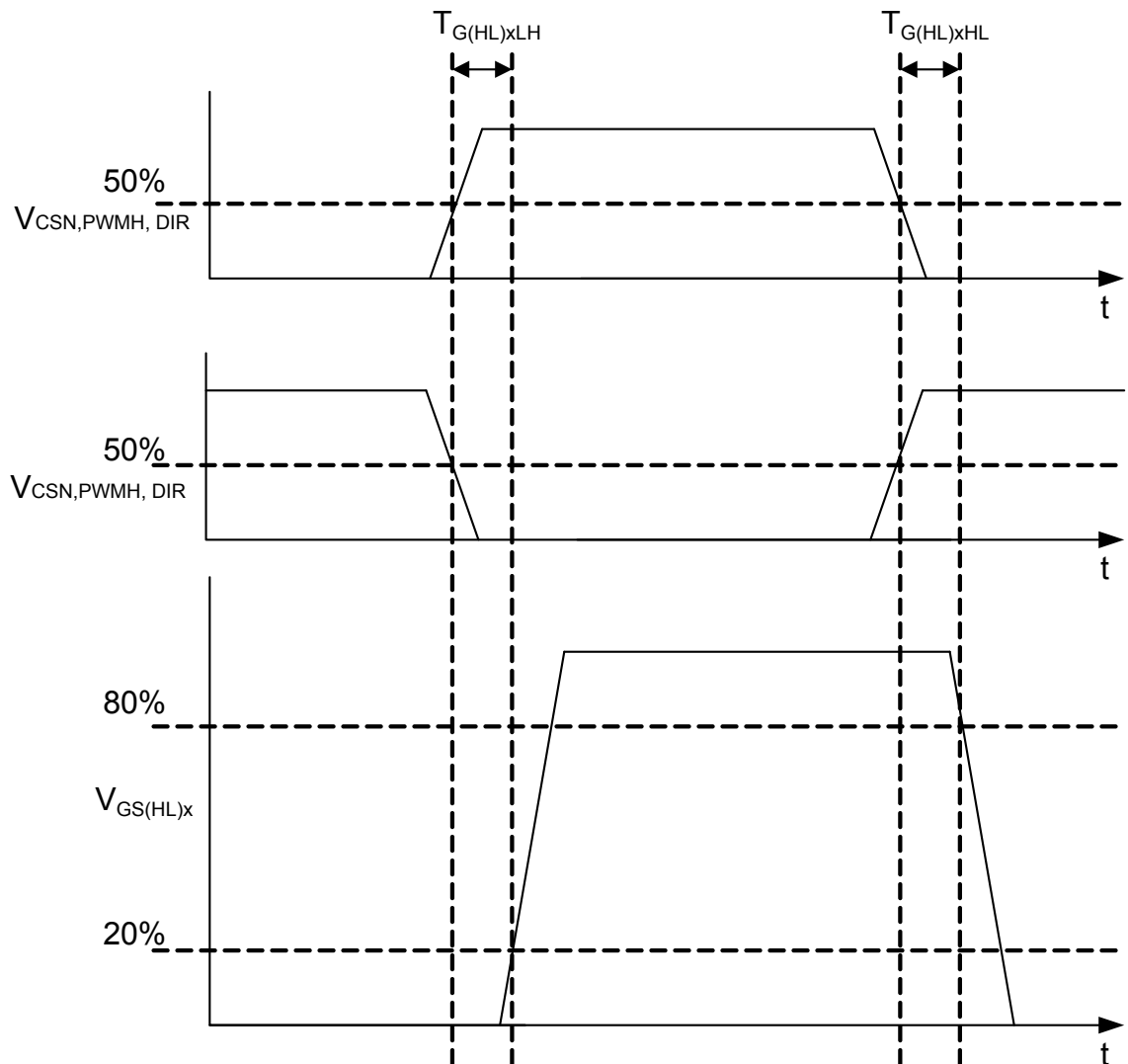


Figure 7. IGHxr range (a)

IGHxr accuracy

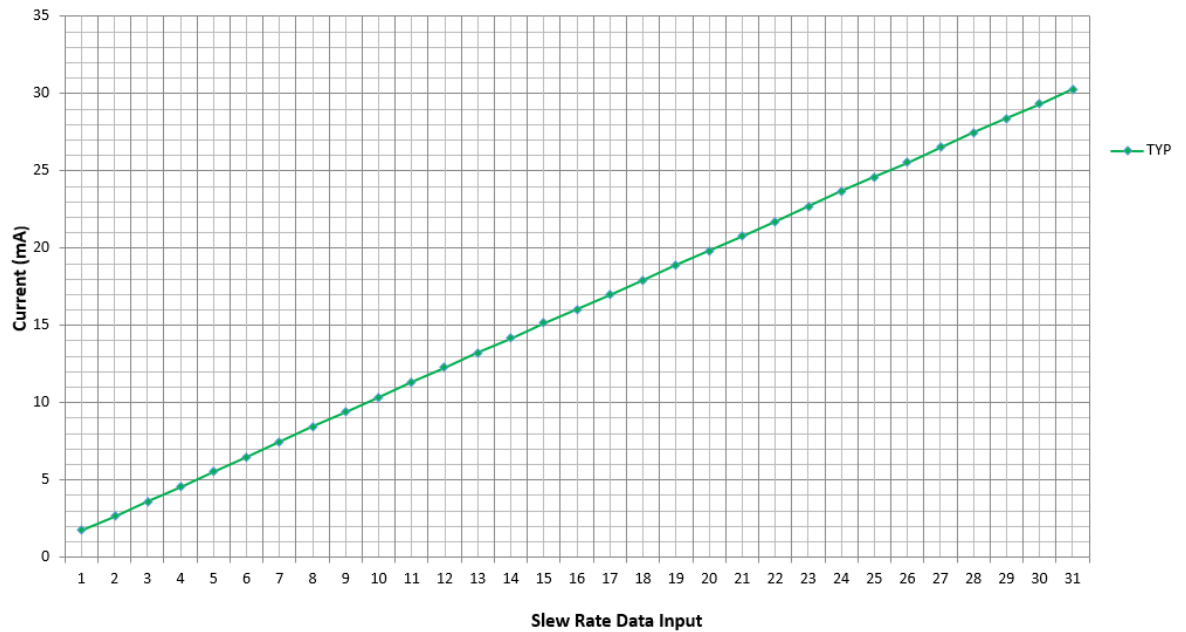
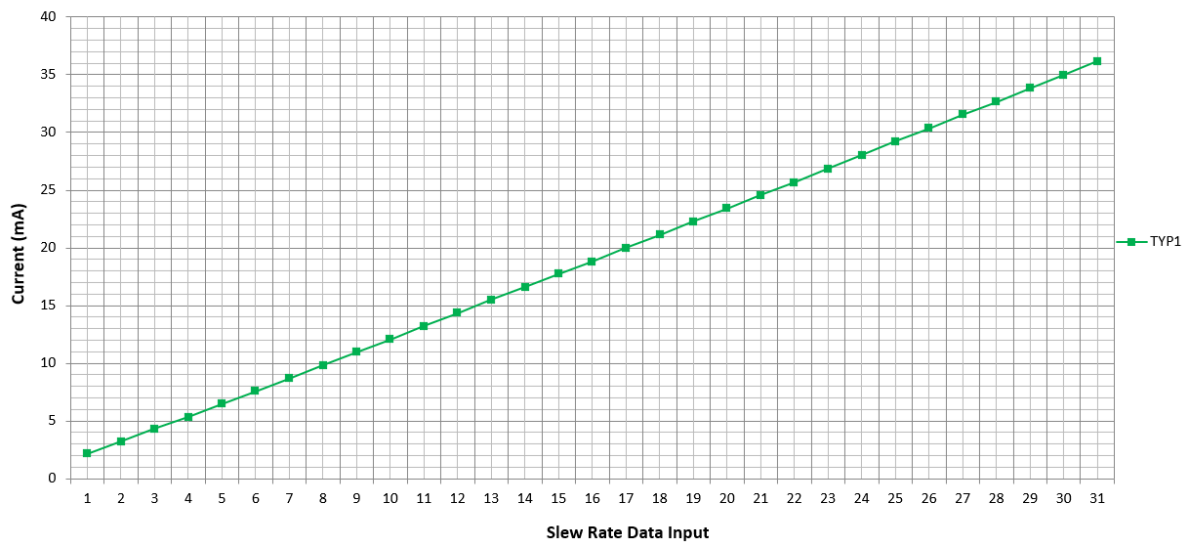


Figure 8. IGHxf range (b)

IGHxf accuracy



2.4.16 Drain-source monitoring external H-bridge

The voltages are referred to power ground and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_S < 28\text{ V}$, $6\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40$ to 150°C , unless otherwise specified.

Table 22. Drain-source monitoring external H-bridge

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{scd1_HS}	Drain-source threshold voltage on HS		0.4	0.55	0.7	V	A.110
V_{scd1_LS}	Drain-source threshold voltage on LS		0.3	0.45	0.6	V	A.196
V_{scd2_HS}	Drain-source threshold voltage on HS		0.9	1.05	1.2	V	A.111
V_{scd2_LS}	Drain-source threshold voltage on LS		0.75	0.95	1.15	V	A.197
V_{scd3_HB}	Drain-source threshold voltage		1.27	1.5	1.73	V	A.112
V_{scd4_HB}	Drain-source threshold voltage		1.7	2	2.3	V	A.113
t_{scd_HB}	Drain-source monitor filter time	Tested by scan		6		μs	A.117
t_{scs_HB}	Drain-source comparator settling time	$V_S = 13.5\text{ V}$, $V_{SH} = \text{jump from GND to } V_S$			5	μs	A.118

2.4.17 Drain-source monitoring external heater Power MOSFET

The voltages are referred to power ground and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_S < 28\text{ V}$, $6\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40$ to 150°C , unless otherwise specified.

Table 23. Drain-source monitoring external heater Power MOSFET

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{SCd1_HE}	Drain-source threshold voltage		175	205	240	mV	A.119
V_{SCd2_HE}	Drain-source threshold voltage		220	256	295	mV	A.120
V_{SCd3_HE}	Drain-source threshold voltage		265	308	350	mV	A.121
V_{SCd4_HE}	Drain-source threshold voltage		310	360	405	mV	A.122
V_{SCd5_HE}	Drain-source threshold voltage		350	410	460	mV	A.123
V_{SCd6_HE}	Drain-source threshold voltage		395	460	515	mV	A.124
V_{SCd7_HE}	Drain-source threshold voltage		440	513	570	mV	A.125
V_{SCd8_HE}	Drain-source threshold voltage		480	564	625	mV	A.126
V_{SCd9_HE}	Drain-source threshold voltage		525	615	680	mV	A.184
V_{SCd10_HE}	Drain-source threshold voltage		570	666	735	mV	A.185
t_{scd_HE}	Drain-source monitor filter time	Tested by scan		6		μs	A.127
t_{scs_HE}	Drain-source comparator settling time	$V_S = 13.5\text{ V}$; $V_{SH} = \text{jump from GND to } V_S$			5	μs	A.128

2.4.18 Open-load monitoring external H-bridge

The voltages are referred to power ground and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_S < 28\text{ V}$, $6\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40$ to 150°C , unless otherwise specified.

Table 24. Open-load monitoring external H-bridge

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{ODSL}	Low-side drain-source monitor low threshold voltage	$V_{SLx} = 0\text{ V}$; $V_S = 13.5\text{ V}$	$0.05 \times V_S$	$0.15 \times V_S$	$0.25 \times V_S$	V	A.130
V_{ODSH}	Low-side drain-source monitor high off threshold voltage	$V_{SLx} = 0\text{ V}$; $V_S = 13.5\text{ V}$	$0.75 \times V_S$	$0.85 \times V_S$	$0.95 \times V_S$	V	A.131
V_{OLSHx}	Output voltage of selected S_{Hx} in open-load test mode	$V_{SLx} = 0\text{ V}$; $V_S = 13.5\text{ V}$	$0.4 \times V_S$	$0.5 \times V_S$	$0.6 \times V_S$	V	A.132
R_{pdOL}	Pulldown resistance of the non selected S_{Hx} pin in open-load mode	$V_{SLx} = 0\text{ V}$; $V_S = 13.5\text{ V}$; $V_{SHx} = 4.5\text{ V}$		20		k Ω	A.133
t_{OL_HB}	Open-load filter time	Tested by scan		2		ms	A.134

2.4.19 Open-load monitoring external heater Power MOSFET

The voltages are referred to power ground and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_S < 28\text{ V}$, $6\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40$ to 150°C , unless otherwise specified.

Table 25. Open-load monitoring external heater Power MOSFET

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$V_{OLheater}$	Open-load threshold voltage	$V_{SLx} = 0\text{ V}$; $V_S = 13.5\text{ V}$	1	2	3	V	A.135
$I_{OLheater}$	Pull-up current source open-load diagnosis activated	$V_{SLx} = 0\text{ V}$; $V_S = 13.5\text{ V}$; $V_{SHheater} = 4.5\text{ V}$	0.5	1	2	mA	A.136
t_{OL_HE}	Open-load filter time	Tested by scan		2		ms	A.137

2.4.20 Electrochrome mirror driver

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_S < 28\text{ V}$, $6\text{ V} < V_{SREG} < 28\text{ V}$, $T_J = -40$ to 150°C , unless otherwise specified.

Table 26. Electrochrome mirror driver

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$V_{CTRLmax}$	Maximum EC-control voltage	Bit19 = 1 in CR1 (0x26) ⁽¹⁾	1.4		1.6	V	A.138
		Bit19 = 0 in CR1 (0x26) ⁽¹⁾	1.12		1.28	V	A.139
DNL_{ECV}	Differential Non Linearity		-1		1	LSB ⁽²⁾⁽³⁾	A.140
I_{dVECVI}	Voltage deviation between target and ECV	$dV_{ECV} = V_{target}^{(4)} - V_{ECV}$, $I_{ECDRI} < 1\text{ }\mu\text{A}$	-5%-1LSB ⁽²⁾		+5%+1LSB ⁽²⁾	mV	A.141
d_{VECVnr}	Difference voltage between target and ECV sets flag if VECV is below it	$dV_{ECV} = V_{target}^{(4)} - V_{ECV}$ toggle bitx = 1 status reg. x		120		mV	A.142
d_{VECVhi}	Difference voltage between target and ECV sets flag if VECV is above it	$dV_{ECV} = V_{target}^{(4)} - V_{ECV}$ toggle bitx = 1 status reg. x		-120		mV	A.143
t_{FEVCNR}	ECVNR filter time	Tested by scan		32		μs	A.144

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
t_{FECVHI}	ECVHI filter time	Tested by scan		32		μs	A.145
$V_{ECDRminHIGH}$	Output voltage range	$I_{ECDR} = -10 \mu A$	V1-0.3		V1	V	A.146
$V_{ECDRmaxLOW}$		$I_{ECDR} = 10 \mu A$	0		0.7	V	A.147
I_{ECDR}	Current into ECDR	$V_{target}^{(4)} > V_{ECV} + 500 mV$, $V_{ECDR} = 3.5 V$	-100		-10	μA	A.148
		$V_{target}^{(4)} < V_{ECV} - 500 mV$, $V = 1.0 V$; $V_{target} = 0 V$; $V_{ECV} = 0.5 V$	10		100	μA	A.149
$R_{ecdrdis}$	Pull-down resistance at ECDR in fast discharge mode and while EC mode is off.	$V_{ECDR} = 0.7 V$; ECON = '1', EC<5:0> = 0 or ECON = '0'			10	k Ω	A.150

1. Bit ECV_HV = '1' or '0': ECV voltage, where I_{ECDR} can change sign.
2. 1 LSB (least significant bit) = $23.8 m V_{typ}$.
3. 0000 DAC code is not included in DNL_{ECV} test.
4. V_{target} is set by bits EC_[5:0] and bit ECV_HV; tested for each individual bit.

2.4.21 External interrupts (EI1, EI2)

The voltages are referred to GND and currents are assumed positive, when the current flows into the pin.
 $6 V < V_{SREG} < 28 V$, $T_J = -40$ to $150^\circ C$, unless otherwise specified.

Table 27. External interrupts

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{WU_THn}	Wake-up negative edge threshold voltage		$0.4 V_{SREG}$	$0.45 V_{SREG}$	$0.5 V_{SREG}$	V	A.159
V_{WU_THp}	Wake-up positive edge threshold voltage		$0.5 V_{SREG}$	$0.55 V_{SREG}$	$0.65 V_{SREG}$	V	A.160
V_{HYST}	Hysteresis		$0.05 V_{SREG}$	$0.1 V_{SREG}$	$0.15 V_{SREG}$	V	A.161
t_{wu_stat}	Static wake filter time	Tested by scan		$64^{(1)}$		μs	A.162
I_{wu_stdby}	Input current in standby mode on Elx pins	$V_{WU} < 1 V$ or $V_{WU} > (V_S - 1.5 V)$	2	30	60	μA	A.163
R_{wu_act}	Input resistor to Gnd in active mode and in standby mode during wake-up input sensing		80	160	300	k Ω	A.164
t_{wu_cyc}	Cyclic wake filter time	Tested by scan		16		μs	A.165

1. Specified by design, not tested in production.

2.4.22

CAN FD transceiver

ISO 11898-2:2016 compliant.

SAE J2284 compliant.

The voltages are referred to GND and currents are assumed positive when the current flows into the pin.

$6\text{ V} < V_{\text{SREG}} < 18\text{ V}$, $4.8\text{ V} < V_{\text{cansup.}} < 5.2\text{ V}$, $T_J = -40^\circ\text{C}$ to 150°C , unless otherwise specified.

$-12\text{ V} \leq (\text{CANH} + \text{CANL})/2 \leq 12\text{ V}$.

Table 28. CAN communication operating range

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$V_{\text{SREG_Transmitter}}$	Supply voltage operating range for CAN transmitter ⁽¹⁾		5.5		18	V	E.001
$V_{\text{SREG_Receiver}}$	Supply voltage operating range for CAN receiver		5		18	V	E.093
$V_{\text{CANSUPlow}}$	CAN supply low voltage flag	$V_{V1} = V_{\text{CANSUP}}$ decreasing	3.9	4.2	4.5	V	E.002
$V_{\text{CANHL,CM}}$	Common mode bus voltage ($V_{\text{CANH}} + V_{\text{CANL}}/2$)	Measured with respect to the ground of each CAN transceiver	-12		12	V	E.003
I_{TRCV}	Transceiver current consumption during normal mode	Active mode: $R_L =$ from $50\ \Omega$ to $65\ \Omega$, $C_{\text{RXD}} = 15\text{ pF}$, $70\% V_{\text{RXDC}}$ (rising) - $30\% V_{\text{RXDC}}$ (falling), TXD rise and fall time = 10 ns ($10\% - 90\%$, $90\% - 10\%$), Test signal to be applied on the TXD input of the implementation is a square wave signal with a positive duty cycle of $1/6$ and a period of six times the nominal recessive bit width rectangular pulse signal $T_{\text{TXDC}} = 6 \cdot \text{TBIT}^{(2)}$, high pulse $1 \cdot \text{TBIT}$, low pulse $5 \cdot \text{TBIT}$			120	mA	E.094
$I_{\text{TRCV_short}}$	Transceiver current consumption during output short	$R_L = 50\ \Omega$ to $65\ \Omega$, $V_{\text{CANH}} = -3\text{ V}$ or $V_{\text{CANL}} = 40\text{ V}$			120	mA	E.095
$I_{\text{TRCVLPbias}}$	Transceiver current consumption; biasing active	$R_L =$ from $50\ \Omega$ to $65\ \Omega$, $V_{\text{TXDC}} = V_{\text{TXDCHIGH}}$		400	600	μA	E.096
I_{TRCVLP}	Transceiver current consumption during low-power mode; biasing inactive	$R_L = 50\ \Omega$ to $65\ \Omega$, $V_{\text{TXDC}} = V_{\text{TXDCHIGH}}$			50	μA	E.097

1. At $V_{\text{SREG}} < V_{\text{SREG_Transmitter(min)}}$ the transceiver shall enter high impedance state.

2. The bit time T_{BIT} is the nominal bit time at a given bit rate ($T_{\text{BIT}} = 1/\text{BR}$). For example: at $\text{BR} = 2\text{ Mb/s} \Rightarrow T_{\text{BIT}} = 500\text{ ns}$.

Table 29. CAN transmit data input: pin TXDC

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$V_{TXDCLOW}$	Input voltage dominant level	Active mode	1.0	1.45	2.0	V	E.004
$V_{TXDCHIGH}$	Input voltage recessive level	Active mode	1.2	1.85	2.3	V	E.005
$V_{TXDCHYS}$	$V_{TXDCHIGH} - V_{TXDCLOW}$	Active mode	0.2		0.7	V	E.006
R_{TXDCPU}	TXDC pull-up resistor	Active Mode	20	50	110	k Ω	E.007
$t_{d,TXDC(dom-rec)}$	TXDC - CAN _{H,L} delay time dominant - recessive	$R_L =$ from 50 Ω to 65 Ω , 70 % V_{TXD} – 30% V_{DIFF} , 5.5 V $\leq V_S \leq$ 18 V, TXDC rise time = 10 ns (10% - 90%)		120		ns	E.008
$t_{d,TXDC(rec-diff)}$	TXDC - CAN _{H,L} delay time recessive - dominant	$R_L =$ from 50 Ω to 65 Ω , 30 % V_{TXD} – 70% V_{DIFF} , 5.5 V $\leq V_S \leq$ 18 V, TXDC fall time = 10 ns (90% - 10%)		120		ns	E.009
$t_{dom}(TXDC)$	TXDC dominant time-out	Tested by scan	0.8	2	5	ms	E.010

Table 30. CAN receive data output: pin RXDC

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$V_{RXDCLOW}$	Output voltage dominant level	Active mode, $I_{RXDC} = 2$ mA	0	0.2	0.5	V	E.011
$V_{RXDCHIGH}$	Output voltage recessive level	Active mode, $I_{RXDC} = -2$ mA	V1-0.5	V1-0.2	V1	V	E.012
$t_{r,RXDC}^{(1)}$	RXDC rise time	$C_L = 15$ pF, 30% - 70% V_{RXDC}	0		25	ns	E.013
$t_{f,RXDC}^{(1)}$	RXDC fall time	$C_L = 15$ pF, 70% - 30% V_{RXDC}	0		25	ns	E.014
$t_{d,RXDC(dom-rec)}^{(1)}$	CAN _{H,L} – RXDC delay time dominant - recessive	$C_L = 15$ pF, 30% V_{DIFF} – 70% V_{RXDC}		120		ns	E.015
$t_{d,RXDC(rec-dom)}^{(1)}$	CAN _{H,L} – RXDC delay time recessive - dominant	$C_L = 15$ pF, 70% V_{DIFF} – 30% V_{RXDC}		120		ns	E.016

1. Specified by design, not tested in production.

Table 31. CAN transmitter dominant output characteristics

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$V_{CANHdom}$	Single ended CANH voltage level in dominant state	$V_{TXDC} = V_{TXDCLOW}$, $R_L =$ from 50 Ω to 65 Ω	2.75	3.5	4.5	V	E.017
$V_{CANLdom}$	Single ended CANL voltage level in dominant state	$V_{TXDC} = V_{TXDCLOW}$, $R_L =$ from 50 Ω to 65 Ω	0.5	1.5	2.25	V	E.018
$V_{DIFF,dom}$	Differential output voltage in dominant state: $V_{CANHdom} - V_{CANLdom}$	$V_{TXDC} = V_{TXDCLOW}$, $R_L =$ from 50 Ω to 65 Ω	1.5	2.0	3	V	E.019
V_{DIFF_Arb}	Differential output voltage in dominant state during arbitration: $V_{CANHdom} - V_{CANLdom}$	$V_{TXDC} = V_{TXDCLOW}$, $R_L = 2240$ Ω	1.5		5	V	E.099

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{DIFF,dom_ext}	Differential output voltage in dominant state on extended bus load range: $V_{CANHdom} - V_{CANLdom}$	$V_{TXDC} = V_{TXDCLOW}$, $R_L = \text{from } 45 \Omega \text{ to } 70 \Omega$	1.4		3.3	V	E.100
$V_{DIFF,domVsLow}$	Differential output voltage in dominant state: $V_{CANHdom} - V_{CANLdom}$ at low V_S	$V_{TXDC} = V_{TXDCLOW}$, $R_L = \text{from } 50 \Omega \text{ to } 65 \Omega$, $5 V < V_S < 5.5 V$ ⁽¹⁾	1.35		3	V	E.101
V_{DIFF,dom_ext_VsLow}	Differential output voltage in dominant state: $V_{CANHdom} - V_{CANLdom}$ with 45Ω to 70Ω load at low V_S	$V_{TXDC} = V_{TXDCLOW}$, $R_L = \text{from } 45 \Omega \text{ to } 70 \Omega$, $5 V < V_S < 5.5 V$ ⁽¹⁾	1.25		3.3	V	E.102
V_{SYM}	Driver symmetry $V_{SYM} = (V_{CANH} + V_{CANL}) / V_{CANSUP}$ $V_{CANSUP} = 5 V$ ⁽²⁾	$R_L = 60 \Omega \pm 1\%$, $f_{TXDC} = 1 \text{ MHz}$, ⁽³⁾ $C_{SPLIT} = 4.7 \text{ nF} (\pm 5\%)$	0.9	1	1.1		E.020
$I_{OCANH,dom} (-3V)$	CANH output current in dominant state	$V_{TXDC} = V_{TXDCLOW}$, $V_{CANH} = \text{from } -3 V \text{ to } 18 V$	-115		115	mA	E.021
$I_{OCANL,dom} (18V)$	CANL output current in dominant state	$V_{TXDC} = V_{TXDCLOW}$, $V_{CANL} = \text{from } -3 V \text{ to } 18 V$	-115		115	mA	E.022
$I_{OCANH,dom} (40V)$	CANH output current in dominant state	$V_{TXDC} = V_{TXDCLOW}$, $V_{CANH} = 40 V$, $V_S = 40 V$	0		15	mA	E.023
$I_{OCANL,dom} (40V)$	CANL output current in dominant state	$V_{TXDC} = V_{TXDCLOW}$, $V_{CANL} = 40 V$, $V_S = 40 V$	0		115	mA	E.024

- V_S at device pin after reverse battery protection, while application is supplied with 6 V. Operating condition has to be adapted, if a higher voltage drop occurs in the application.
- If it is an external pin, it should be supplied externally.
- Measurement equipment input load $< 20 \text{ pF}$, $> 1 \text{ M}\Omega$, guaranteed by E.017, E.018, E.021, E.022, E.045, E.046 measurements.

Table 32. CAN transmitter recessive output characteristics, CAN normal mode

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$V_{CANHrec}$	CANH voltage level in recessive state (normal mode)	$V_{TXDC} = V_{TXDCHIGH}$, no load	2	2.5	3	V	E.025
$V_{CANLrec}$	CANL voltage level in recessive state (normal mode)	$V_{TXDC} = V_{TXDCHIGH}$, no load	2	2.5	3	V	E.026
$V_{DIFF,recOUT}$	Differential output voltage in recessive state (normal mode): $V_{CANHrec} - V_{CANLrec}$	$V_{TXDC} = V_{TXDCHIGH}$, no load	-50		50	mV	E.027

Note: CAN normal mode: tested in TRX ready state while the device is in active mode.

Table 33. CAN receiver input characteristics during CAN normal mode

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{THdom}	Differential receiver threshold voltage recessive to dominant state	$-12\text{ V} \leq V_{CANH} \leq 12\text{ V}$, $12\text{ V} \leq V_{CANL} \leq 12\text{ V}$	0.5		0.9	V	E.034
V_{dom_range}	Differential dominant input level voltage range	$-12\text{ V} \leq V_{CANH} \leq 12\text{ V}$, $-12\text{ V} \leq V_{CANL} \leq 12\text{ V}$	0.9		10	V	E.103
V_{THrec}	Differential receiver threshold voltage dominant to recessive state	$12\text{ V} \leq V_{CANH} \leq 12\text{ V}$, $-12\text{ V} \leq V_{CANL} \leq 12\text{ V}$	0.5		0.9	V	E.035
V_{rec_range}	Differential recessive input level voltage range	$-12\text{ V} \leq V_{CANH} \leq 12\text{ V}$, $-12\text{ V} \leq V_{CANL} \leq 12\text{ V}$	-5		0.5	V	E.104

Note: CAN normal mode: tested in TRX ready state while the device is in active mode.

Table 34. CAN receiver input characteristics during CAN low-power mode, biasing inactive

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$V_{THdomLP}$	Differential receiver threshold voltage recessive to dominant state	$12\text{ V} \leq V_{CANH} \leq 12\text{ V}$, $-12\text{ V} \leq V_{CANL} \leq 12\text{ V}$	0.4		1.15	V	E.038
$V_{dom_range_LP}$	Differential dominant input level voltage range	$-12\text{ V} \leq V_{CANH} \leq 12\text{ V}$, $-12\text{ V} \leq V_{CANL} \leq 12\text{ V}$	1.15		10	V	E.105
$V_{THrecLP}$	Differential receiver threshold voltage dominant to recessive state	$12\text{ V} \leq V_{CANH} \leq 12\text{ V}$, $-12\text{ V} \leq V_{CANL} \leq 12\text{ V}$	0.4		1.15	V	E.039
$V_{rec_range_LP}$	Differential recessive input level voltage range	$-12\text{ V} \leq V_{CANH} \leq 12\text{ V}$, $-12\text{ V} \leq V_{CANL} \leq 12\text{ V}$	-5		0.4	V	E.106
$V_{CANHrecLP}$	CANH output voltage in recessive state		-0.1		0.1	V	E.120
$V_{CANLrecLP}$	CANL output voltage in recessive state		-0.1		0.1	V	E.121
$V_{DIFF,recOUTLP}$	Differential output voltage in recessive state: $V_{CANHrecLP} - V_{CANLrecLP}$		-0.2		0.2	V	E.122

Note: CAN low-power mode, biasing inactive: tested in CAN TRX STDBY (bias off) state while the device is in active mode, V1_Standby mode and VBAT_Standby mode.

Table 35. CAN receiver input resistance

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
R_{diff}	Differential internal resistance	$V_{TXDC} = V_{TXDCHIGH}$, No load $R_{diff} = R_{CANH} + R_{CANL}$ $-2\text{ V} \leq V_{CANH} \leq 7\text{ V}$, $-2\text{ V} \leq V_{CANL} \leq 7\text{ V}^{(1)}$	12		100	k Ω	E.040
$R_{CANH, CANL}$	Single ended internal resistance	$V_{TXDC} = V_{TXDCHIGH}$, No load $-2\text{ V} \leq V_{CANH} \leq 7\text{ V}$, $-2\text{ V} \leq V_{CANL} \leq 7\text{ V}^{(1)}$	6		50	k Ω	E.041
m_R	Internal resistance matching $R_{CANH, CANL}$	Biasing active, $V_{TXDC} = V_{TXDCHIGH}$, no load, $m_R = 2 \times (R_{CAN_H} - R_{CAN_L}) / (R_{CAN_H} + R_{CAN_L})$, 10 k Ω resistor between CANH-CANL pin with external 5 V	-0.03		0.03		E.042

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$C_{in}^{(2)}$	Internal capacitance			20	40	pF	E.043
$C_{in,diff}^{(2)}$	Differential internal capacitance			10	20	pF	E.044

1. Voltage range is taken from ISO CD 16845-2 (high speed medium access unit - conformance test plan).
2. Parameter specified by design, not tested in production.

Note:

CAN normal and low-power mode, biasing active: tested in CAN TRX normal and CAN TRX STDBY (bias on) state while the device is in active and V1_Standby mode.

Table 36. CAN transceiver delay

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$t_{LOOP,hl}$	Loop delay TXDC to RXDC (high to low)	5.5 V < V_S < 18 V, $R_L = 60 \Omega \pm 1\%$, $C_L = 100$ pF, $C_{RXDC} = 15$ pF, 30% V_{TXDC} - 30% V_{RXDC} , TXDC fall time = 10 ns (90% - 10%)			255	ns	E.045
$t_{LOOP,lh}$	Loop delay TXDC to RXDC (low to high)	5.5 V < V_S < 18 V, $R_L = 60 \Omega \pm 1\%$, $C_L = 100$ pF, $C_{RXDC} = 15$ pF, 70% V_{TXD} - 70% V_{RXD} , TXDC rise time = 10 ns (10% - 90%)			255	ns	E.046
$t_{LOOP150,hl}$	Loop delay TXDC to RXDC (high to low) with 150 Ω bus load	5.5 V < V_S < 18 V, $R_L = 150 \Omega$, $C_L = 100$ pF, $C_{RXDC} = 15$ pF, 30% V_{TXDC} - 30% V_{RXDC} , TXDC fall time = 10 ns (90% - 10%)			350	ns	E.107
$t_{LOOP150,lh}$	Loop delay TXDC to RXDC (low to high) with 150 Ω bus load	5.5 V < V_S < 18 V, $R_L = 150 \Omega$, $C_L = 100$ pF, $C_{RXDC} = 15$ pF, 70% V_{TXD} - 70% V_{RXD} , TXDC rise time = 10 ns (10% - 90%)			350	ns	E.108
$T_{Bit(RXD)} \leq 1$ Mb/s ⁽¹⁾	Recessive bit symmetry at RXDC	5.5 V < V_S < 18 V, $R_L = 60 \Omega \pm 1\%$, $C_L = 100$ pF, $C_{RXD} = 15$ pF, 70% V_{RXDC} (rising) - 30% V (falling), TXDC rise and fall time = 10 ns (10% - 90%, 90% - 10%), Test signal to be applied on the TXDC input of the implementation is a square wave signal with a positive duty cycle of 1/6 and a period of six times the nominal recessive bit width. Rectangular pulse signal $T_{TXDC} = 6000$ ns, high pulse 1000 ns, low pulse 5000 ns	900	1000	1050	ns	E.047
$T_{Bit(RXD)}_{150 \Omega} \leq 1$ Mb/s		$R_L = 150 \Omega$, other conditions as $T_{Bit(RXD)} \leq 1$ Mb/s, value may be obtained by characterization only.	800		1050		E.109
$T_{Bit(RXD)} \leq 2$ Mb/s		Conditions as $T_{Bit(RXD)} \leq 1$ Mb/s, Rectangular pulse signal $T_{TXDC} = 3000$ ns, high pulse 500 ns, low pulse 2500 ns	400	500	550		E.110
$T_{Bit(RXD)}_{150 \Omega} \leq 2$ Mb/s		$R_L = 150 \Omega$, other conditions as $T_{Bit(RXD)} \leq 1$ Mb/s, value may be obtained by characterization only	300		550		E.111

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$T_{\text{Bit(RXD)}} \leq 5 \text{ Mb/s}$	Recessive bit symmetry at RXDC	Conditions as $T_{\text{Bit(RXD)}} \leq 1 \text{ Mb/s}$, Rectangular pulse signal $T_{\text{TXDC}} = 1200 \text{ ns}$, high pulse 200 ns, low pulse 1000 ns	120	200	220	ns	E.112
$T_{\text{Bit(BUS)}} \leq 1 \text{ Mb/s}$	Recessive bit symmetry at CAN-Bus	5.5 V < V_S < 18 V, $R_L = 60 \Omega \pm 1\%$, $C_L = 100 \text{ pF}$, $C_{\text{RXD}} = 15 \text{ pF}$, V_{DIFF} : 0.5 V (falling) - 0.9 V (rising), TXD rise and fall time = 10 ns (10% - 90%, 90% - 10%), test signal to be applied on the TXD input of the implementation is a square wave signal with a positive duty cycle of 1/6 and a period of six times the nominal recessive bit width. Rectangular pulse signal $T_{\text{TXDC}} = 6000 \text{ ns}$, high pulse 1000 ns, low pulse 5000 ns	935	1000	1030	ns	E.113
$T_{\text{Bit(BUS)}} \leq 2 \text{ Mb/s}$		Conditions as $T_{\text{Bit(BUS)}} \leq 1 \text{ Mb/s}$, Rectangular pulse signal $T_{\text{TXDC}} = 3000 \text{ ns}$, high pulse 500 ns, low pulse 2500 ns	435	500	530		E.114
$T_{\text{Bit(BUS)}} \leq 5 \text{ Mb/s}$		Conditions as $T_{\text{Bit(BUS)}} \leq 1 \text{ Mb/s}$, Rectangular pulse signal $T_{\text{TXDC}} = 1200 \text{ ns}$, high pulse 200 ns, low pulse 1000 ns	155	200	210		E.115
$\Delta t_{\text{REC}} \leq 2 \text{ Mb/s}$	Receiver timing symmetry ($T_{\text{Bit(RXD)}} - T_{\text{Bit(BUS)}}$)	5.5 V < V_S < 18 V, $R_L = 60 \Omega \pm 1\%$, $C_L = 100 \text{ pF}$, $C_{\text{RXD}} = 15 \text{ pF}$, Rectangular pulse signal $T_{\text{TXDC}} = 3000 \text{ ns}$, high pulse 500 ns, low pulse 2500 ns	-65		40	ns	E.116
$\Delta t_{\text{REC}} \leq 5 \text{ Mb/s}$		5.5 V < V_S < 18 V, $R_L = 60 \Omega \pm 1\%$, $C_L = 100 \text{ pF}$, $C_{\text{RXD}} = 15 \text{ pF}$, Rectangular pulse signal $T_{\text{TXDC}} = 1200 \text{ ns}$, high pulse 200 ns, low pulse 1000 ns	-45		15		E.117
$t_{\text{CAN}}^{(2)}$	CAN permanent dominant time out	Tested by scan		700		μs	E.118
$t_{\text{WUP-V}_{\text{Cansup}}}$	Time between WUP ⁽³⁾ on the CAN bus until V_{Cansup} goes active	Wake-up pattern wake-up 70% V_{DIFF} – 90% $V_{\text{Cansup(min)}}$	0		200	μs	E.049
$t_{\text{WUP-RXD}}$	Time between WUP ⁽³⁾ on the CAN bus until RXD is active (the CAN signal is represented at the RXD output)	Wake-up pattern wake-up RXD output enabled	0		1	ms	E.119
$t_{\text{VCANSUPlow}}$	Filter time needed to display CANSUPlow flag	Tested by SCAN		5		μs	E.124

1. $T_{\text{Bit(RXD)}}$ for the highest supported data rate has to be specified (1 Mb/s, 2 Mb/s, 5 Mb/s).
2. At the expiration of this filter time a flag is set.
3. Time starts with the end of last dominant phase of the WUP.

Table 37. CAN receiver input current

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$I_{\text{Leakage, CANH}}$	Input leakage current CANH	Unpowered device, $V_{\text{CANH}} = 5 \text{ V}$, $V_{\text{CANL}} = 5 \text{ V}$, $V_{\text{S}} < V_{\text{POR_F}}^{(1)}$, V_{S} , $V_{\text{CANSUP}}^{(2)}$ connected via 0Ω to GND, V_{S} , $V_{\text{CANSUP}}^{(2)}$ connected via $47 \text{ k}\Omega$ to GND, $T_{\text{J}} = -40$ to $130 \text{ }^{\circ}\text{C}$	-5		5	μA	E.050
$I_{\text{Leakage, CANL}}$	Input leakage current CANL	Unpowered device, $V_{\text{CANH}} = 5 \text{ V}$, $V_{\text{CANL}} = 5 \text{ V}$, $V_{\text{S}} < V_{\text{POR_F}}^{(1)}$, V_{S} , $V_{\text{CANSUP}}^{(3)}$ connected via 0Ω to GND, V_{S} , $V_{\text{CANSUP}}^{(3)}$ connected via $47 \text{ k}\Omega$ to GND, $T_{\text{J}} = -40$ to $130 \text{ }^{\circ}\text{C}$	-5		5	μA	E.052

1. V_{S} not floating.
2. Related to the external supply pin of the CAN-transceiver. If the transceiver supply is generated entirely inside the device the parameter is measured with respect to the supply of the device.
3. Related to the external supply pin of the CAN-transceiver. If the transceiver supply is generated entirely inside the device the parameter is measured with respect to the supply of the device; if the transceiver is supplied by its own supply pin, this pin has to fulfill this specification as well as the supply that is used to generate the transceiver voltage in case it is on the same device.

Note: The leakage currents have to be measured with the supply of the CAN-transceiver connected to ground either directly or via $47 \text{ k}\Omega$. If the CAN-transceiver supply is generated by the device from V_{S} , V_{S} has to be connected to ground. If the CAN-transceiver is supplied by another device, the supply of the CAN-transceiver has to be connected to ground.

Table 38. Biasing control timings

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
t_{filter}	CAN activity filter time		0.5		1.8	μs	E.054
t_{wake}	Wake-up time out	Tested by scan	0.8	1	5	ms	E.055
t_{Silence}	CAN timeout	Tested by scan	600	700	1200	ms	E.056
T_{Bias}	CAN bias reaction time				250	μs	E.123

2.4.23 LIN transceiver

LIN ISO 17987-4:2016 compliant for data rates up to 20 kBit/s

The voltages are referred to GND and currents are assumed positive, when the current flows into the pin.

$6 \text{ V} < V_{\text{SREG}} < 18 \text{ V}$, $T_{\text{J}} = -40 \text{ }^{\circ}\text{C}$ to $150 \text{ }^{\circ}\text{C}$ unless otherwise specified.

Table 39. LIN transmit data input: pin TXD

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{TXDLOW}	Input voltage dominant level	Active mode	1.0	1.45		V	E.058
V_{TXDHIGH}	Input voltage recessive level	Active mode		1.85	2.3	V	E.059
V_{TXDHYS}	$V_{\text{TXDHIGH}} - V_{\text{TXDLOW}}$	Active mode	0.2	0.4		V	E.060
R_{TXDPU}	TXD pull-up resistor	Active mode	13	29	49	$\text{k}\Omega$	E.061

Table 40. LIN receive data output: pin RXD

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V _{RXDLOW}	Output voltage dominant level	Active mode		0.2	0.5	V	E.062
V _{RXDHIGH}	Output voltage recessive level	Active mode	V1-0.5	V1-0.2		V	E.063

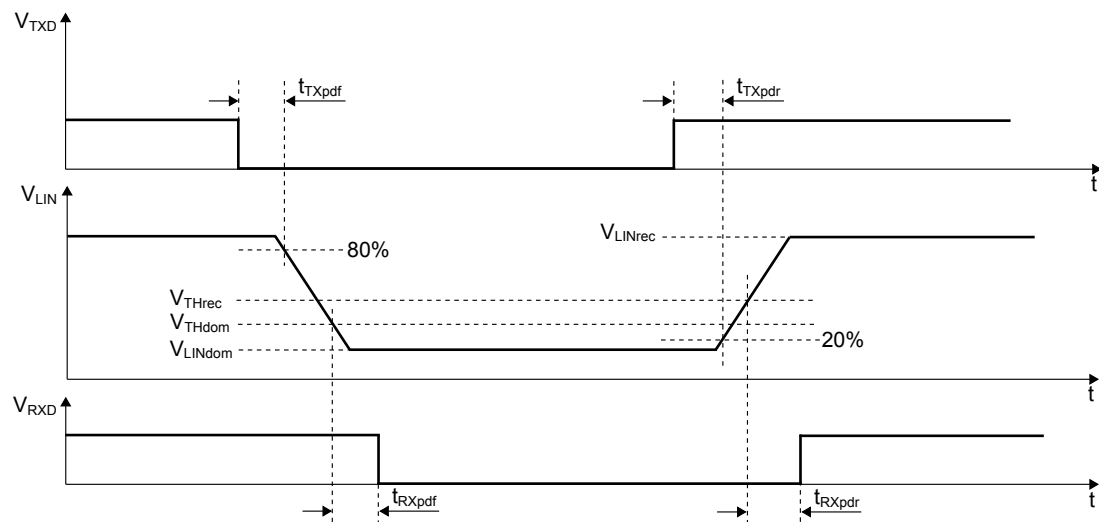
Table 41. LIN transmitter and receiver: pin LIN

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V _{THdom}	Receiver threshold voltage recessive to dominant state		0.4* V _{SREG}	0.45* V _{SREG}	0.5* V _{SREG}	V	E.064
V _{Busdom}	Receiver dominant state				0.4* V _{SREG}	V	E.065
V _{THrec}	Receiver threshold voltage dominant to recessive state		0.5* V _{SREG}	0.55* V _{SREG}	0.6* V _{SREG}	V	E.066
V _{Busrec}	Receiver recessive state		0.6* V _{SREG}			V	E.067
V _{THhys}	Receiver threshold hysteresis: V _{THrec} - V _{THdom}		0.07* V _{SREG}	0.1* V _{SREG}	0.175* V _{SREG}	V	E.068
V _{THcnt}	Receiver tolerance center value: (V _{THrec} + V _{THdom})/2		0.475* V _{SREG}	0.5* V _{SREG}	0.525* V _{SREG}	V	E.069
V _{THwkup}	Receiver wakeup threshold activation voltage (rising edge)		0.5* V _{SREG}	0.55* V _{SREG}	0.6* V _{SREG}	V	E.070
V _{THwkdown}	Receiver wakeup threshold activation voltage (falling edge)		0.4* V _{SREG}	0.45* V _{SREG}	0.5* V _{SREG}	V	E.071
t _{linbus}	LIN bus wake-up dominant filter time	Sleep mode; Edge: rec-dom; Tested by scan		64		μs	E.072
t _{dom_LIN}	LIN bus wake-up dominant filter time	Sleep mode; Edge: rec-dom-rec; Tested by scan	28			μs	E.073
I _{LINDomSC}	Transmitter input current limit in dominant state	V _{TXD} = V _{TXDLOW} ; V _{LIN} = V _{BAT} = 18 V	40	100	180	mA	E.074
I _{bus_PAS_dom}	Input leakage current at the receiver incl. pull-up resistor	V _{TXD} = V _{TXDHIGH} ; V _{LIN} = 0 V; V _{BAT} = 12 V ⁽¹⁾	-1			mA	E.075
I _{bus_PAS_rec}	Transmitter input current in recessive state	In standby modes; V _{TXD} = V _{TXDHIGH} ; V _{LIN} > 8 V; V _{BAT} < 18 V; V _{LIN} ≥ V _{BAT}			20	μA	E.076
I _{bus_NO_GND}	Input current if loss of GND at Device	GND = V _S ; 0 V < V _{LIN} < 18 V; V _{BAT} = 12 V	-1		1	mA	E.077
I _{bus}	Input current if loss of V _{BAT} at Device	GND = V _S ; 0 V < V _{LIN} < 18 V			30	μA	E.078
V _{LINdom}	LIN voltage level in dominant state	Active mode ; V _{TXD} = V _{TXDLOW} ; R _{bus} = 500 Ω			1.2	V	E.080
V _{LINrec}	LIN voltage level in recessive state	Active mode; V _{TXD} = V _{TXDHIGH} ; I _{LIN} = 10 μA	0.8* V _{SREG}			V	E.081
R _{LINup}	LIN output pull-up resistor	V _{LIN} = 0 V	20	40	60	kΩ	E.082
C _{LIN} ⁽²⁾	LIN input capacitance				30	pF	E.083

1. Slave mode.
2. Specified by design, not tested in production.

Table 42. LIN transceiver timing

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
t_{RXpd}	Receiver propagation delay time	$t_{RXpd} = \max(t_{RXpdr}, t_{RXpdf});$ $t_{RXpdf} = t(0.5 V_{RXD}) - t(0.45 V_{LIN});$ $t_{RXpdr} = t(0.5 V_{RXD}) - t(0.55 V_{LIN});$ $V_S = 12 V; C_{RXD} = 20 pF;$ $R_{bus} = 1 k\Omega, C_{bus} = 1 nF;$ $R_{bus} = 660 \Omega, C_{bus} = 6.8 nF; R_{bus} = 500 \Omega, C_{bus} = 10 nF$			6	μs	E.084
t_{RXpd_sym}	Symmetry of receiver propagation delay time (rising vs. falling edge)	$t_{RXpd_sym} = t_{RXpdr} - t_{RXpdf};$ $V_S = 12 V;$ $R_{bus} = 1 k\Omega, C_{bus} = 1 nF ;$ $C_{RXD} = 20 pF$	-2		2	μs	E.085
D1	Duty cycle 1	$T_{HRec(max)} = 0.744 * V_S; T_{HDom(max)} = 0.581 * V_S;$ $V_S = \text{from } 7 V \text{ to } 18 V, t_{bit} = 50 \mu s;$ $D1 = t_{bus_rec(min)} / (2 * t_{bit});$ $R_{bus} = 1 k\Omega, C_{bus} = 1 nF;$ $R_{bus} = 660 \Omega, C_{bus} = 6.8 nF; R_{bus} = 500 \Omega, C_{bus} = 10 nF$	0.396				E.086
D2	Duty cycle 2	$T_{HRec(min)} = 0.422 * V_S; T_{HDom(min)} = 0.284 * V_S;$ $V_S = \text{from } 7.6 V \text{ to } 18 V, t_{bit} = 50 \mu s;$ $D2 = t_{bus_rec(max)} / (2 * t_{bit});$ $R_{bus} = 1 k\Omega, C_{bus} = 1 nF;$ $R_{bus} = 660 \Omega, C_{bus} = 6.8 nF; R_{bus} = 500 \Omega, C_{bus} = 10 nF$			0.581		E.087
D3	Duty cycle 3	$T_{HRec(max)} = 0.778 * V_S; T_{HDom(max)} = 0.616 * V_S;$ $V_S = \text{from } 7 V \text{ to } 18 V, t_{bit} = 96 \mu s;$ $D3 = t_{bus_rec(min)} / (2 * t_{bit});$ $R_{bus} = 1 k\Omega, C_{bus} = 1 nF;$ $R_{bus} = 660 \Omega, C_{bus} = 6.8 nF; R_{bus} = 500 \Omega, C_{bus} = 10 nF$	0.417				E.088
D4	Duty cycle 4	$T_{HRec(min)} = 0.389 * V_S; T_{HDom(min)} = 0.251 * V_S;$ $V_S = \text{from } 7.6 V \text{ to } 18 V, t_{bit} = 96 \mu s;$ $D4 = t_{bus_rec(max)} / (2 * t_{bit});$ $R_{bus} = 1 k\Omega, C_{bus} = 1 nF;$ $R_{bus} = 660 \Omega, C_{bus} = 6.8 nF; R_{bus} = 500 \Omega, C_{bus} = 10 nF$			0.590		E.089
$t_{dom(TXDL)}$	TXDL dominant time out	Tested by scan		12		ms	E.090
t_{LIN}	LIN permanent recessive time out	Tested by scan		40		μs	E.091
$T_{dom(bus)}$	LIN bus permanent dominant time-out	Tested by scan		12		ms	E.092

Figure 9. LIN transmit, receive timing


2.4.24

SPI

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} < V_{\text{SREG}} < 18\text{ V}$, all outputs open, $T_J = -40\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$, unless otherwise specified.

Table 43. Input: CSN

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{CSNLOW}	Input voltage low level	Normal mode, $V_1 = 5\text{ V}$	1.0	1.45		V	B.001
V_{CSNHIGH}	Input voltage high level	Normal mode, $V_1 = 5\text{ V}$		1.85	2.3	V	B.002
V_{CSNHYS}	$V_{\text{CSNHIGH}} - V_{\text{CSNLOW}}$	Normal mode, $V_1 = 5\text{ V}$	0.2	0.4		V	B.003
I_{CSNPU}	CSN pull-up resistor	Normal mode, $V_1 = 5\text{ V}$	13	29	46	k Ω	B.004

Table 44. Inputs: CLK, DI

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$t_{\text{set}}^{(1)}$	Delay time from V1_Standby to active mode	Switching from V1_Standby to active mode using SPI wake-up access. Time until output drivers (P-channel) are enabled after CSN going to high. (First SPI wake-up access include the enable of the driver)		60		μs	B.005
		Switching from V1_Standby to active mode using SPI wake-up access. Time until output drivers (N-channel) are enabled after CSN going to high.		600		μs	B.006
$V_{\text{in L}}$	Input low level	$V_1 = 5\text{ V}$	1.0	1.45		V	B.007
$V_{\text{in H}}$	Input high level	$V_1 = 5\text{ V}$		1.8	2.3	V	B.008
$V_{\text{in Hyst}}$	Input hysteresis	$V_1 = 5\text{ V}$	0.2	0.4		V	B.009
I_{in}	Pull-down current at input	$V_{\text{in}} = 1\text{ V}$	5	30	60	μA	B.010
$C_{\text{in}}^{(1)}$	Input capacitance at input CSN, CLK, DI, PWM1-6 and PWM4-5	$0\text{ V} < V_1 < 5.3\text{ V}$		10	15	pF	B.011
f_{CLK}	SPI input frequency at CLK				4	MHz	B.012

1. Parameter specified by design, not tested in production.

Table 45. DI, CLK and CSN timing

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
t_{CLK}	Clock period	$V_1 = 5\text{ V}$	250			ns	B.013
t_{CLKH}	Clock high time	$V_1 = 5\text{ V}$	106.25			ns	B.014
t_{CLKL}	Clock low time	$V_1 = 5\text{ V}$	106.25			ns	B.015
$t_{set\ CSN}$	CSN setup time, CSN low before rising edge of CLK	$V_1 = 5\text{ V}$	150			ns	B.016
$t_{set\ CLK}$	CLK setup time, CLK high before rising edge of CSN	$V_1 = 5\text{ V}$	150			ns	B.017
$t_{set\ DI}$	DI setup time	$V_1 = 5\text{ V}$	25			ns	B.018
$t_{hold\ DI}$	DI hold time	$V_1 = 5\text{ V}$	25			ns	B.019
$t_{r\ in}^{(1)}$	Rise time of input signal DI, CLK, CSN	$V_1 = 5\text{ V}$			25	ns	B.020
$t_{f\ in}^{(1)}$	Fall time of input signal DI, CLK, CSN	$V_1 = 5\text{ V}$			25	ns	B.021

1. Parameter specified by design, not tested in production.

See also Figure 11. SPI input timing.

Table 46. Output DO

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{DOL}	Output low level	$V_1 = 5\text{ V}$, $I_{DO} = -4\text{ mA}$			0.5	V	B.022
V_{DOH}	Output high level	$V_1 = 5\text{ V}$, $I_{DO} = 4\text{ mA}$	$V_1 - 0.5$			V	B.023
I_{DOLK}	Tristate leakage current	$V_{CSN} = V_1$, $0\text{ V} < V_{DO} < V_1$	-10		10	μA	B.024
$C_{DO}^{(1)}$	Tristate input capacitance	$V_{CSN} = V_1$, $0\text{ V} < V_1 < 5.3\text{ V}$		10	15	pF	B.025

1. Parameter specified by design, not tested in production.

Table 47. DO timing

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$t_{r\ DO}^{(1)}$	DO rise time	$C_L = 50\text{ pF}$, $I_{load} = -1\text{ mA}$ from 0.3 V_1 to 0.7 V_1			25	ns	B.026
$t_{f\ DO}^{(1)}$	DO fall time	$C_L = 50\text{ pF}$, $I_{load} = 1\text{ mA}$ from 0.3 V_1 to 0.7 V_1			25	ns	B.027
$t_{en\ DO\ tri\ L}^{(1)}$	DO enable time from tristate to low level	$C_L = 50\text{ pF}$, $I_{load} = 1\text{ mA}$ pull-up load to V_1		50	100	ns	B.028
$t_{dis\ DO\ L\ tri}^{(1)}$	DO disable time from low level to 3-state	$C_L = 50\text{ pF}$, $I_{load} = 4\text{ mA}$ pull-up load to V_1		50	100	ns	B.029
$t_{en\ DO\ tri\ H}^{(1)}$	DO enable time from tristate to high level	$C_L = 50\text{ pF}$, $I_{load} = -1\text{ mA}$ pull-down load to GND		50	100	ns	B.030
$t_d\ DO^{(1)}$	DO delay time	$V_{DO} < 0.3\text{ V}_1$ or $V_{DO} > 0.7\text{ V}_1$, $C_L = 50\text{ pF}$		30	60	ns	B.032

1. Parameter is specified by design, not tested in production.

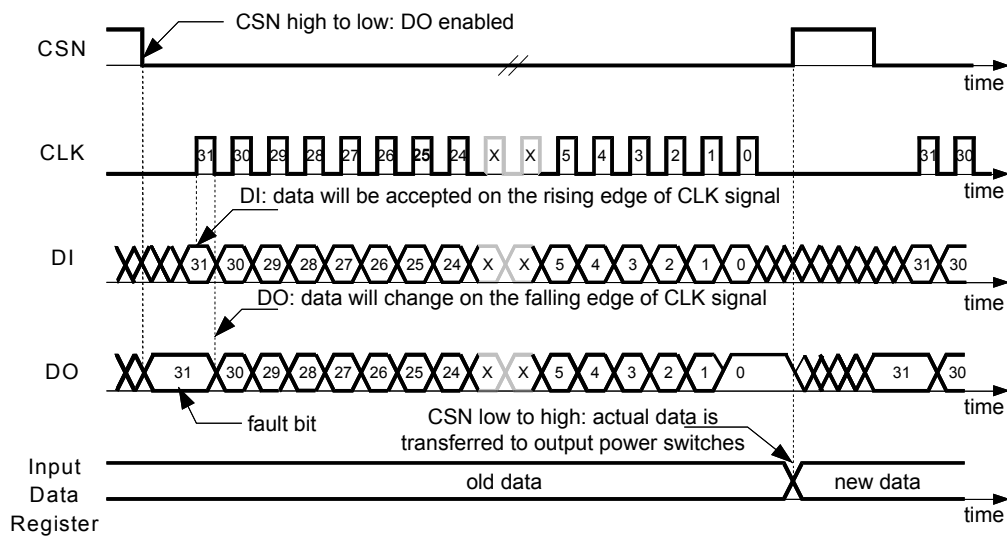
See Figure 12. SPI output timing.

Table 48. CSN timing

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
$t_{CSN_HI,min}^{(1)}$	Minimum CSN HI time, active mode	Transfer of SPI-command to Input register	0.5			μs	B.033
$t_{CSNfail}^{(1)}$	CSN low timeout	Tested by scan	20	35	50	ms	B.034

1. Parameter is specified by design, not tested in production.

Figure 10. SPI transfer timing diagram



The SPI can be driven by a microcontroller with its SPI peripheral running in the following mode: CPOL = 0 and CPHA = 0.

For this mode input data is sampled by the low to high transition of the clock CLK, and output data is changed from the high to low transition of CLK.

Figure 11. SPI input timing

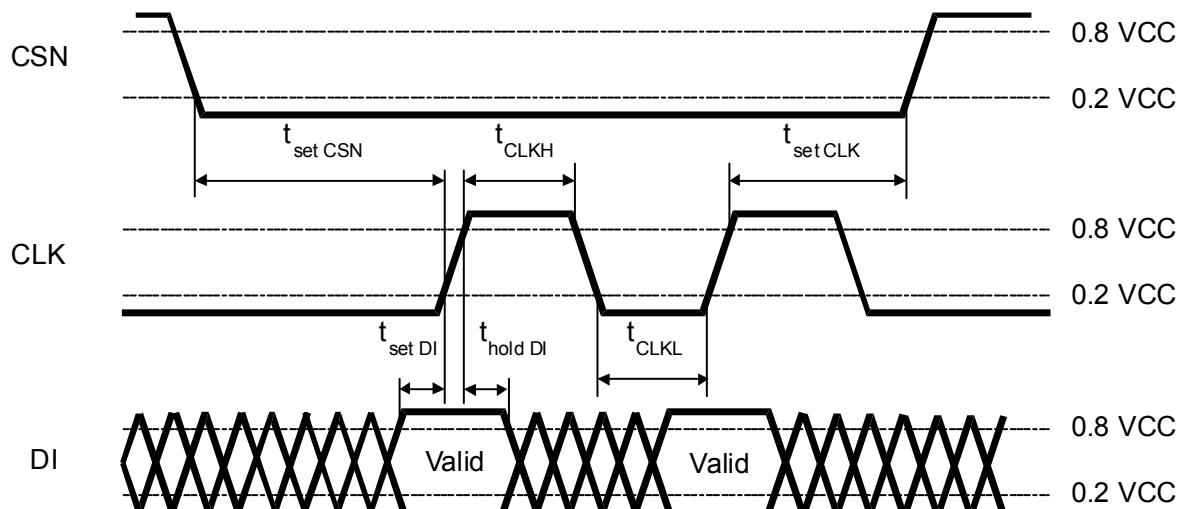


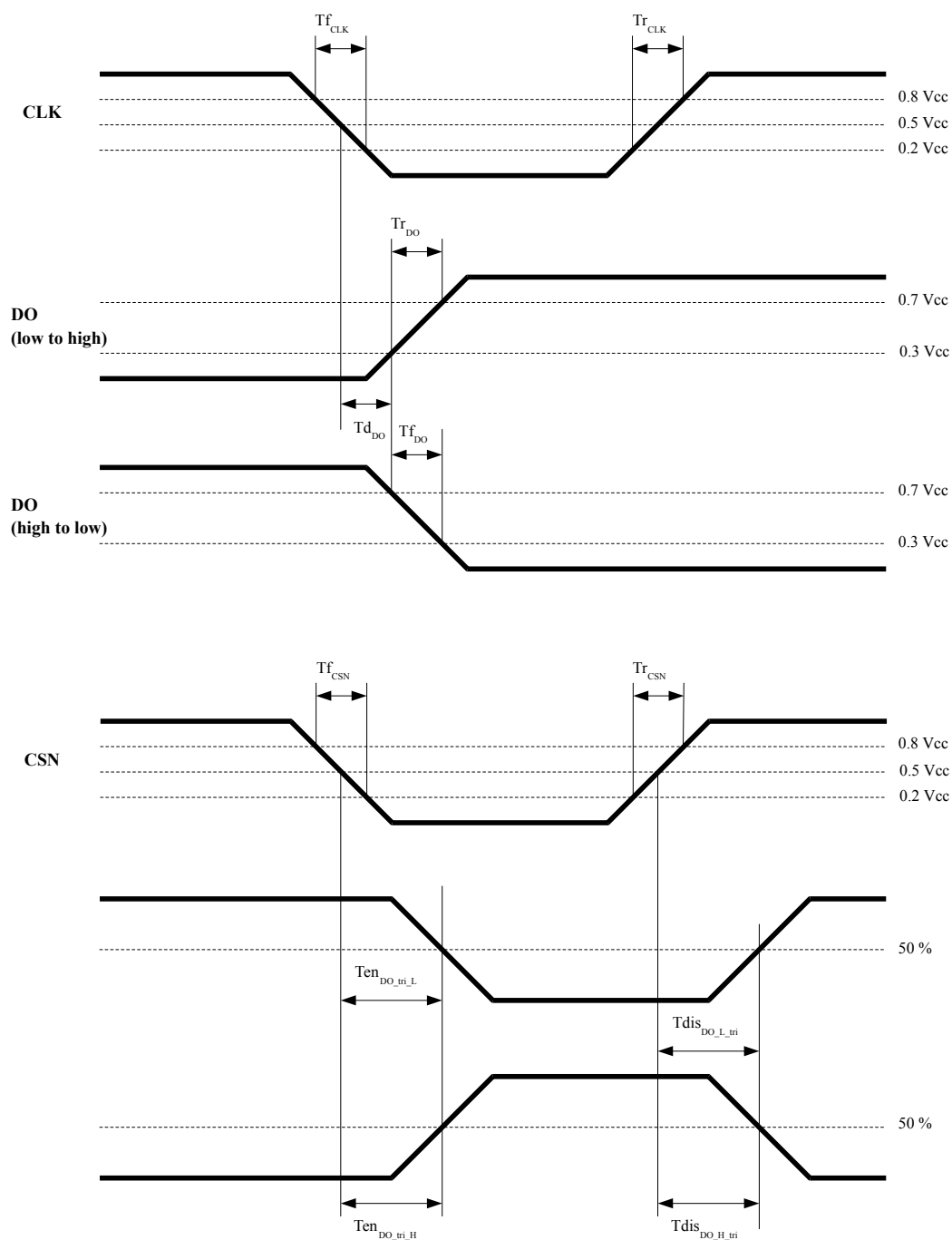
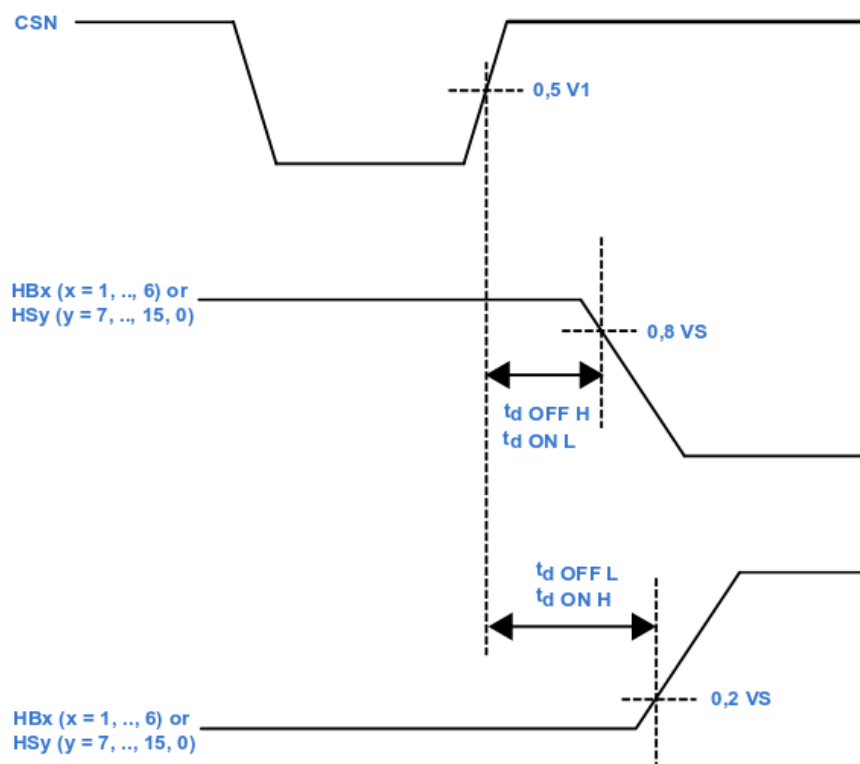
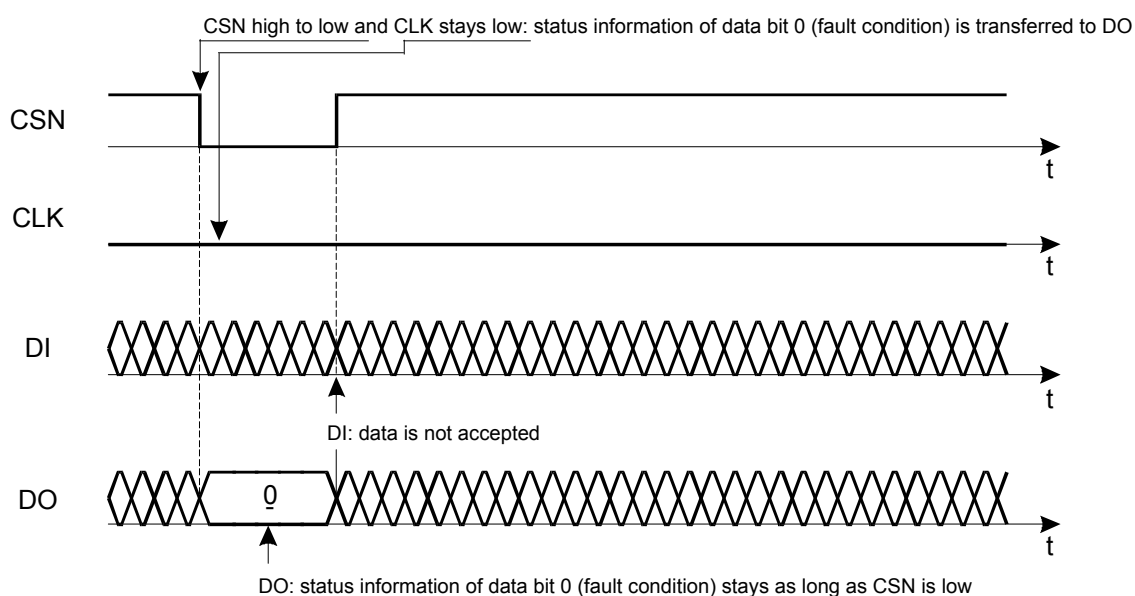
Figure 12. SPI output timing


Figure 13. SPI CSN output timing

Figure 14. SPI - CSN low to high transition and global status bit access


2.4.25 Inputs DIRH, PWMH, PWM4-5, PWM1-6, DIR1, DIR2

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} \leq V_{\text{SREG}} \leq 18\text{ V}$, $T_J = -40^\circ\text{C}$ to 150°C .

Table 49. Inputs: DIRH, PWMH, PWM4-5, PWM1-6, DIR1, DIR2

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{IL}	Input voltage low level	$V_{\text{SREG}} = 13.5\text{ V}$	1	1.45		V	A.169
V_{IH}	Input voltage high level	$V_{\text{SREG}} = 13.5\text{ V}$		1.8	2.5	V	A.170
V_{IHYS}	Input hysteresis	$V_{\text{SREG}} = 13.5\text{ V}$	0.1	0.4		V	A.171
I_{in}	Input pull-down current on PWM1-6 and PWM4-5 pins	$V_{\text{SREG}} = 13.5\text{ V}$	2	30	60	μA	A.172

2.4.26 Debug input pin

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} \leq V_{\text{SREG}} \leq 18\text{ V}$, $T_J = -40^\circ\text{C}$ to 150°C .

Table 50. Debug input

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{diL}	Input voltage low level	$V_{\text{SREG}} = 13.5\text{ V}$	6.1	7.4	8.4	V	A.187
V_{diH}	Input voltage high level	$V_{\text{SREG}} = 13.5\text{ V}$	7.4	8.4	9.4	V	A.188
V_{diHYS}	Input hysteresis	$V_{\text{SREG}} = 13.5\text{ V}$	0.25	1	1.4	V	A.189
R_{in}	Pull-down resistor	$V_{\text{DEBUG}} = 6\text{ V}$ to 28 V	13	29	45	k Ω	A.190

2.4.27 Interrupt output

The voltages are referred to ground, and currents are assumed positive, when the current flows into the pin.
 $6\text{ V} \leq V_{\text{SREG}} \leq 18\text{ V}$, $T_J = -40^\circ\text{C}$ to 150°C .

Table 51. Interrupt output

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{INTL}	output low level	$V_1 = 5\text{ V}$, $I_{\text{INT}} = -4\text{ mA}$		0.2	0.5	V	A.176
V_{INTH}	output high level	$V_1 = 5\text{ V}$, $I_{\text{INT}} = 4\text{ mA}$	$V_1 - 0.5$	$V_1 - 0.2$		V	A.177
I_{INTLK}	Tristate leakage current	$0\text{ V} < V_{\text{INT}} < V_1$	-10		10	μA	A.178
$t_{\text{Interrupt}}$	Interrupt pulse duration (RXDL/NINT)	Tested by scan	42	56	70	μs	A.179
$t_{\text{Int_react}}$	Interrupt reaction time	Tested by scan			40	μs	A.180

2.4.28 Timer1 and Timer2

$6\text{ V} \leq V_{\text{SREG}} \leq 18\text{ V}$, $T_J = -40^\circ\text{C}$ to 150°C .

Table 52. Timer 1 and timer 2 values

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
ton1	Timer on time	Tested by scan	-	0.1	-	ms	F.012
ton2	Timer on time	Tested by scan	-	0.3	-	ms	F.013
ton3	Timer on time	Tested by scan	-	1	-	ms	F.014
ton4	Timer on time	Tested by scan	-	10	-	ms	F.015
ton5	Timer on time	Tested by scan	-	20	-	ms	F.016
T1	Timer period	Tested by scan	-	10	-	ms	F.017
T2	Timer period	Tested by scan	-	20	-	ms	F.018
T3	Timer period	Tested by scan	-	50	-	ms	F.019
T4	Timer period	Tested by scan	-	100	-	ms	F.020
T5	Timer period	Tested by scan	-	200	-	ms	F.021
T6	Timer period	Tested by scan	-	500	-	ms	F.022
T7	Timer period	Tested by scan	-	1000	-	ms	F.023
T8	Timer period	Tested by scan	-	2000	-	ms	F.024

2.4.29 SGND loss comparator

$T_J = -40^\circ\text{C}$ to 150°C , unless otherwise specified.

Table 53. SGND loss comparator

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit	Item
V_{SGNDloss}	Input voltage low level	$V_{\text{SREG}} = 13.5\text{ V}$	200	400	550	mV	A.181
t_{SGNDloss}	Filter time	Tested by scan		7		μs	A.182

3 Functional description

3.1 Supply VS, VSREG

VSREG supplies voltage regulators V1 and V2, all internal regulated voltages for analog and digital functionality, LIN, CAN, the EC control block and two of P-channel high-side switches (HS15 and HS0).

All other high-sides and the charge pump are supplied by VS. In case of VSREG pin disconnected, all power devices connected to VS are automatically switched off.

Filtering capacitors on VS and VSREG lines must be dimensioned to ensure transient slopes $< 100 \text{ mV}/\mu\text{s}$.

3.2 Voltage regulators

The L99DZ300G contains two fully protected low drop voltage regulators, which are designed for very fast transient response and do not require electrolytic output capacitors for stability.

3.2.1 Voltage regulator V1

The V1 voltage regulator provides 5 V supply voltage and up to 250 mA continuous load current to supply the system microcontroller and the integrated CAN transceiver. The V1 regulator is embedded in the power management and fail-safe functionality of the device and operates according to the selected operating mode. The V1 voltage regulator is supplied by pin VSREG.

In addition, the V1 regulator supplies the device internal loads. The voltage regulator is protected against overload and overtemperature. An external reverse current protection has to be provided by the application circuitry to prevent the input capacitor from being discharged by negative transients or low input voltage. Current limitation of the regulator ensures fast charge of external bypass capacitors. The output voltage is stable for ceramic load capacitors $\geq 1 \mu\text{F}$.

In case the device temperature exceeds the TSD1 threshold the V1 regulator remains on. Hence, the microcontroller has the possibility for interaction or error logging. If the chip temperature exceeds TSD2 threshold ($\text{TSD2} > \text{TSD1}$), V1 is deactivated and all wake-up sources (CAN, LIN, EI1, EI2 and timer) are disabled. After t_{TSD} , the voltage regulator restarts automatically. If the restart fails 7 times within one minute the L99DZ300G enters the forced VBAT-standby mode. The status bit Forced_Sleep_TSD2_V1SC is set.

3.2.2 Voltage regulator V2

The voltage regulator V2 is supplied by pin VSREG and can supply additional 5 V loads such as sensors or potentiometers.

Voltage Regulator V2 is tracker of V1 regulator. i.e. provides a 5 V output that tracks the V1 regulator output voltage with ΔV_o (C.038) accuracy.

Load current of V2 can be up to 50 mA.

The V2 regulator is protected against:

- overload
- overtemperature
- short-circuit (short to ground and battery supply voltage)
- reverse biasing

3.2.3 Voltage regulator failure

The V1 and V2 regulator output voltages are monitored.

In case of a drop below the V1, V2 fail thresholds ($V_{1,2} < V_{1,2\text{fail}}$, for $t > t_{V1,2\text{fail}}$), the failure bits V1FAIL, V2FAIL (SR7) are latched. The fail bits can be cleared by a dedicated SPI command.

3.2.4 Short to ground detection

At turn on of the V1 and V2 regulators, a short to GND condition is detected by monitoring the regulator output voltage.

If V1 (V2) is below the $V_{1\text{fail}}$ ($V_{2\text{fail}}$) threshold for $t > t_{V1\text{short}}$ ($t > t_{V2\text{short}}$) after turn on, the L99DZ300G identifies a short-circuit condition at the related regulator output and the regulator is switched off.

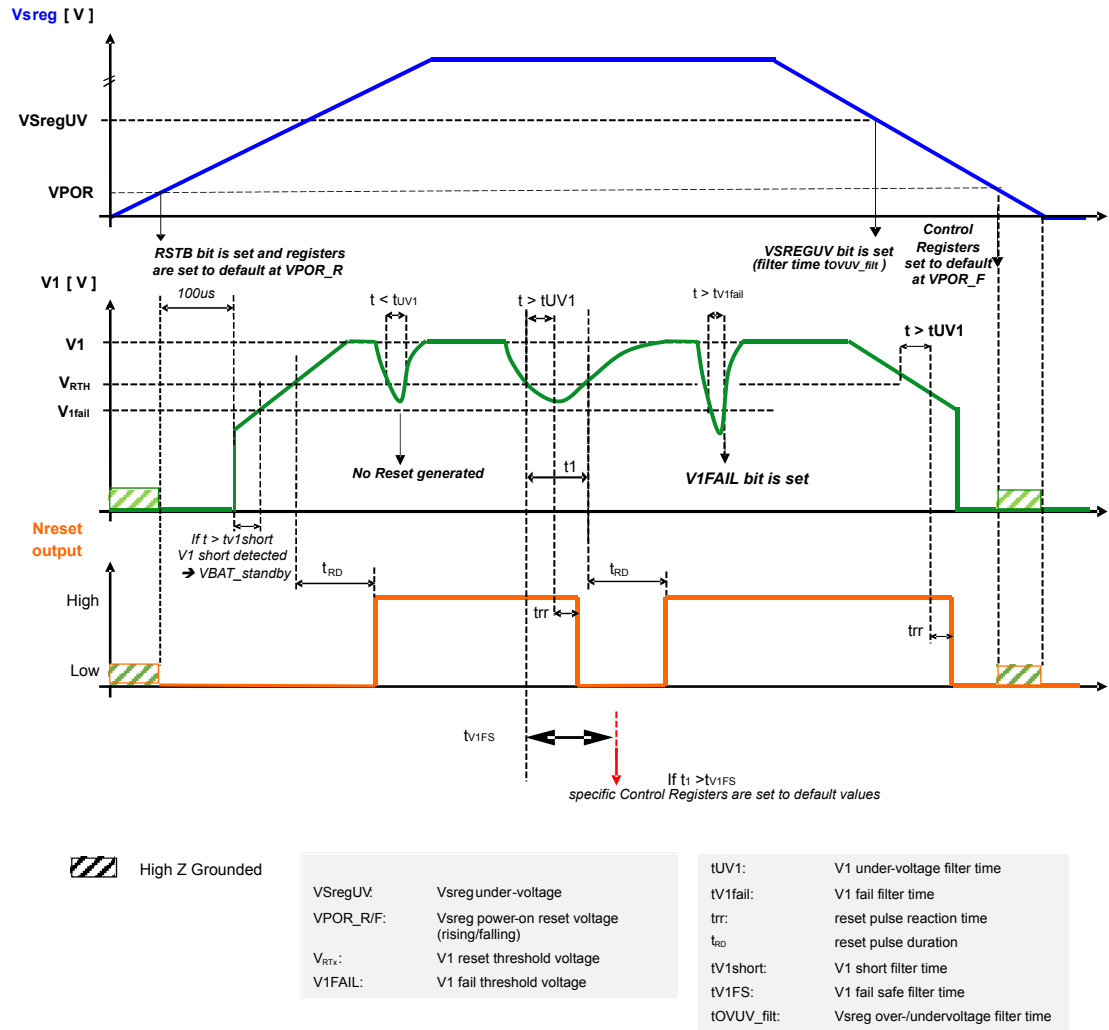
In the case of V1 short to GND, the device enters VBAT-standby mode automatically.

Bits FORCED_SLEEP_TSD2_V1SC (SR8) and V1FAIL (SR7) are set.

In the case of a V2 short to GND failure, the V2SC (SR7) and V1FAIL (SR7) bits are set. Once the output voltage of the corresponding regulator V1 (V2) has exceeded the V_{1fail} (V_{2fail}) threshold, the short to ground detection is disabled. In case of a short to ground condition, the regulator is switched off due to thermal shutdown. V1 is switched off at TSD2, V2 is switched off at TSD1.

3.2.5 Voltage regulator behavior

Figure 15. Voltage regulator behavior and diagnosis during supply voltage ramp-up/ramp-down conditions



3.3 Operating modes

L99DZ300G can be operated in 4 different operating modes:

- Active
- Debug
- V1_Standby
- VBAT_Standby

3.3.1 Active mode

All functions are available, and the device is controlled by SPI.

3.3.2 Debug mode

To allow software debugging, the watchdog can be deactivated by applying an external voltage to the DEBUG input pin ($V_{\text{debug}} > V_{\text{diH}}$).

In debug mode, all device functionality is available, including CAN, which is enabled by default. The watchdog is deactivated.

At exit from debug mode ($V_{\text{debug}} < V_{\text{diL}}$) the watchdog starts with a long open window.

3.3.3 V1_Standby mode

The transition from active mode to V1_Standby mode is controlled by SPI.

To supply the microcontroller in a low-power mode, the V1 voltage regulator remains active.

After the V1 standby command (CSN low to high transition), the device enters V1_Standby mode immediately and the watchdog starts a long open window (t_{LW}). The watchdog is deactivated as soon as the V1 load current drops below the I_{cmp} threshold ($I_{\text{V1}} < I_{\text{cmp}}$).

The V1 load current monitoring can be deactivated by setting $\text{ICMP} = 1$. In this configuration, the watchdog is deactivated upon transition into V1_Standby mode without monitoring the V1 load current.

Writing $\text{ICMP} (\text{CR2}) = 1$ is only possible with the first SPI command after setting $\text{ICMP_CONFIG_EN} (\text{CR1}) = 1$. The ICMP_CONFIG_EN bit is reset to '0' automatically with the next SPI command.

Power outputs (except HS15 & HS0), as well as the LIN and CAN transmitters are switched off in V1_Standby mode.

HS15 and HS0 remain in the configuration programmed before the standby command in order to enable (cyclic) supply of external contacts.

Note: Before going to V1_Standby mode, the OL_H1L2 , OL_H2L1 and GH_OL_EN bits in control register 12 must be set to 0 to achieve the specified current consumption.

3.3.4 Interrupt

The interrupt signal (linked to RXDL/NINT internally) indicates a wake-up event from V1_Standby mode. This is the only mode in which the pin is configured as NINT, otherwise it works as RXDL. In case of a wake-up by wake-up inputs, valid wake-up frames on LIN or CAN, (activity on LIN or CAN), SPI access or timer interrupt, the NINT pin is pulled low for 56 μs , after a reaction time $t_{\text{Int_react}}$ from the related wake-up event.

In case of increasing V1 load current during V1_Standby mode ($I_{\text{V1}} > I_{\text{cmp}}$), the device remains in standby mode and the watchdog starts with a long open window. No interrupt signal is generated.

3.3.5 VBAT_Standby mode

The transition from active mode to VBAT_Standby mode is initiated by an SPI command.

In VBAT_Standby mode, the voltage regulators V1 and V2, the power outputs (except HS15 and HS0) as well as LIN and CAN transmitters are switched off. An NReset pulse is generated upon wake-up from VBAT_Standby mode.

Note: Before going to VBAT_Standby mode, the OL_H1L2 , OL_H2L1 and GH_OL_EN bits in control register 12 must be set to 0 to achieve the specified current consumption.

3.4 Wake-up from standby modes

A wake-up from standby mode switches the device to active mode. This can be initiated by one or more of the following events:

Table 54. Wake-up sources

Wake-up source	Description
LIN bus activity	Can be disabled by SPI
CAN bus activity	Can be disabled by SPI
Level change of EI	Can be configured or disabled by SPI
$I_{V1} > I_{cmp}$	Device remains in V1_Standby mode but watchdog is enabled (if ICMP = 0). No interrupt is generated.
Timer interrupt / Wake-up of microcontroller by TIMER	Programmable by SPI: - V1_Standby mode: device wakes up and interrupt signal is generated at RXDL/NINT when programmable time-out has elapsed - VBAT_Standby mode: device wakes up after programmable timer expiration. V1 regulator is turned on and NReset signal is generated when programmable time-out has elapsed
SPI access	Always active (except in VBAT_Standby mode) Wake-up event: CSN falling edge

To prevent the system from a deadlock condition (no wake-up from standby possible) a configuration where the wake-up by LIN and CAN are both disabled, is not allowed. All wake-up sources are configured to default values in case of such invalid setting. The SPI error bit (SPIE) in the global status register is set.

3.4.1 External interrupts

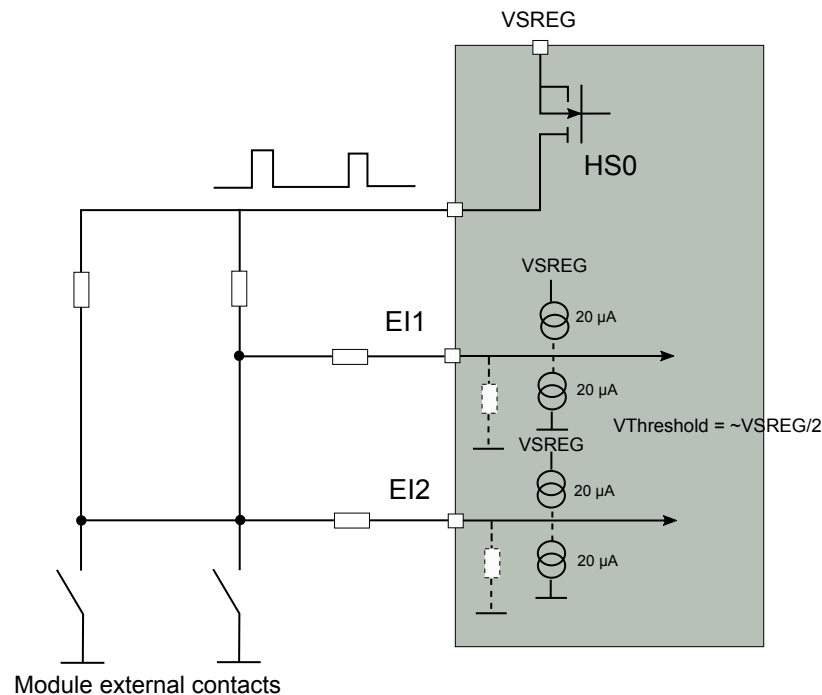
The EI1 and EI2 inputs can be configured as wake-up sources. Each external interrupt input is sensitive to any level transition (positive and negative edge) and can be configured for static or cyclic monitoring of the input voltage level by the suitable setting of the CR18 [8, 9, 14 and 15] bits (Elx_FILT_0 and Elx_FILT_1, with $x = 1, 2$) which allows to choose the monitoring among static, cyclic with timer1 or cyclic with timer2. When the configuration of a timer is changed, the timer is automatically restarted using the new configuration.

For static contact monitoring, a filter time of t_{wu_stat} is implemented. The filter is started when the input voltage passes the specified threshold V_{wu_th} . External interrupt status bit is set only if this threshold is passed for more than t_{wu_stat} (SR4 bit 21 for EI2_STATE, SR4 bit 18 for EI1_STATE).

Cyclic contact monitoring allows instead the periodical (not threshold dependent) activation of the external interrupt input to read the status of the external contact. The periodical activations are driven by timer1 or timer2 whose settings (on time and period) can be configured through CR17 (8...13) and (16...21) bits. The input signal is filtered with a filter time of t_{wu_cyc} after a delay (80% of the configured timer on time). An external interrupt is processed if the status has changed versus the previous cycle, therefore the external interrupt status bit (SR4) is set only if the status during the consecutive on time is different, after configuring the delay and t_{wu_cyc} .

The buffered output HS0 can be used to supply the external contacts with the timer setting according to the cyclic monitoring of the external interrupt input.

Figure 16. Cyclic monitoring: the external contacts are supplied periodically by the internal timer



In standby mode, the inputs are configurable with an internal pull-up or pull-down current source according to the setup of the external contact. Moreover, in the case of cyclic sensing, an internal pull-down resistor (R_{WU_act}) is periodically activated on each rising edge of the `TIMER_ON`. R_{WU_act} is activated also for static wakeup, but in this case it occurs just after the external interrupt request, keeping this condition for at least the filter time t_{wu_stat} (or more, if the EI is valid and the device enters in active mode).

In active mode the inputs have in fact only the internal pull-down resistor and the input status can be read by SPI. Static sense should be configured before the read operation has started in order to reflect the actual input level.

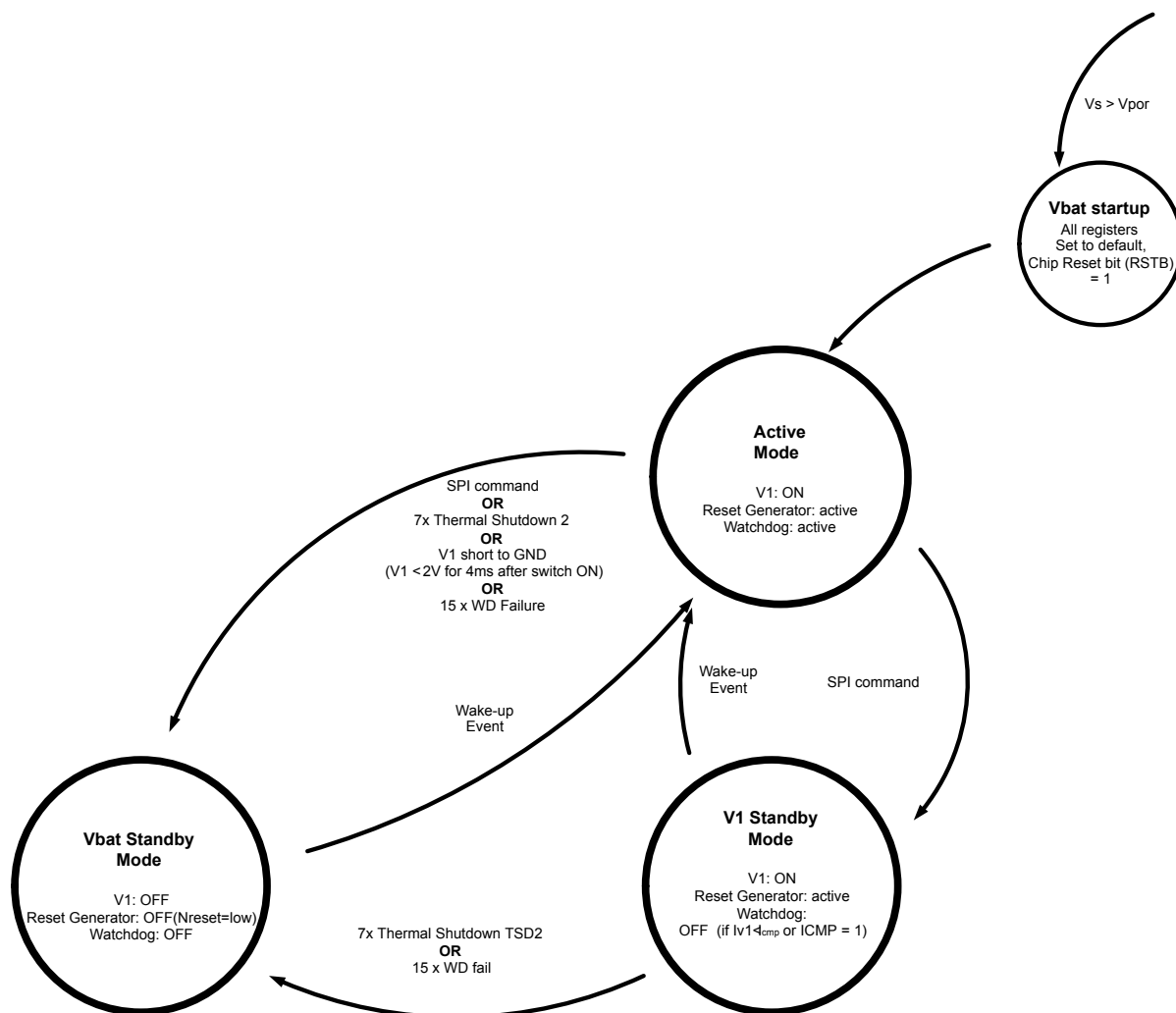
As the `DIR1_EN` enable bit, in `CR1` (0x26), is set to 1 by default, the `DIR1/EI2` pin is a low voltage direct driving of HS0. Threshold is set in this case at 1.5 V.

3.5 Functional overview (truth table)

Table 55. Truth table

Function	Comments	Operating modes		
		Active mode	V1_Standby static mode (cyclic sense)	VBAT_Standby static mode (cyclic sense)
Voltage regulator V1	$V_{OUT} = 5\text{ V}$	On	On ⁽¹⁾	Off
Voltage regulator V2	$V_{OUT} = 5\text{ V}$	On/Off ⁽²⁾	On ⁽²⁾ /Off	Off
Reset generator		On	On	Off
Window watchdog	V1 monitor	On	Off (On if $I_{V1} > I_{CMP}$ and $I_{CMP} = 0$)	Off
Wake-up		Off	Active ⁽³⁾	Active ⁽³⁾
HS cyclic supply	Oscillator time base	On/Off	On ⁽²⁾ /Off	On ⁽²⁾ /Off
LIN	LIN 2.2a	On	Off ⁽⁴⁾	Off ⁽⁴⁾
CAN FD		On/Off ⁽⁵⁾	Off ⁽⁴⁾	Off ⁽⁴⁾
Oscillator		On	On/Off ⁽⁶⁾	On/Off ⁽⁶⁾
Vs monitor		On	⁽⁷⁾	⁽⁷⁾
H-bridge gate driver, EC control, bridge drivers, heater driver, all high-side drivers (except HS15 and HS0)		On/Off ⁽²⁾	Off	Off
HS15 (P-channel HS)		On/Off ⁽²⁾	On/Off ⁽²⁾	On/Off ⁽²⁾
HS0 (P-channel HS)		On/Off ⁽²⁾	On/Off ⁽²⁾	On/Off ⁽²⁾
Charge pump		On	Off	Off
Thermal shutdown TSD2		On	On	Off
Thermal shutdown TSD1x (for P-channel HS)		On	On	On/Off ⁽²⁾

1. Supply the processor in low current mode.
2. According to SPI setting.
3. Unless disabled by SPI.
4. The bus state is internally stored when going to standby mode. A change of bus state leads to a wake-up after exceeding the internal filter time (if wake-up by LIN or CAN is not disabled by SPI).
5. After power on, the CAN FD transceiver is in 'CAN Trx Standby' Mode. It is activated by SPI command (CAN_ACT = 1).
6. ON, if it is enabled at least one of the following: cyclic sense, HS15, HS0, V2.
7. Cyclic activation = pulsed ON during cyclic sense.

Figure 17. Main operating modes


3.6 Configurable window watchdog

During normal operation, the watchdog monitors the microcontroller within a programmable trigger cycle.

After power-on or standby mode, the watchdog starts with a timeout (long open window t_{LW}). The timeout allows the microcontroller to run its own setup and then to start the window watchdog by setting TRIG = 1. Subsequently, the microcontroller has to serve the watchdog by alternating the watchdog trigger bit within the safe trigger area Tswx. The trigger time is configurable by SPI.

A correct watchdog trigger signal immediately starts the next cycle.

After 8 watchdog failures in sequence, the V1 regulator is switched off for tv1off. After 7 additional watchdog failures the V1 regulator is turned off permanently and the device goes into forced VBAT_Standby mode. The status bit FORCED_SLEEP_WD (SR 8) is set. A wake-up is possible by any activated wake-up source.

In case of a watchdog failure, the power outputs and V2 are switched off and the device enters fail-safe mode. All control registers are set to their failsafe values.

The following diagrams illustrate the watchdog behavior of the device. The diagrams are split in 3 parts. The first diagram shows the functional behavior of the watchdog without any error. The second diagram covers the behavior covering all the error conditions, which can affect the watchdog behavior. The third diagram shows the transition in and out of debug mode. All 3 diagrams can be overlapped to get all the possible state transitions under all circumstances. For a better readability, they were split in normal operating, with errors and debug mode.

Figure 18. Watchdog in normal operating mode (no errors)

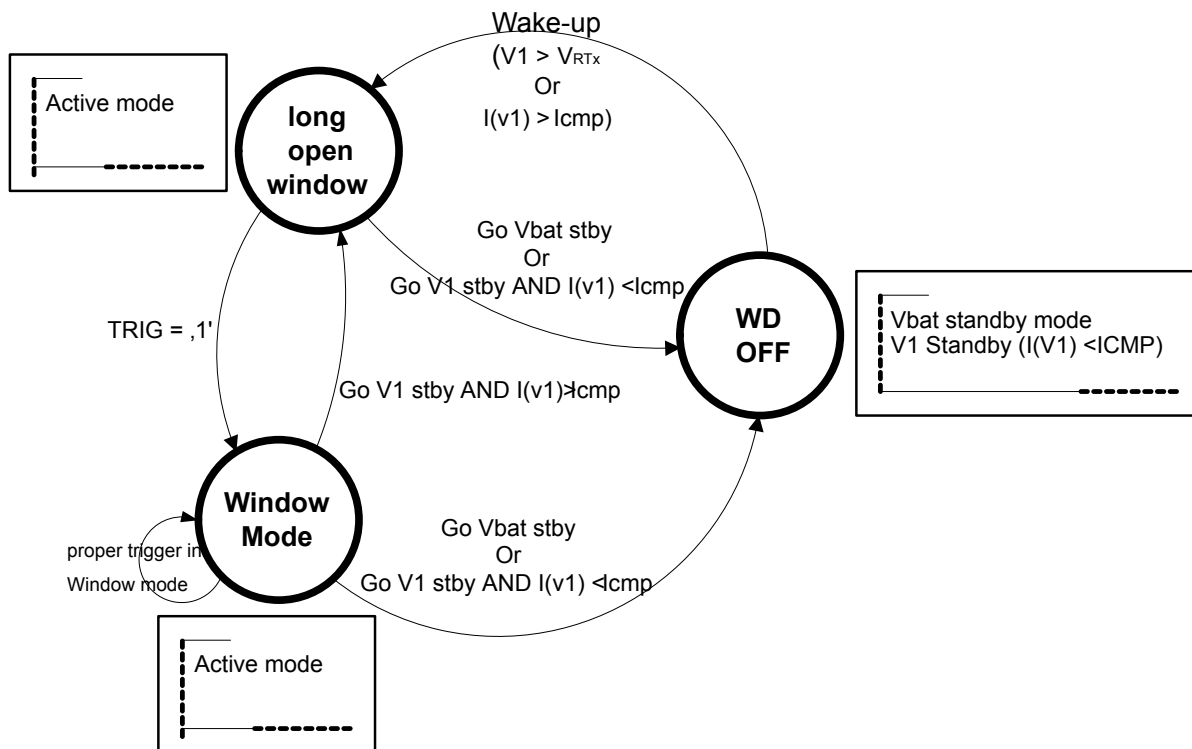


Figure 19. Watchdog with error conditions

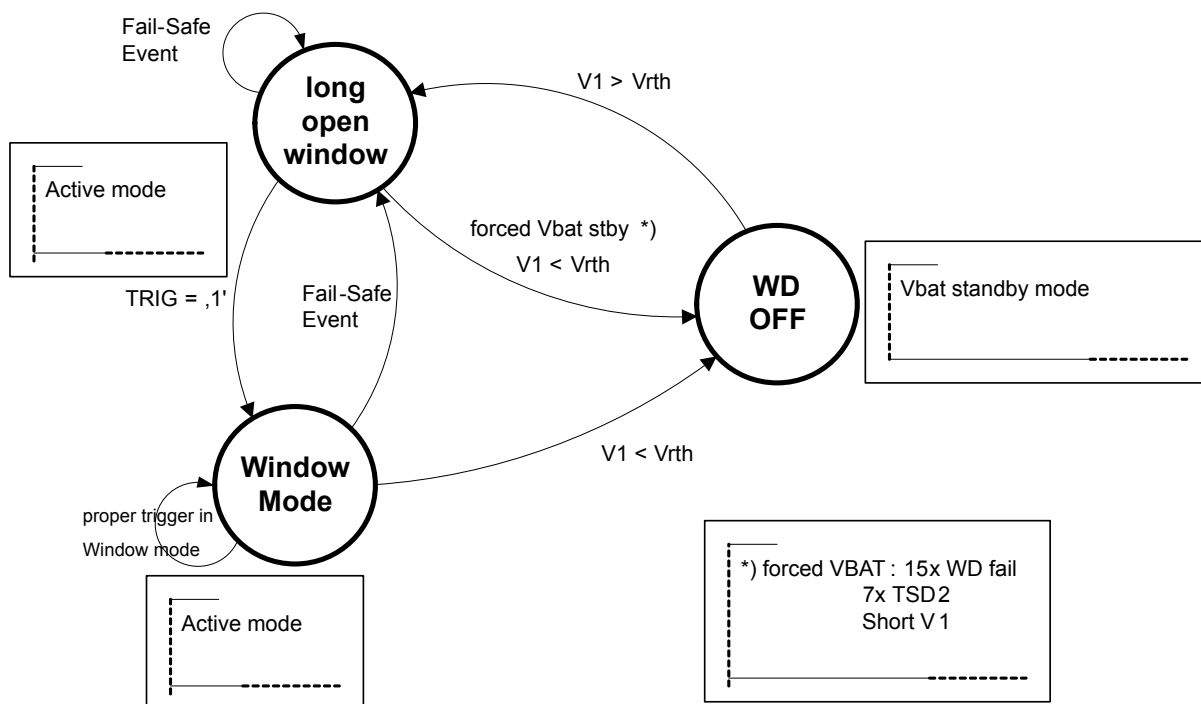
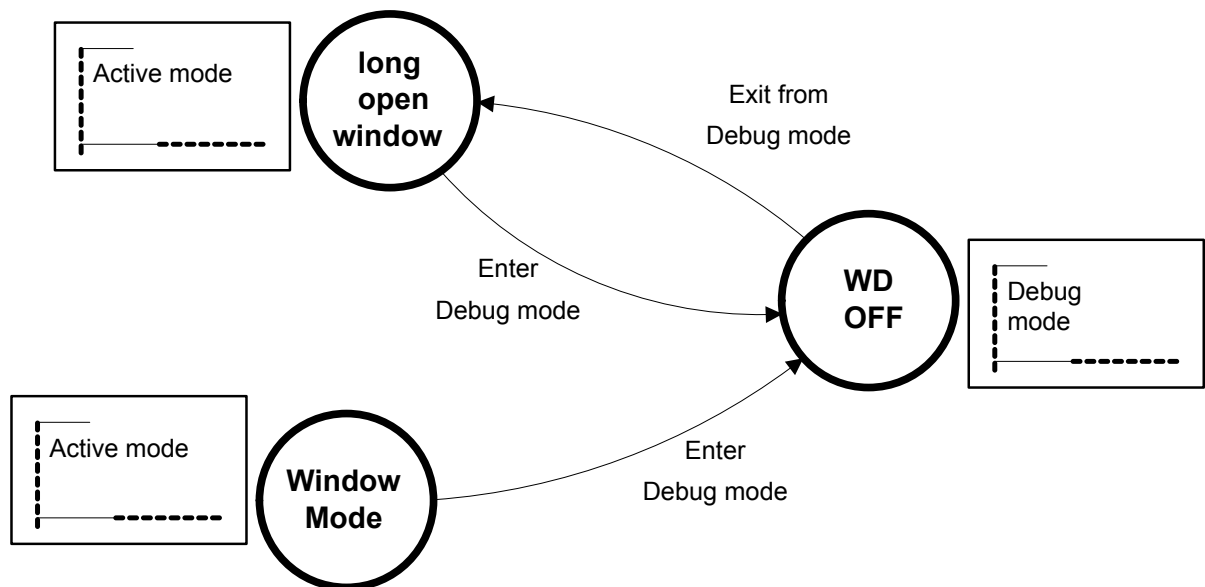


Figure 20. Watchdog in debug mode


Note: Whenever the device is operated without servicing the mandatory watchdog trigger events, a sequence of 15 consecutive reset events is performed and the device enters the Forced_Vbat_Stby mode with the bit **FORCED_SLEEP_WD** in **SR8** set. If the device is woken up after such a forced VBAT_Standby condition and the watchdog is still not serviced, the device, after one long open watchdog window reenters the same Forced_Vbat_Stby mode until the next wake-up event. In this case, an additional watchdog failure is generated, but the fail counter is not cleared, keeping the maximum number of 15 failures. This sequence is repeated until a valid watchdog trigger event is performed by writing **TRIG = 1**.

3.6.1 Change watchdog timing

The watchdog trigger time can be configured by setting the **WD_TIME** (CR 17) bit. Writing to these bits is only possible with the first SPI command after setting **WD_CONFIG_EN = 1**. The **WD_CONFIG_EN** bit is reset to 0 automatically with the next SPI command.

When **FAIL_SAFE** is active these SPI registers are not accessible and therefore in this case first the **FAIL_SAFE** status needs to be cleared. In case of **WD_FAIL**, the clear is performed by triggering in long open window.

When a new configuration has been programmed, the watchdog continues behaving with the old configuration until the next trig event.

The new value of **WD_TIME** is loaded in the watchdog module on the next trig event after the SPI configuration. The following WD cycle uses the new programmed value.

3.7 Fail-safe mode

3.7.1 Temporary failures

L99DZ300G enters fail-safe mode in case of:

- Watchdog failure
- V1 failure ($V1 < V_{rth}$ for $t > t_{V1FS}$)
- Thermal shutdown TSD2

The fail-safe functionality is also available in **V1_Standby** mode. During **V1_Standby** mode the fail-safe mode is entered in the following cases:

- V1 failure ($V1 < V_{rth}$ for $t > t_{V1FS}$)
- Watchdog failure (if watchdog still running due to $Iv1 > Icmp$)
- Thermal shutdown TSD2

In fail-safe mode the device returns to a fail-safe state. The fail-safe condition is indicated to the system in the global status byte. The conditions during fail-safe mode are:

- All outputs are turned off
- All control registers are set to default values
- Write operations to control registers are blocked until the fail-safe condition is cleared (see table below). Only the following bits are not write protected:
 - CR18 (0x3F):
 - TRIG
 - CAN_ACT
 - CR17 (0x3E):
 - Timer settings (bits 8...23)
 - CR14 (0x3B):
 - HS15_x (bits 8...11)
 - HS0_x (bits 12...15)
 - CR5 (0x32) to CR10 (0x37)
 - PWM frequency and duty cycles
 - CR1 (0x26)
 - TRIG
 - V2_0
 - V2_1
- LIN transmitter remains on
- Corresponding failure bits in status registers are set
- FS bit (bit 0 global status byte) is set

In fail-safe mode the device returns to a fail-safe state until the fail-safe condition is removed and the fail-safe was read by SPI. Depending on the root cause of the fail-safe operation, the actions to exit fail-safe mode are as shown in the following table.

Table 56. Temporary failures conditions

Failure source	Failure condition	Diagnosis	Exit from fail-safe mode
Microcontroller (oscillator)	Watchdog Early write failure or expired window	FS (global status byte) = 1 WDFAIL (SR8) = 1 WDFAIL_CNT_x (SR8) = n+1	TRIG = 1 during long open window Read&Clear SR8
V1	Short at turn on	FS (global status byte) = 1 V1FAIL = 1 FORCED SLEEP TSD2/V1SC (SR8) = 1	Wake-up Read&Clear SR8
	Undervoltage	FS (global status byte) = 1 V1UV = 1 ⁽¹⁾ V1FAIL (SR7) = 1 ⁽²⁾	V1 > V _{rth} Read&Clear SR8
Temperature	T _J > TSD2	FS (global status byte) = 1 TW (SR7) = 1 TSD1 (SR8) = 1 TSD2 (SR8) = 1	T _J < TSD2 Read&Clear SR8

1. Bit SR8/V1UV is set for $t > t_{UV1}$ (16 μ s). Fail-safe bit GSR/FS is set only after t_{RD} (NRESET low pulse).

2. If $V1 < V1_{fail}$ (for $t > t_{V1fail}$). The fail-safe bit is located in the global status register.

3.7.2 Non-recoverable failures - entering force VBAT standby mode

If the fail-safe condition persists and all attempts to return to normal system operation fail, the L99DZ300G enters the forced VBAT standby mode in order to prevent damage to the system. The forced VBAT standby mode can be terminated by any wake-up source. The root cause of the forced VBAT standby mode is indicated in the SPI status registers.

In forced VBAT standby mode, all control registers are set to power on default.

The forced VBAT standby mode is entered in case of:

- Multiple watchdog failures: FORCED_SLEEP_WD = 1 (15x watchdog failure)
- Multiple thermal shutdown 2: FORCED_SLEEP_TSD2_V1SC = 1 (7x TSD2)
- V1 short at turn on ($V1 < V1_{fail}$ for $t > t_{V1short}$): FORCED_SLEEP_TSD2_V1SC (SR8) = 1
- Loss of ground: SGNDLOSS (SR3) = 1

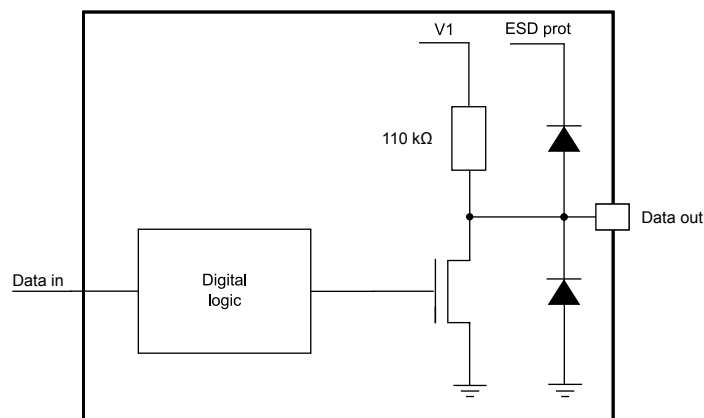
Table 57. Non recoverable failures conditions

Failure source	Failure condition	Diagnosis	Exit from fail-safe mode
Microcontroller (oscillator)	15 consecutive watchdog failures	FS (global status byte) = 1 WDFAIL (SR8) = 1 FORCED_SLEEP_WD (SR8) = 1	Wake-up TRIG = 1 during long open window Read&Clear SR8
V1	Short at turn on	FS (global status byte) = 1 V1FAIL = 1 FORCED_SLEEP_TSD2_V1SC (SR8) = 1	Wake-up Read&Clear SR8
Temperature	7 times TSD2	FS (global status byte) = 1 TW (SR7) = 1 TSD1 (SR8) = 1 TSD2 (SR8) = 1 FORCED_SLEEP_TSD2_V1SC (SR8) = 1	Wake-up Read&Clear SR8
SGND	Loss of ground at SGND pin	FS (global status byte) = 1 SGNDLOSS (SR3) = 1	Wake-up Read&Clear SR3

3.8 Reset output

If V1 is turned on and the voltage exceeds the V1 reset threshold, the reset output “NRESET” is pulled up by the internal pull-up resistor to V1 voltage after a reset delay time (t_{RD}). This is necessary for a defined start of the microcontroller when the application is switched on. Since the NRESET output is realized as an open drain output, it is also possible to connect an external NRESET open drain NRESET source to the output. As soon as the NRESET is released, the watchdog timing starts with a long open window.

Figure 21. NRESET pin



A reset pulse is generated in case of:

- V1 drops below V_{rth} (configurable by SPI) for $t > t_{UV1}$
- Watchdog failure

After turning on the V1 regulator (V_{SREG} power on or wake-up from VBAT_Standby mode), NReset is kept low for t_{RD} in order to keep the microcontroller in reset until supply voltage is stable.

3.9 LIN bus interface

3.9.1 Features

- LIN ISO 17987-4/2016 compliant transceiver
- Meets hardware requirements for transceivers (version 1.3)
- Data rate up to 20 kbit/s
- GND disconnection fail-safe at module level
- Off mode: does not disturb network
- GND shift operation at system level
- Microcontroller interface with CMOS compatible I/O pins
- Internal pull-up resistor
- ESD and transient immunity according to ISO7637 and EN / IEC61000-4-2
- Matched output slopes and propagation delay
- Wake-up behavior according to LIN2.2a and "Hardware requirements for LIN, CAN and flexray interfaces (version 1.3)"

At $V_{SREG} > V_{POR}$ (that is V_{SREG} Power-on Reset threshold), the LIN transceiver is enabled.

The LIN transmitter is disabled in case of the following errors:

- Dominant TXDL time out
- LIN permanent recessive
- TSD1 on cluster 8 (global) if TSD_CLUSTER_EN = 1
- TSD1 on any clusters if TSD_CLUSTER_EN = 0 (default)

The LIN receiver is not disabled in case of any failure condition (it is reactivated in case of FS by thermal shutdown).

3.9.2 Error handling

The device LIN transceiver provides the following three error handling features:

- 1. Dominant TXDL time out**
 If TXDL is in dominant state (low) for $t > t_{dom}(TXDL)$ the transmitter is disabled, the status bit LIN_TXD_DOM (SR7) is set.
 The transmitter remains disabled until the status bit is cleared.
 The TXD dominant timeout detection can be disabled via SPI (LIN_TXD_TOUT = 0).
- 2. Permanent recessive**
 If TXDL changes to dominant (low) state but the RXDL signal does not follow within $t < t_{LIN}$ the transmitter is disabled, the status bit LIN_PERM_REC (SR7) is set.
 The transmitter remains disabled until the status bit is cleared.
- 3. Permanent dominant**
 If the bus state is dominant (low) for $t > t_{dom}(bus)$ a bus permanent dominant failure is detected. The status bit LIN_PERM_DOM (SR7) is set.
 The transmitter is not disabled.

3.9.3 Wake up from standby modes

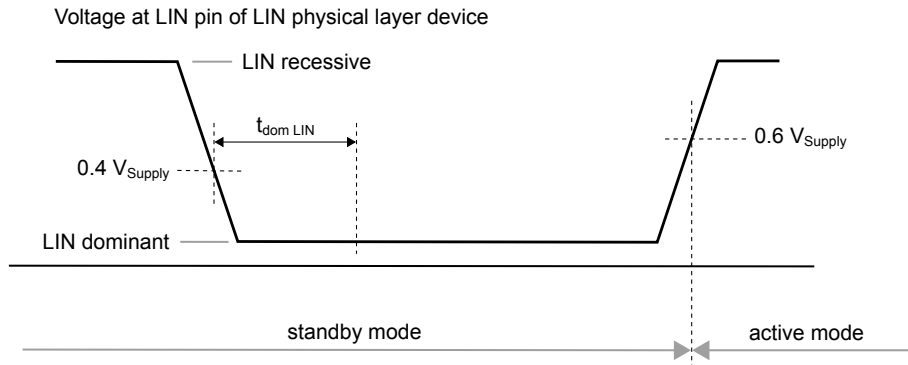
In low-power modes (V1_Standby and VBAT_Standby) the L99DZ300G can receive two types of wake-up signals from the LIN bus (configurable by SPI bit LIN_WU_CONFIG):

- Recessive dominant recessive pattern with $t > t_{dom_LIN}$ (default, according to LIN 2.2a)
- A dominant time of at least 150 μs must be identified as a wake-up. Shorter dominant times may wake-up the device
- State change recessive to dominant or dominant to recessive (according to LIN 2.1)

Note: Dominant levels having duration less than a glitch filter time (it is defined 28 μs minimum, according to OEM requirements version 1.3) have to be filtered and therefore they cannot wake-up the device.

Pattern wake-up (default)

Figure 22. Wake-up behavior according to LIN 2.2a



GADG231020231201GT

Status change wake-up recessive to dominant

Normal wake-up can occur when the LIN transceiver was set in standby mode while LIN was in recessive (high) state. A dominant level at LIN for t_{LINBUS} , switch the device to active mode.

Status change wake-up dominant to recessive

If the LIN transceiver was set in standby mode while LIN was in dominant (low) state, recessive level at LIN for t_{LINBUS} , switch the device to active mode.

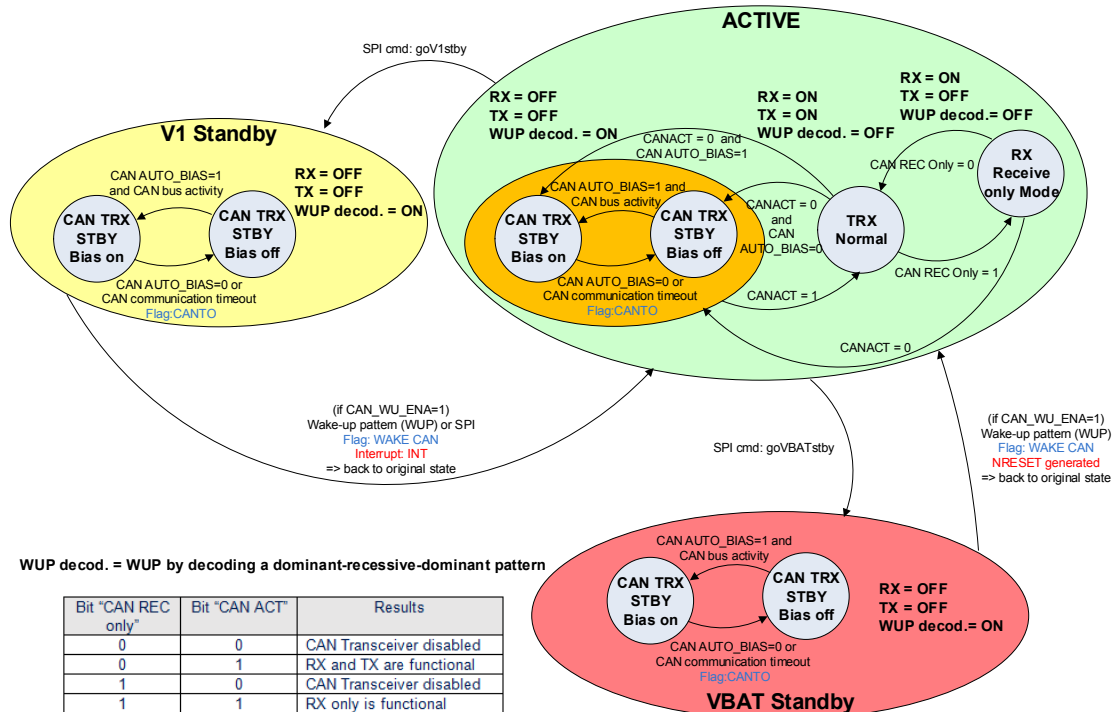
3.10 CAN FD bus transceiver

3.10.1 Features

- ISO 11898-2:2016 compliant
- CAN-FD cell has been designed according to "hardware requirements for transceivers (version 1.3)"
- Listen mode (transmitter disabled)
- SAE J2284 compliant
- Bit rate up to 5 Mbit/s
- Function range from -27 V to 40 V DC at CAN pins
- GND disconnection fail-safe at module level
- GND shift operation at system level
- Microcontroller interface with CMOS compatible I/O pins
- ESD and transient immunity according to ISO7637 and EN/IEC61000-4-2
- Matched output slopes and propagation delay

3.10.2 CAN transceiver operating modes

Figure 23. Transceiver state diagram



TRX normal mode

Full functionality of the CAN transceiver is available (transmitter and receiver) and the automatic voltage biasing is enabled.

State transitions from TRX normal mode to VBAT_Standby and V1_Standby are possible. No interrupt is generated in this mode.

CAN TRX STBY mode

The CAN transmitter is disabled in this mode and the RXDC pin is kept at high (recessive) level. CAN receiver is capable of detecting a wake-up pattern (WUP). In V1_Standby mode and VBAT_Standby mode, a WUP is indicated to the microcontroller by an interrupt signal.

There is no automatic state transition into TRX normal mode in the case of a detected CAN wake-up signal (WUP). After serving the interrupt, the microcontroller can initiate a state transition into TRX normal mode by setting the SPI bit CAN_ACT to '1'. (This can be done 160 µs after enabling the wake-up through CAN_WU_EN=1).

Moreover, in this mode two further submodes are possible ("Bias ON" or "Bias OFF"), depending on the CAN_AUTO_BIAS bit in CR1 (compliant with ISO 11898-2:2016) or timeout conditions.

3.10.3 CAN error handling

The devices provide the following four error handling features.

After power on reset (VS > VPOR) the CAN transceiver is disabled. The transceiver is enabled by setting CAN_ACT = 1.

The CAN transmitter is disabled automatically in case of the following errors:

- Dominant TXDC time out
- CAN permanent recessive
- RXDC permanent recessive
- TSD1 on cluster 8 (global) if TSD_CLUSTER_EN = 1
- TSD1 on any clusters if TSD_CLUSTER_EN = 0 (default)

The CAN receiver is not disabled in case of any failure condition.

Dominant TXDC time out

If TXDC is in dominant state (low) for $t > t_{\text{dom(TXDC)}}$ the transmitter is disabled, status bit is latched and can be read and optionally cleared by SPI. The transmitter remains disabled until the status register is cleared.

CAN Bus permanent recessive

If TXDC changes to dominant (low) state but CAN bus does not follow for 4 times, the transmitter is disabled, status bit is latched and can be read and optionally cleared by SPI. The transmitter remains disabled until the status register is cleared.

CAN permanent dominant

If the bus state is dominant (low) for $t > t_{\text{CAN}}$ a permanent dominant status is detected. The status is latched and can be read and optionally cleared by SPI. The transmitter is not disabled.

RXDC permanent recessive

If RXDC pin is clamped to recessive (high) state, the controller is not able to recognize a bus dominant state and could start messages at any time, which results in disturbing the overall bus communication. Therefore, if RXDC does not follow TXDC for 4 times the transmitter is disabled. The status bit is latched and can be read and optionally cleared by SPI. The transmitter remains disabled until the status register is cleared.

3.10.4

Wake up by CAN

The default setting for the wake-up behavior after Power-on Reset is the wake-up by regular communication on the CAN bus. When the CAN transceiver is in a standby mode (CAN TRX STBY) the device can be woken up by sending 2 consecutive dominant bits separated by a recessive bit.

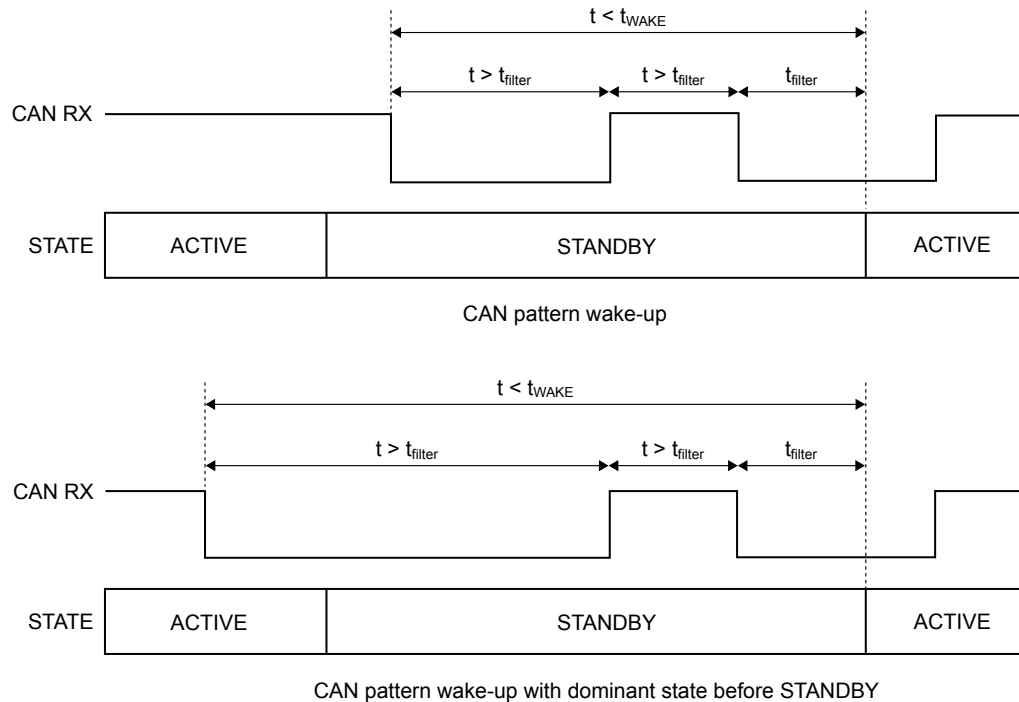
Normal pattern wake-up can occur when the CAN pattern wake-up option is enabled, and the CAN transceiver was set in standby mode (CAN TRX STBY) while CAN bus was in recessive (high) state or dominant (low) state. In order to wake-up the device, the following criteria must be fulfilled:

- The CAN interface wake-up receiver must receive a series of two consecutive valid dominant pulses, each of which must be longer than t_{filter} .
- The distance between 2 pulses must be longer than t_{filter} .
- The two pulses must occur within a time frame of t_{wake} .
- Wake-up occurs when duration of the second pulse becomes longer than t_{filter} .

Note:

A wake-up caused by a message on the bus starts the voltage regulator and the microcontroller to switch the application back to normal operation mode.

Figure 24. CAN wake-up capabilities



GADG041120211203GT

Note: The waveforms above illustrate the wake-up behavior from V1_Standby mode. For wake-up from VBAT_Standby mode the NRESET signal (with 2 ms timing) is generated instead of the RXDL (interrupt) signal.

3.10.5 CAN receive only mode

During TRX normal mode, with the CAN_REC_ONLY bit it is possible to disable the CAN transmitter. In this mode it is possible to listen to the bus but not sending to it. The receiver termination network is still activated in this mode.

3.10.6 CAN looping mode

If the CAN_LOOP_EN (CR1) is set the TXDC input is mapped directly to the RXDC pin. This mode can be used in combination with the CAN receive only mode, to run diagnosis for the CAN protocol handler of the microcontroller.

3.11 Serial peripheral interface (ST SPI standard)

A 32-bit SPI is used for bidirectional communication with the microcontroller.

The SPI is driven by a microcontroller with its SPI peripheral running in the following mode:

- CPOL = 0 and CPHA = 0**
 For this mode input data is sampled by the low to high transition of the clock CLK, and output data is changed from the high to low transition of CLK.
 This device is not limited to microcontroller with a built in SPI. Only three CMOS compatible output pins and one input pin need to communicate with the device. A fault condition can be detected by setting CSN to low. If CSN = 0, the DO pin reflects the global error flag (fault condition) of the device.
- Chip select not (CSN)**
 The input pin is used to select the serial interface of this device. When CSN is high, the output pin (DO) is in high impedance state. A low signal activates the output driver and a serial communication can be started. The state during CSN = 0 is called a communication frame.
 If CSN = low for $t > t_{CSNfail}$ the DO output is switched to high impedance in order not to block the signal line for other SPI nodes.

- **Serial data in (DI)**

The input pin is used to transfer serial data into the device. The data applied to the DI is sampled at the rising edge of the CLK signal and shifted into an internal 32-bit shift register. At the rising edge of the CSN signal the content of the shift register is transferred to the data input register. The writing to the selected data input register is only enabled if exactly 32 bits are transmitted within one communication frame (that is CSN low). If more or less clock pulses are counted within one frame the complete frame is ignored. This safety function is implemented to avoid an activation of the output stages by a wrong communication frame.

Note: Due to this safety functionality a daisy chaining of SPI is not possible. Instead, a parallel operation of the SPI bus by controlling the CSN signal of the connected IC's is recommended.

- **Serial data out (DO)**

The data output driver is activated by a logical low level at the CSN input and switches from high impedance to a low or high level depending on the global error flag (fault condition). The first rising edge of the CLK input after a high to low transition of the CSN pin transfers the content of the selected status register into the data out shift register. Each subsequent falling edge of the CLK shifts the next bit out.

- **Serial clock (CLK)**

The CLK input is used to synchronize the input and output serial bit streams. The data input (DI) is sampled at the rising edge of the CLK and the data output (DO) changes with the falling edge of the CLK signal. The SPI can be driven with a CLK frequency up to 4 MHz.

3.12 Power supply fail

3.12.1 VS supply failure

VS overvoltage

If the supply voltage V_S reaches the overvoltage threshold VSOV:

- LIN remains enabled
- CAN remains enabled
- HB1, ..., HB6 and HS7, .., HS14 are turned off (default)
- The shutdown of outputs may be disabled by SPI (VS_OV_SD_EN = 0)
- Charge pump is disabled (and is switched on automatically in case the supply voltage recovers to normal operating voltage)
- H-bridge gate driver and heater Power MOSFET gate driver are switched into sink condition
- ECV is switched in high impedance state and ECDR is discharged by RECDRDIS (to ensure the gate of the external Power MOSFET is discharged => EC mode considered as off)
- Recovery of outputs after overvoltage condition is configurable by SPI
 - VS_LOCK_EN (CR16) = 1: outputs are off until Read&Clear VS_OV (SR7)
 - VS_LOCK_EN (CR16) = 0: outputs turned on automatically after V_S overvoltage condition has recovered
- The overvoltage bit VS_OV (SR7) is set and can be cleared with a 'Read&Clear' command. The overvoltage bit is reset automatically if VS_LOCK_EN (CR16) = 0 and the overvoltage condition has recovered

V_S undervoltage

If the supply voltage V_S drops below the undervoltage threshold voltage (VSUV):

- LIN remains enabled
- CAN remains enabled
- HB1, ..., HB6 and HS7, .., HS14 are turned OFF (default). The shutdown of outputs may be disabled by SPI (VS_UV_SD_EN (CR16) = 0).⁽¹⁾
- ECV is switched in high impedance state and ECDR is discharged by RECDRDIS (to ensure the gate of the external Power MOSFET is discharged => EC mode considered as off). This occurs if VS_UV_SD_EN = 1, otherwise remains unchanged until CP_LOW = 1
- Recovery of outputs after undervoltage condition is configurable by SPI:
 - VS_LOCK_EN (CR16) = 1: outputs are off until Read&Clear VS_UV (SR7)
 - VS_LOCK_EN (CR16) = 0: outputs turned on automatically after V_S undervoltage condition has recovered

- The undervoltage bit (V_{SUV}) is set and can be cleared with a 'Read and Clear' command. The undervoltage bit is removed automatically if $VS_LOCK_EN = 0$ and the undervoltage condition has recovered
- H-bridge gate driver passes to resistive low condition. (If $VS_UV_SD_EN = 1$, otherwise remains unchanged until $CP_LOW = 1$)
- Heater gate driver passes to resistive low condition. (If $VS_UV_SD_EN = 1$, otherwise remains unchanged until $CP_LOW = 1$)⁽¹⁾

1. The functionality is not guaranteed in the range $V_{por} < V_S < V_{SUV}$.

3.12.2

VSREG supply failure

VSREG overvoltage

If the supply voltages V_{SREG} reaches the overvoltage threshold V_{SREG_OV} :

- LIN is switched to high impedance (RX is still on)
- CAN remains enabled
- HS15 and HS0 are turned off (default).
- The shutdown of outputs may be disabled by SPI ($VSREG_OV_SD_EN$ (CR16) = 0)
- ECV is switched in high impedance state and ECDR is discharged by $R_{ECDRDIS}$ (to ensure the gate of the external Power MOSFET is discharged => EC mode considered as off)
- Recovery of outputs after overvoltage condition is configurable by SPI:
 - $VSREG_LOCK_EN$ (CR16) = 1: outputs are off until Read&Clear $VSREG_OV$ (SR7)
 - $VSREG_LOCK_EN$ (CR16) = 0: outputs turned on automatically after V_{SREG} overvoltage condition has recovered
- The overvoltage bit $VSREG_OV$ (SR7) is set and can be cleared with a 'Read&Clear' command. The overvoltage bit is reset automatically if $VSREG_LOCK_EN$ (CR16) = 0 and the overvoltage condition has recovered.

VSREG undervoltage

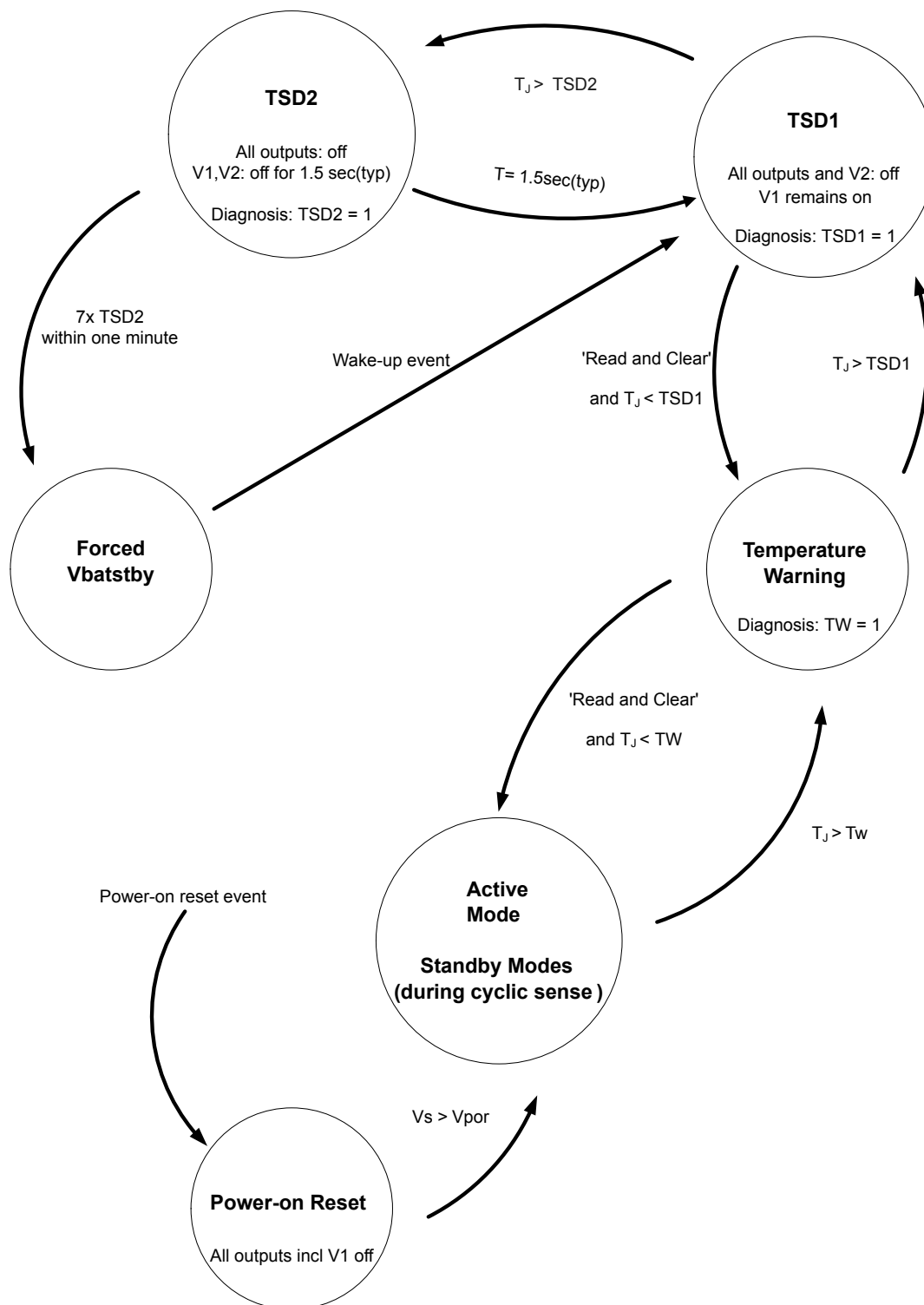
If the supply voltage V_{SREG} drops below the undervoltage threshold voltage ($VSREG_UV$):

- LIN is switched to high impedance (RX is still on)⁽¹⁾
- CAN remains enabled⁽¹⁾
- HS15 and HS0 are turned off (default).
- The shutdown of outputs may be disabled by SPI ($VSREG_UV_SD_EN$ (CR16) = 0)⁽¹⁾
- ECV is switched in high impedance state and ECDR is discharged by $R_{ECDRDIS}$ (to ensure the gate of the external Power MOSFET is discharged => EC mode considered as off)
- recovery of outputs after undervoltage condition is configurable by SPI:
 - $VSREG_LOCK_EN = 1$: outputs are off until Read&Clear $VSREG_UV$ (SR7)
 - $VSREG_LOCK_EN = 0$: outputs turned on automatically after V_{SREG} undervoltage condition has recovered
- The undervoltage bit ($VSREG_UV$ (SR7)) is set and can be cleared with a 'Read&Clear' command. The undervoltage bit is removed automatically if $VSREG_LOCK_EN$ (CR16) = 0 and the undervoltage condition has recovered

1. The functionality is not guaranteed in the range $V_{por} < V_S < V_{SUV}$.

3.13 Temperature warning and thermal shutdown

Figure 25. Thermal shutdown protection and diagnosis



Note: The thermal state machine recovers the same state where it was before entering standby mode. In case of a TSD2 it is entered in TSD1 state.

3.14 Power outputs HB1 .. HB6, HS7 .. HS15 and HS0

The component provides a total of 6 half bridges outputs HB1,..., HB6 to drive motors and 10 stand-alone high-side outputs HS7,..., HS15 and HS0 to drive for example LED's, bulbs or to supply contacts. All high-side outputs, except HS15 and HS0, are supplied by the pin VS. HS15 and HS0 are instead supplied by the buffered supply VSREG. HS0 is intended to be used as contact supply.

Only HS15 and HS0 can be activated in standby modes.

All high-side and low-side outputs switch OFF in case of:

- VS overvoltage and undervoltage (depending on configuration, see [Section 3.12: Power supply fail](#))
- Overcurrent (depending on configuration, overcurrent recovery mode, see below)
- Over temperature (TSD1)
- Fail-safe event
- Loss of ground at SGND pin

In case of overcurrent or over temperature (TSD1 bit in SR8) condition, the drivers switch off. The corresponding status bit is latched and can be read and optionally cleared by SPI. The drivers remain off until the status is cleared.

In case overvoltage/undervoltage condition, the drivers are switched off. The corresponding status bit is latched and can be read and optionally cleared by SPI. If the Vlockout bits are set to '1' the drivers remain off until the status is cleared. If the Vlockout bit is set to '0' the drivers switch on automatically if the error condition disappears. Undervoltage and overvoltage shutdown can be disabled by setting <VS_UV_SD_EN> respectively <VS_OV_SD_EN> to '0'. In case of open-load condition, the corresponding status register is latched. The status can be read and optionally cleared by SPI. The high and low-side outputs are not switched off in case of open-load condition.

For HB1, ..., HB6 the overcurrent recovery feature can be enabled by setting the HBx_OCR bit in CR13 (x = 1,..., 6); for HS7...HS10 the overcurrent recovery feature can be enabled by setting the HSy_OCR bit in CR13 (y = 7,...,10). If these bits are set to '1' the driver is automatically restarted from an overload condition. This overload recovery feature is intended for loads which have an initial current higher than the overcurrent limit of the output (for example inrush current of cold light bulbs). For HB1, HB5 and HB6 only, overcurrent threshold can be set via SPI (HBxOCTH_y bits in CR16, x = 1, 5, 6 and y = 0, 1) among three different values.

Each of the stand-alone high-side driver outputs HS7, ..., HS15 and HS0 can be driven through:

- An internal generated PWM signal
- An internal timer
- One of the two direct drives (DIR1, DIR2)

When L99DZ300G is in V1_Standby or VBAT_Standby modes, HS0 and HS15 can be directly driven with DIR1/EI2 pin or PWM1-6/DIR2 pin.

Moreover, for each high-side driving LEDs, it is also available the "constant current mode" feature, which is configurable by SPI (CR3) and provides a constant current to the related output. This bit can be set only if the related driver is in OFF state and disables also its overcurrent and short-circuit detection (open-load detection remains ON). The "constant current code" is automatically disabled after the expiration time $t_{CCMtimeout}$.

The allowed sequence is the following:

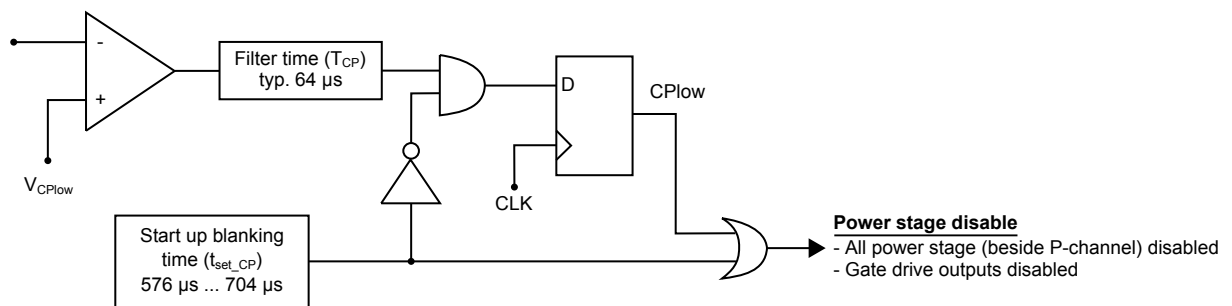
- Set HSx_CCM bit (x = 7, ..., 15, 0), then turn ON the driver (other configurations are ignored): driver starts in current mode for $t_{CCMtimeout}$, then switches to ON mode, CCM is cleared by μC
 - If HSx_CCM bit is cleared by μC before timeout then driver is switched to ON mode
 - If CCM bit is set after driver has been started in ON, PWM, timer modes then CCM bit is ignored
- SC and OC are enabled in ON, PWM and timer modes, not in current mode
- Default value for CCM bit is OFF

3.15 Charge pump

The charge pump uses two external capacitors, which are switched with f_{CP} . The output of the charge pump has a current limitation. In standby mode and after a thermal shutdown has been triggered the charge pump is disabled. If the charge pump output voltage remains too low for longer than TCP, the Power MOSFET outputs and the EC-control are switched off. The H-bridge Power MOSFET gate drivers and the Heater Power MOSFET gate driver are switched to resistive low (according to undervoltage setting described in [Section 3.12.1: VS supply failure](#)) and the CP_LOW (SR7) bit is set. This bit has to be cleared to reactivate the drivers. In case of reaching the overvoltage shutdown threshold V_{SOV} the charge pump is disabled and automatically restarted after VS has restored to normal operating voltage. Charge pump may be also switched off in normal mode by setting the bits CP_OFF in CR2 only if CP_OFF_EN is set to "1" in CR1.

Note: *In order to improve EME performance, the sampling frequency of the charge-pump is modulated (in his functional range) with a triangular function, providing a spreading of its energy spectrum. This "clock dithering" is performed automatically if the bit DISABLE_CP_DITH in CR1 is "0" (default value).*

Figure 26. Charge pump low filtering and startup implementation



3.16 Inductive loads

Each of the half bridges is built by internally connecting high-side and low-side power DMOS transistors. Due to the built-in reverse diodes of the output transistors, inductive loads can be driven at the outputs HB1 to HB6 without external freewheeling diodes. The high-side drivers HS7 to HS15 and HS0 are intended to drive resistive loads only. Therefore, only a limited energy ($E < 1 \text{ mJ}$) can be dissipated by the internal ESD diodes in the freewheeling condition. For inductive loads ($L > 100 \mu\text{H}$) an external freewheeling diode connected between GND and the corresponding output is required. The low-side driver at ECV does not have a freewheel diode built into the device.

3.17 Open-load detection

The open-load detection monitors the load current in each activated output stage. If the load current is below the open-load detection threshold for at least t_{FOL} the corresponding open-load bit is set in the status register.

3.18 Overcurrent detection

An overcurrent condition is detected if the output current exceeds the overcurrent threshold (I_{OCXX}). In this case, a status flag (HBx_LS_OC / HBx_HS_OC with $x = 1, \dots, 6$ and HSY_OC with $y = 0, 7, \dots, 15$) is set in the corresponding status register and the output is turned OFF to reduce the power dissipation and to protect the integrated circuit. The status flag must be cleared before the output can be turned ON by SPI.

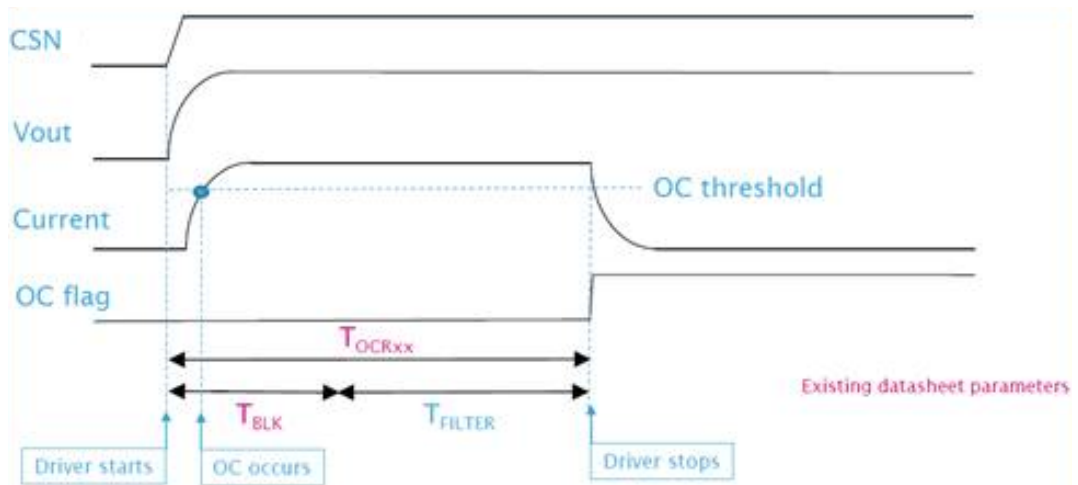
In overcurrent recovery mode (HBx_OCR or HSY_OCR set to 1, see [Control register 13 \(0x3Ah\)](#)) the output is switched OFF, but the correspondent HBx_OC or HSY_OC flag is not set. The output is switched ON automatically according to the configured overcurrent recovery frequency (HBx_OCR_FREQ or HSY_OCR_FREQ, see [Control register 4 \(CR4, 0x30\)](#)).

A blanking time t_{BLK} is applied at turn ON of the output.

The filter time applied is:

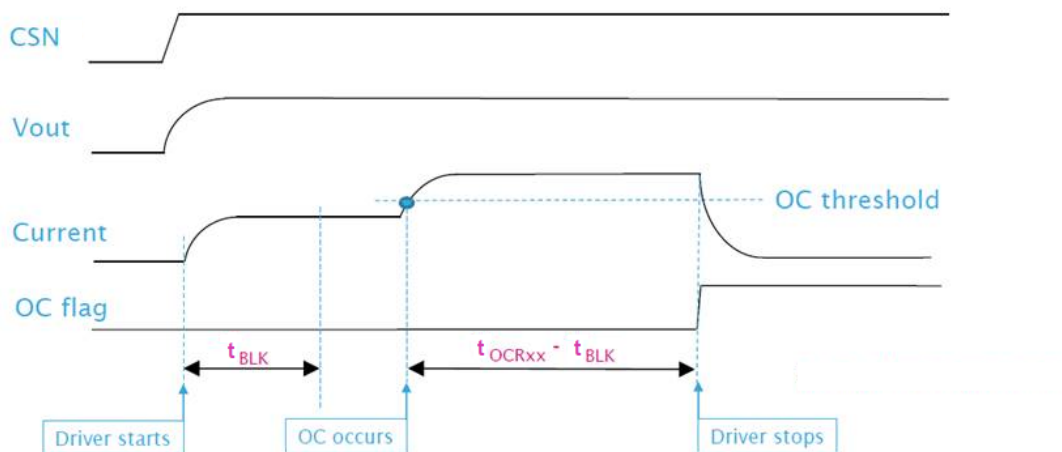
- t_{FOC} for outputs without overcurrent recovery mode (from HS11 to HS15 and HS0)
- t_{OCRxx} (programmable) for outputs with overcurrent recovery mode (from HB1 to HB6 and from HS7 to HS10); independent if overcurrent recovery mode is enabled or disabled by bit HBx_OCR / HSY_OCR.

Figure 27. Overcurrent threshold reached during blanking time

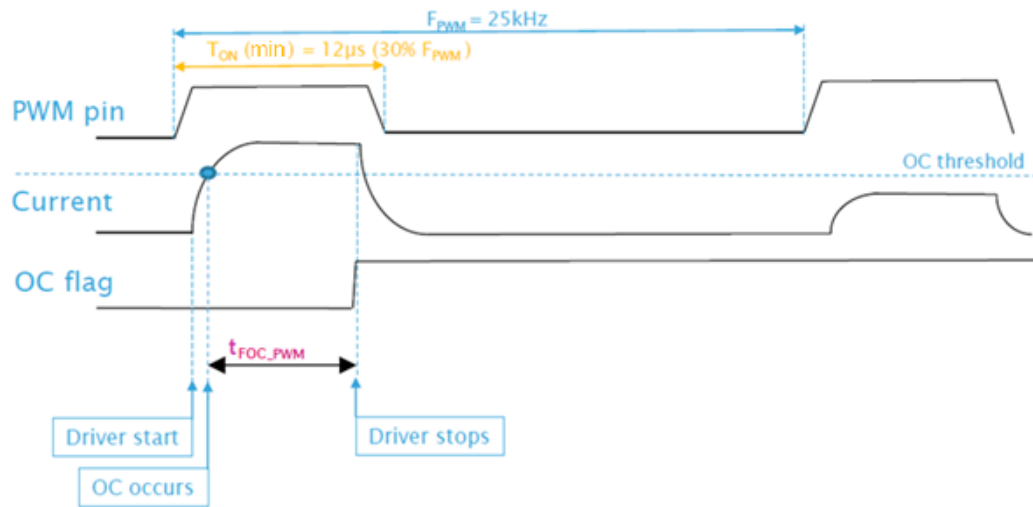


In that case, OC is detected and flagged after $T_{OCRxx} = T_{BLK} + T_{FILTER}$
the blanking time is only present after driver start.

Figure 28. OC threshold reached after blanking time (OC filter time is reduced by the blanking time)



For half bridges configured in PWM mode, no blanking time t_{BLK} is applied and the overcurrent filter time is reduced to t_{FOC_PWM} .

Figure 29. Half bridges in PWM mode: filter time is t_{FOC_PWM}


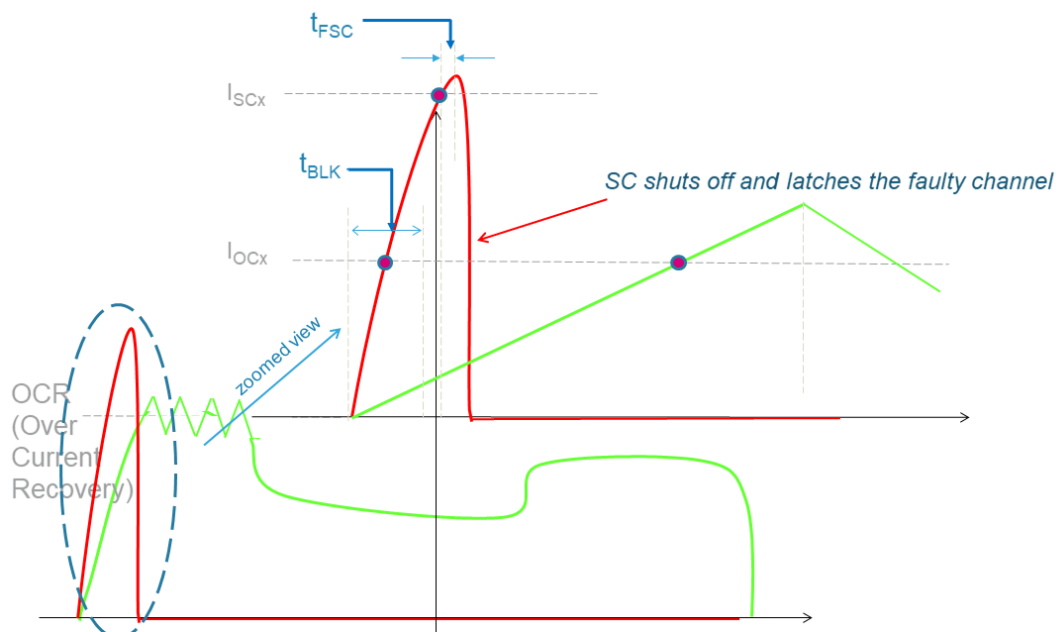
3.19 Short-circuit current detection

To distinguish low resistive short-circuit events from overcurrent conditions (especially in overcurrent recovery mode), a short-circuit current threshold is implemented for all the half bridges (HB1 to HB6).

Short-circuit condition is detected if the output current exceeds the short current threshold (I_{SCx}). In this case, a status flag HBx_HS_SC / HBx_LS_SC is set in the corresponding status register and the output is turned OFF. The corresponding overcurrent flag of the out (HBx_HS_OC / HBx_LS_OC) is also set. The HBx_HS_OC / HBx_LS_OC status flag must be cleared before the output can be turned ON by SPI.

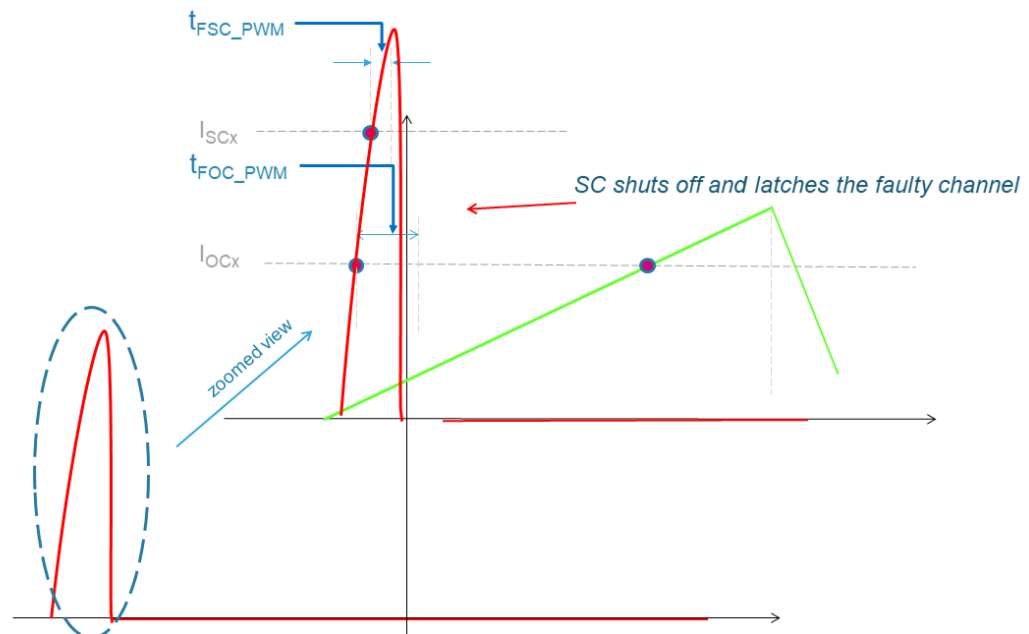
A blanking time t_{BLK} is applied at turn on of the output.

The filter time applied is t_{FSC} .

Figure 30. Half bridge short-circuit detection in latch mode (overcurrent recovery disabled) and OCR mode (overcurrent recovery enabled)


In PWM mode, no blanking time t_{BLK} is applied and the short-circuit filter time is reduced to t_{FSC_PWM} .

Figure 31. Half bridge short-circuit detection in PWM mode: filter time is t_{FSC_PWM}



High-side drivers with overcurrent recovery mode (HS7-HS10) are also short-circuit protected.

A short-circuit condition is detected at turn on of the output if the output voltage level remains low ($< 2\text{ V}$) after the programmed filter time t_{OCRxx} .

If a short-circuit condition is detected, the output is turned OFF and the overcurrent flag HSx_OC is set. This bit must be cleared before the output can be turned ON by SPI.

3.20 Current monitor

The current monitor sources an image of the power stage output current at the CM pin, which has the fixed ratio (I_{CMr} see [Section 2.4.8: Current monitor output](#)) of the instantaneous current of the selected high-side driver. The signal at output CM is blanked after switching on the driver until the correct settlement of the circuitry. The bits CM_SEL_x ($x = 0, \dots, 4$) in CR13 define which of the outputs is multiplexed to the current monitor output CM. The current monitor output allows a more precise analysis of the actual state of the load rather than the detection of an open-load or overload condition. For example, it can be used to detect the motor state (starting, free running, stalled). The current monitor output is enabled after the current monitor blanking time, when the selected output is switched on. If this output is off, the current monitor output is in high impedance mode. The current monitor can be activated/deactivated by selecting the corresponding setting for CM on/off bit.

3.21 PWM mode of the power outputs

All half bridges (except HB2 and HB3) can be, if suitably configured in CR2, directly driven in a 25 kHz PWM mode via pin PWM1-6 and PWM4-5. In this case, for the selected output, blanking time t_{BLK} is replaced by t_{FOC_PWM} .

When the PWM mode is activated on a half bridge low-side driver, all the others remain configurable according to the standard output bits (HBx_LS & HBx_HS) in CR16 (see [Section 6.4.12: Control register 16 \(0x3Dh\)](#)).

Note: *Active freewheeling is not implemented in PWM mode.*

3.22 Cross current protection

The six half bridges of the device are crosscurrent protected by an internal delay time. If one driver (LS or HS) is turned off, the activation of the other driver of the same half bridge is automatically delayed by the crosscurrent protection time. After the crosscurrent protection time has expired the slew rate limited switch off phase of the driver is changed into a fast turn off phase and the opposite driver is turned on with slew rate limitation. Due to this behavior, it is always guaranteed that the previously activated driver is completely turned off before the opposite driver starts to conduct.

3.23 Overcurrent recovery mode

Loads with startup currents higher than the overcurrent limits (for example inrush current of lamps, start current of motors) can be driven by suitably using the programmable overcurrent recovery (OCR) mode. To enable this feature, which is available for HB1-6, HS7-HS10, each of these drivers has a corresponding overcurrent recovery bit. If this bit is set, the output is turned OFF when the overcurrent threshold is reached and turned ON automatically after a programmable recovery time. The PWM modulated current provides sufficient average current to power up the load (for example heat up the bulb) until the load reaches operating condition. The recovery frequency (f_{OCR}) as well as the on time (t_{OCR}) is programmable in CR4.

3.24 H-bridge control

The PWMH and DIRH input controls the drivers of the external H-bridge transistors. In single motor mode the motor direction can be chosen with the direction input (DIRH), the duty cycle and frequency with the PWMH input (single mode). With the SPI-registers SD (CR12) and SDS (CR12) four different slow decay modes (via drivers and via diode) can be selected using the high-side or the low-side transistors. Unconnected inputs are defined by internal pull-down current. Alternatively, the bridge can be driven in half bridge mode (dual mode). By setting the dual mode bit DM = 1, both half bridges can be used for two separated motors, using the same control pins DIRH and PWMH.

Table 58. H-bridge control truth table

Nb	Control pins		Control bits				Failure bits					Output pin				Mode	Description
	DIRH	PWMH	HEN	SD	SDS	DM	CP_LOW	VS_OV	VS_UV	DS	TSD1	GH1	GL1	GH2	GL2		
1	x	x	0	x	x	x	x	x	x	x	x	RL	RL	RL	RL	Single	H-bridge disabled
2	x	x	1	x	x	x	1	0	0	0	0	RL	RL	RL	RL		Charge pump voltage too low
3	x	x	1	x	x	x	0	x	x	x	1	RL	RL	RL	RL		Thermal shutdown
4	x	x	1	x	x	x	0	1	0	0	0	L	L	L	L		Overvoltage
5	x	x	1	x	x	x	0	0	0	1	0	L ⁽¹⁾	L ⁽¹⁾	L ⁽¹⁾	L ⁽¹⁾		Short-circuit ⁽¹⁾
6	0	1	1	x	x	0	0	0	0	0	0	L	H	H	L		Bridge H2/L1 on
7	x	0	1	0	0	0	0	0	0	0	0	L	H	L	H		Slow-decay mode LS1 and LS2 on
8	0	0	1	0	1	0	0	0	0	0	0	L	H	L	L		Slow-decay mode LS1 on
9	1	0	1	0	1	0	0	0	0	0	0	L	L	L	H		Slow-decay mode LS2 on
10	1	1	1	x	x	0	0	0	0	0	0	H	L	L	H		Bridge H1/L2 on
11	x	0	1	1	0	0	0	0	0	0	0	H	L	H	L		Slow-decay mode HS1 and HS2 on
12	0	0	1	1	1	0	0	0	0	0	0	L	L	H	L		Slow-decay mode HS2 on

Nb	Control pins		Control bits				Failure bits					Output pin				Mode	Description
	DIRH	PWMH	HEN	SD	SDS	DM	CP_LOW	VS_OV	VS_UV	DS	TSD1	GH1	GL1	GH2	GL2		
13	1	0	1	1	1	0	0	0	0	0	0	H	L	L	L	Single	Slow-decay mode HS1 on
14	0	0	1	1	0	1	0	0	0	0	0	L	L	L	L	Dual	Half bridge mode
15	0	1	1	1	0	1	0	0	0	0	0	L	L	L	H		
16	1	0	1	1	0	1	0	0	0	0	0	L	H	L	L		
17	1	1	1	1	0	1	0	0	0	0	0	L	H	L	H		
18	0	0	1	0	1	1	0	0	0	0	0	L	L	L	L		
19	0	1	1	0	1	1	0	0	0	0	0	L	L	H	L		
20	1	0	1	0	1	1	0	0	0	0	0	H	L	L	L		
21	1	1	1	0	1	1	0	0	0	0	0	H	L	H	L		
22	0	0	1	1	1	1	0	0	0	0	0	H	L	H	L		
23	0	1	1	1	1	1	0	0	0	0	0	H	L	L	H		
24	1	0	1	1	1	1	0	0	0	0	0	L	H	H	L		
25	1	1	1	1	1	1	0	0	0	0	0	L	H	L	H		

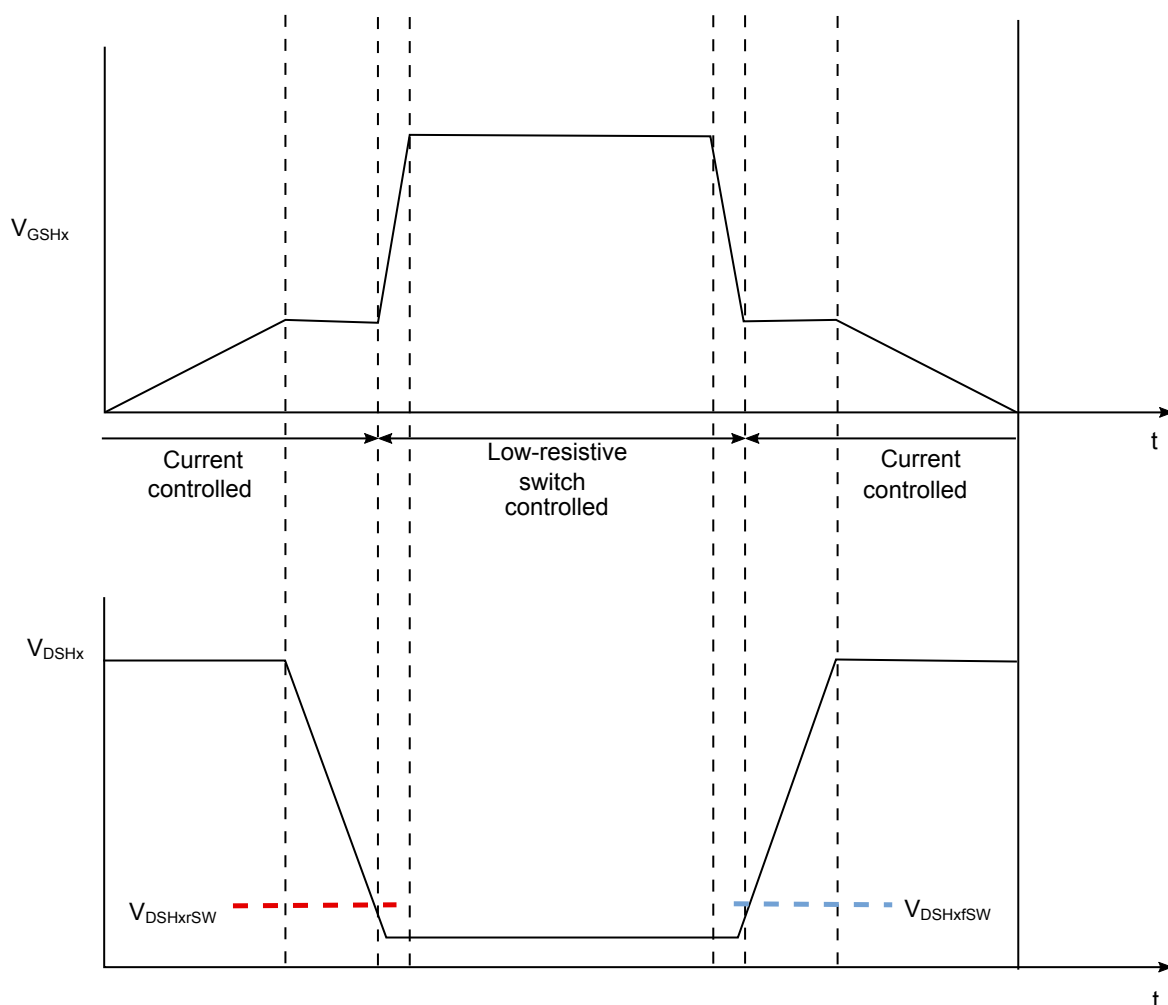
1. Only the half bridge (low-side and high-side), in which one Power MOSFET is in short-circuit condition is switched off. Both Power MOSFETs of the other half bridge remain active and driven by DIRH and PWMH.

H-bridge is forced off during long open window until watchdog kicks in short window, keeping control bits accessible in the meanwhile.

3.25 H-bridge driver slew rate control

The rising and falling slope of the drivers for the external high-side Power MOSFET can be slew rate controlled. If this mode is enabled the gate of the external high-side Power MOSFET is driven by a current source instead of a low impedance output driver switch as long as the drain-source voltage over this Power MOSFET is above the switch threshold. The current is programmed using the bits SLEW<4:0>, which represent a binary number. This number is multiplied by the minimum current step. This minimum current step is the maximum source/sink current ($I_{GHx\max}/I_{GHxf\max}$) divided by 31. Programming SLEW<4:0> to 0 disables the slew rate control and the output is driven by the low impedance output driver switch.

Note: To avoid crosscurrent conduction, it must be avoided the usage of the lowest slew rate configurations.

Figure 32. Half bridge GSHx slope


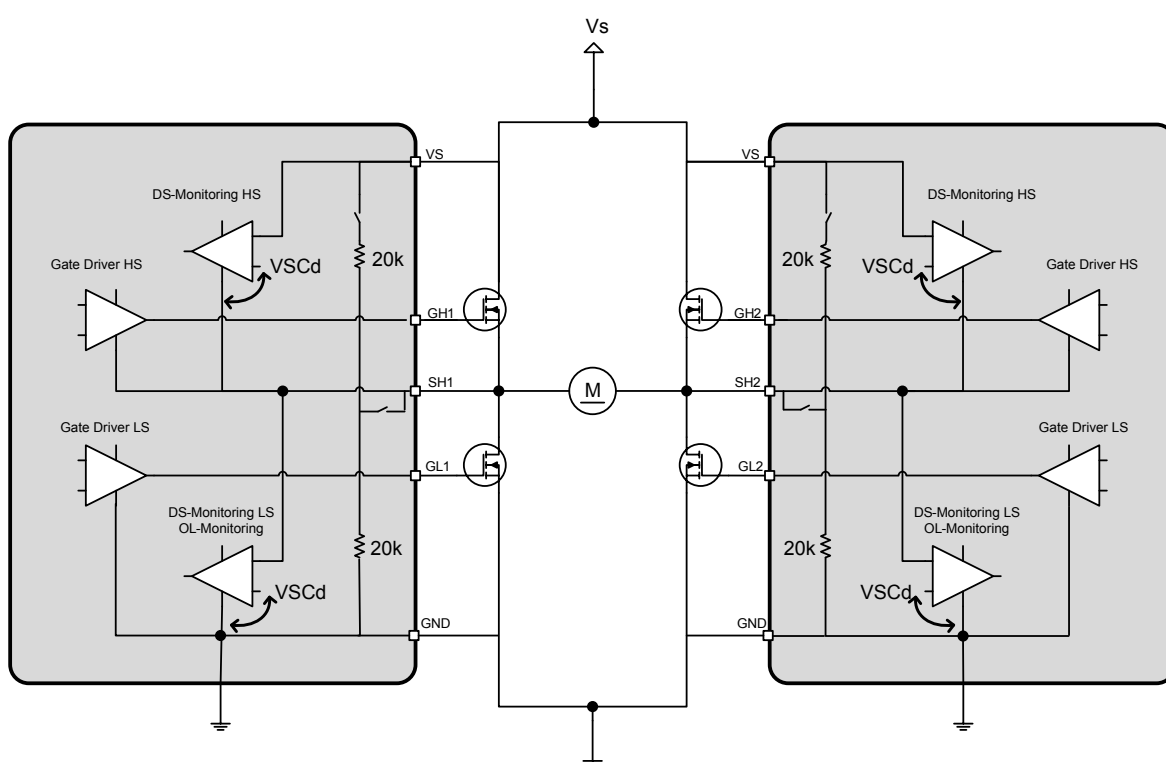
3.26 Resistive low

The resistive output mode protects the device and the H-bridge in the standby mode and in some failure modes (thermal shutdown (TSD), charge pump low (CP_LOW, see also undervoltage setting described in [Section 3.12.1: VS supply failure](#)) and stuck at '1' at DI pin). When a gate driver changes into the resistive output mode due to a failure a sequence is started. In this sequence the concerning driver is switched into sink condition for 32 μ s to 64 μ s to ensure a fast switch off of the H-bridge transistor. If slew rate control is enabled, the sink condition is slew rate controlled. Afterwards the driver is switched into the resistive output mode (resistive path to source).

3.27 Short-circuit detection/ drain-source monitoring

The drain-source voltage of each activated external Power MOSFET of the H-bridge is monitored by comparators to detect shorts to ground or battery. If the voltage drop over the external Power MOSFET exceeds the threshold voltage V_{SCd} for longer than the short current detection time t_{SCd} plus the comparator settling time t_{SCS} , the corresponding gate driver switches the external Power MOSFET off and the corresponding drain-source monitoring flag (DS MON LS1, DS MON LS2, DS MON HS1, DS MON HS2) is set. The DSMON_x bits have to be cleared through the SPI to reactivate the gate drivers. This monitoring is only active while the corresponding gate driver is activated. If a drain-source monitor event is detected (in [Table 59. H-bridge monitoring in off mode](#) is generically indicated as DS=1, meaning an OR among all four DSMON bits), the corresponding gate driver remains activated for at maximum the filter time t_{SCd} plus comparator settling time t_{SCS} . The threshold voltage V_{SCd} can be programmed using the SPI.

Figure 33. H-bridge diagnosis



3.28 H-bridge monitoring in OFF mode

The drain-source voltages of the H-bridge driver external transistors can be monitored, while the transistors are switched off. If either bit OL_H1L2 (CR12) or OL_H2L1 (CR12) is set to '1', while bit HEN (CR 18) = '1', the H-drivers enter resistive low mode and the drain-source voltages can be monitored. Since the pull-up resistance is equal to the pull-down resistance on both sides of the bridge a voltage of $2/3V_S$ on the pull-up high-side and $1/3V_S$ on the low-side is expected, if they drive a low-resistive inductive load (for example motor). If the drain-source voltage on each of these Power MOSFET is less than $1/6 V_S$, the drain-source monitor bit of the associated driver is set. In off-mode monitoring DSMON_HS1 and DSMON_HS2 are not used and set to 0, being relevant only DSMON_LS1 and DSMON_LS2. In case of a short to ground the drain-source monitor bits of both low-side gate drivers are set. A short to V_S can be diagnosed by setting the "H-bridge OL high threshold (H OLTH High)" bit to one. The open-load filter time (t_{fOL}) is 2 ms typical.

Figure 34. H-bridge off state diagnosis (no open-load detected)

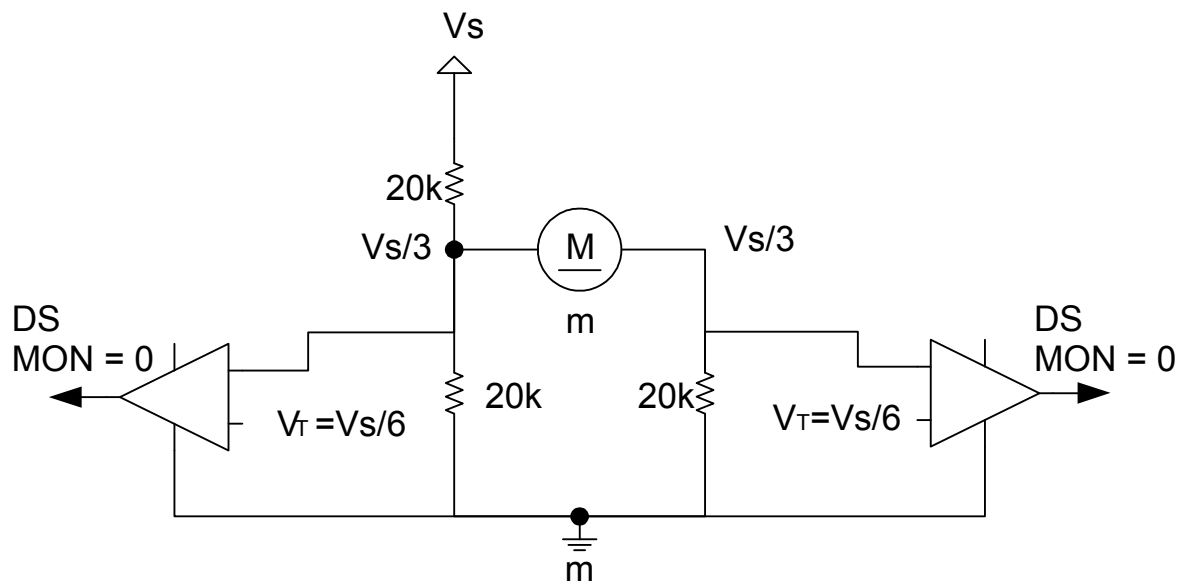


Figure 35. H-bridge off state diagnosis (open-load detected)

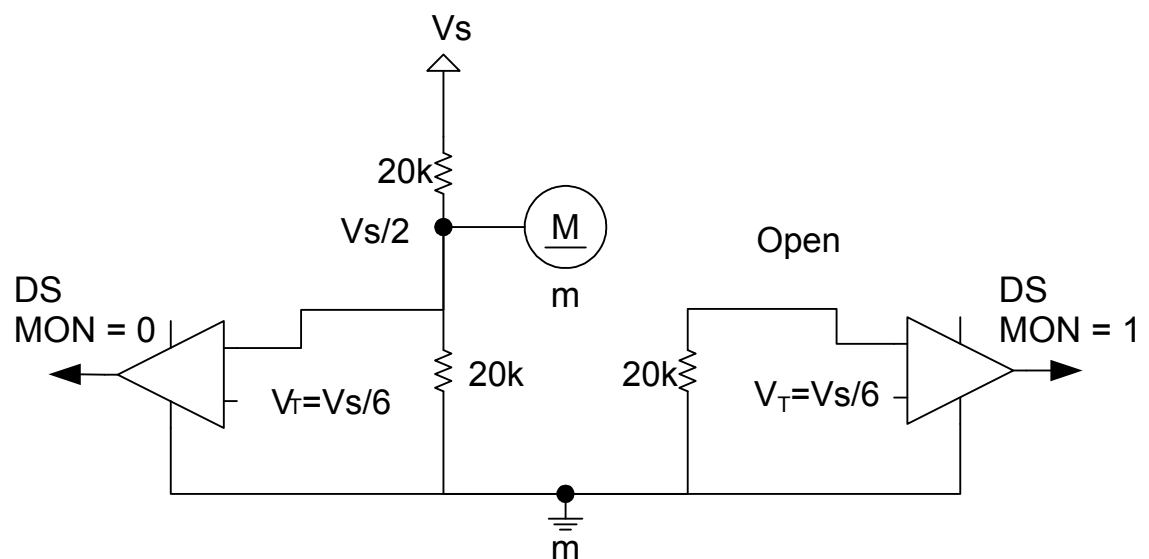


Figure 36. H-bridge off state diagnosis (short to ground detected)

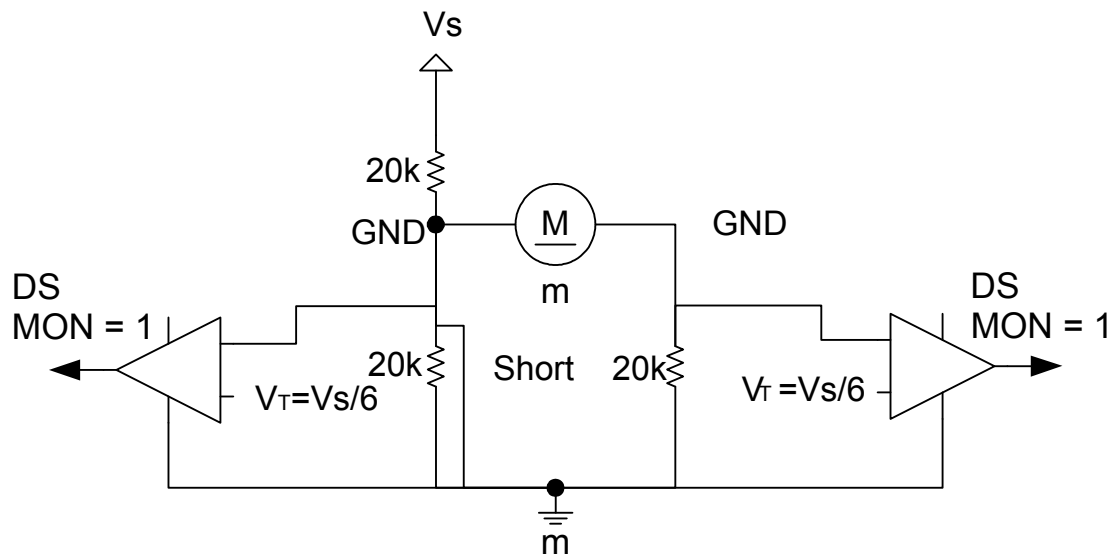
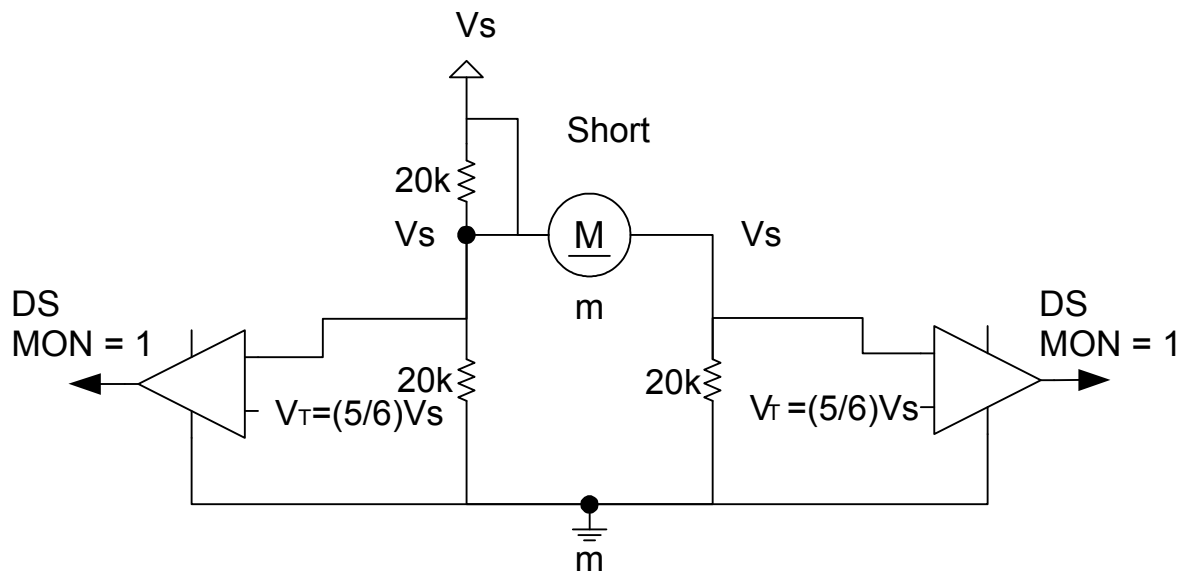


Figure 37. H-bridge off state diagnosis (short to V_s detected)



In this specific case ($H_OLTH_high = 1$) the outputs of the 2 comparators are inverted to be compliant to Table 58. H-bridge control truth table (Nb = 5 and 9).

Table 59. H-bridge monitoring in off mode

Nb	Control bits			Failure bits		Comments
	OL H1L2	OL H2L1	H OLTH High	DSMON LS1	DSMON LS2	
1	0	0	0	0	0	Drain-source monitor disabled
2	1	0	x	0	0	No open-load detected
3	1	0	0	0	1	Open-load
4	1	0	0	1	1	Short to GND
5	1	0	1	1	1	Short to VS
6	0	1	x	0	0	No open-load detected
7	0	1	0	1	0	Open-load
8	0	1	0	1	1	Short to GND
9	0	1	1	1	1	Short to VS

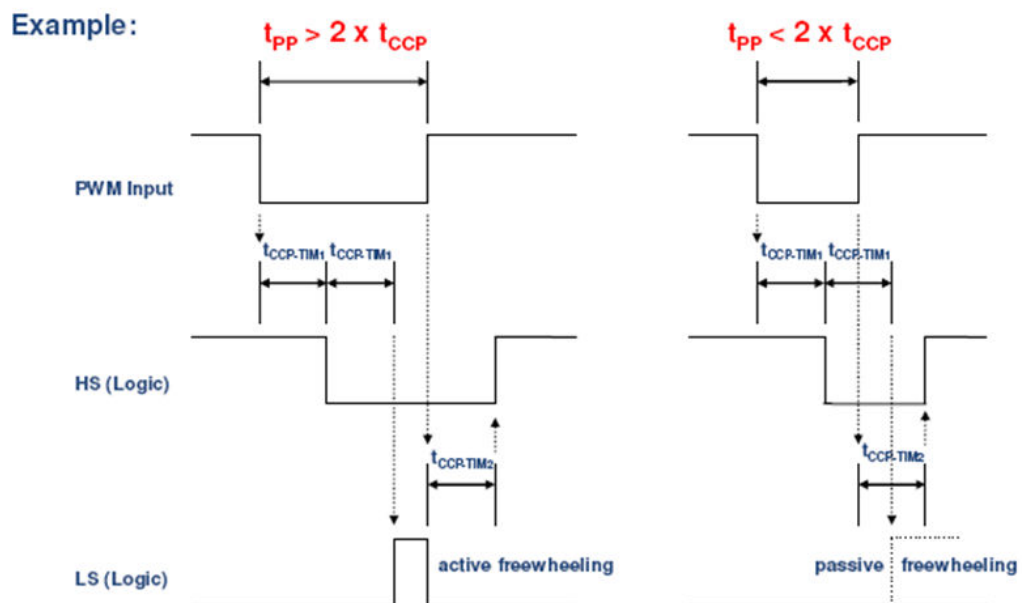
3.29 Programmable cross current solution

The external Power MOSFETs transistors in H-bridge (two half bridges) configuration are switched on with an additional delay time t_{CCP} to prevent cross current in the half bridge. The cross current protection time t_{CCP} can be programmed with the SPI using bits COPT<3:0> (CR12). The timer is started when the gate driver is switched on in the device.

The PWMH module has 2 timers to configure locking time for high-side and freewheeling low-side.

The programmable time $t_{CCP-TIM1/CCP-TIM2}$ is the same. Sequence for switching in PWM mode is as follows:

- HS switches off after locking $t_{CCP-TIM1}$
- LS switches on after 2nd locking $t_{CCP-TIM1}$
- HS switches on after locking $t_{CCP-TIM2}$ which starts with rising edge on PWMH input

Figure 38. PWMH cross current protection time implementation


3.30 Heater Power MOSFET driver

The heater Power MOSFET driver stage is controlled by control bit (GH on/off). The driver contains two diagnosis features to indicate SC in active mode (external Power MOSFET switched on) and OL in off state (external Power MOSFET switched off).

Short circuit detection in ON state is realized by monitoring the drain-source voltage of the activated external Power MOSFET by a comparator to detect a SC of SHheater to ground. If the voltage-drop over the external Power MOSFET exceeds the programmed threshold voltage (V_{SCdx}) for longer than the drain-source monitor filter time (t_{SCdx}) the gate driver switches off the external Power MOSFET and the corresponding drain-source monitoring flag DSMON_HEAT(SR6) is set. The drain-source monitoring bit has to be cleared by SPI to reactivate the gate driver. The drain-source monitoring is only active while the gate driver is activated. If a drain-source monitor event is detected, the gate-driver remains activated for the maximum filter time. The threshold voltage can be programmed using the SPI bits GH_THx (CR12).

Open-load detection in off state is realized by monitoring the voltage difference between SHheater and GND and supplying SHheater by a pull-up current source that can be controlled by the SPI bit GH_OL_EN (CR12). When no load is connected to the external Power MOSFET source, the voltage is pulled to VS and in case of exceeding the threshold VOLheater for a time longer than the open-load filter time TOL the open-load bit GH_OL (SR5) is set.

A 15 kΩ resistor is present to discharge the gate capacitor of the external Power MOSFET.

In case of VS undervoltage, behavior and settings are also described in [Section 3.12.1: VS supply failure](#).

Figure 39. Heater Power MOSFET open-load and short-circuit to GND detection

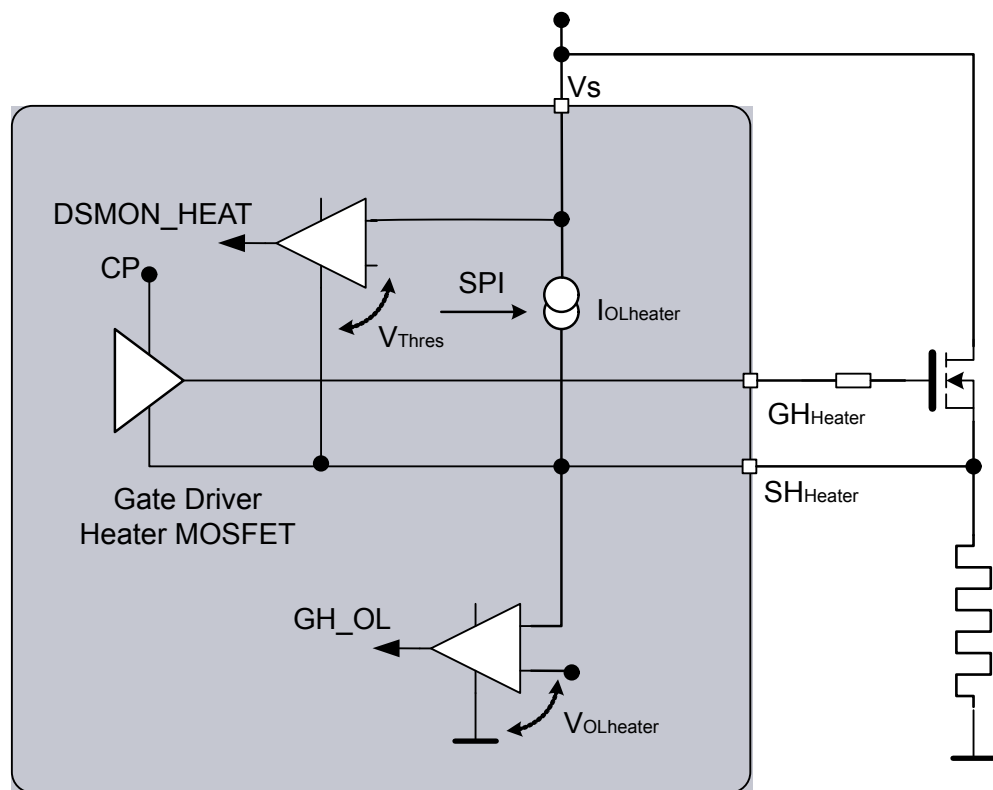


Table 60. Heater Power MOSFET control truth table

Nb	Control bit	Failure bits					Output pin	Comment
	GH ON/OFF	CP_LOW	VS_OV	VS_UV	DS	TSD1	GHheater	
1	x	1	x	x	x	x	RL	Charge pump voltage too low
2	x	0	x	x	x	1	RL	Thermal shutdown
3	x	0	1	x	x	0	RL	Overload
4	1	0	0	x	1	0	RL	Short-circuit condition
5	x	0	0	1	0	0	RL	Undervoltage
6	1	0	0	0	0	0	H	Heater Power MOSFET driver enabled
7	0	0	0	0	0	0	RL	Heater Power MOSFET driver disabled

Note: RL = resistive low, H = active high.

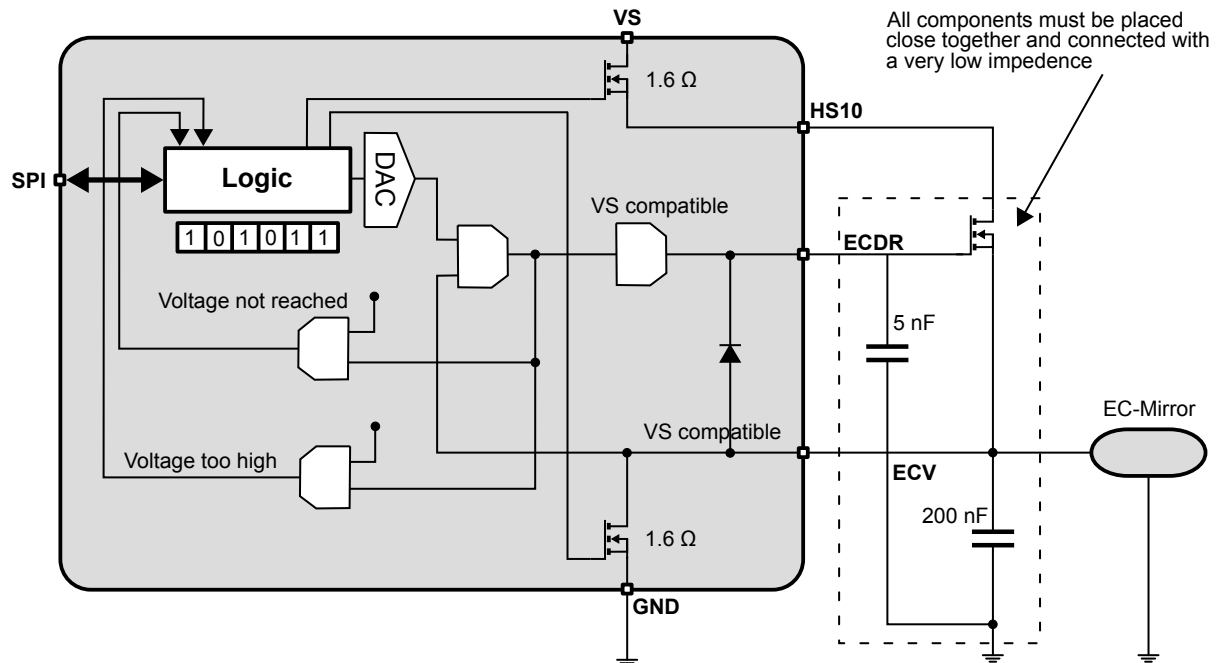
3.31 Control of electrochromic glass

The voltage of an electrochromic element connected at pin ECV can be controlled to a target value, which is set by the bits EC_x<5:0> (CR11). Setting bit ECON (CR11) enables this function. A control loop enables the driving of the electro-chrome mirror voltage on pin ECV thanks to an on-chip differential amplifier and to an external Power MOSFET source follower with its gate connected to pin ECDR. The drain of the external Power MOSFET transistor (the recommended one is STD17NF03L) is supplied by HS10. A diode from pin ECV (anode) to pin ECDR (cathode) has been placed on the chip to protect the external Power MOSFET source follower. A capacitor of at least 5 nF has to be added to pin ECDR for loop stability.

The target voltage is binary coded with a full-scale range of 1.5 V. If Bit ECV HV is set to 0, the maximum controller output voltage is clamped to 1.2 V without changing the resolution of bits EC_x<5:0>. When programming the ECV low-side driver ECV_LS (CR11) to on-state, the voltage at pin ECV is pulled to ground by a 1.6 Ω low-side switch until the voltage at pin ECV is less than $d_{V_{ECV_{hi}}}$ higher than the target voltage (fast discharge). The status of the voltage control loop is reported via SPI. Bit ECV_VHI (SR4) is set, if the voltage at pin ECV is higher, whereas Bit ECV_VNR (SR4) is set, if the voltage at pin ECV is lower than the target value. Both status bits are valid, if they are stable for at least the ECVHI/ECVNR filter time and are not latched. Since HS10 is the output of a high-side driver, it contains the same diagnose functions as the other high-side drivers (for example during an overcurrent detection, the control loop is switched off). Also, ECV overcurrent and open-load are monitored through ECV_OC and ECV_OL in SR6 and SR5. In particular, open-load of electro chrome can be also detected by HS10 OL when ECON and HS10 are enabled¹. In case of failure detection on HS10_OC; UV; OV, but in general when HS10 is switched off, the ECHR DAC control register is forced to 00000 and DAC code is reprogrammed another time (details of overvoltage and undervoltage behavior are reported in [Section 3.12: Power supply fail](#)).

In electrochrome mode, HS10 cannot be controlled by PWM mode. For EMS reasons, the loop capacitor at pin ECDR as well as the capacitor between ECV and GND have to be placed to the respective pins as close as possible (see [Figure 40. Electrochrome control block](#)).

Figure 40. Electrochrome control block



Pin ECDR is pulled resistively ($R_{ECDRDIS}$) to ground while not in electro chrome mode. Otherwise, when $EC<5:0>=0$, it is digitally controlled through the ECV_LS bit.

Note: *It is possible to detect an OL on HS10 between the transition of HS10 driver enable and ECON enable. In this case external MOSFET is OFF so there is no current inside HS10 (HS10 OL bit has to be cleared after ECON enable).*

3.32 Temperature warning and shutdown

If any of the cluster (see [Section 3.33: Digital thermal clusters](#)) junction temperatures rise above the temperature warning threshold (T_{JTW}), a temperature warning flag is set after the temperature warning filter time (t_{FTJTW}) and can be read via SPI. If the junction temperature increases above the temperature shutdown threshold (T_{JTS}), the thermal shutdown bit is set and the power transistors of all output stages are switched off to protect the device after the thermal shutdown filter time. The gates of the H-bridge and the heater MOSFET are discharged by the 'resistive low' mode. The temperature warning and thermal shutdown flags are latched and must be cleared by the microcontroller. This is done by a read and clear command on an arbitrary register, because both bits are part of the global status register (TSD1 is bit 4 in SR 8 while TW is in bit 8 in SR 7).

After these bits have been cleared, the output stages are reactivated. If the temperature is still above the thermal warning threshold, the thermal warning bit is set after t_{FTJTW} . Once this bit is set, and the temperature is still above the shutdown threshold, temperature shutdown is detected after t_{FTJTW} and the outputs are switched off.

Therefore, the minimum time after which the outputs are switched off in this case, is twice the thermo warning/thermo shutdown filter time t_{FTJTW} .

3.33 Digital thermal clusters

In order to provide an advanced on chip temperature control, the power outputs are grouped in eight clusters with dedicated thermal sensors. The sensors are suitably located on the device (see [Figure 41. Digital thermal clusters identification](#)). In case the temperature of an output cluster reaches the thermal shutdown threshold, the outputs assigned to this cluster are shutdown (all other outputs remain active). Each output cluster has a dedicated temperature warning and shutdown flag (SR1 and SR2). Hence, the thermal cluster concept allows to identify a group of outputs in which one or more channels are in the overload condition.

Thermal clusters can be configured using the bit TSD_CLUSTER_EN (CR3):

- Standard mode (default): as soon as any cluster reaches thermal threshold the device is switched off. V1 regulator remains on and it is switched off reaching TSD2. All the thermal sensors are put in "OR". In fact, if one of these sensors reaches TSD1:
 - All outputs drivers, charge-pump and V2 are turned OFF
 - V1 remains on until TSD2
 - LIN and CAN transmitters are turned OFF (but they are forced in "receive only" mode)
- Cluster mode: only the cluster that reaches shutdown temperature is switched off.
 In case cluster Th_CL7 reaches TSD1:
 - HS0, HS15, V2 are turned OFF
 - V1 remains ON until TSD2
 In case cluster Th_CL8 reaches TSD1:
 - all outputs drivers, charge pump and V2 are turned OFF
 - V1 remains on until TSD2
 - LIN and CAN transmitters are turned OFF (they are forced in "receive only" mode)

Figure 41. Digital thermal clusters identification

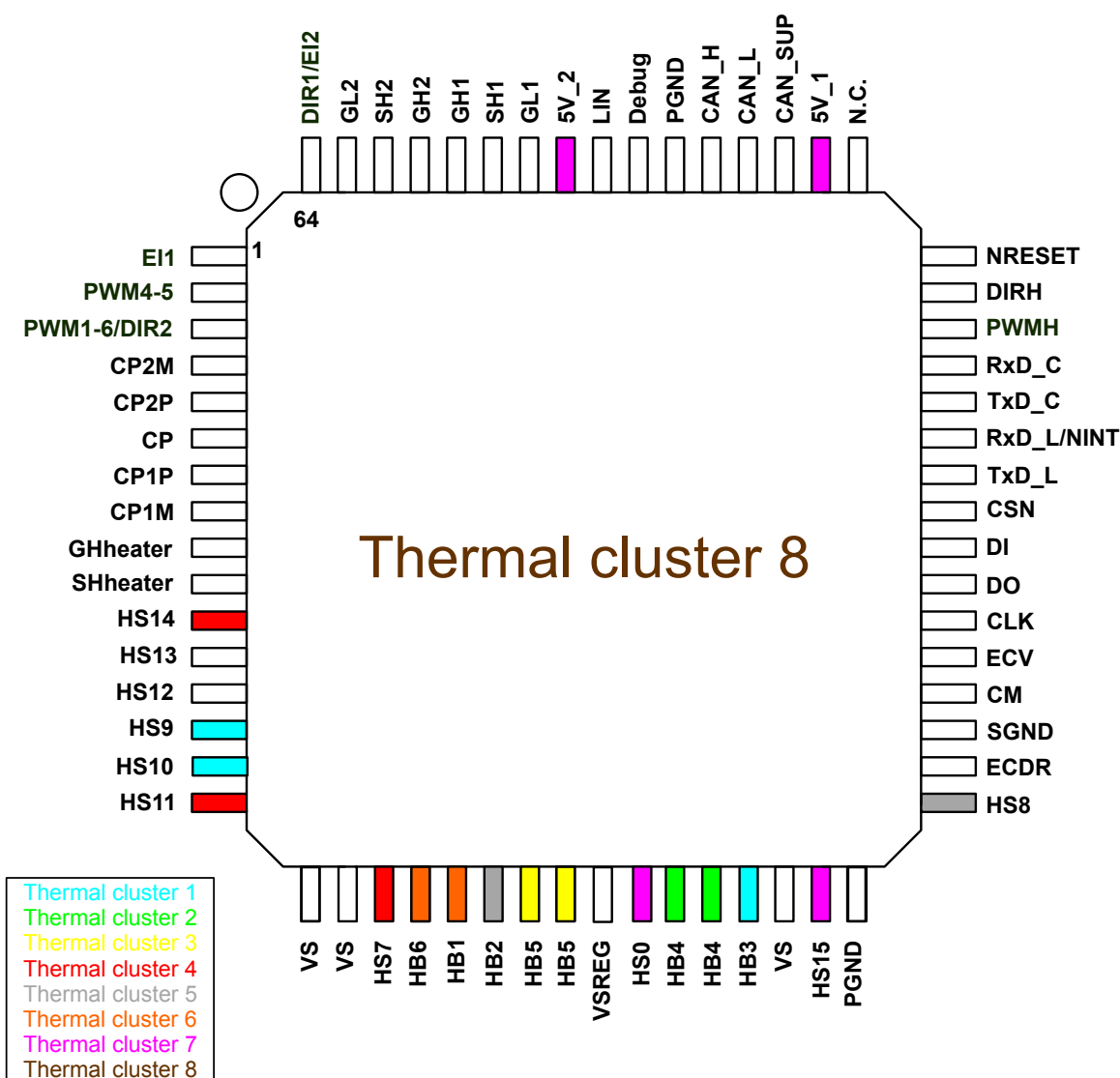


Table 61. Digital thermal clusters definition

Th_CL1	Th_CL2	Th_CL3	Th_CL4	Th_CL5	Th_CL6	Th_CL7	Th_CL8
HB3 HS9-HS10	HB4	HB5	HS7 HS11-HS14	HB2 HS8	HB1 HB6	VREG 1 VREG 2 HS15 HS0	Global
TW & TSD1	TW & TSD1	TW & TSD1	TW & TSD1	TW & TSD1	TW & TSD1	TW &TSD1. TSD2 for VREG1 only ⁽¹⁾	TW, TSD1

1. In default V1_Standby mode, only TSD2 is available for this cluster.

4 Serial peripheral interface (SPI)

A 32-bit SPI is used for bidirectional communication with the microcontroller.

The SPI is driven by a microcontroller with its SPI peripheral running in the following mode:

CPOL = 0 and CPHA = 0.

For this mode input data is sampled by the low to high transition of the clock CLK, and output data is changed from the high to low transition of CLK.

This device is not limited to microcontroller with a built-in SPI. Only three CMOS compatible output pins and one input pin are needed to communicate with the device. A fault condition can be detected by setting CSN to low. If CSN = 0, the DO-pin reflects the global error flag (fault condition) of the device.

Chip select not (CSN)

The input pin is used to select the serial interface of this device. When CSN is high, the output pin (DO) is in high impedance state. A low signal activates the output driver and a serial communication can be started. The state during CSN = 0 is called a communication frame.

If CSN = low for $t > t_{\text{CSNfail}}$ the DO output is switched to high impedance in order to not block the signal line for other SPI nodes.

Serial data in (DI)

The input pin is used to transfer data serial into the device. The data applied to the DI is sampled at the rising edge of the CLK signal and shifted into an internal 32-bit shift register. At the rising edge of the CSN signal the content of the shift register is transferred to the data input register. The writing to the selected data input register is only enabled if exactly 32 bits are transmitted within one communication frame (that is CSN low). If more or less clock pulses are counted within one frame the complete frame is ignored. This safety function is implemented to avoid an activation of the output stages by a wrong communication frame.

Note: due to this safety functionality a daisy chaining of SPI is not possible. Instead, a parallel operation of the SPI bus by controlling the CSN signal of the connected IC's is recommended.

Serial data out (DO)

The data output driver is activated by a logical low level at the CSN input and go from high impedance to a low or high level depending on the global error flag (fault condition). The first rising edge of the CLK input after a high to low transition of the CSN pin transfers the content of the selected status register into the data out shift register. Each subsequent falling edge of the CLK shifts the next bit out.

Serial clock (CLK)

The CLK input is used to synchronize the input and output serial bit streams. The data input (DI) is sampled at the rising edge of the CLK and the data output (DO) changes with the falling edge of the CLK signal. The SPI can be driven with a CLK frequency up to 4 MHz.

4.1 ST SPI 4.0

The ST SPI is a standard used in ST Automotive ASSP devices.

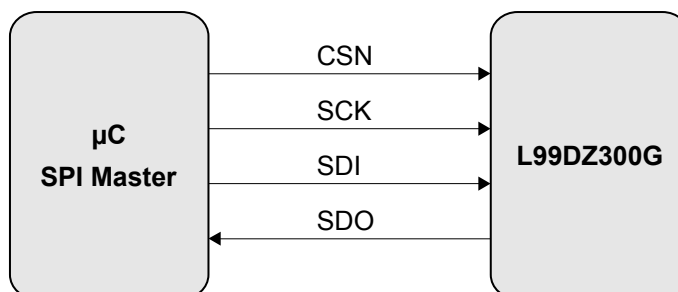
This chapter describes the SPI protocol standardization. It defines a common structure of the communication frames and defines specific addresses for product and status information.

The ST SPI allows the usage of generic software to operate the devices while maintaining the required flexibility to adapt it to the individual functionality of a particular product. In addition, failsafe mechanisms are implemented to protect the communication from external influences and a wrong or unwanted usage.

The device serial peripheral interface is compliant to the ST SPI standard rev. 4.0.

4.1.1 Physical layer

Figure 42. SPI pin description



4.2 Signal description

- **Chip select not (CSN)**

The communication interface is deselected, when this input signal is logically high. A falling edge on CSN enables and starts the communication while a rising edge finishes the communication and the sent command is executed when a valid frame is sent. During communication start and stop the serial clock (SCK) has to be logically low. The serial data out (SDO) is in high impedance when CSN is high or a communication timeout was detected.

- **Serial clock (SCK)**

This SCK provides the clock of the SPI. Data present at serial data input (SDI) is latched on the rising edge of serial clock (SCK) into the internal shift registers while on the falling edge data from the internal shift registers are shifted out to serial data out (SDO).

- **Serial data input (SDI)**

This input is used to transfer data serially into the device. Data is latched on the rising edge of serial clock (SCK).

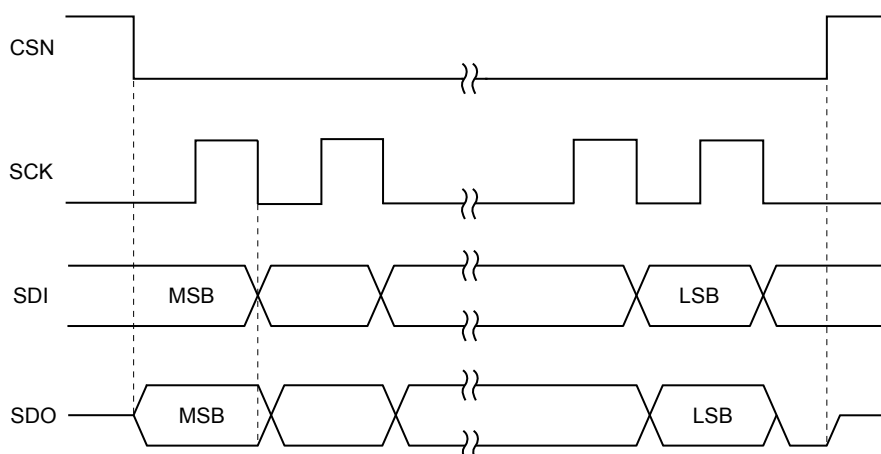
- **Serial data output (SDO)**

This output signal is used to transfer data serially out of the device. Data is shifted out on the falling edge of serial clock (SCK).

4.2.1 Clock and data characteristics

The ST SPI can be driven by a microcontroller with its SPI peripheral running in the following mode:

Figure 43. SPI signal description



The communication frame starts with the falling edge of the CSN (communication start). SCK has to be low.

The SDI data is then latched at all the following rising SCK edges into the internal shift registers.

After communication start the SDO leaves 3-state mode and presents the MSB of the data shifted out to SDO. At all the following falling SCK edges data is shifted out through the internal shift registers to SDO.

The communication frame is finished with the rising edge of CSN. If a valid communication takes place (for example a correct number of SCK cycles, access to a valid address), the requested operation according to the operating code is performed (write or clear operation).

4.2.2 Communication protocol

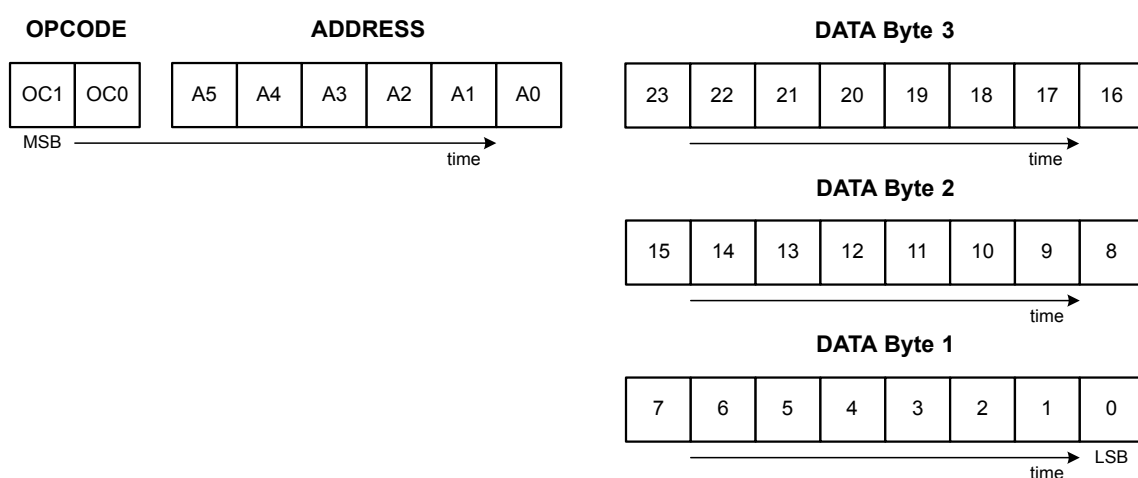
SDI frame

The devices data in the frame consists of 32 bits (OpCode (2 bits) + address (6 bits) + data byte 3 + data byte 2 + data byte 1).

The first two transmitted bits (MSB, MSB-1) contain the operation code that represents the instruction that is performed. The following 6 bits (MSB-2 to MSB-7) represent the address on which the operation is performed.

The subsequent bytes contain the payload.

Figure 44. SDI frame



Operating code

The operating code is used to distinguish between different access modes to the registers of the slave device.

Table 62. Operation codes

OC1	OC0	Description
0	0	Write operation
0	1	Read operation
1	0	Read and clear operation
1	1	Read device information

A "Write operation" leads to a modification of the addressed data by the payload if a write access is allowed (for example, control register, valid data). Besides this, a shift out of the registers content (data present at the communication start) is performed.

A "Read operation" shifts out the data present in the addressed register at the communication start. The payload data is ignored and internal data is not modified. In addition, a burst read can be performed.

A "Read and clear operation" leads to a clear of addressed status bits. The bits to be cleared are defined first by address, second by payload bits set to '1'. Besides this, a shift out of the registers content (data present at the communication start) is performed.

Note: Status registers that change status during communication could be cleared by the actual read and clear operation and are not reported in actual communication or in the following communications. To avoid a loss of any reported status, it is recommended just to clear the status registers that are already reported in the previous communication (selective bitwise clear).

Advanced operation codes

To provide besides the separate write of all the control registers and the bitwise clear of all the status registers, two advanced operation codes can be used to set all the control registers to the default value and to clear all the status registers

A 'set all control registers to default' command is performed when an OpCode '11' at address b'111111 is performed.

Note: Consider that potential device specific write-protected registers cannot be cleared with this command as therefore a device power-on reset is needed.

A 'clear all status registers' command is performed when an OpCode '10' at address b'111111 is performed.

Data in payload

The payload (data byte 1 to data byte 3) is the data transferred to the device with every SPI communication. The payload always follows the OpCode and the address bits.

For write access the payload represents the new data written to the addressed register. For read and clear operations the payload defines which bit of the addressed status register is cleared. In the case of a '1' at the corresponding bit position the bit is cleared.

For a read operation the payload is not used. For functional safety reasons it is recommended to set the unused payload to '0'.

SDO frame

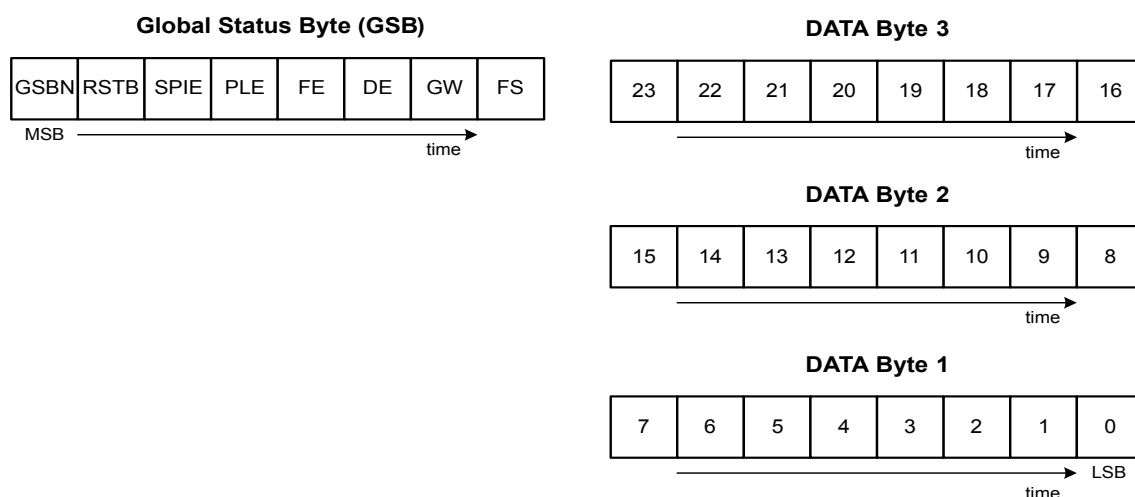
The data out frame consists of 32 bits (GSB + data bytes 1 to 3).

The first eight transmitted bits contain the device-related status information and are latched into the shift register at the time of the communication starts. These 8 bits are transmitted at every SPI transaction.

The subsequent bytes contain the payload data and are latched into the shift register with the eight positive SCK edges.

This could lead to an inconsistency of data between the GSB and the payload due to different shift register load times. Anyway, no unwanted status register clear should appear, as status information should just be cleared with a dedicated bit clear.

Figure 45. SDO frame



Global status byte (GSB)

The bits (Bit 0 to Bit 4) represent a logical OR combination of bits located in the status registers. Therefore, no direct read & clear can be performed on these bits inside the GSB.

Table 63. Global status byte

Bit 31	Bit 30	Bit 29	Bit 28	Bit 27	Bit 26	Bit 25	Bit 24
GSBN	RSTB	SPIE	PLE	FE	DE	GW	FS

Global status bit not (GSBN)

The GSBN is a logical NOR combination of Bit 24 to Bit 30. This bit can also be used as a global status flag without starting a complete communication frame as it is present directly after pulling CSN low.

- **Reset bit (RSTB)**

The RSTB indicates a device reset. In case this bit is set, specific internal control registers are set to default and kept in that state until the bit is cleared.

The RSTB bit is cleared after a read and clear of all the specific bits in the status registers that caused the reset event.

- **SPI error (SPIE)**

The SPIE is a logical OR combination of errors related to a wrong SPI communication.

- **Physical layer error (PLE)**

The PLE is a logical OR combination of errors related to the LIN and CAN FD transceivers.

- **Functional error (FE)**

The FE is a logical OR combination of errors coming from functional blocks (for example high-side overcurrent).

- **Device error (DE)**

The DE is a logical OR combination of errors related to device specific blocks (for example VS overvoltage, over temperature).

- **Global warning (GW)**

The GW is a logical OR combination of warning flags (for example thermal warning).

- **Fail-safe (FS)**

The FS bit indicates that the device was forced into a safe state due to mistreatment or fundamental internal errors (for example watchdog failure, voltage regulator failure).

Data out payload

The payload (data bytes 1 to 3) is the data transferred from the slave device with every SPI communication to the master device. The payload always follows the OpCode and the address bits of the actual shifted in data (in frame response).

4.2.3 Address definition

Table 64. Address definition - device application access

Device application access	
Operating code	
OC1	OC0
0	0
0	1
1	0

Table 65. Address definition - device information read access

Device information read access	
Operating code	
OC1	OC0
1	1

Table 66. Address definition - RAM access

RAM address	Description	Access
3FH	Configuration register	R/W
...	...	...
3DH	Status register 13	R/C
...	...	...
32H	Status register 2	R/C
31H	Status register 1	R/C
...	...	...
22H	Control register 34	R/W
1DH	Control register 29	R/W
...	...	...
02H	Control register 2	R/W
01H	Control register 1	R/W
00H	Reserved	

Table 67. Address definition - ROM access

ROM Address	Description	Access
3FH	<Advanced op.>	W
3EH	<GSB options>	R
...		
20H	<SPI CPHA test>	R
16H	<WD bit pos. 4>	R
15H	<WD bit pos. 3>	R
14H	<WD bit pos. 2>	R
13H	<WD bit pos. 1>	R
12H	<WD type 2>	R
11H	<WD type 1>	R
10H	<SPI mode>	R
...		
0AH	<Silicon ver.>	R
...		
05H	<Device n.4>	R
04H	<Device n.3>	R
03H	<Device n.2>	R
02H	<Device n.1>	R
01H	<Device family>	R
00H	<Company code>	R

Information registers

The device information registers can be read by using OpCode '11'. After shifting out the GSB the 8-bit wide payload is transmitted. By reading device information registers a communication width which is minimum 16 bits plus a multiple by 8 can be used. After shifting out the GSB followed by the 8-bit wide payload a series of '0' is shifted out at the SDO.

Table 68. L99DZ300G information register map

ROM address	Description	Access	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
3FH	<Advanced op.>									
3EH	<GSB options>	R	0	0	0	0	0	0	0	0
...										
20H	<SPI CPHA test>	R	0	1	0	1	0	1	0	1
16H	<WD bit pos. 4>	R	C0H							
15H	<WD bit pos. 3>	R	7FH							
14H	<WD bit pos. 2>	R	C0H							
13H	<WD bit pos. 1>	R	66H							
12H	<WD type 2>	R	91H							
11H	<WD type 1>	R	3CH							
10H	<SPI mode>	R	B0H							
...										
0AH	<Silicon ver.>	R	major revision				minor revision			
...										
05H	<Device n.4>	R	46H							
04H	<Device n.3>	R	35H							
03H	<Device n.2>	R	52H							
02H	<Device n.1>	R	44H							
01H	<Device family>	R	01H							
00H	<Company code>	R	00H							

Device identification registers

These registers represent a unique signature to identify the device and silicon version.

<Company code>: 00H (STMicroelectronics)

<Device family>: 01H (BCD power management)

<Device n. 1>: 44H (ASCII code for D)

<Device n. 2>: 52H (ASCII code for R)

<Device n. 3>: 35H (ASCII code for 5)

<Device n. 4>: 46H (ASCII code for F)

SPI modes

By reading out the <SPI mode> register general information of SPI usage of the device application registers can be read.

Table 69. SPI mode registers

Bit7	Bit6	Bit5	Bit 4	Bit 3	Bit 2	Bit1	Bit0
BR	DL2	DL1	DL0	0	0	S1	S0
1	0	1	1	0	0	0	0

<SPI mode>: B0H (burst mode read available, 32-bit, no data consistency check)

SPI burst read

Table 70. Burst read bit

Bit 7	Description
0	BR not available
1	BR available

The SPI burst read bit indicates if a burst read operation is implemented. The intention of a burst read is for example used to perform a device internal memory dump to the SPI master.

The start of the burst read is like a normal read operation. The difference is that after the SPI data length the CSN is not pulled high and the SCK is continuously clocked. When the normal SCK max count is reached (SPI data length) the consecutive addressed data is latched into the shift register. This procedure is performed every time when the SCK payload length is reached.

In case the automatic incremented address is not used by the device, undefined data is shifted out. An automatic address overflow is implemented when address 3FH is reached.

The SPI burst read is limited by the CSN low timeout.

SPI data length

The SPI data length value indicates the length of the SCK count monitor which is running for all accesses to the device application registers. In case a communication frame with an SCK count is not equal to the reported one it will lead to a SPI error and the data will be rejected.

Table 71. SPI data length

Bit 6	Bit 5	Bit 4	Description
DL2	DL1	DL0	
0	0	0	Invalid
0	0	1	16-bit SPI
0	1	0	24-bit SPI
0	1	1	32-bit SPI
1	1	1	64-bit SPI

Table 72. Data consistency check (parity-check)

Bit 1	Bit 0	Description
S1	S0	
0	0	Not used
0	1	Parity used
1	0	CRC used
1	1	Invalid

Watchdog definition

(see also [Section 2.4.7: Watchdog](#))

In case a watchdog is implemented the default settings can be read out via the device information registers.

Table 73. WD type/timing

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	WD1	WD0						
<WD type 1/2>	0	0			Register is not used			

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
<WD type 1>	0	1	WT5	WT4	WT3	WT2	WT1	WT0
		1	1	1	1	1	0	0
			Watchdog timeout/long open window WT[5:0] * 5 ms					
<WD type 2>	1	0	OW2	OW1	OW0	CW2	CW1	CW0
	1	0	0	1	0	0	0	1
			Open window OW[2:0] *			Closed window CW[2:0] *		
				5 ms			5 ms	
<WD type 1/2>	1	1	Invalid					

<WD type 1>: 3CH (long open window: 300 ms)

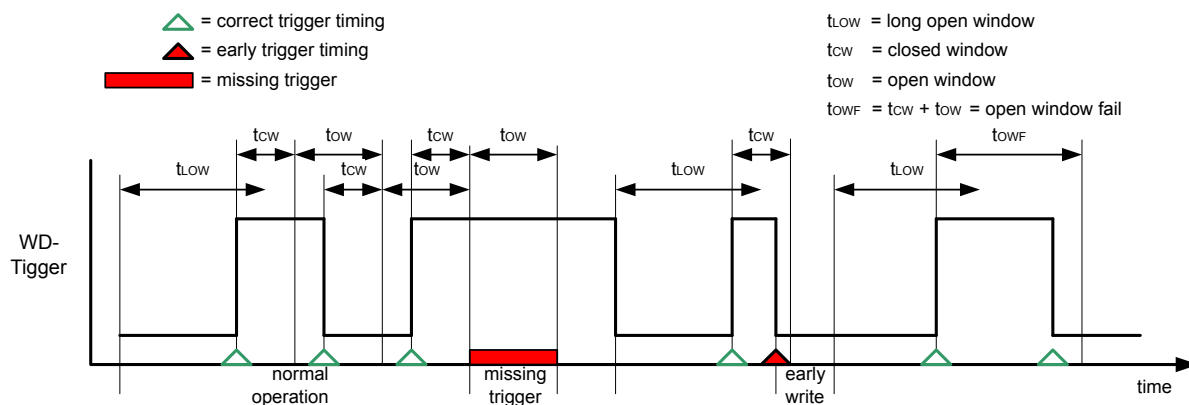
<WD type 2>: 91H (open window: 10 ms, closed window: 5 ms)

<WD type 1> indicates the long open window (timeout) which is opened at the start of the watchdog. The binary value of WT [5:0] times 5 ms indicates the typical value of the timeout time.

<WD type 2> describes the default timing of the window watchdog.

The binary value of CW [2:0] times 5 ms defines the typical closed window time (t_{CW}) and OW [2:0] times 5 ms defines the typical open window time (t_{OW}). See Figure 46. Window watchdog operation, which recalls with Figure 4. Watchdog timing $t_{CW} = T_{EFW}$ and $t_{OW} = T_{LFW} - T_{EFW}$

Figure 46. Window watchdog operation



The watchdog trigger bit location is defined by the <WD bit pos. X> registers.

Table 74. WD bit position

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	WB1	WB0						
<WD bit pos. X>	0	0			Register is not used			
<WD bit pos. X>	0	1	WBA5	WBA4	WBA3	WBA2	WBA1	WBA0
<WD bit pos. 1>	0	1	0	0	0	0	0	1
<WD bit pos. 3>	0	1	1	1	1	1	1	1
			Defines the register addresses of the WD trigger bits					
<WD bit pos. X>	1	0	WBA5	WBA4	WBA3	WBA2	WBA1	WBA0
			Defines the stop address of the address range (previous <WD bit pos. X> is a WB = '01'). The consecutive <WD bitpos. X> has to be a WB = '11'					
<WD bit pos. X>	1	1	0	WBP 4	WBP3	WBP2	WBP1	WBP0
<WD bit pos. 2>	1	1	0	0	0	0	0	0
<WD bit pos. 4>	1	1	0	0	0	0	0	0
			Defines the binary bit position of the WD trigger					
					bit within the register			

<WD bit pos 1>: 41H; watchdog trigger bit located at address 01H (CR18)

<WD bit pos 2>: C0H; watchdog trigger bit location is bit0

<WD bit pos 3>: 7FH; watchdog trigger bit located at address 3FH (CR1)

<WD bit pos 4>: C0H; watchdog trigger bit location is bit0

Device application registers (DAR)

The device application registers are all accessible using OpCode '00', '01' and '10'. The functions of these registers are defined in the device specification.

4.2.4

Protocol failure detection

To realize a protocol which covers certain failsafe requirements a basic set of failure detection mechanisms is implemented.

Clock monitor

During communication (CSN low to high phase) a clock monitor counts the valid SCK clock edges. If the SCK edges do not correlate with the SPI data length an SPIE is reported with the next command and the actual communication is rejected.

By accessing the device information registers (OpCode = '11') the clock monitor is set to a minimum of 16 SCK edges plus a multiple by 8 (for example 16, 25, 32, ...).

Providing no SCK edge during a CSN low to high phase is not recognized as a SPIE. For a SPI burst read also the SPI data length plus multiple numbers of payloads SCK edges are assumed as a valid communication.

SCK polarity (CPOL) check

To detect the wrong polarity access via SCK the internal clock monitor is used. Providing first a negative edge on SCK during communication (CSN low to high phase) or a positive edge at last leads to an SPI error reported in the next communication and the actual data is rejected.

SCK phase (CPHA) check

To verify, that the SCK Phase of the SPI master is set correctly a special device information register is implemented. By reading this register the data must be 55 H. In case AAH is read the CPHA setting of the SPI master is wrong and a proper communication cannot be guaranteed.

CSN timeout

By pulling CSN low the SDO is set active and leaves its tristate condition. To ensure communication between other SPI devices within the same bus even in case of CSN stuck at low a CSN timeout is implemented. By pulling CSN low an internal timer is started. After timer end is reached the actual communication is rejected and the SDO is set to tristate condition.

SDI stuck at GND

As a communication with data all '-0' and OpCode '00' on address b'000000 cannot be distinguished between a valid command and a SDI stuck at GND this communication is not allowed. Nevertheless, in case a stuck at GND is detected the communication is rejected and the SPIE is set with the next communication.

SDI stuck at HIGH

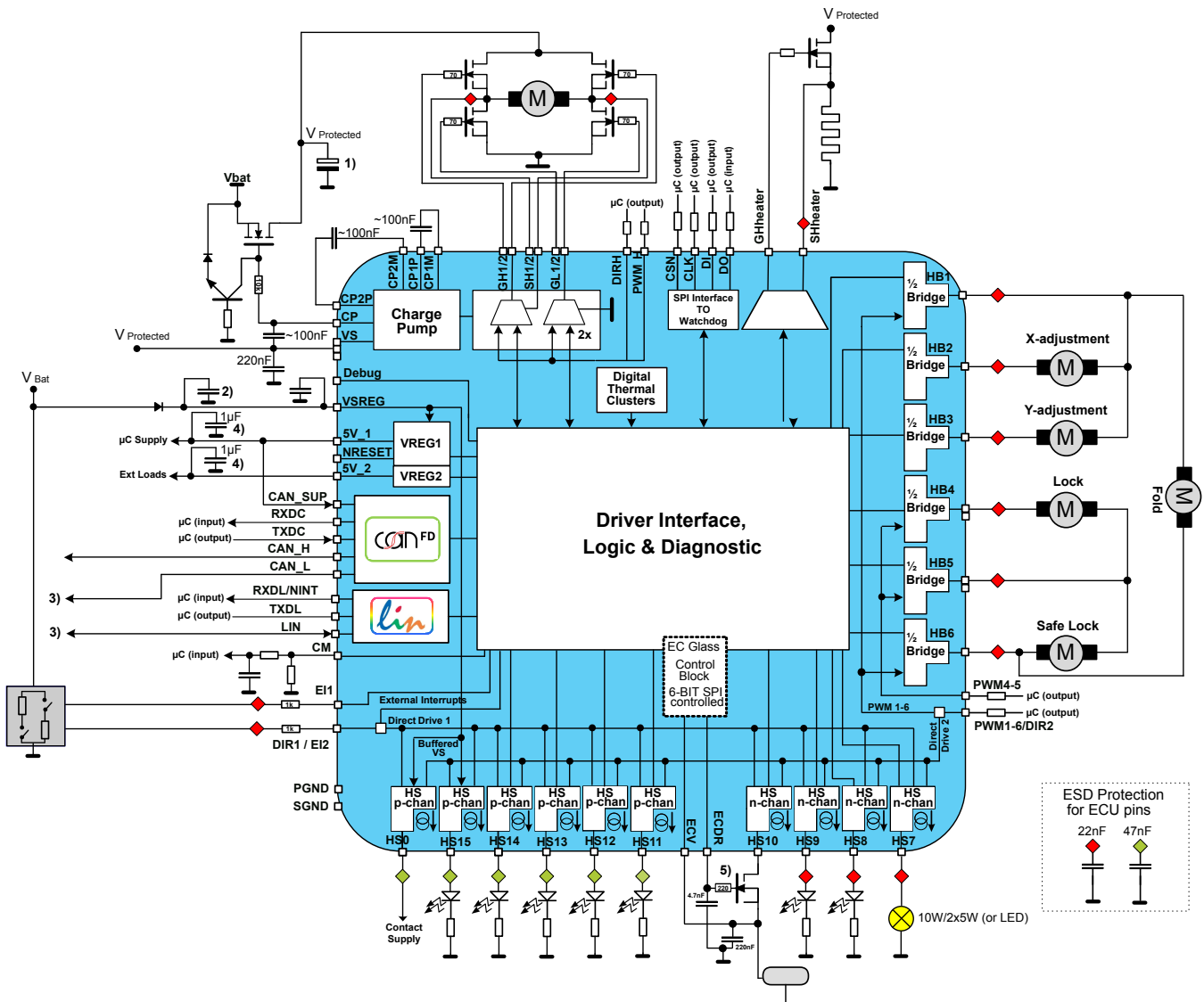
As a communication with data all '-1' and OpCode '11' on address b'111111 cannot be distinguished between a valid command and a SDI stuck at HIGH this communication is not allowed. In case a stuck at HIGH is detected the communication is rejected and the SPIE is set with the next communication.

SDO stuck at

The SDO stuck at GND and stuck at HIGH has to be detected by the SPI master. As the definition of the GSB guarantees at least one toggle, a GSB with all '-0' or all '-1' reports a stuck at error.

5 Application circuit

Figure 47. Application circuit



- 1) Capacitance to be dimensioned according to load current (rule of thumb 500 μ F each 10A)
- 2) Capacitance to be dimensioned e.g. according to voltage drop out requirements
- 3) OEM requirements and external components for LIN resp CAN to be fulfilled.
- 4) For EMC optimization purposes, capacitance could be redimensioned (2.2 μ F recommended)
- 5) Optional resistance may be needed for improving stability; value has to be selected according to external EC circuitry. A suitable range is between 120 .. 220 Ω

6 SPI Registers

6.1 Global status byte (GSB)

Table 75. Global status byte (GSB)

Global status byte (GSB)							
Bit 31	Bit 30	Bit 29	Bit 28	Bit 27	Bit 26	Bit 25	Bit 24
1 (R)	0 (R)	0 (R)	0 (R)	0 (R)	0 (R)	0 (R)	0 (R)
GSBN	RSTB	SPIE	PLE	FE	DE	GW	FS
Global status bit inverted	Reset	SPI error	Physical layer error (CAN,LIN)	Functional error	Device error	Global warning	Fail-safe

Table 76. Global status byte (GSB) description

Bit	Name	Description
31	GSBN	Global status bit inverted The GSBN is a logically NOR combination of GSB Bits 24 to Bit 30 ⁽¹⁾ . This bit can also be used as global status flag without starting a complete communication frame as it is present at SDO directly after pulling CSN low. 0 = error detected (1 or several GSB bits from 24 to 30 are set) 1 = no error detected (default after Power on)
30	RSTB	Reset The RSTB indicates a device reset and is set in case of the following events: SR8 (0x8) - VPOR - WDFAIL - V1UV (when UV is more than 16 µs) - FORCED_SLEEP_TSD2_V1SC 0 = no reset signal has been generated (default) 1 = Reset signal has been generated RSTB is cleared by a read & clear command to all bits in status register 8 causing the reset event.
29	SPIE ⁽²⁾	SPI error bit The SPIE indicates errors related to a wrong SPI communication. SR7 (0x7) - SPI_INV_CMD - SPI_SCK_CNT The bit is also set in case of an SPI CSN Time-out detection 0 = no error (default) 1 = error detected
28	PLE ⁽²⁾	Physical layer error The PLE is a logical OR combination of errors related to the LIN and CAN transceivers. SR7 (0x7): - LIN_PERM_DOM - LIN_TXD_DOM - LIN_PERM_REC - CAN_RXD_REC - CAN_PERM_REC - CAN_PERM_DOM

Bit	Name	Description
		CAN_TXD_DOM 0 = no error (default) 1 = error detected PLE is cleared by a read & clear command to all related bits in status registers 7.
27	FE	Functional error bit The FE is a logical OR combination of errors coming from functional blocks. SR7 (0x7): - V2SC - DSMONx SR6 (0x6): - HSx_OC (x = 0, 7, ..., 15) - HBx_LS_OC / HBx_HS_OC (x = 1, ..., 6) - ECV_OC - DSMON_HEAT SR5 (0x5)⁽³⁾: - HSx_OL (x = 0, 7, ..., 15) - HBx_LS_OL / HBx_HS_OL (x = 1, ..., 6) - ECV_OL - GH_OL 0 = no error (default) 1 = error detected FE is cleared by a read & clear command to all related bits in status registers 5, 6, 7
26	DE	Device error bit DE is a logical OR combination of global errors related to the device. SR8 (0x8): - TSD1 SR7 (0x7): - VS_OV - VS_UV - VSREG_OV - VSREG_UV - CP_LOW 0 = no error (default) 1 = error detected DE is cleared by a read and clear command to all related bits in status registers 7 and 8
25	GW ⁽²⁾	Global warning bit GW is a logical OR combination of warning flags. Warning bits do not lead to any device state change or switch OFF of functions. SR7 (0x7): - V1FAIL - V2FAIL - CAN_RXD_REC - TW⁽³⁾ - SPI_INV_CMD - SPI_SCK_CNT SR3 (0x3): - CAN_SUP_LOW 0 = no error (default) 1 = error detected GW is cleared by a read & clear command to all related bits in status registers 7 and 3.

Bit	Name	Description
24	FS	Fail-safe The FS bit indicates the device was forced into a safe state due to the following failure conditions: SR8 (0x8): • WDFAIL • V1UV(when UV is more than 2 ms) • TSD2 • FORCED_SLEEP_TSD2_V1SC SR3 (0x03): • SGNDLOSS All control registers are set to default Control registers are blocked for WRITE access except the following bits: CR18 (0x3F): • TRIG • CAN_ACT CR17 (0x3E): • Timer settings (bits 8...21) CR14 (0x3B): • HS15_x (bits 8...11) • HS0_x (bits 12...15) CR5 (0x32) to CR10 (0x37) • PWM frequency and duty cycles CR1 (0x26) • V2_0 • V2_1 0 = failsafe inactive (default) 1 = failsafe active FS is cleared upon exit from failsafe mode (refer to chapter Section 3.7: Fail-safe mode)

1. Individual failure flags may be masked in the CR1 (0x26).
2. Bit may be masked in the CR1 (0x26), that is the bit is not included in the global status bit (GSB).
3. The open-load status flags may be masked in the CR1 (0x26), that is the open-load flag is included in the FE flag but it does not set the GSB. TW failure status flags may be masked in the CR1 (0x26), that is the TW flag is included in the GW flag, but it does not set the GSB.

6.2 Control registers overview

Table 77. Global control registers

Bit								Mode
31	30	29	28	27	26	25	24	
GSBN	RSTB	SPIE	PLE	FE	DE	GW	FS	R

Table 78. Control registers overview

Addr./ DZ300 G	CR#	Bits	23	22	21	20	19	18	17	16	Mode
			15	14	13	12	11	10	9	8	
			7	6	5	4	3	2	1	0	
0x26	CR1	MSB	CAN_LOOP_EN	LIN_TXD_TOUT	LIN_WU_CONFIG	-	ECV_HV	DISABLE_CP_DITH	ICMP_CONFIG_EN	WD_CONFIG_EN	R/W
			MASK_OL_HS1	MASK_OL_LS1	MASK_TW	MASK_EC_OL	MASK_OL	MASK_SPIE	MASK_PLE	MASK_GW	
		LSB	CP_OFF_EN	-	-	CAN_AUTO_BIAS	DIR1_EN	V2_1	V2_0	TRIG	
0x27	CR2	MSB	-	-	-	-	-	-	-	-	R/W
			-	-	-	-	-	-	-	-	
		LSB	-	PWM1-6_1	PWM1-6_0	PWM4-5_1	PWM4-5_0	CP_OFF	ICMP	-	
0x2C	CR3	MSB	-	-	-	TSD_CLUSTER_EN	-	-	-	-	R/W
			-	-	HS0_CCM	-	-	-	-	HS15_CCM	
		LSB	HS14_CCM	HS13_CCM	HS12_CCM	HS11_CCM	HS10_CCM	HS9_CCM	HS8_CCM	HS7_CCM	
0x30	CR4	MSB	-	-	-	-	-	-	-	-	R/W
			-	-	-	-	HS7_OCR_TON_1	HS7_OCR_TON_0	HS_OCR_TON_1	HS_OCR_TON_0	
		LSB	HB_OCR_TON_1	HB_OCR_TON_0	HS7_OCR_FREQ_1	HS7_OCR_FREQ_0	HS_OCR_FREQ_1	HS_OCR_FREQ_0	HB_OCR_FREQ_1	HB_OCR_FREQ_0	
0x32	CR5	MSB	-	-	PWM9_DC_9	PWM9_DC_8	PWM9_DC_7	PWM9_DC_6	PWM9_DC_5	PWM9_DC_4	R/W
			PWM9_DC_3	PWM9_DC_2	PWM9_DC_1	PWM9_DC_0	-	-	PWM10_DC_9	PWM10_DC_8	
		LSB	PWM10_DC_7	PWM10_DC_6	PWM10_DC_5	PWM10_DC_4	PWM10_DC_3	PWM10_DC_2	PWM10_DC_1	PWM10_DC_0	
0x33	CR6	MSB	-	-	PWM7_DC_9	PWM7_DC_8	PWM7_DC_7	PWM7_DC_6	PWM7_DC_5	PWM7_DC_4	R/W
			PWM7_DC_3	PWM7_DC_2	PWM7_DC_1	PWM7_DC_0	-	-	PWM8_DC_9	PWM8_DC_8	





Addr./ DZ300 G	CR#	Bits	23	22	21	20	19	18	17	16	Mode
			15	14	13	12	11	10	9	8	
			7	6	5	4	3	2	1	0	
0x33	CR6	LSB	PWM8_DC_7	PWM8_DC_6	PWM8_DC_5	PWM8_DC_4	PWM8_DC_3	PWM8_DC_2	PWM8_DC_1	PWM8_DC_0	R/W
0x34	CR7	MSB	-	-	PWM5_DC_9	PWM5_DC_8	PWM5_DC_7	PWM5_DC_6	PWM5_DC_5	PWM5_DC_4	R/W
			PWM5_DC_3	PWM5_DC_2	PWM5_DC_1	PWM5_DC_0	-	-	PWM6_DC_9	PWM6_DC_8	
		LSB	PWM6_DC_7	PWM6_DC_6	PWM6_DC_5	PWM6_DC_4	PWM6_DC_3	PWM6_DC_2	PWM6_DC_1	PWM6_DC_0	
0x35	CR8	MSB	-	-	PWM3_DC_9	PWM3_DC_8	PWM3_DC_7	PWM3_DC_6	PWM3_DC_5	PWM3_DC_4	R/W
			PWM3_DC_3	PWM3_DC_2	PWM3_DC_1	PWM3_DC_0	-	-	PWM4_DC_9	PWM4_DC_8	
		LSB	PWM4_DC_7	PWM4_DC_6	PWM4_DC_5	PWM4_DC_4	PWM4_DC_3	PWM4_DC_2	PWM4_DC_1	PWM4_DC_0	
0x36	CR9	MSB	-	-	PWM1_DC_9	PWM1_DC_8	PWM1_DC_7	PWM1_DC_6	PWM1_DC_5	PWM1_DC_4	R/W
			PWM1_DC_3	PWM1_DC_2	PWM1_DC_1	PWM1_DC_0	-	-	PWM2_DC_9	PWM2_DC_8	
		LSB	PWM2_DC_7	PWM2_DC_6	PWM2_DC_5	PWM2_DC_4	PWM2_DC_3	PWM2_DC_2	PWM2_DC_1	PWM2_DC_0	
0x37	CR10	MSB	-	-	-	-	-	-	-	-	R/W
			-	-	-	-	-	-	PWM10_FREQ	PWM9_FREQ	
		LSB	PWM8_FREQ	PWM7_FREQ	PWM6_FREQ	PWM5_FREQ	PWM4_FREQ	PWM3_FREQ	PWM2_FREQ	PWM1_FREQ	
0x38	CR11	MSB	-	-	-	-	-	-	-	-	R/W
			-	-	ECV_LS	ECV_OCR	-	-	-	ECON	
		LSB	-	-	EC_5	EC_4	EC_3	EC_2	EC_1	EC_0	
0x39	CR12	MSB	-	DIAG_1	DIAG_0	GH_OL_EN	GH	GH_TH_3	GH_TH_2	GH_TH_1	R/W
			GH_TH_0	SD	SDS	DM	COPT_3	COPT_2	COPT_1	COPT_0	
		LSB	H_OLTH_HIGH	OL_H1L2	OL_H2L1	SLEW_4	SLEW_3	SLEW_2	SLEW_1	SLEW_0	
0x3A	CR13	MSB	HS7_RDSON	-	-	-	-	-	HS10_OCR	HS9_OCR	R/W
			HS8_OCR	HS7_OCR	HB6_OCR	HB5_OCR	HB4_OCR	HB3_OCR	HB2_OCR	HB1_OCR	
		LSB	-	-	CM	CM_SEL_4	CM_SEL_3	CM_SEL_2	CM_SEL_1	CM_SEL_0	
0x3B	CR14	MSB	-	-	-	-	-	-	-	-	R/W
			HS0_3	HS0_2	HS0_1	HS0_0	HS15_3	HS15_2	HS15_1	HS15_0	
		LSB	HS14_3	HS14_2	HS14_1	HS14_0	HS13_3	HS13_2	HS13_1	HS13_0	
0x3C	CR15	MSB	HS12_3	HS12_2	HS12_1	HS12_0	HS11_3	HS11_2	HS11_1	HS11_0	R/W
			HS10_3	HS10_2	HS10_1	HS10_0	HS9_3	HS9_2	HS9_1	HS9_0	
		LSB	HS8_3	HS8_2	HS8_1	HS8_0	HS7_3	HS7_2	HS7_1	HS7_0	



Addr./ DZ300 G	CR#	Bits	23	22	21	20	19	18	17	16	Mode
			15	14	13	12	11	10	9	8	
			7	6	5	4	3	2	1	0	
0x3D	CR16	MSB	VSREG_LOCK_ENA	VS_LOCK_ENA	VSREG_OV_SD_ENA	VSREG_UV_SD_ENA	VS_OV_SD_ENA	VS_UV_SD_ENA	HB6OCTH_1	HB6OCTH_0	R/W
			HB5OCTH_1	HB5OCTH_0	HB1OCTH_1	HB1OCTH_0	HB6_HS	HB6_LS	HB5_HS	HB5_LS	
		LSB	HB4_HS	HB4_LS	HB3_HS	HB3_LS	HB2_HS	HB2_LS	HB1_HS	HB1_LS	
0x3E	CR17	MSB	-	-	T2_ON_2	T2_ON_1	T2_ON_0	T2_PER_2	T2_PER_1	T2_PER_0	R/W
			-	-	T1_ON_2	T1_ON_1	T1_ON_0	T1_PER_2	T1_PER_1	T1_PER_0	
		LSB	V1_RESET_1	V1_RESET_0	-	WD_TIME	-	-	STBY_SEL	GO_STBY	
0x3F	CR18	MSB	EI2_PU	-	-	EI1_PU	EI2_EN	-	-	EI1_EN	R/W
			EI2_FILT_1	EI2_FILT_0	-	-	-	-	EI1_FILT_1	EI1_FILT_0	
		LSB	HEN	CAN_REC_ONLY	CAN_ACT	LIN_WU_EN	CAN_WU_EN	TIMER_NINT_WAKE_SEL	TIMER_NINT_EN	TRIG	

6.3 Status register overview

Table 79. Global status registers

Bit								Mode
31	30	29	28	27	26	25	24	
GSBN	RSTB	SPIE	PLE	FE	DE	GW	FS	R

Table 80. Status registers overview

Addr./ DZ300 G	CR#	Bits	23	22	21	20	19	18	17	16	Mode
			15	14	13	12	11	10	9	8	
			7	6	5	4	3	2	1	0	
0x01	SR1	MSB	TW_CL8	TW_CL7	TW_CL6	TW_CL5	TW_CL4	TW_CL3	TW_CL2	TW_CL1	R
			-	-	HB6_LS_SC	HB5_LS_SC	HB4_LS_SC	HB3_LS_SC	HB2_LS_SC	HB1_LS_SC	
		LSB	-	-	-	-	-	-	-	-	
0x02	SR2	MSB	TSD1_CL8	TSD1_CL7	TSD1_CL6	TSD1_CL5	TSD1_CL4	TSD1_CL3	TSD1_CL2	TSD1_CL1	R
			-	-	HB6_HS_SC	HB5_HS_SC	HB4_HS_SC	HB3_HS_SC	HB2_HS_SC	HB1_HS_SC	
		LSB	-	-	-	-	-	-	-	-	
0x03	SR3	MSB	-	-	-	-	-	-	-	-	R
			-	-	-	-	-	-	-	-	
		LSB	-	-	SGNDLOSS	IP_SUP_LOW	CAN_SUP_LOW	-	-	-	
0x04	SR4	MSB	WD_TIMER_ST ATE_1	WD_TIMER_ST ATE_0	EI2_STATE	-	-	EI1_STATE	ECV_VNR	ECV_VHI	R
			-	-	-	-	-	-	-	-	
		LSB	-	-	-	-	-	-	-	-	
0x05	SR5	MSB	ECV_OL	GH_OL	HS0_OL	HS15_OL	HS14_OL	HS13_OL	HS12_OL	HS11_OL	R
			HS10_OL	HS9_OL	HS8_OL	HS7_OL	HB6_LS_OL	HB6_HS_OL	HB5_LS_OL	HB5_HS_OL	
		LSB	HB4_LS_OL	HB4_HS_OL	HB3_LS_OL	HB3_HS_OL	HB2_LS_OL	HB2_HS_OL	HB1_LS_OL	HB1_HS_OL	
0x06	SR6	MSB	ECV_OC	DSMON_HEAT	HS0_OC	HS15_OC	HS14_OC	HS13_OC	HS12_OC	HS11_OC	R
			HS10_OC	HS9_OC	HS8_OC	HS7_OC	HB6_LS_OC	HB6_HS_OC	HB5_LS_OC	HB5_HS_OC	
		LSB	HB4_LS_OC	HB4_HS_OC	HB3_LS_OC	HB3_HS_OC	HB2_LS_OC	HB2_HS_OC	HB1_LS_OC	HB1_HS_OC	
0x07	SR7	MSB	LIN_PERM_DOM M	LIN_TXD_DOM	LIN_PERM_REC	CAN_RXD_REC	CAN_PERM_RE C	CAN_PERM_DOM M	CAN_TXD_DOM	CANTO	R





Addr./ DZ300 G	CR#	Bits	23	22	21	20	19	18	17	16	Mode
			15	14	13	12	11	10	9	8	
			7	6	5	4	3	2	1	0	
0x07	SR7		DSMON_HS2	DSMON_HS1	DSMON_LS2	DSMON_LS1	SPI_INV_CMD	SPI_SCK_CNT	CP_LOW	TW	R
		LSB	V2SC	V2FAIL	V1FAIL	-	VSREG_OV	VSREG_UV	VS_OV	VS_UV	
0x08	SR8	MSB	EI2_WAKE	-	-	EI1_WAKE	WAKE_CAN	WAKE_LIN	WAKE_TIMER	DEBUG_ACTIVE	R
			V1UV	V1_RESTART_2	V1_RESTART_1	V1_RESTART_0	WDFAIL_CNT_3	WDFAIL_CNT_2	WDFAIL_CNT_1	WDFAIL_CNT_0	
		LSB	DEVICE_STATE_1	DEVICE_STATE_0	TSD2	TSD1	FORCED_SLEEP_TSD2_V1SC	FORCED_SLEEP_WD	WDFAIL	VPOR	

6.4 Control registers

6.4.1 Control register 1 (CR1, 0x26)

Table 81. Control register 1

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	CAN_LOOP_EN	LIN_TXD_TOUT	LIN_WU_CONFIG	RESERVED	ECV_HV	DISABLE_CP_DITH	ICMP_CONFIG_EN	WD_CONFIG_EN	MASK_OL_HS1	MASK_OL_LS1	MASK_TW	MASK_EC_OL	MASK_OL	MASK_SPIE	MASK_PLE	MASK_GW	CP_OFF_EN	RESERVED	RESERVED	CAN_AUTO_BIAS	DIR1_EN	V2_1	V2_0	TRIG
Reset value	0	1							0								1		0		1		0	
Access	RW			R	RW															R		RW		

Table 82. CR1 signals description

Bit	Name	Description
23	CAN_LOOP_EN	CAN looping of TXDC to RXDC 0: CAN looping disabled (default) 1: CAN looping enabled
22	LIN_TXD_TOUT	LIN TXD timeout detection 0: LIN TXD timeout detection disabled 1: LIN TXD timeout detection enabled (default)
21	LIN_WU_CONFIG	Configuration of LIN wake-up behavior 0: wake-up at recessive-dominant-recessive with $t_{dom} > 28 \mu s$ (default) (according to LIN 2.2a and hardware requirements for transceivers version 1.3) 1: wake-up at recessive-dominant transition
20	RESERVED	-
19	ECV_HV	Electro chrome controller voltage 0: electro chrome controller voltage set to minimum value (default) 1: electro chrome controller voltage set to maximum value
18	DISABLE_CP_DITH	Charge pump dithering 0: charge pump dithering enabled (default) 1: charge pump dithering disabled
17	ICMP_CONFIG_EN	ICMP configuration enable 0: writing ICMP = 1 is blocked (writing ICMP = 0 is possible); (default) 1: writing ICMP = 1 is possible with next SPI command bit is automatically reset to 0 after next SPI command
16	WD_CONFIG_EN	Watchdog configuration enable 0: writing to WD configuration (CR17 [0:1]) is blocked (default) 1: writing to WD configuration bits is possible with next SPI command bit is automatically reset to 0 after next SPI command
15	MASK_OL_HS1	0: open-load condition at HS1 (half bridge HB1) is not masked (default) 1: open-load condition at HS1 (half bridge HB1) is masked that is reported as a functional error (GSB bit 27) but not as a global error (GSB bit 31)
14	MASK_OL_LS1	0: open-load condition at LS1 (half bridge HB1) is not masked (default)

Bit	Name	Description
		1: open load condition at LS1 (half bridge HB1) is masked that is reported as a functional error (GSB bit 27) but not as a global error (GSB bit 31)
13	MASK_TW	0: thermal warning is not masked (default) 1: thermal warning is masked that is reported as a global warning (GSB bit 25) but not as a global error (GSB bit 31)
12	MASK_EC_OL	0: open-load condition at ECV is not masked (default) 1: open-load condition at ECV is masked that is reported as a functional error (GSB bit 27), but not as a global error (GSB bit 31) ⁽¹⁾
11	MASK_OL	0: open-load condition at all outputs are not masked (default) 1: open-load condition at all outputs are masked except HB1 (see bit 14,15 CR1 for HB1) that is reported as a functional error (GSB bit 27), but not as a global error (GSB bit 31)
10	MASK_SPIE	0: SPI errors are not masked (default) 1: SPI errors are masked that are reported as an SPI error (GSB bit 29) but not as a global error (GSB bit 31)
9	MASK_PLE	0: physical layer errors are not masked (default) 1: physical layer errors are masked that are reported as a physical layer error (GSB bit 28) but not as a global error (GSB bit 31)
8	MASK_GW	0: global warning conditions are not masked (default) 1: global warning conditions are masked that are reported as a global warning (GSB bit 25) but not as a global error (GSB bit 31)
7	CP_OFF_EN	Charge pump OFF enable 0: writing CP_OFF = 1 is blocked (writing CP_OFF = 0 is possible) 1: writing CP_OFF = 1 is possible (default)
6	RESERVED	-
5	RESERVED	-
4	CAN_AUTO_BIAS	CAN automatic biasing activation 0: auto biasing disabled (default) 1: auto biasing enabled
3	DIR1_EN	Enable DIR1 input or EI2 0: EI2 configured as wake-up input 1: DIR1 function enabled (default)
2	V2_1	Voltage regulator V2 configuration 00: V2 OFF in all modes (default)
1	V2_0	01: V2 ON in active mode; V2 OFF in standby modes 10: V2 ON in active and V1_Standby mode; V2 OFF in VBAT_Standby mode 11: V2 ON in active and V1_Standby mode; V2 OFF in VBAT_Standby mode
0	TRIG	Watchdog trigger bit

1. Open-load condition at HS10 can be masked by writing MASK_OL = 1.

6.4.2 Control register 2 (CR2, 0x27)

Table 83. Control register 2

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	PWM1-6_1	PWM1-6_0	PWM4-5_1	PWM4-5_0	CP_OFF	ICMP	RESERVED
Reset value	0																							
Access	R																	RW				R		

Table 84. CR2 signals description

Bit	Name	Description
23:7	RESERVED	-
6	PWM1-6_1	PWM control for HB1 and HB6
5	PWM1-6_0	PWM1-6/DIR2 control 00: PWM1-6 disabled, DIR2 function enabled (default) 01: PWM1-6 applied to HB1 LS 10: PWM1-6 applied to HB6 LS 11: PWM1-6 applied to both HB1 and HB6 low-sides at the same time
4	PWM4-5_1	PWM control for HB4 and HB5
3	PWM4-5_0	PWM4-5 control 00: OFF, PWM4-5 not applied (default) 01: PWM4-5 applied to HB4 LS 10: PWM4-5 applied to HB5 LS 11: PWM4-5 applied to both HB4 and HB5 low-sides at the same time
2	CP_OFF	Switch OFF the charge pump 0: charge pump ON (default) 1: charge pump OFF <i>Note: Setting CP_OFF = 1 is possible only if CP_OFF_EN is set to "1" in CR1.</i>
1	ICMP	V1 load current supervision 0: enabled; watchdog is disabled in V1_Standby when IV1 < ICMP (default) 1: disabled; watchdog is disabled upon transition into V1_Standby mode <i>Note: Setting ICMP = 1 is only possible when ICMP_CONFIG_EN = 1 in CR1.</i>
0	RESERVED	-

6.4.3 Control register 3 (CR3, 0x2C)

Table 85. Control register 3

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	RESERVED	RESERVED	RESERVED	TSD_CLUSTER_EN	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	HS0_CCM	RESERVED	RESERVED	RESERVED	RESERVED	HS15_CCM	HS14_CCM	HS13_CCM	HS12_CCM	HS11_CCM	HS10_CCM	HS9_CCM	HS8_CCM	HS7_CCM
Reset value	0																							
Access	R		RW	R						RW	R					RW								

Table 86. CR3 signals description

Bit	Name	Description
23:21	RESERVED	-
20	TSD_CLUSTER_EN	Enables thermal warning and shutdown of outputs by cluster 0: TSD and TW by cluster OFF (default) 1: TSD and TW by cluster ON
19:14	RESERVED	-
13	HS0_CCM	Constant current mode on HS0 enable ⁽¹⁾ 0: disabled (default) 1: enabled
12:9	RESERVED	-
8	HS15_CCM	Constant current mode on HS15 enable ⁽¹⁾ 0: disabled (default) 1: enabled
7	HS14_CCM	Constant current mode on HS14 enable ⁽¹⁾ 0: disabled (default) 1: enabled
6	HS13_CCM	Constant current mode on HS13 enable ⁽¹⁾ 0: disabled (default) 1: enabled
5	HS12_CCM	Constant current mode on HS12 enable ⁽¹⁾ 0: disabled (default) 1: enabled
4	HS11_CCM	Constant current mode on HS11 enable ⁽¹⁾ 0: disabled (default) 1: enabled
3	HS10_CCM	Constant current mode on HS10 enable ⁽¹⁾ 0: disabled (default) 1: enabled
2	HS9_CCM	Constant current mode on HS9 enable ⁽¹⁾ 0: disabled (default) 1: enabled
1	HS8_CCM	Constant current mode on HS8 enable ⁽¹⁾

Bit	Name	Description
		0: disabled (default) 1: enabled
0	HS7_CCM	Constant current mode on HS7 enable ⁽¹⁾ 0: disabled (default) 1: enabled

1. Refer to [Section 3.14: Power outputs HB1,..., HB6, HS7,..., HS15, HS0](#) for the correct sequence of constant current mode activation.

6.4.4 Control register 4 (CR4, 0x30)

Table 87. Control register 4

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	
Bit name	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	HS7_OCR_TON_1	HS7_OCR_TON_0	HS_OCR_TON_1	HS_OCR_TON_0	HB_OCR_TON_1	HB_OCR_TON_0	HS7_OCR_FREQ_1	HS7_OCR_FREQ_0	HS_OCR_FREQ_1	HS_OCR_FREQ_0	HB_OCR_FREQ_1	HB_OCR_FREQ_0	
Reset value	0													1	0	1	0	1	0						
Access	R												RW												

Table 88. CR4 signals description

Bit	Name	Description
23:12	RESERVED	-
11	HS7_OCR_TON_1	Overcurrent recovery programmable ON time for HS7 ON time also includes the blanking time t_{BLK}
10	HS7_OCR_TON_0	00: ON time = 88 μ s 01: ON time = 80 μ s (default) 10: ON time = 72 μ s 11: ON time = 64 μ s
9	HS_OCR_TON_1	Overcurrent recovery programmable ON time for HS8, HS9, HS10 and electro chrome ON time also includes the blanking time t_{BLK}
8	HS_OCR_TON_0	00: ON time = 88 μ s 01: ON time = 80 μ s (default) 10: ON time = 72 μ s 11: ON time = 64 μ s
7	HB_OCR_TON_1	Overcurrent recovery programmable ON time for HB1, HB2, HB3, HB4, HB5, HB6 ON time also includes the blanking time t_{BLK}
6	HB_OCR_TON_0	00: ON time = 88 μ s 01: ON time = 80 μ s (default) 10: ON time = 72 μ s 11: ON time = 64 μ s
5	HS7_OCR_FREQ_1	Overcurrent recovery programmable frequency for HS7
4	HS7_OCR_FREQ_0	00: frequency = 1.7 kHz (default) 01: frequency = 2.2 kHz 10: frequency = 3.0 kHz

Bit	Name	Description
		11: frequency = 4.4 kHz
3	HS_OCR_FREQ_1	Overcurrent recovery programmable frequency for HS8, HS9, HS10 and electro chrome
2	HS_OCR_FREQ_0	00: frequency = 1.7 kHz (default) 01: frequency = 2.2 kHz 10: frequency = 3.0 kHz 11: frequency = 4.4 kHz
1	HB_OCR_FREQ_1	Overcurrent recovery programmable frequency for HB1, HB2, HB3, HB4, HB5, HB6
0	HB_OCR_FREQ_0	00: frequency = 1.7 kHz (default) 01: frequency = 2.2 kHz 10: frequency = 3.0 kHz 11: frequency = 4.4 kHz

6.4.5 Control register 5-9 (from CR5 to CR9, [0x32, 0x36])

Table 89. Control register 5-9

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	RESERVED	RESERVED	PWMx_DC_9	PWMx_DC_8	PWMx_DC_7	PWMx_DC_6	PWMx_DC_5	PWMx_DC_4	PWMx_DC_3	PWMx_DC_2	PWMx_DC_1	PWMx_DC_0	RESERVED	RESERVED	PWMx_DC_9	PWMx_DC_8	PWMx_DC_7	PWMx_DC_6	PWMx_DC_5	PWMx_DC_4	PWMx_DC_3	PWMx_DC_2	PWMx_DC_1	PWMx_DC_0
Reset value	0																							
Access	R		RW										R		RW									

Table 90. From CR5 to CR9 signals description

Bit	Name	Description
23:22	RESERVED	-
21	PWMx_DC_9	Binary coded on duty cycle of PWM channel PWMx (x = 9, 7, 5, 3, 1) (see Table 91. Duty cycle coding for channel PWMx(y))
20	PWMx_DC_8	
19	PWMx_DC_7	
18	PWMx_DC_6	
17	PWMx_DC_5	
16	PWMx_DC_4	Binary coded on duty cycle of PWM channel PWMx (x = 9, 7, 5, 3, 1) (see Table 91. Duty cycle coding for channel PWMx(y))
15	PWMx_DC_3	
14	PWMx_DC_2	
13	PWMx_DC_1	
12	PWMx_DC_0	
11:10	RESERVED	-
9	PWMx_DC_9	Binary coded on duty cycle of PWM channel PWMx (y = x + 1) (see Table 91. Duty cycle coding for channel PWMx(y))
8	PWMx_DC_8	
7	PWMx_DC_7	Binary coded on duty cycle of PWM channel PWMx (y = x + 1) (see Table 91. Duty cycle coding for channel PWMx(y))
6	PWMx_DC_6	
5	PWMx_DC_5	
4	PWMx_DC_4	
3	PWMx_DC_3	
2	PWMx_DC_2	
1	PWMx_DC_1	
0	PWMx_DC_0	

Table 91. Duty cycle coding for channel PWMx(y)

PWMx(y)_DC_10	PWMx(y)_DC_9	PWMx(y)_DC_8	PWMx(y)_DC_7	PWMx(y)_DC_6	PWMx(y)_DC_5	PWMx(y)_DC_4	PWMx(y)_DC_3	PWMx(y)_DC_2	PWMx(y)_DC_9	Duty cycle %
0	0	0	0	0	0	0	0	0	0	OFF
0	0	0	0	0	0	0	0	0	1	1*100/1024
0	0	0	0	0	0	0	0	1	0	2*100/1024
										...
1	1	1	1	1	1	1	1	0	1	1021*100/1024
1	1	1	1	1	1	1	1	1	0	1022*100/1024
1	1	1	1	1	1	1	1	1	1	1023*100/1024

Note: To have a duty cycle equal to 100%, the output configuration shall be set in ON mode.

6.4.6 Control register 10 (0x37)

Table 92. Control register 10

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	PWM10_FREQ	PWM9_FREQ	PWM8_FREQ	PWM7_FREQ	PWM6_FREQ	PWM5_FREQ	PWM4_FREQ	PWM3_FREQ	PWM2_FREQ	PWM1_FREQ
Reset value	0																							
Access	R												RW											

Table 93. CR10 signals description

Bit	Name	Description
23:10	RESERVED	-
9	PWM10_FREQ	Select PWM10 frequency 0: $f_{PWM1} = 100$ Hz (default) 1: $f_{PWM2} = 200$ Hz
8	PWM9_FREQ	Select PWM9 frequency 0: $f_{PWM1} = 100$ Hz (default) 1: $f_{PWM2} = 200$ Hz
7	PWM8_FREQ	Select PWM8 frequency 0: $f_{PWM1} = 100$ Hz (default) 1: $f_{PWM2} = 200$ Hz
6	PWM7_FREQ	Select PWM7 frequency 0: $f_{PWM1} = 100$ Hz (default) 1: $f_{PWM2} = 200$ Hz

Bit	Name	Description
5	PWM6_FREQ	Select PWM6 frequency 0: $f_{PWM1} = 100$ Hz (default) 1: $f_{PWM2} = 200$ Hz
4	PWM5_FREQ	Select PWM5 frequency 0: $f_{PWM1} = 100$ Hz (default) 1: $f_{PWM2} = 200$ Hz
3	PWM4_FREQ	Select PWM4 frequency 0: $f_{PWM1} = 100$ Hz (default) 1: $f_{PWM2} = 200$ Hz
2	PWM3_FREQ	Select PWM3 frequency 0: $f_{PWM1} = 100$ Hz (default) 1: $f_{PWM2} = 200$ Hz
1	PWM2_FREQ	Select PWM2 frequency 0: $f_{PWM1} = 100$ Hz (default) 1: $f_{PWM2} = 200$ Hz
0	PWM1_FREQ	Select PWM1 frequency 0: $f_{PWM1} = 100$ Hz (default) 1: $f_{PWM2} = 200$ Hz

6.4.7 Control register 11 (0x38)

Table 94. Control register 11

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	ECV_LS	ECV_OCR	RESERVED	RESERVED	RESERVED	ECON	RESERVED	RESERVED	EC_5	EC_4	EC_3	EC_2	EC_1	EC_0
Reset value	0																							
Access	R										RW		R		RW		R				RW			

Table 95. CR11 signals description

Bit	Name	Description
23:14	RESERVED	-
13	ECV_LS	Control of ECV low-side switch 0: ECV low-side switch OFF (default) 1: ECV low-side switch ON
12	ECV_OCR	Overcurrent recovery for output ECV 0: overcurrent recovery is turned OFF (default) 1: overcurrent recovery is turned ON
11:9	RESERVED	-

Bit	Name	Description
8	ECON	Electro chrome control; the electro chrome control enables the driver at pin ECDR and switches HS10 directly ON ignoring the control bits HS10_x (x = 3, 2, 1, 0) in CR15 0: electro chrome control OFF (default) 1: electro chrome control ON
7:6	RESERVED	-
5	EC_5	000000: voltage value is 0 V (default)
4	EC_4	000001: voltage value is 1/63*1.5 V
3	EC_3	000010: voltage value is 2/63*1.5 V
2	EC_2	...
1	EC_1	111110: voltage value is 62/63*1.5 V
0	EC_0	111111: voltage value is 1.5 V

Note: The reference voltage for the electro chrome voltage controller at pin ECV is binary coded. If the ECV_HV bit (CR1) is "0" all codes higher than 110011 are clamped to reach 1.2 V max on ECV pin.

6.4.8 Control register 12 (0x39)

Table 96. Control register 12

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	RESERVED	DIAG_1	DIAG_0	GH_OL_EN	GH	GH_TH_3	GH_TH_2	GH_TH_1	GH_TH_0	SD	SDS	DM	COPT_3	COPT_2	COPT_1	COPT_0	H_OLTH_HIGH	OL_H1L2	OL_H2L1	SLEW_4	SLEW_3	SLEW_2	SLEW_1	SLEW_0
Reset value	0	1		0	1	0		1		0			1							0				
Access	R																							

Table 97. CR12 signals description

Bit	Name	Description
23	RESERVED	-
22	DIAG_1	Drain-source monitoring threshold for external H-bridge
21	DIAG_1	Monitoring threshold voltage 00 V _{SCd1} 01 V _{SCd2} 10 V _{SCd3} 11 V _{SCd4} (default)
20	GH_OL_EN ⁽¹⁾	Control open-load diagnosis for gate heater output 0: open-load diagnosis OFF (default) 1: open-load diagnosis ON
19	GH	Gate heater enable 0: gate heater disabled (default) 1: gate heater enabled
18	GH_TH_3	Drain-source monitoring threshold voltage for external heater Power MOSFET. Invalid setting is ignored; SPI error bit (SPIE) in global status register is set

Bit	Name	Description
17	GH_TH_2	0000 V _{SCd1}
16	GH_TH_1	0001 V _{SCd2}
15	GH_TH_0	0010 V _{SCd3} 0011 V _{SCd4} 0100 V _{SCd5} 0101 V _{SCd6} 0110 V _{SCd7} 0111 V _{SCd8} 1000 V _{SCd9} 1001 V _{SCd10} (default) 1010 invalid configuration ... 1111 invalid configuration
14	SD	Slow decay 0: slow decay mode low-side ON (default, LS1 or LS2 depending only on DIRH pin) 1: slow decay mode high-side ON (HS1 or HS2 depending only on DIRH pin)
13	SDS	Slow decay single 0: slow decay mode both legs ON (default) 1: slow decay mode single leg ON
12	DM	Dual motor H-bridge configuration 0: single motor mode (default) 1: dual motor mode
11	COPT_3	Cross current protection time ⁽²⁾ 0010 tccp ₀₀₁₀ 0011 tccp ₀₀₁₁ 0100 tccp ₀₁₀₀ 0101 tccp ₀₁₀₁ 0110 tccp ₀₁₁₀ 0111 tccp ₀₁₁₁ 1000 tccp ₁₀₀₀ 1001 tccp ₁₀₀₁ 1010 tccp ₁₀₁₀ 1011 tccp ₁₀₁₁ 1100 tccp ₁₁₀₀ 1101 tccp ₁₁₀₁ 1110 tccp ₁₁₁₀ 1111 tccp ₁₁₁₁ (default)
10	COPT_2	
9	COPT_1	
8	COPT_0	
7	H_OLTH_HIGH	H-bridge OL high threshold (5/6 * V _S) select 0: V _{SCd} threshold low (default, 1/6 * V _S) 1: V _{SCd} threshold high (5/6 * V _S)
6	OL_H1L2 ⁽³⁾	Test open-load condition between H1 and L2 0: no pull-up on H1 (default, no test on H1 L2) 1: pull-up resistor on H1 (test on H1 L2)

Bit	Name	Description
5	OL_H2L1 ⁽³⁾	Test open-load condition between H2 and L1 0: no pull-up on H2 (default, no test on H1 L2) 1: pull-up resistor on H2 (test on H2 L1)
4	SLEW_4	Binary coded slew rate of the H-bridge Slew rate value 00000: control disabled (default) 00001: 1/31 00010: 2/31 ... 11110: 30/31 11111: 1
3	SLEW_3	
2	SLEW_2	
1	SLEW_1	
0	SLEW_0	

1. Before going to standby mode, GH_OL_EN must be set to 0 to achieve the specified current consumption.
2. t_{ccp} values "0000" and "0001" are not allowed.
3. Before going to standby mode, OL_H1L2 and OL_H2L1 must be set to 0 to achieve the specified current consumption.

6.4.9 Control register 13 (0x3A)

Table 98. Control register 13

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	HS7_RDSON	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	HS10_OCR	HS9_OCR	HS8_OCR	HS7_OCR	HB6_OCR	HB5_OCR	HB4_OCR	HB3_OCR	HB2_OCR	HB1_OCR	RESERVED	RESERVED	CM	CM_SEL_4	CM_SEL_3	CM_SEL_2	CM_SEL_1	CM_SEL_0
Reset value	0																		1	0				
Access	RW	R					RW										R		RW					

Table 99. CR13 signals description

Bit	Name	Description
23	HS7_RDSON	Select R_{dson} for HS7 0 r_{ON1} (0.3 Ω) (default) 1 r_{ON2} (1.6 Ω)
22:18	RESERVED	-
17	HS10_OCR	Overcurrent recovery for HS10 0 overcurrent recovery is turned OFF (default) 1 overcurrent recovery is turned ON
16	HS9_OCR	Overcurrent recovery for HS9 0 overcurrent recovery is turned OFF (default) 1 overcurrent recovery is turned ON
15	HS8_OCR	Overcurrent recovery for HS8 0 overcurrent recovery is turned OFF (default) 1 overcurrent recovery is turned ON
14	HS7_OCR	Overcurrent recovery for HS7 0 overcurrent recovery is turned OFF (default)

Bit	Name	Description
		1 overcurrent recovery is turned ON
13	HB6_OCR	Overcurrent recovery for HB6 0 overcurrent recovery is turned OFF (default) 1 overcurrent recovery is turned ON
12	HB5_OCR	Overcurrent recovery for HB5 0 overcurrent recovery is turned OFF (default) 1 overcurrent recovery is turned ON
11	HB4_OCR	Overcurrent recovery for HB4 0 overcurrent recovery is turned OFF (default) 1 overcurrent recovery is turned ON
10	HB3_OCR	Overcurrent recovery for HB3 0 overcurrent recovery is turned OFF (default) 1 overcurrent recovery is turned ON
9	HB2_OCR	Overcurrent recovery for HB2 0 overcurrent recovery is turned OFF (default) 1 overcurrent recovery is turned ON
8	HB1_OCR	Overcurrent recovery for HB1 0 overcurrent recovery is turned OFF (default) 1 overcurrent recovery is turned ON
7:6	RESERVED	-
5	CM	Current monitor 0 OFF (tristate) 1 ON (default)
4	CM_SEL_4	A current image of the selected binary coded output is multiplexed to the CM output. If a corresponding output does not exist, the current monitor is deactivated. Selected output 00000 tristate (default) 00001 HB1 00010 HB2 00011 HB3 00100 HB4 00101 HB5 00110 HB6 00111 HS7 01000 HS8 01001 HS9 01010 HS10 01011 HS11 01100 HS12 01101 HS13 01110 HS14 01111 HS15 10000 HS0 10001 tristate tristate
3	CM_SEL_3	
2	CM_SEL_2	
1	CM_SEL_1	
0	CM_SEL_0	

Bit	Name	Description
		11111 tristate

6.4.10 Control register 14 (0x3B)

Table 100. Control register 14

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	HS0_3	HS0_2	HS0_1	HS0_0	HS15_3	HS15_2	HS15_1	HS15_0	HS14_3	HS14_2	HS14_1	HS14_0	HS13_3	HS13_2	HS13_1	HS13_0
Reset value	0																							
Access	R												RW											

Table 101. CR14 signals description

Bit	Name	Description
23:16	RESERVED	-
15	HS0_3	High-side driver HS0 configuration HS0 config 0000: OFF (default) 0001: ON 0010: Timer 1 0011: Timer 2 0100: PWM1 0101: PWM2 0110: PWM3 0111: PWM4 1000: PWM5 1001: PWM6 1010: PWM7 1011: PWM8 1100: PWM9 1101: PWM10 1110: DIR1 1111: DIR2
14	HS0_2	
13	HS0_1	
12	HS0_0	
11	HS15_3	High-side driver HS15 configuration HS15 config 0000: OFF (default) 0001: ON 0010: Timer 1 0011: Timer 2 0100: PWM1 0101: PWM2 0110: PWM3
10	HS15_1	
9	HS15_1	
8	HS15_0	

Bit	Name	Description
		0111: PWM4 1000: PWM5 1001: PWM6 1010: PWM7 1011: PWM8 1100: PWM9 1101: PWM10 1110: DIR1 1111: DIR2
7	HS14_3	High-side driver HS14 configuration HS14 config 0000: OFF (default) 0001: ON 0010: Timer 1 0011: Timer 2 0100: PWM1 0101: PWM2 0110: PWM3 0111: PWM4 1000: PWM5 1001: PWM6 1010: PWM7 1011: PWM8 1100: PWM9 1101: PWM10 1110: DIR1 1111: DIR2
6	HS14_2	
5	HS14_1	
4	HS14_0	
3	HS13_3	High-side driver HS13 configuration HS13 config 0000: OFF (default) 0001: ON 0010: Timer 1 0011: Timer 2 0100: PWM1 0101: PWM2 0110: PWM3 0111: PWM4 1000: PWM5 1001: PWM6 1010: PWM7 1011: PWM8 1100: PWM9 1101: PWM10 1110: DIR1 1111: DIR2
2	HS13_2	
1	HS13_1	
0	HS13_0	

6.4.11 Control register 15 (0x3C)

Table 102. Control register 15

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	HS12_3	HS12_2	HS12_1	HS12_0	HS11_3	HS11_2	HS11_1	HS11_0	HS10_3	HS10_2	HS10_1	HS10_0	HS9_3	HS9_2	HS9_1	HS9_0	HS8_3	HS8_2	HS8_1	HS8_0	HS7_3	HS7_2	HS7_1	HS7_0
Reset value	0																							
Access	RW																							

Table 103. CR15 signals description

Bit	Name	Description
23	HS12_3	High-side driver HS12 configuration HS12 config
22	HS12_2	
21	HS12_1	
20	HS12_0	0000: OFF (default) 0001: ON 0010: Timer 1 0011: Timer 2 0100: PWM1 0101: PWM2 0110: PWM3 0111: PWM4 1000: PWM5 1001: PWM6 1010: PWM7 1011: PWM8 1100: PWM9 1101: PWM10 1110: DIR1 1111: DIR2
19	HS11_3	High-side driver HS11 configuration HS11 config
18	HS11_2	
17	HS11_1	
16	HS11_0	0000: OFF (default) 0001: ON 0010: Timer 1 0011: Timer 2 0100: PWM1 0101: PWM2 0110: PWM3 0111: PWM4 1000: PWM5 1001: PWM6 1011: PWM8

Bit	Name	Description
		1100: PWM9 1101: PWM10 1110: DIR1 1111: DIR2
15	HS10_3	High-side driver HS10 configuration HS10 config 0000: OFF (default) 0001: ON 0010: Timer 1 0011: Timer 2 0100: PWM1 0101: PWM2 0110: PWM3 0111: PWM4 1000: PWM5 1001: PWM6 1010: PWM7 1011: PWM8 1100: PWM9 1101: PWM10 1110: DIR1 1111: DIR2
14	HS10_2	
13	HS10_1	
12	HS10_0	
11	HS9_3	High-side driver HS9 configuration HS9 config 0000: OFF (default) 0001: ON 0010: Timer 1 0011: Timer 2 0100: PWM1 0101: PWM2 0110: PWM3 0111: PWM4 1000: PWM5 1001: PWM6 1010: PWM7 1011: PWM8 1100: PWM9 1101: PWM10 1110: DIR1 1111: DIR2
10	HS9_2	
9	HS9_1	
8	HS9_0	
7	HS8_3	High-side driver HS8 configuration HS8 config 0000: OFF (default) 0001: ON 0010: Timer 1 0011: Timer 2
6	HS8_2	
5	HS8_1	
4	HS8_0	

Bit	Name	Description
		0100: PWM1 0101: PWM2 0110: PWM3 0111: PWM4 1000: PWM5 1001: PWM6 1010: PWM7 1011: PWM8 1100: PWM9 1101: PWM10 1110: DIR1 1111: DIR2
3	HS7_3	High-side driver HS7 configuration HS7 config 0000: OFF (default) 0001: ON 0010: Timer 1 0011: Timer 2 0100: PWM1 0101: PWM2 0110: PWM3 0111: PWM4 1000: PWM5 1001: PWM6 1010: PWM7 1011: PWM8 1100: PWM9 1101: PWM10 1110: DIR1 1111: DIR2
2	HS7_2	
1	HS7_1	
0	HS7_0	

6.4.12 Control register 16 (0x3D)

Table 104. Control register 16

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	VSREG_LOCK_ENA	VS_LOCK_ENA	VSREG_OV_SD_ENA	VSREG_UV_SD_ENA	VS_OV_SD_ENA	VS_UV_SD_ENA	HB6OCTH_1	HB6OCTH_0	HB5OCTH_1	HB5OCTH_0	HB1OCTH_1	HB1OCTH_0	HB6_HS	HB6_LS	HB5_HS	HB5_LS	HB4_HS	HB4_LS	HB3_HS	HB3_LS	HB2_HS	HB2_LS	HB1_HS	HB1_LS
Reset value	1						0																	
Access	RW																							

Table 105. CR16 signals description

Bit	Name	Description
23	VSREG_LOCK_ENA	Lockout of VSREG related outputs after VSREG over/undervoltage shutdown: 0 VSREG related outputs are turned ON automatically and status bits (VSREG_UV, VSREG_OV) are cleared 1 VSREG related outputs remain turned OFF until status bits (VSREG_UV, VSREG_OV) are cleared (default) <i>Note:</i> lockout is always disabled in standby modes in order to ensure supply of external contacts and detect wake-up conditions.
22	VS_LOCK_ENA	Lockout of V_S related outputs after V_S over/undervoltage shutdown: 0 V_S related outputs are turned ON automatically and status bits (VS_UV, VS_OV) are cleared 1 V_S related outputs remain turned OFF until status bits (VS_UV, VS_OV) are cleared (default) <i>Note:</i> lockout is always disabled in standby modes in order to ensure supply of external contacts and detect wake-up conditions.
21	VSREG_OV_SD_ENA	Shutdown of VSREG related outputs in case of VSREG overvoltage: 0 no shutdown of VSREG related outputs in case of VSREG overvoltage 1 shutdown of VSREG related outputs in case of VSREG overvoltage (default)
20	VSREG_UV_SD_ENA	Shutdown of VSREG related outputs in case of VSREG undervoltage: 0 no shutdown of VSREG related outputs in case of VSREG undervoltage 1 shutdown of VSREG related outputs in case of VSREG undervoltage (default) <i>Note:</i> in case of V1 undervoltage due to VSREG UV, the device enters failsafe mode and the related outputs are turned OFF.
19	VS_OV_SD_ENA	Shutdown of V_S related outputs in case of V_S overvoltage: 0 no shutdown of V_S related outputs in case of V_S overvoltage if charge pump output voltage is still sufficient (until CPLOW threshold is reached) 1 shutdown of V_S related outputs in case of V_S overvoltage (default)
18	VS_UV_SD_ENA	Shutdown of V_S related outputs in case of V_S undervoltage: 0 no shutdown of V_S related outputs in case of V_S UnderVoltage 1 shutdown of V_S related outputs in case of V_S UnderVoltage (default) <i>Note:</i> In case of V1 UnderVoltage due to VS UV, the device enters fail-safe mode and the related outputs are turned OFF.
17	HB6OCTH_1	Selectable overcurrent threshold on HB6: 00 I_{OC6th3}(default) 01 I_{OC6th1}
16	HB6OCTH_0	

Bit	Name	Description
		10 I _{OC6th2} 11 I _{OC6th3}
15	HB5OCTH_1	Selectable overcurrent threshold on HB5:
14	HB5OCTH_0	00 I _{OC5th3} (default) 01 I _{OC5th1} 10 I _{OC5th2} 11 I _{OC5th3}
13	HB1OCTH_1	Selectable overcurrent threshold on HB1:
12	HB1OCTH_0	00 I _{OC1th3} (default) 01 I _{OC1th1} 10 I _{OC1th2} 11 I _{OC1th3}
11	HB6_HS	HB6 high-side driver control: 0 HB6 HS is turned off (default) 1 HB6 HS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half bridge HB6 are switched on simultaneously
10	HB6_LS	HB6 low-side driver control: 0 HB6 LS is turned off (default) 1 HB6 LS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half bridge HB6 are switched on simultaneously
9	HB5_HS	HB5 high-side driver control: 0 HB5 HS is turned off (default) 1 HB5 HS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half bridge HB5 are switched on simultaneously
8	HB5_LS	HB5 low-side driver control: 0 HB5 LS is turned off (default) 1 HB5 LS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half bridge HB5 are switched on simultaneously
7	HB4_HS	HB4 high-side driver control: 0 HB4 HS is turned off (default) 1 HB4 HS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half bridge HB4 are switched on simultaneously
6	HB4_LS	HB4 low-side driver control: 0 HB4 LS is turned off (default) 1 HB4 LS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half bridge HB4 are switched on simultaneously
5	HB3_HS	HB3 high-side driver control: 0 HB3 HS is turned off (default) 1 HB3 HS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half bridge HB3 are switched on simultaneously
4	HB3_LS	HB3 low-side driver control: 0 HB3 LS is turned off (default)

Bit	Name	Description
		1 HB3 LS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half bridge HB3 are switched on simultaneously
3	HB2_HS	HB2 high-side driver control: 0 HB2 HS is turned off (default) 1 HB2 HS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half-bridge HB2 are switched on simultaneously
2	HB2_LS	HB2 low-side driver control: 0 HB2 LS is turned off (default) 1 HB2 LS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half bridge HB2 are switched on simultaneously
1	HB1_HS	HB1 high-side driver control: 0 HB1 HS is turned off (default) 1 HB1 HS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half bridge HB1 are switched on simultaneously
0	HB1_LS	HB1 low-side driver control: 0 HB1 LS is turned off (default) 1 HB1 LS is turned on An internal cross-current protection prevents, that both the low-side and high-side drivers of the half bridge HB1 are switched on simultaneously

6.4.13 Control register 17 (0x3E)

Table 106. Control register 17

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	RESERVED	RESERVED	T2_ON_2	T2_ON_1	T2_ON_0	T2_PER_2	T2_PER_1	T2_PER_0	RESERVED	RESERVED	T1_ON_2	T1_ON_1	T1_ON_0	T1_PER_2	T1_PER_1	T1_PER_0	V1_RESET_1	V1_RESET_0	RESERVED	WD_TIME	RESERVED	RESERVED	STBY_SEL	GO_STBY
Reset value	0																							
Access	R				RW				R					RW					R	RW		R		RW

Table 107. CR17 signals description

Bit	Name	Description
23:22	RESERVED	-
21	T2_ON_2	Configuration of Timer 2 ON-time T2 Config
20	T2_ON_1	
19	T2_ON_0	
		001 ton2
		010 ton3
		011 ton4
		100 ton5
		101 invalid setting; command is ignored and SPI INV CMD is set

Bit	Name	Description
		110 invalid setting; command is ignored and SPI INV CMD is set 111 invalid setting; command is ignored and SPI INV CMD is set <i>Note:</i> When the configuration of a timer is changed, the timer is automatically restarted using the new configuration.
18	T2_PER_2	Configuration of Timer 2 Period
17	T2_PER_1	T2 Period
16	T2_PER_0	000 T1 (default) 001 T2 010 T3 011 T4 100 T5 101 T6 110 T7 111 T8 <i>Note:</i> When the configuration of a timer is changed, the timer is automatically restarted using the new configuration.
15:14	RESERVED	-
13	T1_ON_2	Configuration of Timer 1 ON-time
12	T1_ON_1	T1 Config
11	T1_ON_0	000 ton1 (default) 001 ton2 010 ton3 011 ton4 100 ton5 101 invalid setting; command is ignored and SPI INV CMD is set 110 invalid setting; command is ignored and SPI INV CMD is set 111 invalid setting; command is ignored and SPI INV CMD is set <i>Note:</i> When the configuration of a timer is changed, the timer is automatically restarted using the new configuration.
10	T1_PER_2	Configuration of Timer 1 Period
9	T1_PER_1	T1 Period
8	T1_PER_0	000 T1 (default) 001 T2 010 T3 011 T4 100 T5 101 T6 110 T7 111 T8 <i>Note:</i> When the configuration of a timer is changed, the timer is automatically restarted using the new configuration.
7	V1_RESET_1	Voltage regulator V1 reset level
6	V1_RESET_0	V1 reset level 00 V _{RT4} (default) 01 V _{RT3} 10 V _{RT2}

Bit	Name	Description
		11 V _{RT1}
5	RESERVED	-
4	WD_TIME	Window Watchdog Trigger Time 0 TSW1 (default) 1 TSW2 Writing to WD_TIME_x is blocked unless WD_CONFIG_EN = 1
3	RESERVED	-
1	STBY_SEL	see Table 108. STBY_SEL and GO_STBY bits
0	GO_STBY	see Table 108. STBY_SEL and GO_STBY bits

Table 108. STBY_SEL and GO_STBY bits

STBY_SEL	GO_STBY	
1	1	Go to V1_Standby
0	1	Go to VBAT_Standby
1	0	No transition to standby
0	0	No transition to standby (default)

Note: After wake-up event, STBY_SEL and GO_STBY bits do not change the value remaining with the same setting.

6.4.14 Control register 18 (0x3F)

Table 109. Control register 18

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	
Bit name	EI2_PU	RESERVED	RESERVED	EI1_PU	EI2_EN	RESERVED	RESERVED	EI1_EN	EI2_FILT_1	EI2_FILT_0	RESERVED	RESERVED	RESERVED	RESERVED	EI1_FILT_1	EI1_FILT_0	HEN	CAN_REC_ONLY	CAN_ACT	LIN_WU_EN	CAN_WU_EN	TIME_NINT_WA KE_SEL	TIMER_NINT_ EN	TRIG	
Reset value	0				1				0											1		0			
Access	RW	R		RW		R		RW			R					RW									

Table 110. CR18 signals description

Bit	Name	Description
23	EI2_PU	External Interrupt 2: configuration of internal current source 0: pull-down (default) 1: pull-up <i>Note: the setting is valid only if input is configured as External Interrupt in CR1 (0x26).</i>
22:21	RESERVED	-
20	EI1_PU	External Interrupt 1: configuration of internal current source 0: pull-down (default) 1: pull-up
19	EI2_EN	External Interrupt 2 enable 0: EI2 disabled

Bit	Name	Description
		1: EI2 enabled (default) <i>Note: the setting is valid only if input is configured as External Interrupt in CR1 (0x26).</i>
18:17	RESERVED	-
16	EI1_EN	External Interrupt 2 enable 0: EI1 disabled 1: EI1 enabled (default)
15	EI2_FILT_1	External Interrupt 2: configuration of input filter
14	EI2_FILT_0	Input Filter Configuration 00 External Interrupt 2 monitored in static mode (filter time t_{WU_stat}) (default) 01 External Interrupt 2 monitored in cyclic mode with Timer2 (filter time: t_{WU_cyc} ; blanking time 80% of timer ON time) ⁽¹⁾ 10 External Interrupt 2 monitored in cyclic mode with Timer1 (filter time: t_{WU_cyc} ; blanking time 80% of timer ON time) ⁽¹⁾ 11 Invalid setting; command is ignored and SPI INV CMD id set <i>Note: EI2_FILT_[1:0] setting is only valid if input is configured as External Interrupt in CR1 (0x26).</i>
13:10	RESERVED	-
9	EI1_FILT_1	External Interrupt 1: configuration of input filter
8	EI1_FILT_0	Input Filter Configuration 00 External Interrupt 1 monitored in static mode (filter time t_{WU_stat}) (default) 01 External Interrupt 1 monitored in cyclic mode with Timer 2 (filter time: t_{WU_cyc} ; blanking time 80% of timer ON time) ⁽¹⁾ 10 External Interrupt 1 monitored in cyclic mode with Timer 1 (filter time: t_{WU_cyc} ; blanking time 80% of timer ON time) ⁽¹⁾ 11 Invalid setting; command is ignored and SPI INV CMD is set
7	HEN	Enable H-bridge 0: H-bridge disabled (default) 1: H-bridge enabled Refer to Section 2.4.14: H-bridge driver for details.
6	CAN_REC_ONLY	CAN receive only mode 0: CAN receive Only mode disabled (default) 1: CAN receive Only mode enabled (CAN Trx must be activated, see CAN_ACT bit)
5	CAN_ACT	CAN transceiver activation 0: CAN Trx low-power mode (default) 1: CAN Trx normal mode
4	LIN_WU_EN ⁽²⁾	Enable wake-up by LIN 0: disabled 1: enabled (default) <i>Note: the wake-up behavior is configurable in the CR1 (0x26).</i>
3	CAN_WU_EN ⁽²⁾	Enable wake-up by CAN 0: disabled 1: enabled (default) <i>Note: wake-up occurs at a wake-up event according to ISO 11898-2.</i>
2	TIME_NINT_WAKE_SEL	Select timer for periodic interrupt in standby modes 0: Timer 2 (default) 1: Timer 1

Bit	Name	Description
1	TIMER_NINT_EN	Enable timer interrupt in standby modes 0: Timer Interrupt disabled (default) 1: Timer Interrupt enabled V1_Standby mode: device wakes up and interrupt signal is generated at RXDL/NINT when programmable time-out has elapsed. VBAT_Standby mode: device wakes up after timer expiration and generates Nreset.
0	TRIG	Watchdog Trigger bit

1. Lower is the timer duration and major is the contribution of output $t_{d\ ON}$.
2. Either LIN or CAN must be enabled as wake-up source. Setting both bits 3 and 4 to '0' is an invalid setting. All wake-up sources are configured according to default setting; SPI Error Bit (SPIE) in Global Status Register is set.

6.5 Status registers

6.5.1 Status register 1 (0x01)

Table 111. Status register 1

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	TW_CL8	TW_CL7	TW_CL6	TW_CL5	TW_CL4	TW_CL3	TW_CL2	TW_CL1	RESERVED	RESERVED	HB6_LS_SC	HB5_LS_SC	HB4_LS_SC	HB3_LS_SC	HB2_LS_SC	HB1_LS_SC	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED
Access	R&C																							

Table 112. Status register 1 description

Bit	Name	Description
23	TW_CL8	Temperature warning cluster 8: '1' indicates cluster 8 has reached the thermal warning threshold Bit is latched until a "Read & Clear" command
22	TW_CL7	Temperature warning cluster 7: '1' indicates cluster 7 has reached the thermal warning threshold Bit is latched until a "Read & Clear" command
21	TW_CL6	Temperature warning cluster 6: '1' indicates cluster 6 has reached the thermal warning threshold Bit is latched until a "Read & Clear" command
20	TW_CL5	Temperature warning cluster 5: '1' indicates cluster 5 has reached the thermal warning threshold Bit is latched until a "Read & Clear" command
19	TW_CL4	Temperature warning cluster 4: '1' indicates cluster 4 has reached the thermal warning threshold Bit is latched until a "Read & Clear" command
18	TW_CL3	Temperature warning cluster 3: '1' indicates cluster 3 has reached the thermal warning threshold Bit is latched until a "Read & Clear" command
17	TW_CL2	Temperature warning cluster 2: '1' indicates cluster 2 has reached the thermal warning threshold Bit is latched until a "Read & Clear" command
16	TW_CL1	Temperature warning cluster 1: '1' indicates cluster 1 has reached the thermal warning threshold Bit is latched until a "Read & Clear" command
15:14	RESERVED	-
13	HB6_LS_SC	Short-circuit on HB6 low-side: "1" indicates short-circuit condition on LS of HB6 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
12	HB5_LS_SC	Short-circuit on HB5 low-side:

Bit	Name	Description
		"1" indicates short-circuit condition on LS of HB5 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
11	HB4_LS_SC	Short-circuit on HB4 low-side: "1" indicates short-circuit condition on LS of HB4 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
10	HB3_LS_SC	Short-circuit on HB3 low-side: "1" indicates short-circuit condition on LS of HB3 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
9	HB2_LS_SC	Short-circuit on HB2 low-side: "1" indicates short-circuit condition on LS of HB2 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
8	HB1_LS_SC	Short-circuit on HB1 low-side: "1" indicates short-circuit condition on LS of HB1 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
7:0	RESERVED	-

6.5.2 Status register 2 (0x02)

Table 113. Status register 2

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	TSD1_CL8	TSD1_CL7	TSD1_CL6	TSD1_CL5	TSD1_CL4	TSD1_CL3	TSD1_CL2	TSD1_CL1	RESERVED	RESERVED	HB6_HS_SC	HB5_HS_SC	HB4_HS_SC	HB3_HS_SC	HB2_HS_SC	HB1_HS_SC	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED
Access	R&C																							

Table 114. Status register 2 description

Bit	Name	Description
23	TSD1_CL8	Thermal shutdown of cluster 8 '1' indicates cluster 8 has reached the thermal shutdown threshold (TSD1) and the output cluster was shutdown Bit is latched until a "Read & Clear" command
22	TSD1_CL7	Thermal shutdown of cluster 7 '1' indicates cluster 7 has reached the thermal shutdown threshold (TSD1) and the output cluster was shutdown Bit is latched until a "Read & Clear" command
21	TSD1_CL6	Thermal shutdown of cluster 6 '1' indicates cluster 6 has reached the thermal shutdown threshold (TSD1) and the output cluster was shutdown Bit is latched until a "Read & Clear" command
20	TSD1_CL5	Thermal shutdown of cluster 5 '1' indicates cluster 5 has reached the thermal shutdown threshold (TSD1) and the output cluster was shutdown Bit is latched until a "Read & Clear" command
19	TSD1_CL4	Thermal shutdown of cluster 4 '1' indicates cluster 4 has reached the thermal shutdown threshold (TSD1) and the output cluster was shutdown

Bit	Name	Description
		Bit is latched until a "Read & Clear" command
18	TSD1_CL3	Thermal shutdown of cluster 3 '1' indicates luster 3 has reached the thermal shutdown threshold (TSD1) and the output cluster was shutdown Bit is latched until a "Read & Clear" command
17	TSD1_CL2	Thermal shutdown of cluster 2 '1' indicates cluster 2 has reached the thermal shutdown threshold (TSD1) and the output cluster was shutdown Bit is latched until a "Read & Clear" command
16	TSD1_CL1	Thermal shutdown of cluster 1 '1' indicates cluster 1 has reached the thermal shutdown threshold (TSD1) and the output cluster was shutdown Bit is latched until a "Read & Clear" command
15:14	RESERVED	-
13	HB6_HS_SC	Short-circuit on HB6 high-side '1' indicates short circuit condition on HS of HB6 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
12	HB5_HS_SC	Short-circuit on HB5 high-side '1' indicates short-circuit condition on HS of HB5 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
11	HB4_HS_SC	Short-circuit on HB4 high-side '1' indicates short circuit condition on HS of HB4 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
10	HB3_HS_SC	Short-circuit on HB3 high-side '1' indicates short circuit condition on HS of HB3 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
9	HB2_HS_SC	Short-circuit on HB2 high-side '1' indicates short-circuit condition on HS of HB2 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
8	HB1_HS_SC	Short-circuit on HB1 high-side '1' indicates short-circuit condition on HS of HB1 (second overcurrent threshold in overcurrent recovery mode) Bit is latched until a "Read & Clear" command
7:0	RESERVED	-

6.5.3 Status register 3 (0x03)

Table 115. Status register 3

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0		
Bit name	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	SGNDLOSS	IP_SUP_LOW	CAN_SUP_LOW	RESERVED	RESERVED	RESERVED		
Access	R&CR								R	R&CR								R	R&CR							

Table 116. Status register 3 description

Bit	Name	Description
23:6	RESERVED	-
5	SGNDLOSS	Loss of ground status bit '1' indicates that ground at SGND pin has been lost Bit is not latched
4	IP_SUP_LOW	Internal IP supply low warning threshold '1' indicates that Internal IP voltage supply (analog and/or digital) is less than 3V Bit is latched until a "Read & Clear" command
3	CAN_SUP_LOW	CAN supply low warning threshold '1' indicates that voltage at CAN supply pin reached the CAN supply low warning threshold $V_{CANSUP} < V_{CANSUP_{low}}$ Bit is latched until a "Read & Clear" command
2:0	RESERVED	-

6.5.4 Status register 4 (0x04)

Table 117. Status register 4

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	WD_TIMER_STA TE_1	WD_TIMER_STA TE_0	EI2_STATE	RESERVED	RESERVED	EI1_STATE	ECV_VNR	ECV_VHI	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED
Access	R&C			R			R&C																	

Table 118. Status register 4 description

Bit	Name	Description
23	WD_TIMER_STATE_1	Watchdog timer status
22	WD_TIMER_STATE_0	Status 00 0 - 33% 01 33 - 66% 11 66 - 100% 10 invalid configuration
21	EI2_STATE	State of EI2 input 0 input level is low 1 input level is high The bit shows the momentary status of EI2 and cannot be cleared ("live bit") <i>Note: the status is only valid if it has been configured as wake-up input in CR1 (0x26). Otherwise this bit is read as '0'</i>
20	RESERVED	-
18	EI1_STATE	State of EI1 input 0 input level is low 1 input level is high The bit shows the momentary status of EI1 and cannot be cleared ("live bit")

Bit	Name	Description
17	ECV_VNR	Electro chrome voltage not reached '1' indicates the electro chrome voltage is not reached. Bit is not latched
16	ECV_VHI	Electro chrome voltage high '1' indicates the electro chrome voltage is too high. Bit is not latched
15:0	RESERVED	-

6.5.5 Status register 5 (0x05)

Table 119. Status register 5

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	ECV_OL	GH_OL	HS0_OL	HS15_OL	HS14_OL	HS13_OL	HS12_OL	HS11_OL	HS10_OL	HS9_OL	HS8_OL	HS7_OL	HB6_LS_OL	HB6_HS_OL	HB5_LS_OL	HB5_HS_OL	HB4_LS_OL	HB4_HS_OL	HB3_LS_OL	HB3_HS_OL	HB2_LS_OL	HB2_HS_OL	HB1_LS_OL	HB1_HS_OL
Access	R&C																							

Table 120. Status register 5 description

Bit	Name	Description
23	ECV_OL	Electrochromic open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
22	GH_OL	'1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
21	HS0_OL	HS0 open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
20	HS15_OL	HS15 open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
19	HS14_OL	HS14 open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
18	HS13_OL	HS13 open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
17	HS12_OL	HS12 open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
16	HS11_OL	HS11 open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
15	HS10_OL	HS10 open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
14	HS9_OL	HS9 open-load

Bit	Name	Description
		'1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
13	HS8_OL	HS8 open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
12	HS7_OL	HS7 open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
11	HB6_LS_OL	HB6 low-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
10	HB6_HS_OL	HB6 high-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
9	HB5_LS_OL	HB5 low-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
8	HB5_HS_OL	HB5 high-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
7	HB4_LS_OL	HB4 low-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
6	HB4_HS_OL	HB4 high-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
5	HB3_LS_OL	HB3 low-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
4	HB3_HS_OL	HB3 high-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
3	HB2_LS_OL	HB2 low-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
2	HB2_HS_OL	HB2 high-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
1	HB1_LS_OL	HB1 low-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command
0	HB1_HS_OL	HS1 high-side open-load '1' indicates an open-load condition was detected at the output Bit is latched until a "Read & Clear" command

6.5.6 Status register 6 (0x06)

Table 121. Status register 6

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	ECV_OC	DSMON_HEAT	HS0_OC	HS15_OC	HS14_OC	HS13_OC	HS12_OC	HS11_OC	HS10_OC	HS9_OC	HS8_OC	HS7_OC	HB6_LS_OC	HB6_HS_OC	HB5_LS_OC	HB5_HS_OC	HB4_LS_OC	HB4_HS_OC	HB3_LS_OC	HB3_HS_OC	HB2_LS_OC	HB2_HS_OC	HB1_LS_OC	HB1_HS_OC
Access	R&C																							

Table 122. Status register 6 description

Bit	Name	Description
23	ECV_OC	Electro chrome overcurrent shutdown: '1' indicates the output was shut down due to overcurrent condition. Bit is latched until a "Read & Clear" command
22	DSMON_HEAT	Drain-source monitoring heater output '1' indicates a short-circuit condition was detected Bit is latched until a "Read & Clear" command
21	HS0_OC	HS0 overcurrent shutdown: '1' indicates the output was shutdown due to overcurrent condition. Bit is latched until a "Read & Clear" command
20	HS15_OC	HS15 overcurrent shutdown: '1' indicates the output was shutdown due to overcurrent condition Bit is latched until a "Read & Clear" command
19	HS14_OC	HS14 overcurrent shutdown: '1' indicates the output was shutdown due to overcurrent condition Bit is latched until a "Read & Clear" command
18	HS13_OC	HS13 overcurrent shutdown: '1' indicates the output was shutdown due to overcurrent condition Bit is latched until a "Read & Clear" command
17	HS12_OC	HS12 overcurrent shutdown: '1' indicates the output was shutdown due to overcurrent condition Bit is latched until a "Read & Clear" command
16	HS11_OC	HS11 overcurrent shutdown: '1' indicates the output was shutdown due to overcurrent condition Bit is latched until a "Read & Clear" command
15	HS10_OC	HS10 overcurrent shutdown: '1' indicates the output was shutdown due to overcurrent condition Bit is latched until a "Read & Clear" command
14	HS9_OC	HS9 overcurrent shutdown '1' indicates the output was shutdown due to overcurrent condition Bit is latched until a "Read & Clear" command
13	HS8_OC	HS8 overcurrent shutdown: '1' indicates the output was shutdown due to overcurrent condition Bit is latched until a "Read & Clear" command
12	HS7_OC	HS7 overcurrent shutdown:

Bit	Name	Description
		'1' indicates the output was shutdown due to overcurrent condition Bit is latched until a "Read & Clear" command
11	HB6_LS_OC	HB6 overcurrent shutdown:
10	HB6_HS_OC	'1' indicates the output was shutdown due to overcurrent condition. If overcurrent recovery is disabled (CR13: HB6_OCR = 0): Bit is set upon overcurrent condition and HB6 is turned off If overcurrent recovery is enabled (CR13: HB6_OCR = 1): in case of overcurrent condition this bit is not set. The HB6 goes into Overcurrent Recovery mode. Bit is latched until a "Read & Clear" command
9	HB5_LS_OC	HB5 overcurrent shutdown:
8	HB5_HS_OC	'1' indicates the output was shutdown due to overcurrent condition If overcurrent recovery is disabled (CR13: HB5_OCR = 0): bit is set upon overcurrent condition and HB5 is turned off If overcurrent recovery is enabled (CR13: HB5_OCR = 1): in case of overcurrent condition this bit is not set. The HB5 goes into overcurrent recovery mode Bit is latched until a "Read & Clear" command
7	HB4_LS_OC	HB4 overcurrent shutdown:
6	HB4_HS_OC	'1' indicates the output was shutdown due to overcurrent condition. If overcurrent recovery is disabled (CR13: HB4_OCR = 0): bit is set upon overcurrent condition and HB4 is turned off If overcurrent recovery is enabled (CR13: HB4_OCR = 1): In case of overcurrent condition this bit is not set. The HB4 goes into overcurrent recovery mode Bit is latched until a "Read & Clear" command
5	HB3_LS_OC	HB3 overcurrent shutdown:
4	HB3_HS_OC	'1' indicates the output was shutdown due to overcurrent condition If overcurrent recovery is disabled (CR13: HB3_OCR = 0): bit is set upon overcurrent condition and HB3 is turned off If overcurrent recovery is enabled (CR13: HB3_OCR = 1): in case of overcurrent condition this bit is not set. The HB3 goes into overcurrent recovery mode Bit is latched until a "Read & Clear" command
3	HB2_LS_OC	HB2 overcurrent shutdown:
2	HB2_HS_OC	'1' indicates the output was shutdown due to overcurrent condition If overcurrent recovery is disabled (CR13: HB2_OCR = 0): bit is set upon overcurrent condition and HB2 is turned off If overcurrent recovery is enabled (CR13: HB2_OCR = 1): in case of overcurrent condition this bit is not set. The HB2 goes into overcurrent recovery mode Bit is latched until a "Read & Clear" command
1	HB1_LS_OC	HB1 overcurrent shutdown:
0	HB1_HS_OC	'1' indicates the output was shutdown due to overcurrent condition If overcurrent recovery is disabled (CR13: HB1_OCR = 0): bit is set upon overcurrent condition and HB1 is turned off If overcurrent recovery is enabled (CR13: HB1_OCR = 1): in case of overcurrent condition this bit is not set. The HB1 goes into overcurrent recovery mode Bit is latched until a "Read & Clear" command

6.5.7 Status register 7 (0x07)

Table 123. Status register 7

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	LIN_PERM_DOM	LIN_TXD_DOM	LIN_PERM_REC	CAN_RXD_REC	CAN_PERM_REC	CAN_PERM_DOM	CAN_TXD_DOM	CANTO	DSMON_HS2	DSMON_HS1	DSMON_LS2	DSMON_LS1	SPI_INV_CMD	SPI_SCK_CNT	CP_LOW	TW	V2SC	V2FAIL	V1FAIL	RESERVED	VSREG_OV	VSREG_UV	VS_OV	VS_UV
Access	R&C																			R	R&C			

Table 124. Status register 7 description

Bit	Name	Description
23	LIN_PERM_DOM	LIN bus signal dominant timeout LIN bus signal is dominant for $t > T_{dom(bus)}$ Bit is latched until a "Read & Clear" command
22	LIN_TXD_DOM	LIN TXD signal dominant timeout TXDL pin is dominant for $t > t_{dom(TXDL)}$ The LIN transmitter is disabled until the bit is cleared. Bit is latched until a "Read & Clear" command
21	LIN_PERM_REC	LIN bus signal permanent recessive LIN bus signal does not follow TXDL within t_{LIN} The LIN transmitter is disabled until the bit is cleared. Bit is latched until a "Read & Clear" command
20	CAN_RXD_REC	CAN RXD signal permanent recessive RXDC has not followed TXDC for 4 times The CAN transmitter is disabled until the bit is cleared. Bit is latched until a "Read & Clear" command
19	CAN_PERM_REC	CAN bus signal permanent recessive CAN bus signal did not follow TXDC for 4 times The CAN transmitter is disabled until the bit is cleared. Bit is latched until a "Read & Clear" command
18	CAN_PERM_DOM	CAN bus signal permanent dominant CAN bus signal is dominant for $t > t_{CAN}$ Bit is latched until a "Read & Clear" command
17	CAN_TXD_DOM	CAN TXD signal permanent dominant TXDC pin is dominant for $t > t_{dom(TXDC)}$ The CAN transmitter is disabled until the bit is cleared. Bit is latched until a "Read & Clear" command
16	CANTO	CAN communication timeout Bit is set if there is no communication on the bus for $t > t_{Silence}$; CANTO indicates that there was a transition from BIAS ON to BIAS OFF Bit is latched until a "Read & Clear" command
15	DSMON_HS2	Drain-source monitoring HS2 '1' indicates a short-circuit or open-load condition was detected Bit is latched until a "Read & Clear" command
14	DSMON_HS1	Drain-source monitoring HS1 '1' indicates a short-circuit or open-load condition was detected Bit is latched until a "Read & Clear" command
13	DSMON_LS2	Drain-source monitoring LS2

Bit	Name	Description
		'1' indicates a short-circuit or open-load condition was detected Bit is latched until a "Read & Clear" command
12	DSMON_LS1	Drain-source monitoring LS1 '1' indicates a short-circuit or open-load condition was detected Bit is latched until a "Read & Clear" command
11	SPI_INV_CMD	Invalid SPI command '1' indicates one of the following conditions was detected: - Access to undefined address - Write operation to Status Register - DI stuck at '0' or '1' - CSN timeout - Parity failure - Invalid or undefined setting The SPI frame is ignored. Bit is latched until a "Read & Clear" command
10	SPI_SCK_CNT	SPI clock counter '1' indicates an SPI frame with wrong number of CLK cycles was detected Bit is latched until a "Read & Clear" command
9	CP_LOW	Charge pump voltage low '1' indicates that the charge pump voltage is too low Bit is latched until a "Read & Clear" command
8	TW	Thermal warning '1' indicates the temperature has reached the thermal warning threshold Bit is latched until a "Read & Clear" command
7	V2SC	V2 short-circuit detection '1' indicates a short-circuit to GND condition of V2 at turn on of the regulator ($V2 < V2_{fail}$ for $t > t_{v2short}$) Bit is latched until a "Read & Clear" command
6	V2FAIL	V2 failure detection '1' indicates a V2 fail event occurred since last readout ($V2 < V2_{fail}$ for $t > t_{v2fail}$) Bit is latched until a "Read & Clear" command
5	V1FAIL	V1 failure detection '1' indicates a V1 fail event occurred since last readout ($V1 < V1_{fail}$ for $t > t_{v1fail}$) Bit is latched until a "Read & Clear" command
4	RESERVED	-
3	VSREG_OV	Vsreg overvoltage '1' indicates the voltage at Vsreg has reached the overvoltage threshold Bit is latched until a "Read & Clear" command
2	VSREG_UV	Vsreg under voltage '1' indicates the voltage at Vsreg has reached the undervoltage threshold Bit is latched until a "Read & Clear" command
1	VS_OV	Vs overvoltage '1' indicates the voltage at Vs has reached the overvoltage threshold Bit is latched until a "Read & Clear" command
0	VS_UV	Vs under voltage '1' indicates the voltage at Vs has reached the undervoltage threshold Bit is latched until a "Read & Clear" command

6.5.8 Status register 8 (0x08)

Table 125. Status register 8

	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Bit name	EI2_WAKE	RESERVED	RESERVED	EI1_WAKE	WAKE_CAN	WAKE_LIN	WAKE_TIMER	DEBUG_ACTIVE	V1UV	V1_RESTART_2	V1_RESTART_1	V1_RESTART_0	WDFAIL_CNT_3	WDFAIL_CNT_2	WDFAIL_CNT_1	WDFAIL_CNT_0	DEVICE_STATE_1	DEVICE_STATE_0	TSD2	TSD1	FORCED_SLEE P_TSD2_V1SC	FORCED_SLEE P_WD	WDFAIL	VPOR
Access	R&C	R			R&C																			

Table 126. Status register 8 description

Bit	Name	Description
23	EI2_WAKE	External interrupt 2 wake-up '1' means wake-up from external interrupt 2 Bit is latched until a "Read & Clear" command
22:21	RESERVED	-
20	EI1_WAKE	External interrupt 1 wake-up '1' means wake-up from external interrupt Bit is latched until a "Read & Clear" command
19	WAKE_CAN	Wake-up from CAN '1' means wake-up from CAN Bit is latched until a "Read & Clear" command
18	WAKE_LIN	Wake-up from LIN '1' means wake-up from LIN Bit is latched until a "Read & Clear" command
17	WAKE_TIMER	Wake-up from timer '1' means wake-up from timer Bit is latched until a "Read & Clear" command
16	DEBUG_ACTIVE	Debug mode active '1' means debug mode Bit is latched until a "Read & Clear" command
15	V1UV	Voltage regulator V1 undervoltage '1' indicates undervoltage condition at voltage regulator V1 ($V1 < V_{RTx}$) Bit is latched until a "Read & Clear" command
14	V1_RESTART_2	Voltage regulator V1 restart Indicates the number of TSD2 events that caused a restart of voltage regulator V1 Bits cannot be cleared; the counter is cleared automatically if no additional TSD2 event occurs within 1 minute
13	V1_RESTART_1	
12	V1_RESTART_0	
11	WDFAIL_CNT_3	Watchdog failure counter Indicates number of subsequent watchdog failures Bits cannot be cleared; is cleared with a valid watchdog trigger
10	WDFAIL_CNT_2	
9	WDFAIL_CNT_1	
8	WDFAIL_CNT_0	
7	DEVICE_STATE_1	V2 short-circuit detection
6	DEVICE_STATE_0	Actual state 00 active mode after power-on or after "Read & Clear" command

Bit	Name	Description
		01 active mode after wake-up from V1_Standby mode (before "Read & Clear" command) 10 active mode after wake-up from VBAT_Standby mode (before "Read & Clear" command) 11 not used Bit is latched until a "Read & Clear" command; after a "Read & Clear access", the device state is updated
5	TSD2	Thermal shutdown 2 '1' indicates thermal shutdown 2 was reached Bit is latched until a "Read & Clear" command
4	TSD1	Thermal shutdown 1 '1' indicates thermal shutdown 1 was reached Bit is latched until a "Read & Clear" command
3	FORCED_SLEEP_TSD2_V1SC	Forced sleep TSD2 / V1 short-circuit Device entered forced sleep mode due to: - Thermal shutdown or - Short-circuit on V1 during startup Bit is latched until a "Read & Clear" command
2	FORCED_SLEEP_WD	Forced sleep watchdog Device entered forced sleep mode due to multiple watchdog failures Bit is latched until a "Read & Clear" command
1	WDFAIL	Watchdog failure Watchdog failure Bit is latched until a "Read & Clear" command
0	VPOR	Power-on Reset: VSREG Power-on Reset threshold (V_{POR}) reached Bit is latched until a "Read & Clear" command <i>Note: If VPOR is set after a cold startup, the device comes from a power on reset.</i>

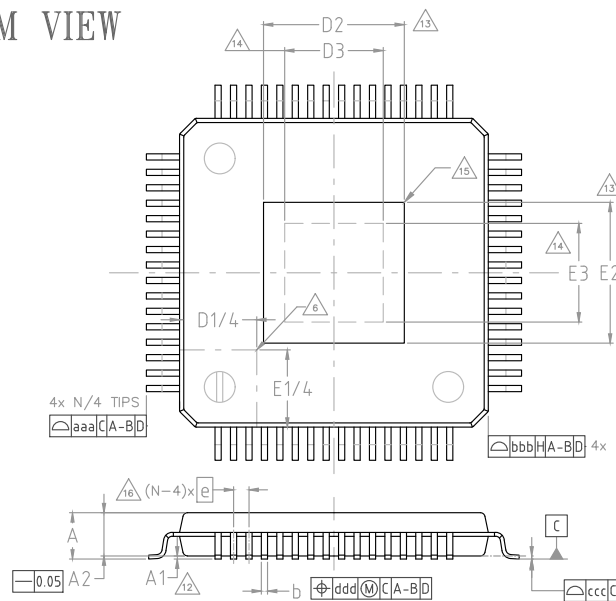
7 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

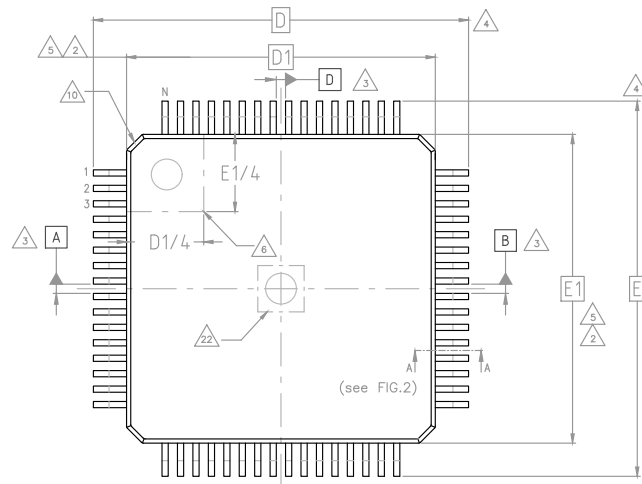
7.1 LQFP-64 package information

Figure 48. LQFP-64 package dimension

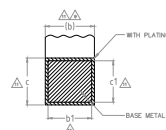
BOTTOM VIEW



TOP VIEW



SECTION B-B
NOT TO SCALE



SECTION A-A
NOT TO SCALE

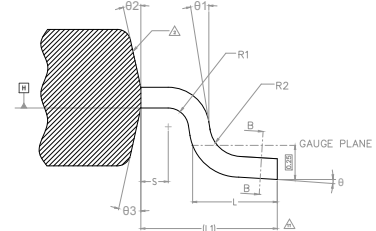
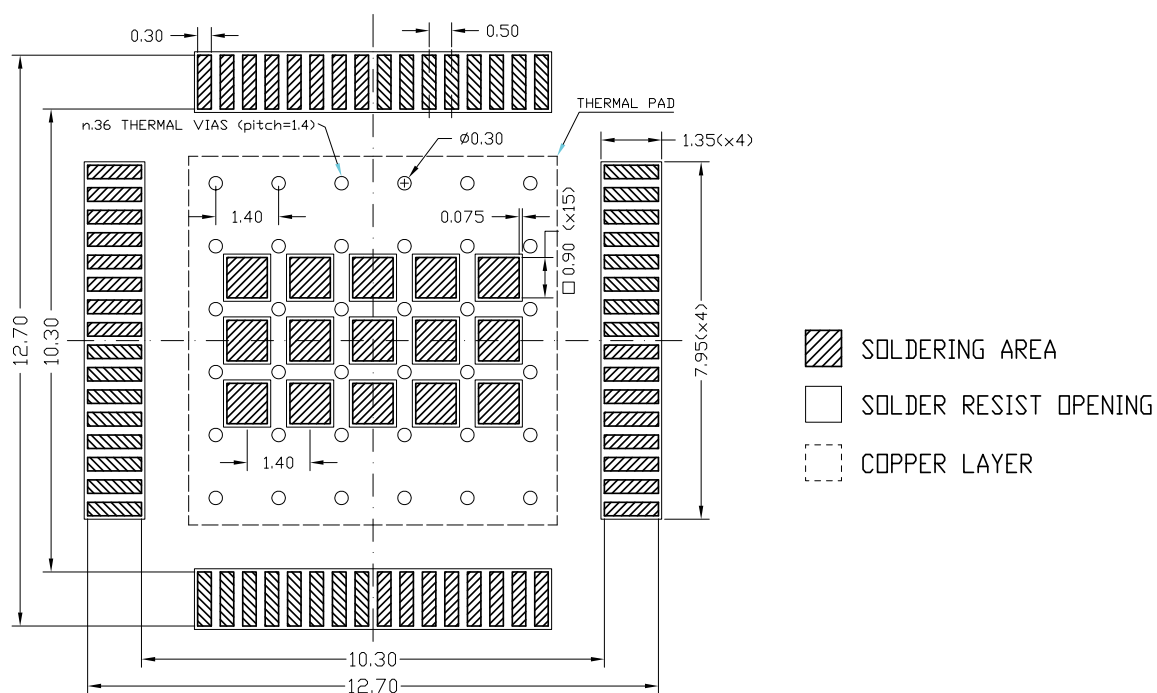


Table 127. LQFP-64 mechanical data

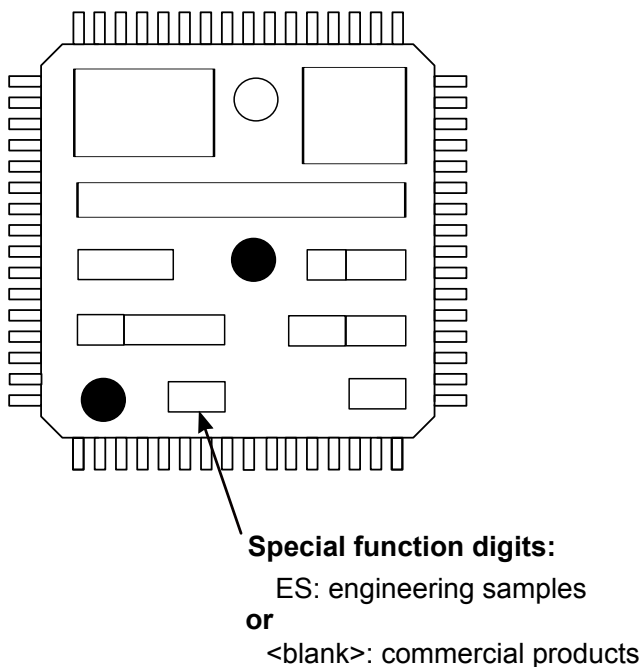
Symbol	Millimeters/degrees		
	Min.	Typ.	Max.
Θ	0°	3.5°	7°
$\Theta 1$	0°	-	-
$\Theta 2$	10°	12°	14°
$\Theta 3$	10°	12°	14°
A	-	-	1.60
A1	0.05	-	0.15
A2	1.35	1.40	1.45
b	0.17	0.22	0.27
b1	0.17	0.20	0.23
c	0.09	-	0.20
c1	0.09	-	0.16
D	12.00 BSC		
D1	10.00 BSC		
D2			6.85
D3	5.7		
e	0.50 BSC		
E	12.00 BSC		
E1	10.00 BSC		
E2			4.79
E3	3.3		
L	0.45	0.60	0.75
L1	1.00 REF		
N	64		
R1	0.08	-	-
R2	0.08	-	0.20
S	0.20	-	-
Tolerance of form and position			
aaa	0.20		
bbb	0.20		
ccc	0.08		
ddd	0.08		

Figure 49. LQFP-64 footprint



7.2 LQFP-64 marking information

Figure 50. LQFP-64 marking information



Parts marked as ES are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event ST is liable for the customer using any of these engineering samples in production. ST's quality department must be contacted to run a qualification activity before any decision to use these engineering samples.

Revision history

Table 128. Document revision history

Date	Revision	Changes
21-Feb-2022	1	Initial release.
19-May-2022	2	Updated: -Features; Minor changes.
01-Jun-2022	3	Updated: - <i>Device summary</i> on cover page; - <i>Figure 1. Block diagram</i> ; - <i>Table 37. CAN receiver input current</i> . Minor changes.
10-Oct-2022	4	Updated <i>Features</i> on cover page. Updated <i>Section 2.2 ESD protection</i> . Updated <i>Section 2.4.1 Supply, supply monitoring and current consumption</i> , <i>Section 2.4.4 Voltage regulator V1</i> , <i>Section 2.4.6 Reset output</i> , <i>Section 2.4.10 Outputs HB1-HB6, HS7-HS15, HS0, ECV, ECDR</i> , <i>Section 2.4.12 Output current thresholds</i> and <i>Section 2.4.17 Drain-source monitoring external heater Power MOSFET</i> . Updated <i>Section 3.2.5 Voltage regulator behavior</i> , <i>Section 3.5 Functional overview (truth table)</i> , <i>Section 3.9.1 Features</i> , <i>Section 3.10.1 Features</i> and <i>Section 3.12.2 VSREG supply failure</i> . Updated <i>Section 5 Application circuit</i> . Added "Reset value" in <i>Section 6.4 Control registers</i> . Minor text changes.
16-Nov-2022	5	Updated <i>Device summary</i> and <i>Features</i> on cover page. Updated <i>Table 2</i> , <i>Table 6</i> , <i>Table 7</i> , <i>Table 10</i> , <i>Table 11</i> , <i>Table 12</i> , <i>Table 14</i> , <i>Table 18</i> , <i>Table 22</i> , <i>Table 28</i> , <i>Table 36</i> and <i>Table 48</i> . Updated <i>Section 3.3.5 VBAT_Standby mode</i> , <i>Table 54</i> , <i>Section 3.10.1 Features</i> , <i>Section 3.15 Charge pump</i> , <i>Section 3.21 PWM mode of the power outputs</i> and <i>Table 60</i> . Updated <i>Table 82</i> , <i>Table 84</i> , <i>Table 90</i> , <i>Table 99</i> , <i>Table 109</i> , <i>Table 112</i> and <i>Table 125</i> . Minor text changes.
04-Apr-2023	6	Updated <i>Device summary</i> and <i>Description</i> on cover page. Updated <i>Figure 1. Block diagram</i> . Updated <i>Table 13</i> and <i>Table 21</i> . Updated <i>Section 3.3.3 V1_Standby mode</i> , <i>Section 3.3.5 VBAT_Standby mode</i> , <i>Section 3.10.2 CAN transceiver operating modes</i> , <i>Table 58</i> and <i>Figure 40</i> . Updated <i>Table 80</i> , <i>Table 82</i> , <i>Table 99</i> and <i>Table 114</i> . Minor text changes.
03-May-2023	7	Updated <i>Section 3.1 Supply VS</i> , <i>VSREG</i> , <i>Section 5 Application circuit</i> , <i>Table 82. CR1 signals description</i> and <i>Table 99. CR12 signals description</i> .
25-Jul-2023	8	Updated <i>Table 5</i> , <i>Table 7</i> , <i>Table 11</i> , <i>Table 14</i> , <i>Table 17</i> , <i>Table 37</i> , <i>Table 41</i> and <i>Table 44</i> . Updated <i>Section 3.3.5 VBAT_Standby mode</i> , <i>Section 3.4 Wake-up from standby modes</i> and <i>Section 3.7.1 Temporary failures</i> . Minor text changes.
19-Oct-2023	9	Updated <i>Table 129. LQFP-64 mechanical data</i> .
14-Feb-2024	10	Updated <i>Table 7. Supply, supply monitoring and current consumption</i> and <i>Figure 4. Watchdog timing</i> . Updated <i>Figure 49. LQFP-64 footprint</i> .

Date	Revision	Changes
09-Oct-2024	11	Updated Section 3.2.2: Voltage regulator V2, Section 3.9.1: Features, Section 3.10.3: CAN error handling, Table 11. Voltage regulator 2 and Table 78. Control registers overview. Minor text changes in Section Features, Section 3.7.1: Temporary failures and Figure 23. Transceiver state diagram. Removed Section 6.4.5 Control register 4bis (CR4bis, 0x31).

Contents

1	Block diagram and pin description	3
2	Electrical specifications	7
2.1	Absolute maximum ratings	7
2.2	ESD protection	9
2.3	Thermal data	9
2.3.1	LQFP64 thermal data	10
2.3.2	L99DZ300G thermal profiles	10
2.4	Electrical characteristics	11
2.4.1	Supply, supply monitoring and current consumption	12
2.4.2	Oscillator	13
2.4.3	Power-on Reset (V_{SREG})	14
2.4.4	Voltage regulator V1	14
2.4.5	Voltage regulator V2	15
2.4.6	Reset output	16
2.4.7	Watchdog	16
2.4.8	Current monitor output	18
2.4.9	Charge pump	19
2.4.10	Outputs HB1-HB6, HS7-HS15, HS0, ECV, ECDR	20
2.4.11	Power outputs switching times	21
2.4.12	Output current thresholds	23
2.4.13	Heater	26
2.4.14	H-bridge driver	26
2.4.15	Gate drivers for the external Power MOSFET switching times	27
2.4.16	Drain-source monitoring external H-bridge	31
2.4.17	Drain-source monitoring external heater Power MOSFET	31
2.4.18	Open-load monitoring external H-bridge	32
2.4.19	Open-load monitoring external heater Power MOSFET	32
2.4.20	Electrochrome mirror driver	32
2.4.21	External interrupts (EI1, EI2)	33
2.4.22	CAN FD transceiver	34
2.4.23	LIN transceiver	40
2.4.24	SPI	43
2.4.25	Inputs DIRH, PWMH, PWM4-5, PWM1-6, DIR1, DIR2	48
2.4.26	Debug input pin	48
2.4.27	Interrupt output	48
2.4.28	Timer1 and Timer2	49

2.4.29	SGND loss comparator	49
3	Functional description	50
3.1	Supply VS, VSREG	50
3.2	Voltage regulators	50
3.2.1	Voltage regulator V1	50
3.2.2	Voltage regulator V2	50
3.2.3	Voltage regulator failure	50
3.2.4	Short to ground detection	50
3.2.5	Voltage regulator behavior	51
3.3	Operating modes	52
3.3.1	Active mode	52
3.3.2	Debug mode	52
3.3.3	V1_Standby mode	52
3.3.4	Interrupt	52
3.3.5	VBAT_Standby mode	52
3.4	Wake-up from standby modes	53
3.4.1	External interrupts	53
3.5	Functional overview (truth table)	55
3.6	Configurable window watchdog	56
3.6.1	Change watchdog timing	58
3.7	Fail-safe mode	58
3.7.1	Temporary failures	58
3.7.2	Non-recoverable failures - entering force VBAT standby mode	59
3.8	Reset output	60
3.9	LIN bus interface	61
3.9.1	Features	61
3.9.2	Error handling	61
3.9.3	Wake up from standby modes	61
3.10	CAN FD bus transceiver	62
3.10.1	Features	62
3.10.2	CAN transceiver operating modes	63
3.10.3	CAN error handling	63
3.10.4	Wake up by CAN	64
3.10.5	CAN receive only mode	65
3.10.6	CAN looping mode	65
3.11	Serial peripheral interface (ST SPI standard)	65
3.12	Power supply fail	66

3.12.1	VS supply failure	66
3.12.2	VSREG supply failure	67
3.13	Temperature warning and thermal shutdown	68
3.14	Power outputs HB1 .. HB6, HS7 .. HS15 and HS0	69
3.15	Charge pump	70
3.16	Inductive loads	70
3.17	Open-load detection	70
3.18	Overcurrent detection	70
3.19	Short-circuit current detection	72
3.20	Current monitor	73
3.21	PWM mode of the power outputs	73
3.22	Cross current protection	74
3.23	Overcurrent recovery mode	74
3.24	H-bridge control	74
3.25	H-bridge driver slew rate control	75
3.26	Resistive low	76
3.27	Short-circuit detection/ drain-source monitoring	77
3.28	H-bridge monitoring in OFF mode	77
3.29	Programmable cross current solution	80
3.30	Heater Power MOSFET driver	80
3.31	Control of electrochromic glass	82
3.32	Temperature warning and shutdown	83
3.33	Digital thermal clusters	83
4	Serial peripheral interface (SPI)	86
4.1	ST SPI 4.0	86
4.1.1	Physical layer	87
4.2	Signal description	87
4.2.1	Clock and data characteristics	87
4.2.2	Communication protocol	88
4.2.3	Address definition	90
4.2.4	Protocol failure detection	95
5	Application circuit	97
6	SPI Registers	98
6.1	Global status byte (GSB)	98
6.2	Control registers overview	101
6.3	Status register overview	104

6.4	Control registers	106
6.4.1	Control register 1 (CR1, 0x26)	106
6.4.2	Control register 2 (CR2, 0x27)	108
6.4.3	Control register 3 (CR3, 0x2C)	109
6.4.4	Control register 4 (CR4, 0x30)	110
6.4.5	Control register 5-9 (from CR5 to CR9, [0x32, 0x36])	112
6.4.6	Control register 10 (0x37)	113
6.4.7	Control register 11 (0x38)	114
6.4.8	Control register 12 (0x39)	115
6.4.9	Control register 13 (0x3A)	117
6.4.10	Control register 14 (0x3B)	119
6.4.11	Control register 15 (0x3C)	121
6.4.12	Control register 16 (0x3D)	124
6.4.13	Control register 17 (0x3E)	126
6.4.14	Control register 18 (0x3F)	128
6.5	Status registers	131
6.5.1	Status register 1 (0x01)	131
6.5.2	Status register 2 (0x02)	132
6.5.3	Status register 3 (0x03)	133
6.5.4	Status register 4 (0x04)	134
6.5.5	Status register 5 (0x05)	135
6.5.6	Status register 6 (0x06)	137
6.5.7	Status register 7 (0x07)	139
6.5.8	Status register 8 (0x08)	141
7	Package information	143
7.1	LQFP-64 package information	143
7.2	LQFP-64 marking information	146
	Revision history	147

List of tables

Table 1.	Pin function	4
Table 2.	Absolute maximum ratings	7
Table 3.	ESD protection	9
Table 4.	Operation junction temperature	9
Table 5.	Temperature warning and thermal shutdown	9
Table 6.	Electrical parameters numbering	12
Table 7.	Supply monitoring and current consumption	12
Table 8.	Oscillator	13
Table 9.	Power-on Reset.	14
Table 10.	Voltage regulator 1.	14
Table 11.	Voltage regulator 2.	15
Table 12.	Reset output	16
Table 13.	Watchdog	16
Table 14.	Current monitor output	18
Table 15.	Charge pump	19
Table 16.	Outputs HB1–HB6, HS7–HS15, HS0, ECV, ECDR.	20
Table 17.	Power outputs switching times.	21
Table 18.	Output current thresholds	23
Table 19.	Heater	26
Table 20.	H-bridge driver.	26
Table 21.	Gate drivers for external Power MOSFET switching times	27
Table 22.	Drain-source monitoring external H-bridge	31
Table 23.	Drain-source monitoring external heater Power MOSFET	31
Table 24.	Open-load monitoring external H-bridge	32
Table 25.	Open-load monitoring external heater Power MOSFET	32
Table 26.	Electrochrome mirror driver	32
Table 27.	External interrupts	33
Table 28.	CAN communication operating range	34
Table 29.	CAN transmit data input: pin TXDC	35
Table 30.	CAN receive data output: pin RXDC	35
Table 31.	CAN transmitter dominant output characteristics	35
Table 32.	CAN transmitter recessive output characteristics, CAN normal mode	36
Table 33.	CAN receiver input characteristics during CAN normal mode	37
Table 34.	CAN receiver input characteristics during CAN low-power mode, biasing inactive.	37
Table 35.	CAN receiver input resistance	37
Table 36.	CAN transceiver delay	38
Table 37.	CAN receiver input current	40
Table 38.	Biasing control timings	40
Table 39.	LIN transmit data input: pin TXD	40
Table 40.	LIN receive data output: pin RXD	41
Table 41.	LIN transmitter and receiver: pin LIN.	41
Table 42.	LIN transceiver timing.	42
Table 43.	Input: CSN	43
Table 44.	Inputs: CLK, DI	43
Table 45.	DI, CLK and CSN timing	44
Table 46.	Output DO	44
Table 47.	DO timing	44
Table 48.	CSN timing	45
Table 49.	Inputs: DIRH, PWMH, PWM4-5, PWM1-6, DIR1, DIR2	48
Table 50.	Debug input	48
Table 51.	Interrupt output	48
Table 52.	Timer 1 and timer 2 values	49
Table 53.	SGND loss comparator.	49

Table 54.	Wake-up sources	53
Table 55.	Truth table	55
Table 56.	Temporary failures conditions	59
Table 57.	Non recoverable failures conditions	60
Table 58.	H-bridge control truth table	74
Table 59.	H-bridge monitoring in off mode	80
Table 60.	Heater Power MOSFET control truth table	82
Table 61.	Digital thermal clusters definition	85
Table 62.	Operation codes	88
Table 63.	Global status byte	90
Table 64.	Address definition - device application access	90
Table 65.	Address definition - device information read access	90
Table 66.	Address definition - RAM access	91
Table 67.	Address definition - ROM access	91
Table 68.	L99DZ300G information register map	92
Table 69.	SPI mode registers	92
Table 70.	Burst read bit	93
Table 71.	SPI data length	93
Table 72.	Data consistency check (parity-check)	93
Table 73.	WD type/timing	93
Table 74.	WD bit position	95
Table 75.	Global status byte (GSB)	98
Table 76.	Global status byte (GSB) description	98
Table 77.	Global control registers	101
Table 78.	Control registers overview	101
Table 79.	Global status registers	104
Table 80.	Status registers overview	104
Table 81.	Control register 1	106
Table 82.	CR1 signals description	106
Table 83.	Control register 2	108
Table 84.	CR2 signals description	108
Table 85.	Control register 3	109
Table 86.	CR3 signals description	109
Table 87.	Control register 4	110
Table 88.	CR4 signals description	110
Table 89.	Control register 5-9	112
Table 90.	From CR5 to CR9 signals description	112
Table 91.	Duty cycle coding for channel PWMx(y)	113
Table 92.	Control register 10	113
Table 93.	CR10 signals description	113
Table 94.	Control register 11	114
Table 95.	CR11 signals description	114
Table 96.	Control register 12	115
Table 97.	CR12 signals description	115
Table 98.	Control register 13	117
Table 99.	CR13 signals description	117
Table 100.	Control register 14	119
Table 101.	CR14 signals description	119
Table 102.	Control register 15	121
Table 103.	CR15 signals description	121
Table 104.	Control register 16	124
Table 105.	CR16 signals description	124
Table 106.	Control register 17	126
Table 107.	CR17 signals description	126
Table 108.	STBY_SEL and GO_STBY bits	128

Table 109.	Control register 18	128
Table 110.	CR18 signals description	128
Table 111.	Status register 1	131
Table 112.	Status register 1 description	131
Table 113.	Status register 2	132
Table 114.	Status register 2 description	132
Table 115.	Status register 3	133
Table 116.	Status register 3 description	134
Table 117.	Status register 4	134
Table 118.	Status register 4 description	134
Table 119.	Status register 5	135
Table 120.	Status register 5 description	135
Table 121.	Status register 6	137
Table 122.	Status register 6 description	137
Table 123.	Status register 7	139
Table 124.	Status register 7 description	139
Table 125.	Status register 8	141
Table 126.	Status register 8 description	141
Table 127.	LQFP-64 mechanical data.	144
Table 128.	Document revision history	147

List of figures

Figure 1.	Block diagram	3
Figure 2.	Pin connection (top view)	4
Figure 3.	LQFP64 printed circuit board	11
Figure 4.	Watchdog timing	17
Figure 5.	Watchdog early, late and safe windows	18
Figure 6.	H-Driver delay times	29
Figure 7.	IGHxr range (a)	30
Figure 8.	IGHxf range (b)	30
Figure 9.	LIN transmit, receive timing	43
Figure 10.	SPI transfer timing diagram	45
Figure 11.	SPI input timing	45
Figure 12.	SPI output timing	46
Figure 13.	SPI CSN output timing	47
Figure 14.	SPI - CSN low to high transition and global status bit access	47
Figure 15.	Voltage regulator behavior and diagnosis during supply voltage ramp-up/ramp-down conditions	51
Figure 16.	Cyclic monitoring: the external contacts are supplied periodically by the internal timer	54
Figure 17.	Main operating modes	56
Figure 18.	Watchdog in normal operating mode (no errors)	57
Figure 19.	Watchdog with error conditions	57
Figure 20.	Watchdog in debug mode	58
Figure 21.	NRESET pin	60
Figure 22.	Wake-up behavior according to LIN 2.2a	62
Figure 23.	Transceiver state diagram	63
Figure 24.	CAN wake-up capabilities	65
Figure 25.	Thermal shutdown protection and diagnosis	68
Figure 26.	Charge pump low filtering and startup implementation	70
Figure 27.	Overcurrent threshold reached during blanking time	71
Figure 28.	OC threshold reached after blanking time (OC filter time is reduced by the blanking time)	71
Figure 29.	Half bridges in PWM mode: filter time is t_{FOC_PWM}	72
Figure 30.	Half bridge short-circuit detection in latch mode (overcurrent recovery disabled) and OCR mode (overcurrent recovery enabled)	72
Figure 31.	Half bridge short-circuit detection in PWM mode: filter time is t_{FSC_PWM}	73
Figure 32.	Half bridge GSHx slope	76
Figure 33.	H-bridge diagnosis	77
Figure 34.	H-bridge off state diagnosis (no open-load detected)	78
Figure 35.	H-bridge off state diagnosis (open-load detected)	78
Figure 36.	H-bridge off state diagnosis (short to ground detected)	79
Figure 37.	H-bridge off state diagnosis (short to Vs detected)	79
Figure 38.	PWMH cross current protection time implementation	80
Figure 39.	Heater Power MOSFET open-load and short-circuit to GND detection	81
Figure 40.	Electrochrome control block	83
Figure 41.	Digital thermal clusters identification	84
Figure 42.	SPI pin description	87
Figure 43.	SPI signal description	87
Figure 44.	SDI frame	88
Figure 45.	SDO frame	89
Figure 46.	Window watchdog operation	94
Figure 47.	Application circuit	97
Figure 48.	LQFP-64 package dimension	143
Figure 49.	LQFP-64 footprint	145
Figure 50.	LQFP-64 marking information	146

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